



Cardiac Rhythm Disease Management

Product Performance Report

Important Patient Management Information for Physicians

2012

First Edition – Issue 66

A Message from the Vice President

Dear Customer,

At Medtronic, product quality and reliability have been and will continue to be a priority. For over 28 years, Medtronic has compiled and produced product performance reports with one primary goal, to provide you with the product information you need to best care for your patients.

Our commitment to you is best expressed in Medtronic's mission: "To strive without reserve for the greatest possible reliability and quality in our products; to be the unsurpassed standard of comparison and to be recognized as a company of dedication, honesty, integrity, and service." To this end, we continually explore new ways to expand, improve, and learn from our product performance systems and measures.

Our quality goals cannot be reached alone. We welcome your collaboration, insight, and recommendations. Please contact our Technical Services Department at 1 (800) 723-4636 with your feedback comments and any questions.

Your participation and assistance in returning explanted products are also critical. Returned products are tested and evaluated so that we can fully measure the performance of our devices. Please refer to the instructions on the next page for assistance in returning products to the Medtronic CRDM Returned Product Analysis Laboratory.

As we constantly strive to exceed your expectations, we thank you for your dedication to improving and saving the lives of those suffering from cardiac rhythm disorders.

With appreciation and warm regards,

Tim Samsel

Vice President, Quality and Regulatory

Medtronic Cardiac Rhythm Disease Management

Medtronic, Inc.

Contact Information

We invite our customers to use these telephone numbers to call with suggestions, inquiries, or specific problems related to our products.

US Technical Services Department

Phone: 1 (800) 723-4636 (Tachy)

1 (800) 505-4636 (Brady)

1 (800) 824-2362 Fax:

www.medtronic.com/corporate/contact.jsp

International Technical Centers

Europe (Heerlen NL) +31-45-566-8844 Japan (Tokyo) +81-3-5753-4116

For questions related to this CRDM Product Performance Report, please call US Technical Services at the number above, or write to:

Jia Guo, Ph.D. Medtronic, Inc. 8200 Coral Sea Street NE MS MVN61 Mounds View, MN 55112 USA

Email: jia.guo@medtronic.com

For questions related to returning explanted product or returning product that shows signs of malfunction, please contact:

Outside the United States:

Your Medtronic representative or international technical center at the number above.

Within the United States:

Your Medtronic representative or

CRDM Returned Product Analysis Laboratory

1 (800) 328-2518, ext. 44800 crdm.returned product @med tronic.comEmail:

Editorial Staff

Independent Physician Quality Panel

Steven J. Compton, MD, Anchorage, AK John P. DiMarco, MD, PhD, Charlottesville, VA Kevin Hackett, MD, Columbus, OH R. Hardwin Mead, MD, Palo Alto, CA N.A. Mark Estes, MD, Boston, MA

Editor

Tim Samsel, Vice President, CRDM Quality and Regulatory

Jia Guo, Ph.D. Senior Statistician ${\it Customer Quality Engineering Services, CRDM}$ Becky DeBus, Senior Principal Clinical IT Developer, Medtronic Clinical Research Institute

Acknowledgement

Mary Learmont, Principal Reliability Engineer, Released Product Reliability Device Vigilance, CRDM Sherice Nelson, Communications Specialist, Marketing Communications Christine Altenhofen-Sonner, Graphic Production, CRDM

Carol Spooner, Proofreader, CRDM

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2012 First Edition

Leads data

Issue 66

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This report is available online at

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ProductPerformance

CRDM Product Performance Report

Introduction 1
Method for Estimating CRT, ICD, and IPG Device Performance 6

CRT Cardiac Resynchronization Therapy 10

CRT Survival Summary 19 CRT Reference Chart 22

ICD Implantable Cardioverter Defibrillators 24

ICD Survival Summary 36 ICD Reference Chart 40 ICD Connector Styles 42

IPG Implantable Pulse Generators 43

IPG Survival Summary 71 IPG Reference Chart 78

Leads

Method for Estimating Lead Performance 81

Left-Heart Leads 86

Lead Survival Summary 90 US Returned Product Analysis Summary 90 US Reports of Acute Lead Observations 90 Reference Chart 91

Defibrillation Leads 92

Lead Survival Summary 100 US Returned Product Analysis Summary 101 US Reports of Acute Lead Observations 101 Reference Chart 102

Pacing Leads 103

Lead Survival Summary 126
US Returned Product Analysis Summary 129
US Reports of Acute Lead Observations 130
Reference Chart 131

Epi/Myocardial Pacing Leads 133

Lead Survival Summary 135 US Returned Product Analysis Summary 136 US Reports of Acute Lead Observations 136 Reference Chart 136

VDD Single Pass Pacing Leads 137

Lead Survival Summary 138
US Returned Product Analysis Summary 138
US Reports of Acute Lead Observations 138
Reference Chart 138

ICD and CRT-D Charge Time Performance 139

Advisories 147

(in order of communication date, from most recent to oldest)

Performance Notes 159

Dual Chamber Pacemakers with Measurement Lock-up ERI
Kappa 600, 700, 800, 900, EnPulse, Adapta, Versa, Sensia, Relia,
and Vitatron Models E50A1, E60A1, and G70A1 159
Helix Retraction of the Sprint Quattro Secure S 6935 and
Sprint Quattro Secure 6947 160

Potential Malfunction of CRT, ICD, and IPG Products due to Anomalies in MOSFET Integrated Circuit Technology 161

Clinical Management of VCM near Elective Replacement 162
Ensuring the Accuracy of Battery Longevity Estimates 163
AT500 Pacing System Follow-Up Protocol 164
Insertion of the Lead into the Device 165
GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior 166
General Follow-Up and Replacement of ICD Leads 167

Clinical Management of High-Voltage Lead System Oversensing 168
Tests and Observations for Clinical Assessment of Chronic Pacing Leads 169

February 2012

Introduction

All product performance reports are not created equal. For 28 years, Medtronic has monitored performance via both returned product analysis and multicenter clinical studies.

This Product Performance Report (PPR) presents device survival estimates, advisory summaries, performance notes, and other information pertinent to assessing the performance of Medtronic implantable pulse generators (IPGs), implantable cardioverter defibrillators (ICDs), cardiac resynchronization therapy (CRT) devices, and implantable pacing and defibrillation leads.

This Product Performance Report has been prepared in accordance with International Standard ISO 5841- 2:2000(E).

The survival estimates provided in this report are considered to be representative of worldwide performance.

Survival Estimates

Medtronic, like other companies, monitors CRT, ICD, and IPG device performance using returned product analysis. We also monitor CRT, ICD, and IPG device performance using an active multicenter clinical study.

Returned product analysis is a passive approach to assessing product performance. This approach provides a suitable measure of product performance only when a significant number of explanted products are returned to the manufacturer. Returned product analysis provides a measure of hardware performance, but not necessarily the total clinical performance (e.g., the incidence of complications such as infection, erosion, muscle stimulation, etc. are not estimated).

The survival estimates provided in this report for CRT, ICD, and IPG devices are based on returned product analysis. This approach is suitable because a significant number of explanted generators are returned for analysis.

Lead performance is monitored differently. In contrast to CRT, ICD, and IPG devices, a very small percentage of leads are returned to the manufacturer due to the difficulty of explanting them. For leads, an active clinical study provides more accurate survival estimates compared to estimates based solely on returned product analysis.

Survival estimates for leads are based on clinical observations recorded via Medtronic CRDM's System Longevity Study. This multicenter clinical study is designed to record clinical observations representative of the total clinical experience. Therefore, the lead survival estimates include both lead hardware failure and lead-related medical complications, and do not differentiate a lead hardware failure from other clinical events such as exit block, perforation, dislodgement, or concurrent pulse generator failure.

The actuarial life table method is applied to the data collected for CRT, ICD, and IPG devices and leads to provide the survival estimates included in this report. A general introduction to understanding this method of survival analysis is given later in this introduction.

ICD Charge Times

Since May 2000, Medtronic has provided important information on charge time performance of ICDs. The information provided in this report shows how ICD charge time can vary during the time a device is implanted. The information is presented in graphical format showing charge time as a function of implant time. The data for charge times are collected from devices enrolled in the System Longevity Study.

Advisory Summaries

This Product Performance Report includes summaries of all advisories applicable to the performance of the products included in the report. An advisory is added to the report when any product affected by the advisory remains in service and at risk of experiencing the behavior described in the advisory. The advisory will remain in the report until Medtronic estimates no product affected by the advisory remains active, or the risk of experiencing the behavior described in the advisory has passed.

For most advisories, the products subject to the advisory retain essentially the same survival probability as the products of the same model(s) not affected by the advisory. For those advisories where the survival probabilities of the affected and non-affected populations do differ significantly, Medtronic will provide separate survival data for each population. The separate survival data will remain in the report until Medtronic estimates no affected product remains in active service.

Performance Notes

This report concludes with a number of Performance Notes developed by Medtronic to provide additional product performance information relevant to follow-up practice and patient management.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

How You Can Help

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of the reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRTs, ICDs, IPGs, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of explanted products from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab. For information on how to contact the Lab, refer to the Contact Information page of this report.

We continually strive to improve this CRDM Product Performance Report. In keeping with this philosophy, we ask for your suggestions on the content and format of this report, as well as any information you have regarding the performance of Medtronic products. For information on how to comment on this report, see the Contact Information page of this report.

Overview of Survival Analysis

Medtronic uses the Cutler-Ederer actuarial life table method to estimate the length of time over which devices and leads will perform within performance limits established by Medtronic. This probability to perform within performance limits over time is called the *survival probability*.

Devices and leads are followed until an *event* occurs where the device or lead ceases to operate within performance limits. The length of time from implant to the event is recorded for individual devices and leads in the *population sample*. The population sample for

CRT, ICD, and IPG devices is made up of patients whose devices are registered as implanted in the United States. For leads, the population sample is the patients enrolled in our multicenter, international prospective System Longevity Study.

For IPGs and ICDs, the events can be normal battery depletion or a device malfunction. For leads, the events are complications as defined in the study protocol.

The actuarial life table method allows Medtronic to account for devices and leads removed from service for reasons unrelated to performance. Devices and leads removed for these reasons are said to be *suspended*. Examples include devices and leads:

- still in service at the time the analysis is performed
- removed to upgrade the device or lead
- no longer in service due to the death of the patient for reasons unrelated to the device or leads
- implanted in patients who are lost to follow-up

For each suspension, the device or lead has performed within performance limits for a period of time, after which its performance is unknown.

An Example

The following example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads. The example is intended to provide an overview of the analysis process. The definitions of malfunctions and complications, and other details specific to calculating device and lead survival estimates, are provided in the articles Method for Estimating CRT, ICD, and IPG Device Performance (page 6) and Method for Estimating Lead Performance (page 81).

This simple example describes the survival analysis method used to establish the survival probability estimates for Medtronic CRDM devices and leads.

Figure 1

Implant times for devices of 16 patients. Gray bars with a yellow X indicate devices removed from service due to an event. Blue bars indicate suspended devices.

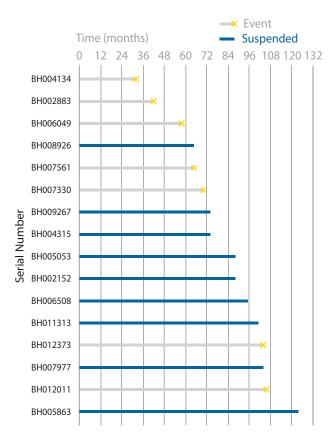


Figure 1 illustrates 16 patients who have implanted devices. The first patient's device (serial number BH004134) operated within performance limits for 32 months. At that time an event occurred. The fourth patient's device (serial number BH008926) did not have an event but is suspended, perhaps because it was still in service at the time of the analysis. This patient had 66 months of implant experience. In this example, Figure 1 shows that seven of the 16 devices suffered events, and nine are suspended.

The first step in the life table method is to divide the implant time into intervals of a specific length. This example will use 12-month intervals. The number of devices entered, suspended, and removed due to an event are counted and summarized, as shown in Table 1. For the first two intervals, all 16 devices survived and none were removed. In the interval (24-36 months), device BH004134 was removed due to an event. Therefore the table entries show that 16 entered the interval, none were suspended, and one was removed due to an event.

For the interval from 36-48 months, only 15 devices entered the interval and one was removed for an event. The remaining intervals are examined and the data entered in columns A, B, and C in like manner. The rest of the columns are filled in using calculations on the data in columns A, B, and C.

The Effective Sample Size (D) is the number of devices with full opportunity to experience a qualifying event in the interval. This is computed by subtracting one half the number suspended in the interval from the number that entered the interval. This calculation more accurately reflects the number of devices that could have experienced a qualifying event than simply using the number that entered the interval. Using the number of devices that enter an interval overestimates the sample size because the suspended devices do not complete the interval. Ignoring the suspended devices underestimates the sample size because suspended devices are not credited with their full service time. Using one half the number of suspended devices effectively splits the difference.

The next column in the table is the *Proportion with Event* (E). This is the proportion of devices that had an event in the interval. It is calculated by dividing the *Number of Events* (C) by the *Effective Sample Size* (D). The number can be interpreted as the estimated rate at which events occur in the time interval.

The Interval Survival Probability (**F**) is the estimate of probability of surviving to the end of the interval assuming the device was working at the beginning of the interval. It is calculated as 1 minus the Proportion with Event (**E**). This number can be interpreted as the estimated rate at which events **do not** occur in the time interval.

The Cumulative Survival Probabilities (G) from the last column of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data shown in Table 1.

Table 1 Life Table for Figure 1

	Α	В	C	D	E	F	G
Interval in Months	Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
0	16	0	0	16	0.000	1.000	1.000
0-12	16	0	0	16	0.000	1.000	1.000
12-24	16	0	0	16	0.000	1.000	1.000
24-36	16	0	1	16	0.063	0.938	0.938
36-48	15	0	1	15	0.067	0.933	0.875
48-60	14	0	1	14	0.071	0.929	0.813
60-72	13	1	2	12.5	0.160	0.840	0.683
72-84	10	2	0	9	0.000	1.000	0.683
84-96	8	3	0	6.5	0.000	1.000	0.683
96-108	5	2	2	4	0.500	0.500	0.341
108-120	1	0	0	1	0.000	1.000	0.341
120-132	1	1	0	0.5	0.000	1.000	0.341

Definitions:

Α	В	C	D	E	F	G
Number Entered	Number Suspended	Number of Events	Effective Sample Size	Proportion with Event	Interval Survival Probability	Cumulative Survival Probability
Number of devices active at the start of the interval	Number of devices removed from service for reasons other than an event	Number of units removed from service due to an event	Number of units with full opportunity to experience a qualifying event in the interval. Computed by subtracting one half the Number Suspended from the Number Entered.	Proportion of devices that had an event in the interval. Computed by dividing the Number of Events by the Effective Sample Size.	The probability of surviving to the end of the interval, assuming the device was working at the beginning of the interval. Computed as 1 minus the Proportion With Event.	The overall probability of surviving to the end of the interval. Computed by multiplying the Interval Survival Probability by the previous interval's Cumulative Survival Probability.

Cumulative Survival Probability (G) is the estimate of the unconditional probability of surviving to the end of the interval. It is computed by multiplying the Interval Survival Probability (F) by the previous interval's Cumulative Survival Probability. The probability of surviving to 132 months in the example is estimated for the table to be 0.341, or 34.1%.

The *Cumulative Survival Probabilities* (G) of the life table can be plotted versus time intervals in the first column to give a survival curve. Figure 2 shows the survival curve for the data in Table 1.

Cumulative Survival Probability (% 100 90 80 70 60 40 30 12 0 24 36 48 60 72 84 96 108 120 Time (months) 24 36 48 60 72 96 108 12 84 120 132 93.8 87.5 81.3 68.3 68.3 68.3 34.1 34.1 100 100 100 34.1 16 16 16 15 12.5 0.5 16 **Effective Sample Size**

Survival Curve for Data Given in Table 1 Figure 2

Confidence Intervals

Since survival curves are based on a sample of the device and lead population, they are only estimates of survival. The larger the effective sample size, the more confident the estimate. A confidence interval can be calculated to assess the confidence in an estimate. In the Product Performance Report, Medtronic provides a 95% confidence interval. This can be interpreted as meaning that 95% of the time, the true survival of the device will fall somewhere in the interval.

Survival Curves in the Product **Performance Report**

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRTs, ICDs, and IPGs, and when the number entered is less than 50 for leads. The survival charts in the Product Performance Report show the effective sample size for each year interval where Medtronic has experience. When the effective sample size reaches 100 for CRTs, ICDs, and IPGs or when the number entered reaches 50 for leads, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using 1-month intervals (for CRT, ICD, and IPG devices) or 3-month intervals (for leads).

A number of references are available for additional information on survival analysis using the Cutler-Ederer life table method.1

¹ Lee, Elisa T.(2003) Statistical Methods for Survival Data Analysis – 3rd Edition (Wiley Series in Probability and Statistics).

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

The performance of CRT, ICD, and IPG devices is expressed in terms of device survival estimates, where "survival" refers to the function of the device, not the survival of the patient. These survival estimates are intended to illustrate the probability that a device will survive for a given number of years with neither malfunction nor battery depletion.

The survival estimates are determined from the analysis of Medtronic CRDM's United States device registration data and US returned product analysis data. These data are presented graphically and numerically.

Because this analysis is based on returned product analysis, the performance data does not reflect any device-related medical complications such as erosion, infection, muscle stimulation, or muscle inhibition.

Categorization of Depleted and Malfunctioning Devices for Survival Analysis

For survival estimation, every device returned to Medtronic CRDM and analyzed in the CRDM Returned Product Analysis laboratory is assigned to one of three categories. The device 1) is functioning normally, 2) has reached normal battery depletion, or 3) has malfunctioned. This categorization is combined with data from our device registry for the total number of implants and the implant durations to create the survival curves presented on the following pages.

Definition of Malfunction

Medtronic CRDM considers a device as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction or battery depletion, the device must have been returned to Medtronic and analyzed.

Devices damaged after explant, damaged due to failure to heed warnings or contraindications in the labeling, or damaged due to interaction with other implanted devices (including leads) are not considered device malfunctions.

A device subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

Not all malfunctions expose the patient to a loss of pacing or defibrillation therapy. Some malfunctions included in the following survival estimates may not have been detected at all by the physician or the patient. These malfunctions, however, are included in the survival estimates and provide important feedback to our product development organization.

To provide insight into the nature of malfunctions, each malfunction is categorized as Malfunction with Compromised Therapy Function or Malfunction without Compromised Therapy Function. A summary of these malfunctions is presented for the most recently market-released models.

For this report, Normal Battery Depletion, Malfunction with Compromised Therapy Function, and Malfunction without Compromised Therapy Function are defined as follows:

Normal Battery Depletion - The condition when:

- (a) a device is returned with no associated complaint and the device has reached its elective replacement indicator(s) with implant time that meets or exceeds the nominal (50 percentile) predicted longevity at default (labeled) settings, or
- (b) a device is returned and the device has reached its elective replacement indicator(s) with implant time exceeding 80% of the expected longevity calculated using the available device setting information.

Medtronic CRDM establishes expected longevity by statistically characterizing the power consumed by the device and the power available from the device battery. This characterization is applied to a number of parameter configurations to derive a statistical mean longevity value and standard deviation for each parameter configuration. The statistical mean value minus three standard deviations is used as the expected longevity for determining if a battery depleted normally.

The Standard Actuarial Method is used to estimate IPG and ICD survival. This product performance report has been prepared in accordance with International Standard ISO 5841-2:2000(E).

For reference purposes, the following pages include estimated longevities for each model. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

Malfunction with Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that compromised pacing or defibrillation therapy (including complete loss or partial degradation), while implanted and in service, as confirmed by returned product analysis.

Examples: Sudden loss of battery voltage; accelerated current drain such that low battery was not detected before loss of therapy; sudden malfunction during defibrillation therapy resulting in aborted delivery of therapy, intermittent malfunction where therapy is compromised while in the malfunction state.

Malfunction without Compromised Therapy Function

The condition when a device is found to have malfunctioned in a manner that *did not* compromise pacing or defibrillation therapy, while implanted and in service, as confirmed by returned product analysis.

Examples: Error affecting diagnostic functions, telemetry function, data storage; malfunction of a component that causes battery to lose power quickly enough to cause premature battery depletion, but slowly enough that the condition is detected through normal follow-up before therapy is lost; mechanical problems with connector header that do not affect therapy.

Expanded Malfunction Detail

The malfunctions are further divided into categories that identify the subject area of the malfunction. The malfunctions are divided into the following subject areas:

Electrical Component - Findings linked to electrical components such as integrated circuits, resistors, capacitors, diodes, etc.

Electrical Interconnect – Findings linked to the connections between electrical components such as wires, solder joints, wire bonds, etc.

Battery - Findings linked to the battery and its components

Software/Firmware - Findings linked to software or firmware function

Possible Early Battery Depletion – Findings where the actual reported implant time is less than 80% of the expected longevity calculated using the available device setting information with no device malfunction observed. There may not be sufficient device setting information to determine conclusively if battery depletion was normal or premature in the absence of a specific root cause finding. However, returned devices meeting the above criteria are conservatively classified as Possible Early Battery Depletion malfunctions.

Other – Findings related to other components such as insulators, grommets, setscrews, and packaging, and findings where analysis is inconclusive

Returned Product Analysis Process

Analysis of returned product is performed according to written procedures. These procedures determine the minimum analysis required. The analysis required varies depending on the type of device, age of the device, the associated information received with the device, actual experience with models of similar design, and other factors. Additional analysis is performed as necessary to investigate a performance concern from a customer, or to collect specific reliability data.

When a device is returned with a performance concern from a customer, the general analysis process includes a preliminary analysis of the device in its as-received condition, followed by an automated functional test using test equipment equivalent to the equipment used in manufacturing.

When a malfunction is identified, failure analysis is performed to provide the detailed information necessary to investigate possible causes and actions. Medtronic CRDM maintains in-house expertise and performs its failure analysis using facilities it owns and supports. This capability permits detailed failure analysis.

Medtronic CRDM adjusts all-cause survival estimates to account for underreporting. While this lowers our all-cause survival estimates, we feel it gives a more accurate perspective on real performance.

Statistical Methods for Survival Analysis

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed evenly within the intervals (Cutler-Ederer Method), is used to determine estimates of IPG and ICD survival. This method is commonly used by medical researchers and clinicians.

Implant times are calculated from the implant date to the earlier of the explant date or the cutoff date of the report. From this data an estimate of the probability of device survival is calculated at each monthly interval.

On the following pages, each graph includes a survival curve where events include malfunctions and normal battery depletions. This survival curve is a good representation of the probability a device will survive a period of time without malfunction and without battery depletion. For example, if a device survival probability is 95% after 5 years of service, then the device has a 5% chance of being removed due to battery depletion or malfunction in the first 5 years following implant.

In addition, a second curve is included to show survival excluding normal battery depletion. This curve is a good representation of the probability for a device to survive without malfunction. This curve includes only malfunctions as events and excludes normal battery depletion.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the effective sample size is less than 100 for CRT, ICD, and IPG devices. The survival charts in the Product Performance Report show the effective sample size for each year interval where we have experience. When the effective sample size reaches 100, the next data point is added to the survival curve.

Although the report provides tabular data in one-year intervals, the curves are actually computed and plotted using one-month intervals.

The data in the tables are rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more malfunctions or battery depletions. This occurs because, even with the malfunctions or battery depletions, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates.

Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Sample Size and How the Population and **Population Samples Are Defined**

The population sample from which the survival estimates are derived is comprised of the devices registered as implanted in the United States as of the report cutoff date. The number of registered implants, as well as an estimate of the number that remain in active service, is listed for each model. To be included in the population, the device must have been registered with Medtronic's registration system and implanted for at least one day.

This sample based on US implants is considered to be representative of the worldwide population, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

A CRT, ICD, or IPG model or model family will be included in this report when it has accumulated at least 10,000 implant months and will remain in the report as long as at least 500 devices remain active.

Methods Used to Adjust for Underreporting of Malfunction and Battery Depletion

The tables on the following pages show the actual number of malfunctions and battery depletions recorded by the analysis lab for US registered devices. Since not all devices are returned to Medtronic CRDM for analysis, these numbers underestimate the true number of malfunctions and battery depletions. To more accurately estimate the all-cause device survival probabilities, the number of malfunctions and battery depletions used to plot each interval of the all-cause survival curves is adjusted (multiplied) by a factor that is based on an estimate of the magnitude of underreporting. The magnitude of underreporting is estimated by analyzing experience in Medtronic's Device And Registrant Tracking (DART) system.

The DART system is an important element of Medtronic's Quality System. The DART system is designed to meet or exceed the US FDA's device tracking requirements set forth by the Safe Medical Devices Act. In the United States, over 98% of Medtronic's CRT, ICD, and IPG implants become registered in the DART

continued

Because pacemakers do not cure the patient's underlying health problem, when a pacemaker stops functioning (due to either normal battery replacement or malfunction) it is replaced with a new pacemaker. Therefore, the replacement recorded in the DART system is a good indication that the previous pacemaker experienced either battery depletion or malfunction. The fraction of replaced devices that are subsequently returned can be used to estimate the correction factor for the under reporting of the combination of battery depletion and malfunction.

Note that devices of patients who have expired do not factor into the calculation of the correction. It is possible some proportion of these device experienced battery depletion or malfunction. Since these are not counted into the correction factor based on the return rate of replaced devices, a correction factor based only on the return rate of replaced devices may still underestimate the true rate of battery depletion and malfunction. However, devices that are replaced because the patient is receiving a system upgrade or are removed because the patient no longer needs it (e.g., due to heart transplant) do contribute to the calculation of the correction factor and therefore impart an opposite bias.

Also note that this method of calculating the correction factor cannot distinguish between devices that are removed due to malfunction and those due to normal battery depletion. It might seem intuitive that devices that unexpectedly malfunction should be much more likely to be returned to the manufacturer than a device with ordinary normal battery depletion. But this has not been conclusively demonstrated. Therefore, this method only provides a correction factor reflecting the combination of battery depletion and malfunction.

No adjustment for underreporting is applied to the malfunction-free survival curve because a method for estimating malfunction-only underreporting has not been developed.

Adjustments to Registered Implants to Compensate for Unreported Devices Removed from Service

Devices are at times removed from service for reasons other than device malfunction or battery depletion. Examples are devices removed from service due to non-device related patient mortality and devices removed due to changes in the patient's medical condition. Because an accurate estimate of device survival depends on an accurate estimate of the number of devices in service, it is important not to overstate the number of devices in service.

To ensure the number of devices in service is not overstated, Medtronic addresses this underreporting in two ways. Regular updates obtained from the Social Security Administration about deceased persons is used to update Medtronic's DART data about patients who have died but whose deaths had not been reported to Medtronic. In addition, the patient mortality rate derived from our DART system is monitored and compared to published mortality rates for comparable patient populations. If, during calculation of the survival curves, the patient mortality indicated by the data in DART is significantly different from published rates, an adjustment is applied to correct the difference.

%

#

99.6

Effective Sample Size

23,800

96.7

18,000

83.0

12,600

23.7

2,350

arquis							Product Characteristics	
	Aug-03	Malfund	tions (US)			304	NBD Code	VVED
	27,800	Thera	y Function	Not Compromise	d :	272	Serial Number Prefix	PRJ
ants	1,400	Ele	ctrical Com	ponent		25	Max Delivered Energy	30 J
ns (US)	6,572	So	ftware/Firm	ware		1	Estimated Longevity	See page 2
6 – 2005 Pot	tential	Ро	ssible Early E	Battery Depletion	:	246		
tion Due to B	Battery Short	Thera	y Function	Compromised		32		
		Bat	tery (9 malf	unctions related to	advisory)	10		
		Ele	ctrical Comp	oonent		22		
		\						
		`						
			1					
			1					
	2 3	3	4	5	6	7	8 9	10
	ants ns (US) 66 – 2005 Pot tion Due to B	Aug-03 27,800 ants 1,400 ns (US) 6,572 66 – 2005 Potential tion Due to Battery Short	Aug-03 27,800 Therap ants 1,400 Ele ns (US) 6,572 So Therap Therap Battery Short Therap Battery Short Therap	Aug-03 27,800 Therapy Function ants 1,400 Electrical Com so (US) 6,572 Software/Firm Possible Early I Therapy Function Battery (9 malfi Electrical Comp	Aug-03 27,800 Therapy Function Not Compromise ants 1,400 Electrical Component Software/Firmware Possible Early Battery Depletion Therapy Function Compromised Battery (9 malfunctions related to Electrical Component	Aug-03 27,800 Therapy Function Not Compromised Electrical Component Software/Firmware Possible Early Battery Depletion Therapy Function Compromised Battery (9 malfunctions related to advisory) Electrical Component	Aug-03 27,800 Therapy Function Not Compromised 272 ants 1,400 Electrical Component 25 ans (US) 6,572 Software/Firmware 1 Possible Early Battery Depletion 246 Therapy Function Compromised 32 Battery (9 malfunctions related to advisory) Electrical Component 22	Aug-03 Malfunctions (US) 304 NBD Code 27,800 Therapy Function Not Compromised 272 Serial Number Prefix ants 1,400 Electrical Component 25 Max Delivered Energy as (US) 6,572 Software/Firmware 1 Estimated Longevity Possible Early Battery Depletion 246 Therapy Function Compromised 32 Battery (9 malfunctions related to advisory) Electrical Component 22

0.4

570

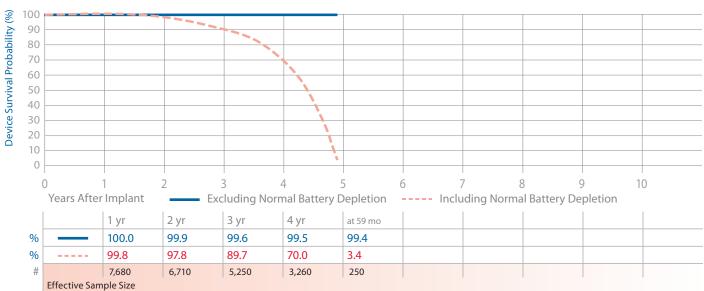


7297 InSync Sentry

US Market Release	Nov-04	Malfunctions (US)	39
Registered US Implants	8,800	Therapy Function Not Compromised	37
Estimated Active US Implants	590	Battery	1
Normal Battery Depletions (US)	2,525	Electrical Component	10
Advisories	None	Software/Firmware	1
		Possible Early Battery Depletion	25
		Therapy Function Compromised	2
		Electrical Component	2

Product Characteristics

NBD Code	VVED
Serial Number Prefix	PRK
Max Delivered Energy	35 J
Estimated Longevity	See page 22



7299 InSync Sentry

Advisories None Possible Early Battery Depletion Other 1 Therapy Function Compromised 10 Electrical Component 10 100 90 80 70 60 50 40 30 20 10						
Estimated Active US Implants 3,070 Electrical Component 17 Max Delivered Energy 35 J Normal Battery Depletions (US) 8,973 Software/Firmware 2 Estimated Longevity See page 2 Advisories None Possible Early Battery Depletion 145 Other 1 Therapy Function Compromised 10 Electrical Component 10	US Market Release	Apr-05	Malfunctions (US)	175	NBD Code	VVED
Normal Battery Depletions (US) 8,973 Software/Firmware 2 Estimated Longevity See page 2 Advisories None Possible Early Battery Depletion 145 Other 1 Therapy Function Compromised 10 Electrical Component 10 100 90 80 70 60 50 40 30 20 10	Registered US Implants	31,100	Therapy Function Not Compre	omised 165	Serial Number Prefix	PRK
Advisories None Possible Early Battery Depletion Other 1 Therapy Function Compromised 10 Electrical Component 10 100 100 100 100 100 100 100 100 10	Estimated Active US Implants	3,070	Electrical Component	17	Max Delivered Energy	35 J
Other 1 Therapy Function Compromised 10 Electrical Component 10	Normal Battery Depletions (US)	8,973	Software/Firmware	2	Estimated Longevity	See page 22
Therapy Function Compromised 10 Electrical Component 10 100 90 80 70 60 50 40 30 20 10	Advisories	None	Possible Early Battery Depl	etion 145		
Electrical Component 10 5 100 90 80 70 60 50 40 30 20 10			Other	1		
100 90 80 70 60 50 40 30 20			Therapy Function Compromis	ed 10		
90 80 70 60 50 40 30 20			Electrical Component	10		
90 80 70 60 50 40 30 20						
90 80 70 60 50 40 30 20	100					
10	90					
10	80					
10	70					
10	60					
10	50					
10	40					
10	30					
10	30					
10	20					
	10					
	0		i			

Jun-04

17,300

1,090

4,797

None

7303 InSync Maximo

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

US Market Release

Advisories

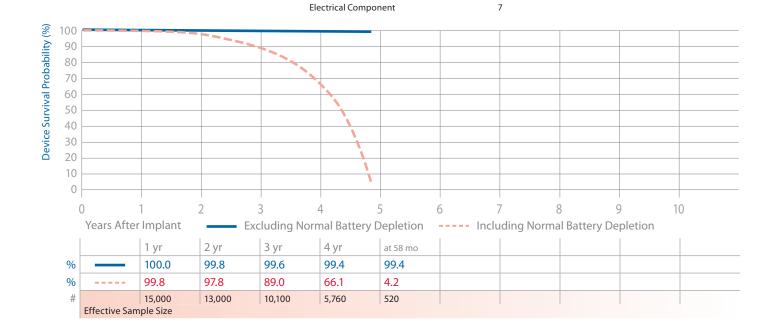
Malfunctions (US)	73
Therapy Function Not Compromised	66
Electrical Component	15
Software/Firmware	2
Possible Early Battery Depletion	49

Therapy Function Compromised

Product Characteristics

7

NBD Code	VVED
Serial Number Prefix	PRL
Max Delivered Energy	35 J
Estimated Longevity	See page 22



7304 InSync Maximo

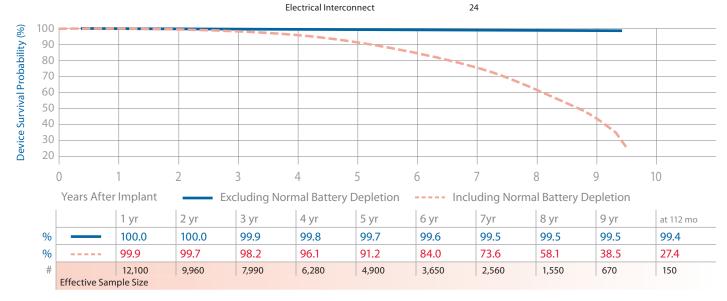
US Market Release		Apr-0	5 Malfu	nctions (US)		100	NBD Code		VVED
Registered US Implants		19,000		apy Function No	nt Compromise		Serial Number	er Prefix	PRL
Estimated Active US Imp		2,930		a py i unction iv o Battery	.compromise	u 90	Max Delivere		35 J
		·		,		•		٠,	
Normal Battery Depleti	ons (US)	4,61		Electrical Compo		12	Estimated Lo	ingevity	See page 2
Advisories		None		Possible Early Bat		83			
				apy Function Co	-	4			
			E	Electrical Compo	nent	4			
100									
90									
80									
70									
60									
50									
40									
30									
20				j					
10				1					
0					_				1.0
0 1			3			6 7		9	10
Years After I	mplant	Exc	luding Nor	rmal Battery [Depletion	Includ	ing Normal Ba	attery Depletic	on
	1 yr	2 yr	3 yr	4 yr	at 58 mo				
	100.0	99.9	99.6	99.2	99.1				
	99.8	97.9	90.9	68.8	3.5				
	16,600	14,400	11,100	6,140	420				
Effective Samp			,					,	



8040 InSync

Product Characteristics

US Market Release	Aug-01	Malfunctions (US)	32	NBG Code	DDDR
Registered US Implants	15,300	Therapy Function Not Compromised	8	Serial Number Prefix	PIN
Estimated Active US Implants	1,690	Electrical Component	4	Estimated Longevity	See page 23
Normal Battery Depletions (US)	1,189	Possible Early Battery Depletion	3		
Advisories	None	Other	1		
		Therapy Function Compromised	24		
		EL . I II .			



8042 InSync III **Product Characteristics**

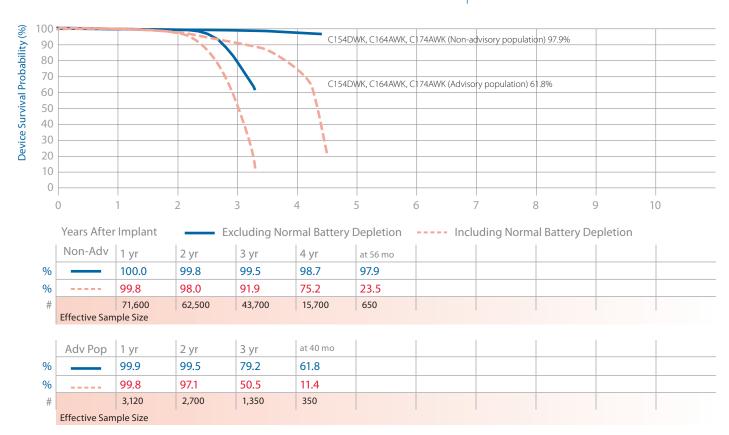
JS Market Release	Feb-03	Malfund	ctions (US)		18	8	NBG Code	9		DDDR
legistered US Implants	39,500	Thera	y Function No	ot Compromise	d !	9	Serial Nur	mber Prefix		PKF
Estimated Active US Implants	17,000	Ele	ectrical Compo	nent		5	Estimated	Longevity		See page 2
Normal Battery Depletions (US)	1,240	Ele	ectrical Interco	nnect		1				
Advisories	None	Po	ssible Early Bat	tery Depletion		1				
		Ot	her			2				
		Thera	y Function Co	mpromised	9	9				
		Ele	ectrical Compo	nent	:	3				
		Ele	ectrical Interco	nnect	(6				
100										
90										
80										
70										
60										
50						-				
40										
30						+				
20										
¹⁰ 0 1	2	3	4	5	6	7	8	3	9	10
Years After Implan	t Exc	luding Nor	mal Battery	Depletion	Incl	udin	ig Norma	al Battery D	Depletion	
1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7)	/r	8 yr		
% 100.0	100.0	100.0	100.0	99.9	99.9	99		99.8		
% 99.9	99.9	99.3	97.7	94.7	88.7	75	.1	34.3		
# 32,800	24,800	17,900	12,700	8,470	5,020	_	160	270		

Effective Sample Size



C154DWK, C164AWK, C174AWK Concerto

	(N)	(A)		(N)	(A)		
US Market Release	May-06	May-06	Malfunctions (US)	657	1,296	NBD Code	DDED
Registered US Implants	81,200	3,500	Therapy Function Not Compromised	624	1,281	Serial Number Prefix	PVU, PVT, PVR
Estimated Active US Implants	41,700	240	Electrical Component	100	1,277	Max Delivered Energy	35 J
Normal Battery Depletions (US)	6,292	245	Electrical Interconnect	2		Estimated Longevity	See page 22
Advisories: See page 150 – 2009		I	Software/Firmware	2			
Potential Reduced Device Longevity			Possible Early Battery Depletion	517	4		
			Other	3			
Performance Note: See page 161 – Anomalies in MOSFET Integrated			Therapy Function Compromised	33	15	(N) = Non-advisory population	า
Circuit Technology			Electrical Component	31	14	(A) = Advisory population	
			Electrical Interconnect	2	1		





D224TRK Consulta CRT-D

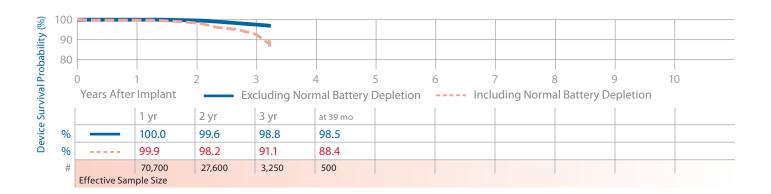
Product Characteristics

US Market Release	Sep-08	Malfunctions (US)	221	NBD Code	DDED
Registered US Implants	58,200	Therapy Function Not Compromised	215	Serial Number Prefix	PUD
Estimated Active US Implants	48,000	Electrical Component	9	Max Delivered Energy	35 J
Normal Battery Depletions (US)	348	Software/Firmware	1	Estimated Longevity	See page 22
Advisories	None	Possible Early Battery Depletion	204		
		Electrical Interconnect	1		
		Therapy Function Compromised	6		
		Electrical Component	6		



D274TRK, D294TRK Concerto II CRT-D

US Market Release	Aug-09	Malfunctions (US)	26	NBD Code	DDED
Registered US Implants	29,400	Therapy Function Not Compromised	25	Serial Number Prefix	PZV
Estimated Active US Implants	25,500	Electrical Component	2	Max Delivered Energy	35 J
Normal Battery Depletions (US)	55	Possible Early Battery Depletion	23	Estimated Longevity	See page 22
Advisories	None	Therapy Function Compromised	1		
		Electrical Component	1		



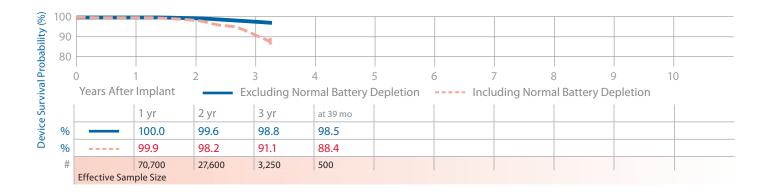


D284TRK Maximo II CRT-D

US Market Release	Sep-08
Registered US Implants	13,000
Estimated Active US Implants	10,500
Normal Battery Depletions (US)	116
Advisories	None

Malfunctions (US)	53
Therapy Function Not Compromised	52
Electrical Component	2
Possible Early Battery Depletion	50
Therapy Function Compromised	1
Electrical Component	1

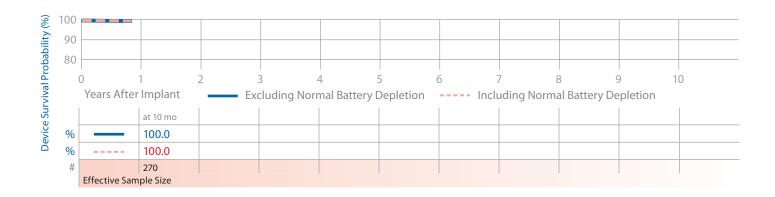
NBD Code	DDED
Serial Number Prefix	PZP
Max Delivered Energy	35 J
Estimated Longevity	See page 22





D314TRG Protecta XT CRT-D

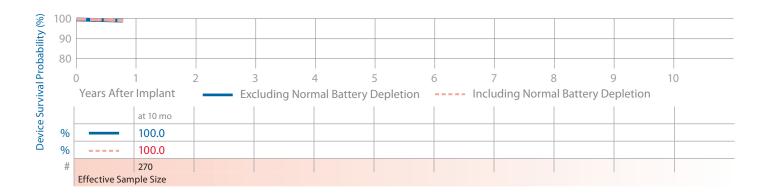
US Market Release	Mar-11	Malfunctions (US)	0	NBD Code	DDED
Registered US Implants	11,400	Therapy Function Not Compromised	0	Serial Number Prefix	PFS
Estimated Active US Implants	11,100	Possible Early Battery Depletion	0	Max Delivered Energy	35J
Normal Battery Depletions (US)	0	Therapy Function Compromised	0	Estimated Longevity	See page 22
Advisories	None				



D334TRG Protecta CRT-D

Product Characteristics

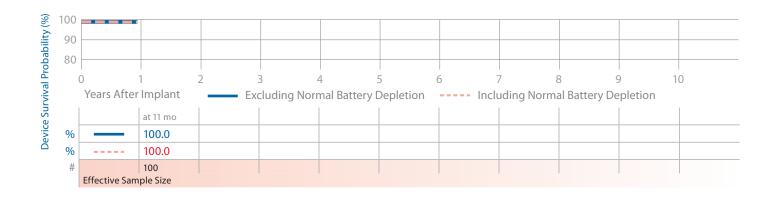
US Market Release	Mar-11	Malfunctions (US)	0	NBD Code	DDED
Registered US Implants	2,300	Therapy Function Not Compromised	0	Serial Number Prefix	PSO
Estimated Active US Implants	2,240	Possible Early Battery Depletion	0	Max Delivered Energy	35J
Normal Battery Depletions (US)	0	Therapy Function Compromised	0	Estimated Longevity	See page 22
Advisories	None				



C2TR01 Syncra CRT-P

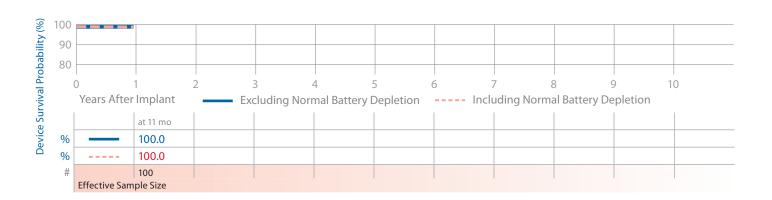
Product Characteristics

US Market Release	Mar-11	Malfunctions (US)	0	NBG Code	OOED
Registered US Implants	2.900	Therapy Function Not Compromised	0	Serial Number Prefix	PZX
Estimated Active US Implants	2,770	Possible Early Battery Depletion	0	Max Delivered Energy	NA
Normal Battery Depletions (US)	0	Therapy Function Compromised	0	Estimated Longevity	See page 23
Advisories	None				



C4TR01 Consulta CRT-P

US Market Release	Mar-11	Malfunctions (US)	0	NBG Code	OAED
Registered US Implants	2,400	Therapy Function Not Compromised	0	Serial Number Prefix	PVX
Estimated Active US Implants	2,280	Possible Early Battery Depletion	0	Max Delivered Energy	NA
Normal Battery Depletions (US)	0	Therapy Function Compromised	0	Estimated Longevity	See page 23
Advisories	None				





The following table shows CRT device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included. Device Survival Summary (95% Confidence Interval)

10 yr 8 yr 7 yr 6 yr 97.9 +0.2/-0.3 at 50 mo 0.4 +0.2/-0.2 at 50 mo 99.0 +0.1/-0.2 at 58 mo 99.4 +0.1/-0.2 at 58 mo 4.2 +0.7/-0.6 at 58 mo 99.1 +0.2/-0.2 at 58 mo 99.4 0.2/-0.3 at 59 mo 5 yr 98.0 +0.2/-0.3 23.7 +0.9/-0.9 99.2 +0.2/-0.2 70.0 +1.2/-1.3 65.7 +0.7/-0.7 99.4 +0.1/-0.2 **66.1** +0.9/-0.9 99.2 +0.1/-0.1 99.5 4 yr Device Survival Probability (%) 98.8 +0.2/-0.2 83.0 +0.6/-0.6 89.7 +0.7/-0.8 99.6 +0.1/-0.1 99.7 +0.1/-0.1 99.6 +0.1/-0.1 99.6 3 yr Years After Implant 97.9 +0.2/-0.2 99.7 +0.1/-0.1 99.9 +0.0/-0.1 9**9.9** +0.0/-0.1 99.8 +0.1/-0.1 9**6.7** 0.2/-0.3 97.8 0.3/-0.4 2 yr 99.9 +0.0/-0.0 100.0 +0.0/-0.0 100.0 +0.0/-0.0 100.0 +0.0/-0.0 100.0 +0.0/-0.0 99.6 +0.1/-0.1 99.8 +0.0/-0.1 99.8 1 yr Excluding Normal Battery Depletion Including Normal Battery Depletion Excluding Normal Battery Depletion Excluding Normal Battery Depletion Excluding Normal Battery Depletion Including Normal Battery Depletion Including Normal Battery Depletion Excluding Normal Battery Depletion Normal Battery Depletion Total 175 100 304 6 (advisory-related subset) 39 73 Malfunctions (US) Ш Ш П П Compromised 165 272 0 37 99 96 Function Not Тһегару + + + + Compromised 9 32 6 / 2 4 Therapy Function 4,614 8,973 4,797 Depletions (US) Normal Battery **Advisories:** See page 156 – 2005 Potential Premature Battery Depletion Due to Battery Short Implants 1,400 2,930 1,090 3,070 **SU** 9vitoA 588 Estimated 19,000 31,100 17,300 8,800 US Implants Registered Nov-04 Apr-05 Apr-05 Jun-04 Release US Market InSync Maximo InSync II Marquis InSync Maximo InSync Sentry InSync Sentry Family Model Number 7304 7289 7297 7299 7303

3.5 +0.7/-0.6 at 58 mo

68.8 +0.9/-0.9

90.9 +0.5/-0.5

97.9 +0.2/-0.2

99.8 +0.1/-0.1

Including Normal Battery Depletion

		1			nerapy	, соп	111000		ı		
		10 yr	99.4 +0.2/-0.3 at 112 mo	27.4 +2.6/-2.5 at 112 mo							
		8 yr	99.5 +0.1/-0.2	58.1 +1.6/-1.6	99.8 +0.1/-0.2	34.3 +2.8/-2.8					
	_	7 yr	99.5	73.6 +1.3/-1.3	99.9 +0.1/-0.2	75.1 +1.2/-1.2					
	_	6 yr	99.6 +0.1/-0.2	84.0 +0.9/-1.0	99.9 +0.0/-0.1	88.7					
	_	5 yr	99.7 +0.1/-0.2	91.2 +0.7/-0.7	99.9	94.7	97.9 +0.2/-0.2 at 56 mo	23.5 +1.9/-1.8 at 56 mo			
y (%)	_	4 yr	99.8 +0.1/-0.1	96.1 +0.4/-0.5	100.0	97.7 +0.2/-0.2	98.7 +0.1/-0.1	75.2 +0.5/-0.5	61.8 +2.0/-2.1 at 40 mo	11.4 +1.5/-1.4 at 40 mo	
Device Survival Probability (%)	nt -	3 yr	99.9 +0.0/-0.1	98.2 +0.3/-0.3	100.0	99.3 +0.1/-0.1	99.5 +0.1/-0.1	91.9 +0.2/-0.2	79.2	50.5 +2.0/-2.0	
Survival F	Years After Implant	2 yr	100.0	99.7 +0.1/-0.1	100.0 +0.0/-0.0	99.9	99.8	98.0 +0.1/-0.1	99.5 +0.2/-0.4	97.1 +0.6/-0.7	
Device 5	Years Af	1 yr	100.0	99.9 +0.0/-0.1	100.0	99.9	100.0 +0.0/-0.0	99.8	99.9 +0.1/-0.2	99.8 +0.1/-0.3	
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	
	lst	οТ	32		~		_		10		
			(1)		18		657		,296		
ions (US)	erapy inction Not impromised	n⊣∣	II ∞	1	II 6	1	624 =		1,281 = 1,296		
Malfunctions (US)	nction Not	HT n4	II		II		II		Ш		
Malfunctions (US)	erapy nction Not	Th Th OO	 & +		H +		+ 624 =	MOSFET	+ 1,281	d Device	MOSFET
Malfunctions (US)	epletions (US) rerapy inction inction inction inction inction Mot	MI No. No. No. No. No. No. No. No. No. No.	24 + 8 =		H 6		33 + 624 =	nomalies in MOSFET	15 + 1,281 =	ntial Reduced Device	nomalies in MOSFET
Malfunctions (US)	rive US plants plants propertions (US) p	LEST NO NO DE LA	1,189 24 + 8 =	,	1,240 9 + 9 =		6,292 33 + 624 =	e note on Anomalies in MOSFET 199y	245 15 + 1,281 =	– 2009 Potential Reduced Device	e note on Anomalies in MOSFET ggy
Malfunctions (US)	filmplants timated tive US tive US small Battery spletions (US) nretapy nretion inction mpromised mretion increasion mretion increasion mretion increasion mretion increasion mretion mretion mretion mretion mretion mretion	Ree USS USS USS USS USS USS USS USS USS U	1,690 1,189 24 + 8 =	•	17,000 1,240 9 + 9 =		41,700 6,292 33 + 624 =	– Performance note on Anomalies in MOSFET ircuit Technology	240 245 15 + 1,281 =	see page 150– 2009 Potential Reduced Device	– Performance note on Anomalies in MOSFET Ircuit Technology
Malfunctions (US)	gistered fimplants fimated five US fiv	Ree USS USS USS USS USS USS USS USS USS U	15,300 1,690 1,189 24 + 8 =		39,500 17,000 1,240 9 + 9 =		81,200 41,700 6,292 33 + 624 =	See page 161 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	3,500 240 245 15 + 1,281 =	Advisories: <u>See page 150</u> – 2009 Potential Reduced Device Longevity	See page 161 – Performance note on Anomalies in MOSFET Integrated Circuit Technology

		10 yr														
		8 yr														
		7 yr														
		6 yr														
		5 yr														
(%) /		4 yr	98.5 +0.3/-0.3 at 39 mo	88.4 +1.0/-1.1 at 39 mo	98.5 +0.3/-0.3 at 39 mo	88.4 +1.0/-1.1 at 39 mo	98.5 +0.3/-0.3 at 39 mo	88.4 +1.0/-1.1 at 39 mo								
robability	ηt	3 yr	98.8 +0.2/-0.2	91.1 +0.6/-0.6	98.8 +0.2/-0.3	91.1	98.8 +0.2/-0.4	91.1 +0.6/-0.8								
Device Survival Probability (%)	Years After Implant	2 yr	99.6	98.2 +0.1/-0.1	99.6	98.2 +0.1/-0.2	99.6	98.2 +0.1/-0.3								
Device S	Years Aft	1 yr	100.0	99.9	100.0	99.9	100.0	99.9 +0.0/-0.2	100.0 +0.0/-0.0 at 10 mo	100.0 +0.0/-0.0 at 10 mo	100.0 +0.0/-0.0 at 10 mo	100.0 +0.0/-0.0 at 10 mo	100.0 +0.0/-0.0 at 11 mo	100.0 +0.0/-0.0 at 11 mo	100.0 +0.0/-0.0 at 11 mo	100.0 +0.0/-0.0 at 11 mo
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
			Norr	Norr	Nor	Norn	Norn	Norm	Norm	Norm	Norm	Norm	Norm	Norm	Norn	Norr
	le	otoT	221	Norr	26 Norr	Norn	53 Norn	Norm	0 Norm	Norm	O Norm	Norm	0 Norm	Norm	O Norn	Norr
ins (US)	npromised	uoɔ		Norr		Norn		Norm		Norm		Norm _	Norn	Norm		Nor
Malfunctions (US)		The roD	= 221	Norr	= 26	Norn	= 53	Nor	0	Norm	0	Norm 	= 0 Norn	Noor	0	Norr
Malfunctions (US)	rapy ction Not pesimorqu	Dep The Con The The no The	+ 215 = 221	Norr	+ 25 = 26	Norn	+ 52 = 53	Norm	0 = 0 +	Norm	0 = 0 +	Norm	+ 0 = 0 +	Norm	0 = 0 +	Norr
Malfunctions (US)	Yqes: oction ction ction Mot yqes: ction Mot basimorqu	Acti Imp Mor Dep The The Con The The	6 + 215 = 221	Norr	1 + 25 = 26	Norn	1 + 52 = 53	Norm	0 = 0 + 0	Norm	0 = 0 + 0	Norm	0 + 0 = 0 Norn	Norm	0 = 0 + 0	Norr
Malfunctions (US)	rients ilants mal Battery viction (CD) rapy rapy rapy repy repy repy repy repy repy repy repy repriou Not repriou Not	Esti Acti Imp Mor Dep The Fun Con The	348 6 + 215 = 221	Norr	55 1 + 25 = 26	Nom	116 1 + 52 = 53	Norm	0 = 0 + 0	Norm	0 = 0 + 0 0	Norm	0 = 0 + 0 0	Norm	0 = 0 + 0 0	Norr
Malfunctions (US)	mated you US you US lants lants lattery lattery latton (US) rapy ction crion crion crion Not crion Not crion Not more crion Not	Regel US1 Estinated Imp Mort Imp Mort Imp Mort The	48,000 348 6 + 215 = 221	Norr	25,500 55 1 + 25 = 26	Nom	$10,500 116 \qquad 1 + 52 = 53$	Norm	$\begin{array}{cccccccccccccccccccccccccccccccccccc$	Norm	2,240 0 0 + 0 = 0	Norm	2,770 0 + 0 = 0 Norm	Norm	2,280 0 0 + 0 = 0	Norr
Malfunctions (US)	passed mplants weded by eVS in the control of the c	Regel US1 Estinated Imp Mort Imp Mort Imp Mort The	58,200 48,000 348 6 + 215 = 221	Norr	29,400 25,500 55 1 + 25 = 26	Nom	13,000 10,500 116 1 + 52 = 53	Norm	11,400	Norm	2,300 2,240 0 0 + 0 = 0	Norm	2,900 2,770 0 0 + 0 = 0	Norm	2,400 $2,280$ 0 0 $+$ 0 $=$ 0	Norr



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

					E:	stimate	d Longev	ity		Elective	Replacement	
					***						ERI)***	End of
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	Life (EOL) Battery Voltage
7289	InSync II Marquis	DR+LV true	38 cc 76 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.6 4.9 5.4	4.0 5.5 6.1	4.2 5.8 6.6	≤ 2.62 V	> 16 second charge time	3 months after ERI
7297	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7299	InSync Sentry	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7303	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI
7304	InSync Maximo	DR+LV true	40 cc 78 g	35 J	Monthly Quarterly Semiannual	3.3 4.5 5.0	3.8 5.3 6.0	4.1 6.2 7.1	4.3 6.6 7.7	≤ 2.62 V	> 16 second charge time	3 months after ERI

					Es	timated	Longe	/ity			mmended	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage deal	Charge Time Time	End of Service (EOS)
C154DWK, C164AWK, C174AWK	Concerto	DR+LV true	38 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.3	4.3 6.8 8.0	4.8 8.0 9.8	5.0 8.8 10.9	≤ 2.62 V	_	3 month after RRT or > 16-second charge time
D224TRK	Consulta CRT-D	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D274TRK D294TRK	Concerto II	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D284TRK	Maximo II CRT-D	DR+LV true	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT or > 16-second charge time
D314TRG	Protecta XT CRT-D	CRT-D	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT
D334TRG	Protecta CRT-D	CRT-D	38 cc/ 68 g	35 J	Monthly Quarterly Semiannual	3.2 4.4 4.8	3.8 5.5 6.2	4.4 6.8 7.9	4.7 7.5 9.0	≤ 2.63 V	_	3 month after RRT

^{*} Volume and mass differ by connector style.

^{**} A full charge is a full energy therapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL (or RRT and EOS) is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is DDD for CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates.

		Estimated Lon	gevity		
Model Number	Family	Amplitude Setting	500 Lead Ω	1,000 Lead Ω	Elective Replacement Time Indicators
8040	InSync	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	11.9 8.9 6.6	13.7 11.4 9.1	*
8042	InSync III	Low 2.5 V (A, RV, LV) Nominal 3.5 V (A, RV, LV) High 5.0 V (A, RV, LV)	8.3 5.9 4.1	9.9 7.8 6.0	*
C2TR01	Syncra CRT-P	Low 2.5 V (A, RV) Normal 3.5 V (A, RV) High 5.0 V (A, RV)	8.7 6.0 3.3	10.7 8.2 5.1	*
C4TR01	Consulta CRT-P	Low 2.5 V (A, RV) Normal 3.5 V (A, RV) High 5.0 V (A, RV)	8.7 6.0 3.3	10.7 8.2 5.1	*

 $^{^*}$ Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

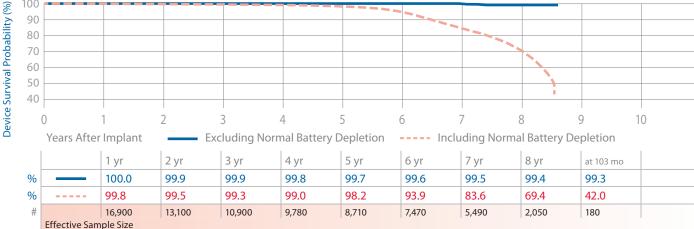
7230 Marquis VR

100

US Market Release Malfunctions (US) Dec-02 Registered US Implants 19,400 **Therapy Function Not Compromised Estimated Active US Implants** 5,400 **Electrical Component** Normal Battery Depletions (US) 1,143 Battery (1 malfunction related to advisory) Advisories: See page 156 – 2005 Potential Software/Firmware Premature Battery Depletion Due to Possible Early Battery Depletion **Battery Short** Other **Therapy Function Compromised** Battery (19 malfunctions related to advisory)

Product Characteristics

58	NBD Code	VVEV
29	Serial Number Prefix	PKD, PLW, PLY
12		
1	Max Delivered Energy	30 J
1	Estimated Longevity	See page 40
14		
1		
29		
20		
9		



Electrical Component

7231Cx GEM III VR

Product Characteristics

ICX	GEMIII	IVK							Product Ch	naractei	ristics	
JS Marl	ket Release		De	c-00	Malfunctions (US)			37	NBD Code			VVEV
Registe	red US Impla	ints	17	7,500	Therapy Functio	n Not Compromi	sed	27	Serial Numbe	er Prefix		PJL
Estimat	ted Active US	Implants	2	,400	Battery			1	Max Delivere	d Energy		30 J
Normal	l Battery Dep	letions (US)	3	,289	Electrical Cor	mponent		22	Estimated Lo	ngevity		See page
		See page 166	_		Possible Early	y Battery Depletic	on	4				
	nance note o rge Behavior	n ICD Battery			Therapy Functio	n Compromised		10				
Jiscriai	ige bellavior				Battery			1				
					Electrical Cor	mponent		9				
100												
90												
80												
70												
60												
50												
40												
30												
20										\ \		
10									<u> </u>	<u>'</u>		
0												
(0	1	2	3	4	5	6	7	8		9	10
	Years Afte	er Implant		Excluding	g Normal Batte	ry Depletion		ncludin	g Normal Ba	ttery De	epletion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7)	r 8 y	r	at 101 mo	
%		99.9	99.9	99.8	99.8	99.8	99.7	99	-		99.7	
%		99.7	99.4	98.9	98.4	96.9	87.0	71	.9 36.	.9	5.3	
#		15,300	13,600	12,000	0 10,500	9,100	7,090	4,8	20 1.74	10	290	

Effective Sample Size

Oct-03

44,300

21,600

1,540



7232 Maximo VR US Market Release

Battery Short

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

Advisories: See page 156 – 2005 Potential Premature Battery Depletion Due to

Malfunctions (US)	63
Therapy Function Not Compromised	48
Electrical Component	21
Possible Early Battery Depletion	23
Other	4
Therapy Function Compromised	15
Electrical Component	13
Electrical Interconnect	1

Possible Early Battery Depletion

Product Characteristics

NBE	O Code	VVEV
Seri	al Number Prefix	PRN, PVF, PVG
Max	Delivered Energy	35 J
Esti	mated Longevity	See page 40

(%)	
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rviva	
Sur	
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De	

100											
90											
80											
70											
60								1			
						_					
()	1)	3	4	5 (6	7	8	9	10
			_			,					
	Years After	Implant	Exc	luding Norn				ıding Norma	al Battery De		
		Implant 1 yr	Exc					iding Norma	al Battery De		
%			I	luding Norn	nal Battery D	epletion	Inclu	ı	ı		
		1 yr	2 yr	luding Norn 3 yr	nal Battery D	epletion 5 yr	6 yr	7 yr	at 88 mo		
%	Years After	1 yr	2 yr 99.9	3 yr 99.9	4 yr 99.9	5 yr 99.8	6 yr 99.8	7 yr 99.8	at 88 mo		

7274 Marquis DR

Product Characteristics

ī	US Mar	ket Release		Mar-02	2 Malfun	ctions (US)			190	NBD Code		VVED
	Registe	ered US Implan	ts	48,300) Thera	py Function No	t Compromise	d	83	Serial Number Prefix		PKC
	Estima	ted Active US Ir	mplants	3,700) Ba	ttery (3 malfund	ctions related to	advisory)	5	Max Delivered Energ	у	30 J
	Norma	l Battery Deple	tions (US)	8,272	2 Ele	ectrical Compoi	nent		27	Estimated Longevity		See page 40
			2005 Po	tential	Po	ssible Early Bat	tery Depletion		51			
	Premat	ture Battery De	pletion Due to		Thera	py Function Co	mpromised		107			
	Duttery	7 311011			Ва	ttery (73 malfur	nctions related to	advisory)	80			
					Ele	ctrical Compor	nent		27			
(%)	100											
Device Survival Probability (%)	90											
oabi	80											
Prok	70											
val	60											
urvi	50 40											
ce S	30											
Devi	20							1				
	10								1			
	0											
		0	1	2 3	3	4	5 (6	7	8	9	10
		Years After	Implant	Ехс	luding Norr	nal Battery [Depletion	Inc	ludin	ng Normal Battery I	Depletion	
			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7)	/r		
	%		99.9	99.9	99.8	99.6	99.4	99.3	99			
	%		99.7	99.4	98.4	96.9	90.4	65.3	10	.6		
	#		42,200	33,900	25,900	21,800	17,700	10,500	1,2	60		

Effective Sample Size



7275 GEM III DR

Product Characteristics

									Product Cha	aracterist	103	
US Mar	ket Release		Nov	v-00 Ma	Ifunctions (US)			43	NBD Code			VVED
Registe	red US Implar	nts	20,	.200 T I	herapy Function	Not Compromise	ed	32	Serial Number	Prefix		PJM
Estimat	ted Active US	Implants	1,	.500	Battery			1	Max Delivered	Energy		30 J
Normal	Battery Depl	etions (US)	4,	,447	Electrical Com	ponent		11	Estimated Long	gevity		See page
		See page 166	_		Software/Firm	ware		1				
	nance note or ge Behavior	ICD Battery			Possible Early Battery Depletion			18				
	g				Other			1				
				T	Therapy Function Compromised				11			
					Battery Electrical Comp	nanant		2 8				
					Electrical Comp			0				
100							_					
90												
80												
70												
60												
50												
40												
30												
20												
10							1					
0							-					
(0	1	2	3	4	5	6	7	8	9		10
	Years Afte	r Implant	E	Excluding N	Normal Batter	y Depletion	Ir	ncluding	Normal Bat	tery Depl	etion	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 73	mo			
%		99.9	99.9	99.8	99.8	99.7	99.7	99.7	,			
%		99.4	98.8	96.7	90.0	64.7	13.2	2.8				
		17,500	15,300	13,100	10,100	5,530	710	350				-

7278 Maximo DR

US Market Release	Oct-03		tions (US)			56	NBD Code		VVED
Registered US Implants	37,600		•	ot Compromise	ed	47	Serial Number Prefix		PRM
Estimated Active US Implants	11,300	Ele	ctrical Compo	nent		19	Max Delivered Energy		35 J
Normal Battery Depletions (US)	5,706	Pos	sible Early Bat	tery Depletion		26	Estimated Longevity		See page 4
Advisories: See page 156 – 2005 Potent	tial	Otl	ner			2			
Premature Battery Depletion Due to Battery Short		Therap	y Function Co	mpromised		9			
, , , , ,		Ele	ctrical Compor	nent		8			
100		Pos	sible Early Bat	tery Depletion		1			
100									
80									
70									
60									
50									
40									
30					1				
20					i				
10					1				
0									
0 1 2	3		1	5	6	7	8	9	10
Years After Implant –	Exclu	uding Norm	nal Battery [Depletion	In	cludir	ng Normal Battery De	pletion	
1 yr 2 y	yr 3	3 yr	4 yr	5 yr	6 yr	at	81 mo		
% 100.0 99	0.9	99.9	99.8	99.8	99.8	99	9.8		
% 99.9 99	0.6	99.1	97.4	88.5	59.9	2.	0		
# 33,700 30,	,000 2	26,500	22,300	16,700	7,730	31	0		
Effective Sample Size									



7288 Intrinsic

Product Characteristics

US Ma	Market Release		Jun	Jun-04 Malfunctions (US)				63	NBD Code	VVED
Regist	stered US Implants			30,600 Therapy Function Not Compromised			ised	56	Serial Number Prefix	PUB
Estima	ated Active US	Implants	10,	600	··				Max Delivered Energy	35 J
Norm	al Battery Dep	letions (US)	4,	623	Electrical Com	ponent		20	Estimated Longevity	See page 4
Advis	ories		Ne	one	Software/Firm	ware		1		
					Possible Early	Battery Depleti	on	32		
					Other			1		
				7	Therapy Function	Compromised		7		
					Electrical Com	ponent		7		
100										
100 90 80 70 60 50 40 30										
80										
70 60										
50										
40										
30							,			
20							1			
	0	1	7	3	4	5	6	7	8 9	10
	0	er Implant	E	xcluding	Normal Batter	y Depletion	~	rcludir	ng Normal Battery Depletic	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr		79 mo	
%		100.0	99.9	99.9	99.8	99.8	99.7	99		
% %		99.9	99.9	99.9	99.8	88.9	64.2	26		
90 #		28,200	25,900	23,200	20,400	00.9	04.2	20	٠.	

7290Cx Onyx

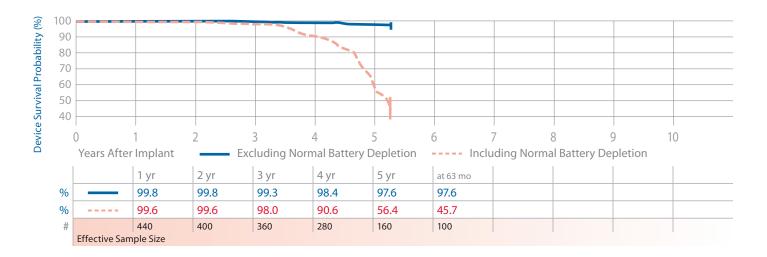
US Market Release Registered US Implants			Mar-0	r-04 Malfunctions (US)					NBD Code		VVEV
			9.	50	Therapy Function Not Compromised				Serial Number Pre	efix	PRP
Estima	ited Active US I	mplants	38	30	Electrical Comp	oonent		3	Max Delivered En	ergy	30 J
Norma	al Battery Deple	etions (US)	10)3	Possible Early E	Battery Deplet	ion	1	Estimated Longe	vity	See page 40
Adviso	ories		Nor	ne	Therapy Function	Compromised	i	1			
					Electrical Comp	oonent		1			
100			T	T							
90											
80											
70							1				
60		1				_					10
2	0	1	2	3	4	5	6	/	8	9	10
ת ט	Years After	^r Implant	Ex	cluding	g Normal Battery	/ Depletion		ncludin	g Normal Batte	ry Depletio	n
90 80 70 60 60		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 7	'8 mo		
%		99.9	99.5	99.5	99.4	99.4	99.4	99	.4		
%		99.8	99.1	98.3	96.8	92.0	77.4	62	.4		
#		870	790	710	620	510	290	120)		
	Effective Sam	nple Size									



D153ATG, D153DRG EnTrust

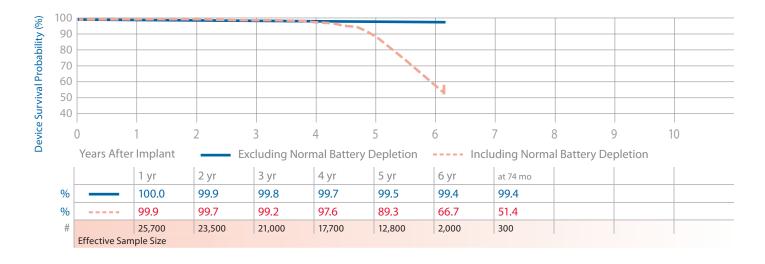
Product Characteristics

US Market Release	Jun-05	Malfunctions (US)	8	NBD Code	DDED, VVED
Registered US Implants	460	Therapy Function Not Compromised	7	Serial Number Prefix	PNR
Estimated Active US Implants	93	Possible Early Battery Depletion	7	Max Delivered Energy	30 J
Normal Battery Depletions (US)	143	Therapy Function Compromised	1	Estimated Longevity	See page 41
Advisories: See page 147 – 2012 Potential Rapid Battery Depletion		Electrical Component	1		



D154ATG, D154DRG EnTrust

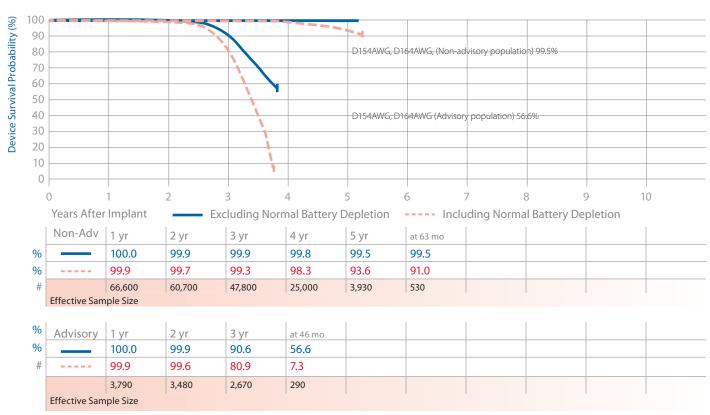
US Market Release	Jun-05	Malfunctions (US)	110	NBD Code	DDED
Registered US Implants	28,100	Therapy Function Not Compromised	97	Serial Number Prefix	PNR
Estimated Active US Implants	13,700	Electrical Component	24	Max Delivered Energy	35 J
Normal Battery Depletions (US)	1,813	Electrical Interconnect	1	Estimated Longevity	See page 41
Advisories: See page 147 – 2012		Software/Firmware	2		
Potential Rapid Battery Depletion		Possible Early Battery Depletion	70		
		Therapy Function Compromised	13		
		Electrical Component	13		





D154AWG, D164AWG Virtuoso DR

	(N)	(A)		(N)	(A)		
US Market Release	May-06		Malfunctions (US)	163	1,861	NBD Code	DDED
Registered US Implants	72,600	4,100	Therapy Function Not Compromised	139	1,850	Serial Number Prefix	PVV, PUL
Estimated Active US Implants	51,400	400	Electrical Component	50	1,849	Max Delivered Energy	35 J
Normal Battery Depletions (US)	502	57	Electrical Interconnect	1	0	Estimated Longevity	See page 41
Advisories: See page 150 – 2009			Possible Early Battery Depletion	86	0		
Potential Reduced Device Longevit	У		Other	1	1		
Performance Note: See page 161			Therapy Function Compromised	24	11		
 Anomalies in MOSFET Integrated Technology 	Circuit		Electrical Component	24	11		





D154VRC EnTrust VR

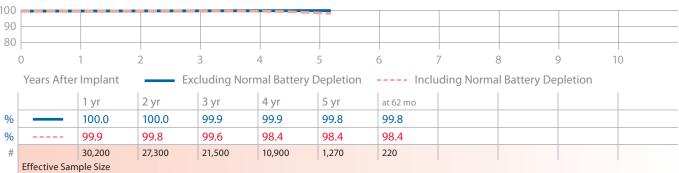
Product Characteristics

כוי	471	C Eniru	StvR							Product	Characte	ristics	
ι	US Market Release Registered US Implants				Jun-05 Malfunctions (US)					NBD Code			VVEV
R					14,400 Therapy Function Not Compromised				60	Serial Number Prefix			PNT
Е	stima	ted Active US I	mplants	8,1	00	Battery			2	Max Delivered Energy Estimated Longevity			35 J
Ν	lorma	l Battery Deple	etions (US)		171	Electrical Com	ponent		28				See page 41
	Advisories: See page 147 – 2012				Possible Early Battery Depletion				29	_			
P	otent	<mark>ial Ra</mark> pid Batte	ry Depletion		Other Therapy Function Compromised Electrical Component				1 9				
									9				
Device Survival Probability (%)	100 90 80												
Proba		0	1	2	3	4	5	6	7	8		9	10
ival		Years After	r Implant	—— Ex	cluding N	lormal Batter	y Depletion		Includir	g Normal	Battery D	epletion	
Sur			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at :	76 mo			
vice	%		99.9	99.9	99.8	99.7	99.4	99.2	99	.2			
De	%		99.9	99.6	99.3	98.8	97.6	91.4	88	.3			
	#		13,200	12,000	10,700	9,130	7,080	1,410	150)			

54VWC D164VWC Virtuoso VR

Effective Sample Size

וט	54V\	NC, D164	PVWC VII	tuoso VK						Product Characterist	tics			
	US Mar	ket Release		May-0	ay-06 Malfunctions (US)					NBD Code		VVEV		
	Registered US Implants				0 T	Therapy Function Not Compromised			29	Serial Number Prefix		PUN, PUP		
	Estima	Estimated Active US Implants			0	Electrical Component (3 malfunctions related to advisory)				Max Delivered Energy		35 J		
	Norma	l Battery Deple	tions (US)	7	6	Electrical Int	erconnect		1	Estimated Longevity		See page 41		
	Advisories: See page 150 – 2009					Possible Early Battery Depletion								
	Poter	itial Reduced D	evice Longevit	/	Therapy Function Compromised				12	12				
					Electrical Component				12					
	Anon		See page 161- T Integrated Ci											
(%)	100													
≟	90													
bab	80		1	2	2	1			7			10		
Pro	0 1 2 3 4 5 6 7 8 9 10													
i×a		Years After Implant E				xcluding Normal Battery Depletion Inc				g Normal Battery Dep	letion			
Surv			1 yr	2 yr	3 yr	4 yr	5 yr	at 62 mo						
ice	%		100.0	100.0	99.9	99.9	99.8	99.8						
Dev	Service Serv				99.6	98.4	98.4	98.4						





D224DRG Secura DR

Product Characteristics

US Mar	rket Release		Sep-0	8 Malfu	unctions (US)			23	NBD Code		DDED
Registe	ered US Implan	ts	45,30	0 The	rapy Function N	ot Compromis	ed	17	Serial Number Prefix	ĸ	PUG
Estima	ted Active US I	mplants	40,00	0	Electrical Compo	nent		7	Max Delivered Ener	gy	35 J
Norma	al Battery Deple	etions (US)	5	6	Possible Early Ba	ttery Depletio	n	7	Estimated Longevit	y	See page
Adviso	ories		Non	e	Software/Firmw	are		3			
				The	rapy Function Co	ompromised		6			
					Electrical Compo	nent		5			
					Software/Firmwa	are		1			
100 90 80											
	0	1	2	3	4	5	6	7	8	9	10
	Years After		I		ormal Battery	Depletion		ncludin	g Normal Battery	Depletion	n
0/		1 yr	2 yr	3 yr	at 40 mo						
%		100.0	100.0	99.9	99.9						
%		99.9	99.7	99.2	99.2						
#		61,000	25,600	4,510	620						

D224VRC Secura VR

Effective Sample Size

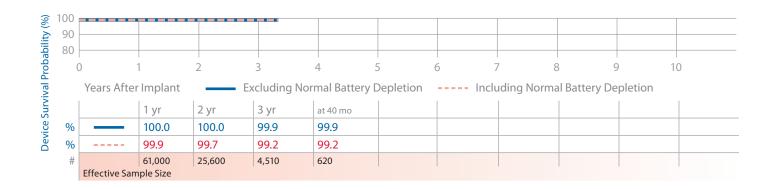
US Market Release		Sep-0	Q Mal	lfunctions (US)			8	NBD Code		VVEV
									D C	
Registered US Implant		17,60		erapy Function N	-	ed	5	Serial Number		PUX
Estimated Active US In	mplants	15,50	0	Electrical Comp	onent		1	Max Delivered	l Energy	35 J
Normal Battery Deplet	tions (US)	1	8	Possible Early B	attery Depletior	n	3	Estimated Lon	gevity	See page 4
Advisories		None	e	Software/Firmw	are		1			
			Th	erapy Function C	ompromised		3			
				Electrical Compo	onent		2			
				Software/Firmw	are		1			
00										
90										
80	1	2	3	4	5	6	7	8	9	10
		2 3 — Exc		4 lormal Battery		6 Ir	7 ncludin	8 g Normal Bat	9 Etery Depletion	10 on
0 1							7 ncludin			
0 1	Implant	— Exc	luding N	lormal Battery			7 ncludin			
80 0 1 Years After	Implant	Exc	luding N	lormal Battery			7			



D274DRG Virtuoso II DR

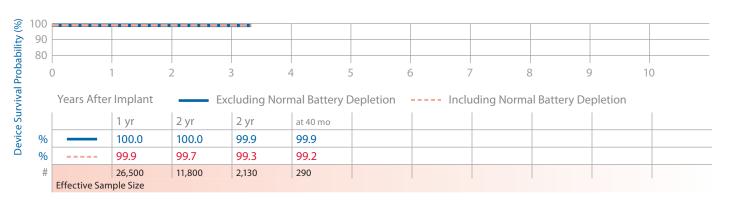
Product Characteristics

US Market Release	Aug-09	Malfunctions (US)	0	NBD Code	VVED
Registered US Implants	21,600	Therapy Function Not Compromised	0	Serial Number Prefix	PZT
Estimated Active US Implants	19,600	Therapy Function Compromised	0	Max Delivered Energy	35 J
Normal Battery Depletions (US)	6			Estimated Longevity	See page 41
Advisories	None				



D274VRC Virtuoso II VR

US Market Release	Aug-09	Malfunctions (US)	0	NBD Code	V	/VEV
Registered US Implants	8,800	Therapy Function Not Compromised	0	Serial Number Prefix	P	ZR
Estimated Active US Implants	8,000	Therapy Function Compromised	0	Max Delivered Energy	3	85 J
Normal Battery Depletions (US)	3			Estimated Longevity	S	See page 41
Advisories	None			,	_	

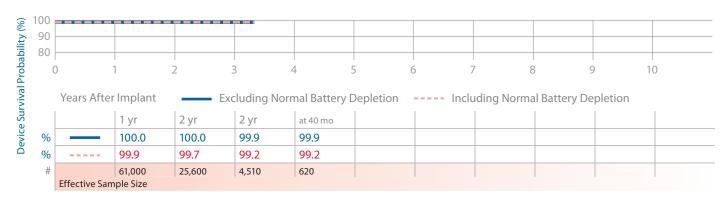




D284DRG Maximo II DR

Product Characteristics

US Market Release	Sep-08	Malfunctions (US)	5	NBD Code	VVED
Registered US Implants	17,200	Therapy Function Not Compromised	2	Serial Number Prefix	PZM
Estimated Active US Implants	15,100	Electrical Component	1	Max Delivered Energy	35 J
Normal Battery Depletions (US)	21	Possible Early Battery Depletion	1	Estimated Longevity	See page 41
Advisories	None	Therapy Function Compromised	3		
		Electrical Component	3		



D284VRC Maximo II VR

The maximum	***						Troduct	Characte	1150105	
US Market Release	Sep	-08 Mal	functions (US)			5	NBD Code			VVEV
Registered US Implants	10,8	300 Th	erapy Function N	ot Compromis	ed	2	Serial Nun	nber Prefix		PZN
Estimated Active US Implants	9,	500	Possible Early Ba	ttery Depletio	n	1	Max Deliv	ered Energy		35 J
Normal Battery Depletions (U	IS)	14	Software Malfur	nction		1	Estimated	Longevity		See page 4
Advisories	No	one Th	erapy Function Co	ompromised		3				
			Electrical Compo	nent		2				
			Software/Firmwa	are		1				
0 1	2	3	4	5	6	7	8		9	10
Years After Impla	ent E	xcluding N	ormal Battery	Depletion	Ind	cludin	ng Normal	Battery D	epletion	
% 100.0		99.9	99.9							
% 99.9	99.7	99.3	99.2							
# 26,500		2,130	290							
Effective Sample Size	e									



D314DRG Protecta XT DR

Product Characteristics

ase	Mar-11	Malfunctions (U	IS)			NBD Code		DDED
mplants	9,700	Therapy Funct	tion Not Comp	romised	0	Serial Number I	Prefix	PSK
e US Implants	9,500	Therapy Funct	tion Comprom	sed	0	Max Delivered	Energy	35 J
Depletions (US)	2	Electrical C	Component		0	Estimated Long	jevity	See page 4
	None	Software/F	irmware		0			
	2 3	4	5	6	7	8	9	10
After Implant at 10 mo 100.0	Exclud	ing Normal Bat	tery Depleti	on	Includin	g Normal Batt	ery Depletio	n
	mplants ve US Implants Depletions (US)	mplants 9,700 ve US Implants 9,500 Depletions (US) 2 None	mplants 9,700 Therapy Functive US Implants 9,500 Therapy Function (US) 2 Electrical Control None Software/I	mplants 9,700 Therapy Function Not Compose US Implants 9,500 Therapy Function Compromise US) 2 Electrical Component None Software/Firmware	mplants 9,700 Therapy Function Not Compromised re US Implants 9,500 Therapy Function Compromised Depletions (US) 2 Electrical Component None Software/Firmware	mplants 9,700 Therapy Function Not Compromised 0 re US Implants 9,500 Therapy Function Compromised 0 Depletions (US) 2 Electrical Component 0 None Software/Firmware 0	mplants 9,700 Therapy Function Not Compromised 0 Serial Number of the US Implants 9,500 Therapy Function Compromised 0 Max Delivered of the US Implants 2 Electrical Component 0 Estimated Long None Software/Firmware 0	mplants 9,700 Therapy Function Not Compromised 0 Serial Number Prefix The US Implants 9,500 Therapy Function Compromised 0 Max Delivered Energy Depletions (US) 2 Electrical Component 0 Estimated Longevity None Software/Firmware 0

D314VRG Protecta XT VR

240

Effective Sample Size

1471	id Flote	Cla XI VI	N .						Produc	t Charac	cteristics		
US Ma	rket Release		Mar-11	Malfu	ınctions (U	S)			NBD Cod	de		VVEV	/
Regist	ered US Implan	nts	3,700	The	rapy Functi	ion Not Comp	romised	0	Serial Nu	ımber Pref	ix	PSA	
Estima	ted Active US I	mplants	3,600	The	rapy Functi	ion Comprom	ised	0	Max Deli	ivered Ene	rgy	35 J	
Norma	l Battery Deple	etions (US)	1		Electrical C	omponent		0	Estimate	d Longevi	ty	See	page 4
Adviso	ories		None		Software/F	irmware		0					
90 80	Years After		2 3		4 rmal Batt	5 tery Depleti	6 on	7	8 ng Norma		9 / Depletio	10 n	
		at 10 mo											
%		100.0											
%		100.0											
#		110											
	Effective Sam	nple Size											



D334DRG Protecta DR

Product Characteristics

/JJ4L		cta Dit						Floudet Ch	iracteristics	
US N	larket Release		Mar-11	Malfunctions (l	JS)			NBD Code		DDED
Regi	stered US Implan	its	3,300	Therapy Func	tion Not Comp	romised	0	Serial Number	Prefix	PSP
Estin	nated Active US I	mplants	3,300	Therapy Func	tion Comprom	ised	0	Max Delivered	Energy	35 J
Norn	nal Battery Deple	etions (US)	0	Electrical	Component		0	Estimated Long	gevity	See page 41
Advi	sories		None	Software/	Firmware		0			
Device Survival Probability (%)	0		2 3 Exclud	4 ling Normal Ba	5 sttery Deplet	6 on	7 Includin	8 g Normal Batt	9 tery Depletic	10 on
Vič.		at 10 mo								
9 %	6	100.0								
9	6	100.0								
i	#	240								

D334VRG Protecta VR

Effective Sample Size

US Ma	arket Release		Mar-11	Malfunctions (US)				NBD Co	de		VVEV
Regist	tered US Implan	ts	1,800	Therapy Function N	ot Compromise	ed	0	Serial N	umber Prefix		PSX
Estima	ated Active US I	mplants	1,800	Therapy Function C	ompromised		0	Max Del	ivered Energy		35 J
Norm	al Battery Deple	etions (US)	0	Electrical Compo	nent		0	Estimate	ed Longevity		See page 41
Adviso	ories		None	Software/Firmw	are		0				
~ 100											
Device Survival Probability (%) 80 00 00											
iii 80											
obal	0	1 :	2 3	4	5	6	7	8	3	9	10
Pro l											
viva	Years After	Implant	Evaludi	ing Normal Pattory	Donlotion	Incl	udin	a Norma	al Battery D	onlotion	
Sur	rears Arter	ППРІАПІ	EXCIUA	ing Normal Battery	Depletion	IIICI	uum	3 MOIIII	ı battery D	epietion	1
ice		at 10 mo									
% Pe		100.0									
%		100.0									
#		110									
	Effective Sam	ple Size									



Device Survival Summary (95% Confidence Interval)

The following table shows ICD device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included.

		10 yr	99.3 +0.2/-0.2 at 103 mo	42.0 +3.5/-3.5 at 103 mo	99.7 +0.1/-0.1 at 101 mo	5.3 +0.9/-0.8 at 101 mo										
		8 yr 10	99.4 +0.2/-0.2 at	69.4 4.1.2/-1.3 at	99.7 +0.1/-0.1 +1	36.9 +1.3/-1.3 +1	99.8 +0.1/-0.1 at 88 mo	67.8 +2.2/-2.3 at 88 mo								
		7 yr 8	99.5	83.6 + 0.8/-0.8 +	99.7 +0.1/-0.1	71.9 +1.0/-1.0	99.8 +0.1/-0.1	79.1 6 +0.8/-0.9 +	99.2 +0.1/-0.1	10.6 +0.7/-0.6	99.7 +0.1/-0.1 at 73 mo	2.8 +0.7/-0.6 at 73 mo	99.8 +0.0/-0.1 at 81 mo	2.0 +0.8/-0.6 at 81 mo	99.7 +0.1/-0.1 at 79 mo	26.3 +1.3/-1.2 at 79 mo
		6 yr 7	99.6	93.9 +0.5/-0.5	99.7	87.0 + +0.7/-0.7	99.8	89.7	99.3	65.3 +0.7/-0.7	99.7 +0.1/-0.1	13.2 +1.0/-1.0	99.8	59.9 +0.8/-0.8	99.7 +0.1/-0.1	64.2 +0.8/-0.8 *
		5 yr	99.7 +0.1/-0.1	98.2	99.8	96.9	99.8 +0.0/-0.1	97.7 +0.2/-0.2	99.4	90.4 +0.4/-0.4	99.7 +0.1/-0.1	64.7 +0.9/-1.0	99.8	88.5	99.8	88.9
(%)		4 yr	99.8	99.0	99.8	98.4 +0.2/-0.2	99.9 +0.0/-0.1	99.1 +0.1/-0.1	99.6	96.9	99.8	90.0	99.8	97.4 +0.2/-0.2	99.8	98.1
Device Survival Probability (%)	ıt	3 yr	99.9	99.3 +0.1/-0.2	99.8 +0.1/-0.1	98.9	99.9	99.5	99.8	98.4 +0.1/-0.1	99.8	96.7	99.9	99.1	99.9	99.2
urvival Pr	Years After Implant	2 yr	99.9	99.5	99.9	99.4 +0.1/-0.1	99.9	99.7 +0.0/-0.1	99.9	99.4 +0.1/-0.1	99.9	98.8 +0.1/-0.2	99.9	99.6	99.9	99.7 +0.1/-0.1
Device S	Years Afi	1 yr	100.0	99.8 +0.1/-0.1	99.9	99.7 +0.1/-0.1	100.0	99.9	99.9	99.7 +0.0/-0.1	99.9	99.4 +0.1/-0.1	100.0	99.9	100.0	99.9
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
			Norm	Norma	Norma	Norm	Norm	Norm	Norm	Norm	Norm	Norma	Norm	Norma	Norm	Norm
Malfunctions (US)	yqeri oʻtion npromised yqeri oʻtion Not bəsimorqn la	run Con The	29 + 29 = 58 Norma	(19) + (1) (20) Norm: (advisory-related subset)	10 + 27 = 37 E	Norm.	15 + 48 = 63 Norm	(0) + (0) = (0) Norm (advisory-related subset)	107 + 83 = 190 Norm	(73) + (3) = (76) (advisory-related subset)	11 + 32 = 43 Norm:	Norm:	9 + 47 = 56 Norm:	(0) + (0) = (0) Norm: (advisory-related subset)	7 + 56 = 63 Norm	Norm
Malfunctions (US)	iction npromised serion nction Not npromised	The Fun Con The The Too	+ 29 = 58 Norm	(19) + (1) (20) Norm (advisory-related subset)	+ 27 = 37 Norm	Norm	+ 48 = 63 Norn	(0) + (0) = (0) (advisory-related subset)	+ 83 = 190	$\frac{(73)}{\text{(advisory-related subset)}} + \frac{(3)}{\text{(advisory-related subset)}}$	32 = 43 Norm	Norma	+ 47 = 56 Norm	$\begin{array}{cccc} (0) & + & (0) & = & (0) \\ (advisory-related subset) & & & & & \\ \end{array}$	56 = 63	Norm
Malfunctions (US)	regons (US) repy refion promised refion refi	Acti Imp Mon Dep The Tho Con The Tho Con	29 + 29 = 58 Norm	(19) + (1) (20) Norm (advisory-related subset)	10 + 27 = 37 Norm		15 + 48 = 63 Norn	(0) + (0) = (0) (advisory-related subset)	107 + 83 = 190	$\frac{(73)}{\text{(advisory-related subset)}} + \frac{(3)}{\text{(advisory-related subset)}}$	11 + 32 = 43 Norm	Norm	9 + 47 = 56 Norm	$\begin{array}{cccc} (0) & + & (0) & = & (0) \\ (advisory-related subset) & & & & & \\ \end{array}$	7 + 56 = 63	Norm
Malfunctions (US)	ilants mal Battery mal Battery sletions (US) repy reproduction repy reproduction repy reproduction reproducti	Esti Acti Imp Mon Mon Dep The Con The Fun The	1,143 29 + 29 = 58 Norm	(19) + (1) (20) Norm (advisory-related subset)	3.289 10 + 27 = 37 Norm		1,540 15 + 48 = 63 Norm	(0) + (0) = (0) (advisory-related subset)	8,272 107 + 83 = 190	S Potential Premature Battery (73) + (3) = (76) Norm (advisory-related subset)	4,447 11 + 32 = 43 Norm	Norm	5,706 9 + 47 = 56 Norm	$\begin{array}{cccc} (0) & + & (0) & = & (0) \\ (advisory-related subset) & & & & & \\ \end{array}$	4,623 7 + 56 = 63	Norm
Malfunctions (US)	mplants bated you lants lants lants lattery lattions latti	Regolarian	5,400 1,143 29 + 29 = 58 Norm	(19) + (1) (20) Norm (advisory-related subset)	2,400 3.289 10 + 27 = 37 Norm		21,600 1,540 15 + 48 = 63 Norm	(0) + (0) = (0) (advisory-related subset)	3,700 8,272 107 + 83 = 190	S Potential Premature Battery (73) + (3) = (76) Norm (advisory-related subset)	1,500 $4,447$ $11 + 32 = 43$ Norm	Norm	11,200 5,706 9 + 47 = 56 Norm	$\begin{array}{cccc} (0) & + & (0) & = & (0) \\ (advisory-related subset) & & & & & \\ \end{array}$	10,600 4,623 7 + 56 = 63	Norm
Malfunctions (US)	istered mplants mated ive US i	Regolarian	19,400 5,400 1,143 29 + 29 = 58 Norm	Norm	17,500 2,400 3.289 10 + 27 = 37 Norm	See page 166 – Performance note on ICD Battery Discharge Behavior	44,300 21,600 1,540 15 + 48 = 63 Norm	= (0) Norm subset)	48,300 3,700 8,272 107 + 83 = 190	(6) Norm	20,100 1,500 4,447 11 + 32 = 43 Norm	See page 166 – Performance note on ICD Battery Discharge Behavior	37,600 11,200 5,706 9 + 47 = 56 Norm	= (0) Norm subset)	30,600 10,600 4,623 7 + 56 = 63	Norm

		Market ease	jistered Implants	bətsmi SU əvi stnslo	rmal Battery Sletions	yepy notion gready yest notion hosed	ls		Years Af	Years After Implant	nt						
Number Family		Belo US	N2 Beg	its∃ toA qml	Noi JeQ	The	тоТ		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr
7290Cx Onyx		Mar-04	950	380	103	+ + =	5	Excluding Normal Battery Depletion	99.9	99.5 +0.3/-0.8	99.5 +0.3/-0.8	99.4 +0.4/-0.9	99.4 +0.4/-0.9	99.4 +0.4/-0.9	99.4 +0.4/-0.9 at 78 mo		
								Including Normal Battery Depletion	99.8 +0.2/-0.7	99.1 +0.5/-1.0	98.3 +0.7/-1.2	96.8 +1.1/-1.6	92.0	77.4 +3.5/-4.0	62.4 +5.0/-5.5 at 78 mo		
D153ATG, Entr	EnTrust	Jun-05	460	93	143	1 + 7	∞	Excluding Normal Battery Depletion	99.8 +0.2/-1.6	99.8 +0.2/-1.6	99.3 +0.5/-1.6	98.4 +0.9/-2.0	97.6 +1.2/-2.4	97.6 +1.2/-2.4 at 63 mo			
Adv	Advisories: See page 147 –2012 Potential Rapid Battery Depletion)age 147	–2012 Potei	ntial Rapid Ba	attery			Including Normal Battery Depletion	99.6 +0.3/-1.5	99.6 +1.3/-1.5	98.0 +1.0/-2.0	90.6	56.4 +5.8/-6.3	45.7 +6.2/-6.4 at 63 mo			
D154ATG, Entr D154DRG	EnTrust	Jun-05	28,100	13,700	1,813	13 + 97 =	110	Excluding Normal Battery Depletion	100.0	99.9	99.8 +0.0/-0.1	99.7 +0.1/-0.1	99.5	99.4 +0.1/-0.1	99.4 +0.1/-0.1 at 74 mo		
Adv	Advisories: See page 147 – 2012 Potential Rapid Battery Depletion) age 147	– 2012 Pote	intial Rapid B	attery			Including Normal Battery Depletion	99.9	99.7 +0.1/-0.1	99.2 +0.1/-0.1	97.6 +0.2/-0.2	89.3 +0.5/-0.5	66.7	51.4 +2.8/-2.9 at 74 mo		
D154AWG D164AWG (Non-advisory population)	Virtuoso DR	May-06	72,600	51,400	502	24 + 139 =	163	Excluding Normal Battery Depletion	100.0	99.9	99.9	99.8	99.5	99.5 +0.1/-0.1 at 63 mo			
								Including Normal Battery Depletion	99.9	99.7	99.3 +0.1/-0.1	98.3 +0.1/-0.1	93.6 +0.5/-0.5	91.0 +1.0/-1.1 at 63 mo			
D154AWG Virti D164AWG (Advisory population)	Virtuoso DR	May-06	4,100	400	57	11 + 1,850 =	1,861	Excluding Normal Battery Depletion	100.0	99.9	90.6	56.6 +1.8/-1.9 at 46 mo					
Adv	Advisories: See page 150 – 2009 Potential Reduced Device Longevity	oage 150	– 2009 Pote	ential Reduce	ed Device			Including Normal Battery Depletion	99.9	99.6 +0.2/-0.3	80.9 +1.3/-1.4	7.3 +1.2/-1.1 at 46 mo					
See Inte	See page 161 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	erformanc Technolo	e note on A gy	nomalies in l	MOSFET												
D154VRC EnTr	EnTrust VR	Jun-05	14,400	8,100	171	= 09 + 6	69	Excluding Normal Battery Depletion	99.9	99.9	99.8	99.7 +0.1/-0.1	99.4 +0.1/-0.2	99.2 +0.2/-0.2	99.2 +0.2/-0.2 at 76 mo		
Adv	Advisories: See page 147 – 2012 Potential Rapid Battery Depletion) age 147	– 2012 Pote	ntial Rapid B	attery			Including Normal Battery Depletion	99.9	99.6 +0.1/-0.1	99.3 +0.1/-0.2	98.8 +0.2/-0.2	97.6 +0.3/-0.3	91.4 +0.9/-1.0	88.3 +2.0/-2.4 at 76 mo		
D154VWC D164VWC (Non-advisory population)	Virtuoso VR	May-06	33,100	23,400	76	12 + 29 =	14	Excluding Normal Battery Depletion	100.0	100.0	99.9	99.9	99.8 +0.1/-0.1	99.8 +0.0/-0.1 at 62 mo			
Adv	Advisories: See page 150 – 2009 Potential Reduced Device Longevity	oage 150	– 2009 Pote	ential Reduce	ed Device	$\frac{(0)}{(advisory-related subset)}$	3 oset)	Including Normal Battery Depletion	99.9	99.8	99.6 +0.1/-0.1	99.3 +0.1/-0.1	98.4 +0.3/-0.3	98.4 +0.3/-0.3 at 62 mo			
See Inte	See page 161 – Performance note on Anomalies in MOSFET Integrated Circuit Technology	erformanc Technolo	e note on A gy	nomalies in I	MOSFET												

					E	Malfunctions	ctior	SI			Device 5	Survival P	Device Survival Probability (%)	(%)					
- G		Market ease	jistered Implants	bətsmi ZU əvi stnslo	mal Battery snoifelons	erapy sction npromised	rapy oction Not	npromised	ls		Years Af	Years After Implant	nt						
Number	Family	NS NS	SU Beg	ĵэА	Noi	ın4	эчт	102	toT		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	
D224DRG	Secura DR	Sep-08	45,300	40,000	99	9	+	17 =	= 23	Excluding Normal Battery Depletion	100.0	100.0	99.9	99.9 +0.0/-0.1 at 40 mo					
										Including Normal Battery Depletion	99.9	99.7 +0.0/-0.1	99.2 +0.1/-0.2	99.2 +0.1/-0.2 at 40 mo					
D224VRC	Secura VR	Sep-08	17,600	15,500	18	ю	+	5 =	∞	Excluding Normal Battery Depletion	100.0	100.0	99.9	99.9 +0.0/-0.1 at 40 mo					
										Including Normal Battery Depletion	99.9	99.7 +0.1/-0.1	99.3 +0.2/-0.2	99.2 +0.2/-0.3 at 40 mo					
D274DRG	Virtuoso II DR	Aug-09	21,600	19,600	9	0	+	0	0	Excluding Normal Battery Depletion	100.0	100.0	99.9	99.9 +0.0/-0.1 at 40 mo					
										Including Normal Battery Depletion	99.9	99.7 +0.0/-0.1	99.2 +0.1/-0.2	99.2 +0.1/-0.2 at 40 mo					
D274VRC	Virtuoso II VR	Aug-09	8,800	8,000	е	0	+	0	0	Excluding Normal Battery Depletion	100.0	100.0	99.9 +0.0/-0.1	99.9 +0.0/-0.1 at 40 mo					
										Including Normal Battery Depletion	99.9	99.7 +0.1/-0.1	99.3	99.2 +0.2/-0.3 at 40 mo					
D284DRG	Maximo II DR	Sep-08	17,200	15,100	21	ю	+	2 =	- 5	Excluding Normal Battery Depletion	100.0	100.0+0.0/-0.0	99.9	99.9 +0.0/-0.1 at 40 mo					
										Including Normal Battery Depletion	99.9	99.7 +0.0/-0.1	99.2 +0.1/-0.2	99.2 +0.1/-0.2 at 40 mo					
D284VRC	Maximo II VR	Sep-08	10,800	6,500	41	ĸ	+	2 =	5	Excluding Normal Battery Depletion	100.0	100.0	99.9	99.9 +0.0/-0.1 at 40 mo					
										Including Normal Battery Depletion	99.9	99.7 +0.1/-0.1	99.3	99.2 +0.2/-0.3 at 40 mo					

		7 yr 8 yr								
		6 yr								
		5 yr								
ty (%)		4 yr								
Device Survival Probability (%)	ant	3 yr								
Survival	Years After Implant	2 yr								
Device	Years A	1 yr	100.0 +0.0/-0.0 at 10 mo							
			Excluding Normal Battery Depletion	Including Normal Battery Depletion						
	ls	toT	0		0		0		0	
tions	yapy nction Not npromised la	107	0		0		0		0	
Malfunctions	ubromised	The The Truit	II		II		II		II	
Malfunctions	nction psemised stapy oction Not sed	The Fur To The The TuT Cor	II 0 +		0 +		0 +		II 0 +	
Malfunctions	yletions yrapy npromised srapy rction Not mpromised	Act Mongard Mo	0 + 0		0 +		0 + 0		0 + 0	
Malfunctions	ive US hlants mal Battery snations repy rction npromised notion ortion Not notion Not my notion Not	Estination of the control of the con	2 0 + 0 =		0 + 0		0 + 0		= 0 + 0 0	
Malfunctions	Implants inated ive US slants slants slattery srapy rrapy srapy srapy rrapy srapy srapy srapy srapy srapy srapy srapy srapy srapy	Reli Nos Imp Imp Imp The Fun Con The Fun Fun Con	9,500 2 0 + 0 =		3,600 1 0 + 0 =		3,300 0 + 0 =		1,800 0 + 0 =	
Malfunctions	pistered Implants Implants Inseed Ins	Reli Nos Imp Imp Imp The Fun Con The Fun Fun Con	9,700 9,500 2 0 + 0 =		3,700 3,600 1 0 + 0 =		3,300 3,300 0 + 0 =		1,800 1,800 0 + 0 =	



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly

					Es	timated	Longev	ity		Elective		
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing		Charge Grant Charg	End of Life (EOL) Battery Voltage
7227	GEM	B, Cx, D, E	49 cc* 90 g	35 J	Monthly Quarterly Semiannual	5.3 7.7 8.8	5.7 8.5 10.0	6.0 9.3 11.0	6.1 9.6 11.5	≤ 2.55 V	_	≤ 2.40 V§
7230	Marquis VR	B, Cx, E	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.9 7.3 8.5	5.2 8.0 9.3	5.4 8.5 10.0	5.5 8.7 10.4	≤ 2.62 V	> 16-second charge time	3 months after ERI
7231Cx	GEM III VR	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	4.3 6.0 6.6	4.7 6.8 7.5	5.0 7.4 8.5	5.2 7.8 8.9	≤ 2.55 V	_	≤ 2.40 V
7232	Maximo VR	B, Cx, E	39 cc 76 g	35 J	Monthly Quarterly Semiannual	4.4 7.0 8.2	4.7 7.5 9.0	4.8 8.0 9.7	4.9 8.3 10.0	≤ 2.62 V	> 16-second charge time	3 months after ERI
7271	GEM DR	DR	62 cc 115 g	35 J	Monthly Quarterly Semiannual	6.0 7.4 7.9	6.9 8.4 9.0	7.5 9.3 10.0	7.8 9.8 10.6	≤ 4.91 V	_	≤ 4.57 V§
7274	Marquis DR	DR+LV	36 cc 75 g	30 J	Monthly Quarterly Semiannual	4.0 5.6 6.2	4.4 6.4 7.2	4.8 7.1 8.1	4.9 7.5 8.6	≤ 2.62 V	> 16-second charge time	3 months after ERI
7275	GEM III DR	DR	39.5 cc 78 g	30 J	Monthly Quarterly Semiannual	3.3 4.2 4.5	3.8 5.0 5.5	4.3 5.8 6.5	4.4 6.3 7.0	≤ 2.55 V	_	≤ 2.40 V
7278	Maximo DR	DR	39 cc 77 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7288	Intrinsic	DR	38 cc 76 g	35 J	Monthly Quarterly Semiannual	3.7 5.3 6.0	4.1 6.1 7.0	4.3 6.8 8.0	4.5 7.1 8.5	≤ 2.62 V	> 16-second charge time	3 months after ERI
7290Cx	Onyx	Сх	39 cc 77 g	30 J	Monthly Quarterly Semiannual	3.8 5.0 5.4	4.1 5.6 6.1	4.3 6.2 6.7	4.5 6.4 7.0	≤ 2.55 V		≤ 2.40 V

^{*} Volume and mass differ by connector style.

 $[\]ensuremath{^{**}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

^{***} The minimum time between ERI and EOL is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber and CRT models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel. CRT models with shared biventricular pacing; InSync Marquis 7277 (LV impedance set to 510 ohms), InSync ICD 7272 (RV amplitude set to 4.0 V).

[§] For Model 7271 and 7227 devices, if charge time exceeds 30 seconds, the device is at EOL. Immediate replacement is recommended. If three consecutive charge cycles exceed 30 seconds, the "charge circuit inactive" indicator is tripped and all therapies except emergency VVI pacing are disabled.



Reference Chart continued

						stimated	d Longe	/ity		Recomn Replac (RRT	ement	
Model Number	Family	Connector Style	Volume/ Mass*	Delivered Energy	Charging Frequency**	100% Pacing‡	50% Pacing‡	15% Pacing‡	100% Sensing	Battery Voltage	Charge Time	End of Service (EOS)
D153ATG, D153DRG	EnTrust	DR	33 cc 63 g	30 J	Monthly Quarterly Semiannual	3.5 4.8 5.3	3.8 5.4 6.1	4.1 6.0 6.9	4.2 6.3 7.2	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154ATG, D154DRG	EnTrust	DR	35 cc 68 g	35 J	Monthly Quarterly Semiannual	3.8 5.5 6.1	4.2 6.1 7.0	4.4 6.8 7.9	4.6 7.0 8.3	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154AWG, D164AWG	Virtuoso DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.1 6.3 7.3	4.5 7.3 8.7	4.8 8.3 10.1	5.0 8.8 11.0	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D154VRC	EnTrust VR	Сх	35 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 7.5 9.0	5.0 8.3 10.0	5.2 8.8 10.7	5.3 9.0 11.0	≤ 2.61 V	_	3 months after RRT or > 16-second charge time
D154VWC, D164VWC	Virtuoso	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.8 8.1 10.0	5.1 9.0 11.2	5.3 9.6 12.3	5.4 10.0 12.9	≤ 2.62 V	_	3 months after RRT or > 16-second charge time
D224DRG	Secura DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.1 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D224VRC	Secura VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.7 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D274DRG	Virtuoso II DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D274VRC	Virtuoso II VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D284DRG	Maximo II DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.1 7.0	4.5 7.0 8.2	4.6 7.5 9.0	≤ 2.63 V	_	3 months after RRT or > 16-second charge time
D284VRC	Maximo II VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.6 7.7	4.6 7.4 8.8	4.9 8.1 9.7	5.0 8.4 10.2	≤ 2.63 V	_	3 months after RRT or > 19-second charge time
D314DRG	Protecta XT DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT
D314VRG	Protecta XT VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT
D334DRG	Protecta DR	DR	37 cc 68 g	35 J	Monthly Quarterly Semiannual	3.6 5.1 5.7	4.1 6.0 7.0	4.5 7.0 8.3	4.7 7.5 9.0	≤ 2.63 V	_	3 months after RRT
D334VRG	Protecta VR	Сх	37 cc 68 g	35 J	Monthly Quarterly Semiannual	4.3 6.7 7.8	4.7 7.5 8.9	4.9 8.1 9.8	5.0 8.4 10.3	≤ 2.63 V	_	3 months after RRT

^{*} Volume and mass differ by connector style.

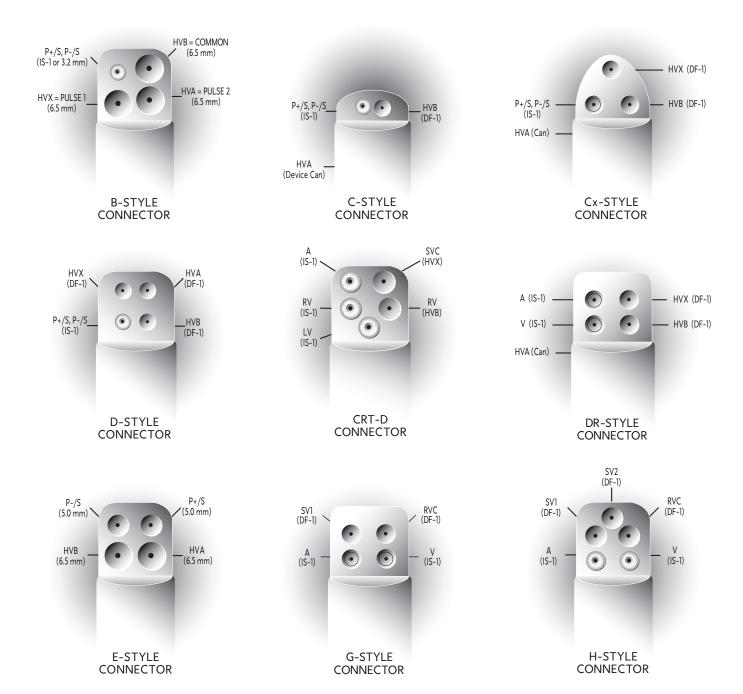
 $[\]ensuremath{^{**}}$ A full charge is a full energy the rapeutic shock or capacitor reformation.

^{***} The minimum time between RRT and EOS is 3 months (100% pacing, two charges per month).

[‡] Pacing mode is VVI for single chamber models and DDD for dual chamber models. Parameter settings; lower rate at 60 ppm, sensing rate at 70 bpm, (A, RV, LV) 3.0 V amplitude, 0.4 ms pulse width, and 510-ohm pace load per applicable channel.



ICD Connector Styles

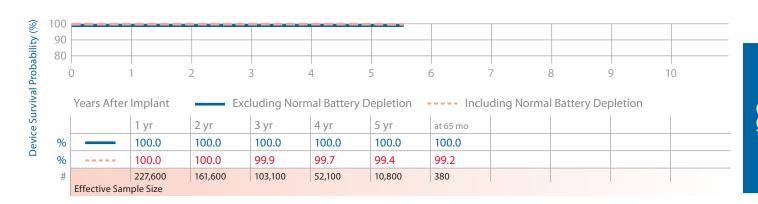




Adapta DR ADDR01, ADDR03, ADDR06, ADD01

Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	51	NBG Code	DDDR, DDD
Registered US Implants	291,500	Therapy Function Not Compromised	32	Serial Number Prefix	PWB, PWD,
Estimated Active US Implants	242,600	Electrical Component	31		PWC, PWF, NWB, NWC,
Normal Battery Depletions (US)	155	Electrical Interconnect	1		NWD, NWF
Performance Note: See page 159 –		Therapy Function Compromised	19	Estimated Longevity	See page 78
Performance note on Dual Chamber Pacemakers with Measurement Lock-up ER		Electrical Component	17		
r decinaters with measurement book up and		Electrical Interconnect	2		



Adapta DR ADDRL1

Product Characteristics

S Marke	et Release		Jul-	06 Malf	unctions (US)			5	NBG Code		DDDR
egister (ed US Implants	5	53,9	00 The	erapy Function	Not Compromis	ed	4	Serial Number Prefix		PWE, NWE
stimate	ed Active US Im	plants	48,9	00	Electrical Comp	onent		4			
ormal F	Battery Deplet	ions (US)		9 The	rapy Function	Compromised		1	Estimated Longevity		See page 78
erforma	ance Note: <u>See</u> ance note on D kers with Measu	ual Chamber	up ERI		Electrical Interd	connect		1			
100 =											
80 -	1		2	3	4	5	6	7	8	9	10
1	Years After I	Implant	Ex	cluding No	ormal Battery	/ Depletion	Inc	ludin	g Normal Battery [)epletion	า
		1 yr	2 yr	3 yr	4 yr	5 yr	at 62 mo				
%		100.0	100.0	100.0	100.0	100.0	100.0				
-		100.0	100.0	99.9	99.7	99.7	99.7				
%		100.0	100.0	22.2	22.7	22.7	99.7				

Effective Sample Size

Adapta DR ADDRS1

Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	5	NBG Code	DDDR
Registered US Implants	28,000	Therapy Function Not Compromised	3	Serial Number Prefix	PWA, NWA
Estimated Active US Implants	21,400	Electrical Component	2		
Normal Battery Depletions (US)	84	Possible Early Battery Depletion	1	Estimated Longevity	See page 78
		Therapy Function Compromised	2		
Performance Note: <u>See page 159</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up EF	RI	Electrical Component	2		

100	0										
90)										
80)										
	1	1	2	2	1	Г Г		7	0	0	10
	0	I	2	3	4	5	6	/	8	9	10
	Years After	Implant	E	xcluding No	ormal Battery	/ Depletion	Inc	luding No	ormal Batte	ry Depletion	on
	Years After	Implant 1 yr	E	xcluding No	ormal Battery 4 yr	Depletion 5 yr	at 63 mo	luding No	ormal Batte	ery Depletio	on
%			1	_			1	luding No	ormal Batte	ry Depletion	on
% %		1 yr	2 yr	3 yr	4 yr	5 yr	at 63 mo	luding No	ormal Batte	ry Depletion	on
		1 yr	2 yr	3 yr	4 yr	5 yr	at 63 mo	luding No	ormal Batte	ery Depletion	on

Adapta SR ADSR01, ADSR03, ADSR06

US Mark	ket Release		Jul-0	6 Malf	unctions (US)			5	NBG Code			SSIR
Register	red US Implant	ts	54,00	00 The	rapy Function	Not Compromi	sed	1	Serial Nun	nber Prefix		NWN, NWM,
Estimate	ed Active US In	nplants	38,10	00	Electrical Comp	oonent		1				NWP, PWP, PWM, PWN
Normal	Battery Deple	tions (US)	7	2 The	erapy Function	Compromised		4	Estimated	Longevity		See page 78
Advisor	ies		Nor	ie	Electrical Comp	oonent		3				
					Electrical Interd	connect		1				
100												
90												
80												
()	1	2	3	4	5	6	7		3	9	10
	Years After	Implant	Exc	cluding No	ormal Battery	y Depletion	Inc	cludir	ng Normal	Battery De	pletion	
90 80		1 yr	2 yr	3 yr	4 yr	5 yr	at 64 mo					
%		100.0	100.0	100.0	100.0	100.0	100.0					
%		100.0	100.0	99.7	99.3	98.3	98.3					
#		38,500	26,400	16,100	7,690	1,450	100					
	Effective Sam	ple Size										



Adapta VDD ADVDD01

Product Characteristics

	DD AD								Product C			
S Market	Release		Jul-0	6 Malfun	ctions (US)			0	NBG Code			VDD
egistered	l US Implant	S	89	0 Thera	py Function N	lot Compromis	ed	0	Serial Numb	er Prefix		PWG, NWG
stimated	Active US In	nplants	69	0 Thera	py Function C	ompromised		0	Estimated Lo	ngevity		See page
ormal Ba	ttery Deplet	ions (US)		0								
erforman	ce note on D	e page 159 – Dual Chamber urement Lock-I	up ERI									
100												
80		1	2	3	4	5	6	7	8	(9	10
	ears After	Implant	— Ехс	cluding Norr	nal Battery	Depletion	Ir	ncludin	g Normal Ba	attery De	epletion	
Y ∈		1 vr	2 vr	3 vr	4 vr	at 53 mo						
		1 yr	2 yr	3 yr	4 yr	at 53 mo						
%		100.0	100.0	100.0	100.0	100.0						
			-	+ -								

AT500 AT501, 7253 **Product Characteristics**

JS Market Re	ease	Mar-0	Malfu	unctions (US)			9	NBG Code		DDDRP
egistered US	Implants	10,80	0 The	rapy Function N	lot Compromise	ed	4	Serial Number Pre	efix	IJF
stimated Ac	ive US Implants	1,14	10	Electrical Compo	onent		1	Estimated Longer	vity	See page
lormal Batte	y Depletions (US)	2,65	58	Possible Early Ba	attery Depletion		3			
	Note: See page 164 –		The	rapy Function C	ompromised		5			
	note on AT500 Pacing v-Up Protocol			Electrical Compo	onent		3			
,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	. op motoco.			Electrical Interco	onnect		1			
					5 1					
				Possible Early Ba	ittery Depletion		1			
100										
100										
90										
70										
60										
50										
40										
30										
20										
10						\				
0										
0	1	2	3	4	5	6	7	8	9	10
		_							-	
Year	s After Implant	Exc	cluding No	rmal Battery	Depletion	Inc	ludin	g Normal Batte	ry Depletion	
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 8	31 mo		
			+ -			+ -				

84.3

5,540

50.7

2,400

9.4

300

99.8

8,920

99.5

8,160

97.6

7,360

99.9

9,660

Effective Sample Size

%



EnPulse DR E1DR01, E1DR03, E1DR06

Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

US Market Release	Dec-03
Registered US Implants	6,820
Estimated Active US Implants	2,630
Normal Battery Depletions (US)	550
Performance Note: See page 159 –	

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P	Product Characteristics					
N	BG Code	DDDR				

Serial Number Prefix	PRA, PRB, PRE
Estimated Longevity	See page 78

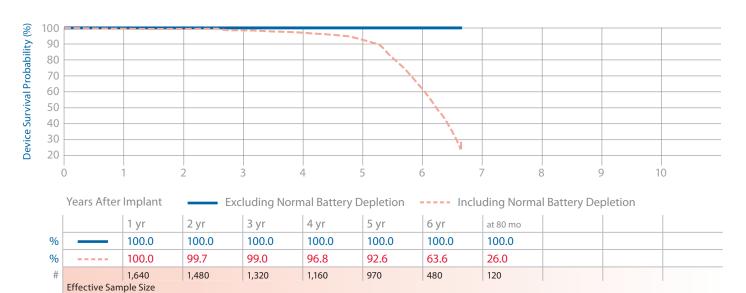
0											
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0 -									1		
0	1		2	3	4	5	6	7	8	9	10
	1 Years After		I	xcluding No	ormal Batter		Inc	7 cluding Norn	nal Battery		
		Implant	2 E			5 y Depletion 5 yr		7 cluding Norn 7 yr			
			I	xcluding No	ormal Batter		Inc	1	nal Battery		
_		1 yr	2 yr	excluding No	ormal Batter	5 yr	Ind	7 yr	nal Battery 8 yr		

EnPulse DR E1DR21

US Market Release	Dec-03
Registered US Implants	1,850
Estimated Active US Implants	190
Normal Battery Depletions (US)	349
D (N . C	

Performance Note: See page 159 -Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

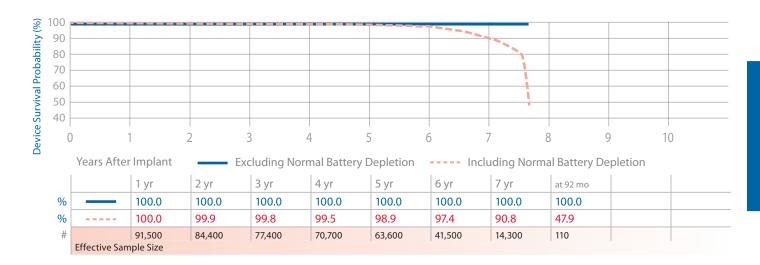
Malfunctions (US)	0	NBG Code	DDDR
Therapy Function Not Compromised	0	Serial Number Prefix	PPT
Therapy Function Compromised	0	Estimated Longevity	See page 78





EnPulse 2 DR E2DR01, E2DR03, E2DR06

	,				
US Market Release	Feb-04	Malfunctions (US)	23	NBG Code	DDDR
Registered US Implants	100,700	Therapy Function Not Compromised	17	Serial Number Prefix	PNB, PNC, PNH
Estimated Active US Implants	54,700	Electrical Component	15		
Normal Battery Depletions (US)	2,003	Electrical Interconnect	2	Estimated Longevity	See page 78
Performance Note: See page 159 –		Therapy Function Compromised	6		
Performance note on Dual Chamber		Battery	1		
Pacemakers with Measurement Lock-up I	-NI	Electrical Component	3		
		Electrical Interconnect	2		

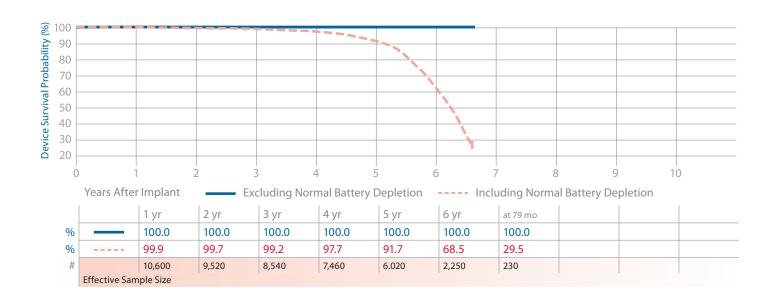


EnPulse 2 DR E2DR21

Performance note on Dual Chamber
Pacemakers with Measurement Lock-up ERI

Product Characteristics

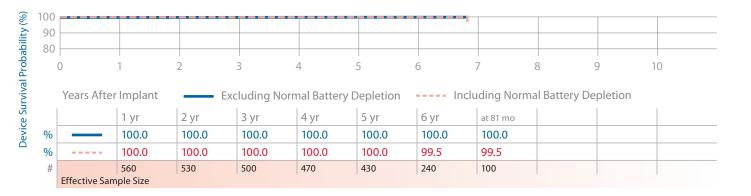
US Market Release	Feb-04	Malfunctions (US)	1	NBG Code	DDDR
Registered US Implants	12,200	Therapy Function Not Compromised	0	Serial Number Prefix	PMU
Estimated Active US Implants	3,560	Therapy Function Compromised	1	Estimated Longevity	See page 78
Normal Battery Depletions (US)	1,268	Electrical Component	1		
Performance Note: See page 159 –					



EnPulse 2 DR E2DR31, E2DR33

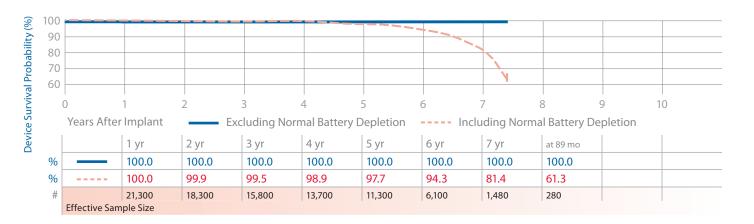
Product Characteristics

US Market Release	Feb-04	Malfunctions (US)	0	NBG Code	DDDR
Registered US Implants	580	Therapy Function Not Compromised	0	Serial Number Prefix	PNL, PNM
Estimated Active US Implants	420	Therapy Function Compromised	0	Estimated Longevity	See page 78
Normal Battery Depletions (US)	2				
Performance Note: <u>See page 159</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI					



EnPulse 2 SR E2SR01, E2SR03, E2SR06

US Market Release	Dec-03	Malfunctions (US)	4	NBG Code	SSIR
Registered US Implants	25,500	Therapy Function Not Compromised	3	Serial Number Prefix	PMW, PMY,
Estimated Active US Implants	9,160	Electrical Component	2		PNA
Normal Battery Depletions (US)	638	Possible Early Battery Depletion	1	Estimated Longevity	See page 78
Advisories	None	Therapy Function Compromised	1		
		Other	1		



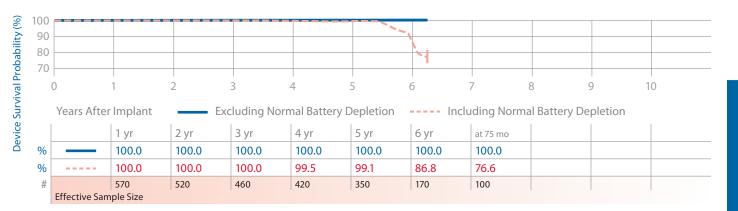


EnPulse 2 VDD E2VDD01

Pacemakers with Measurement Lock-up ERI

Product Characteristics

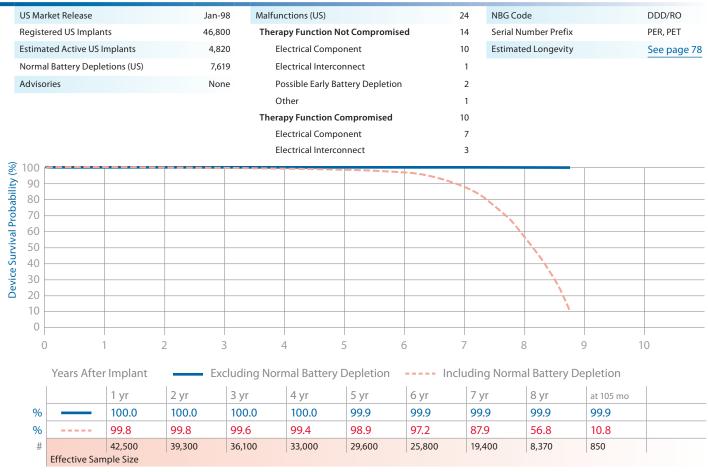
US Market Release	Dec-03	Malfunctions (US)	0	NBG Code	VDD
Registered US Implants	640	Therapy Function Not Compromised	0	Serial Number Prefix	PMV
Estimated Active US Implants	260	Therapy Function Compromised	0	Estimated Longevity	See page 78
Normal Battery Depletions (US)	44				
Performance Note: <u>See page 159</u> – Performance note on Dual Chamber					



EnRhythm DR P1501DR

US Ma	rket Release		May-0	5 Malfu	nctions (US)			2,898	NBG Code	DDDRP
Regist	tered US Implan	ts	109,70) Ther	Therapy Function Not Compromised			2,851	Serial Number Prefix	PNP
Estima	ated Active US Ir	mplants	76,30)	Battery (183 mo	alfunctions rela	ted to advisory)	2,794	Estimated Longevity	See page 78
Norma	al Battery Deple	tions (US)	29	5	Electrical Comp to advisory)	ponent (1 malf	unction related	22		
					Possible Early E related to advis		on (1 malfuncti	ion 33		
					Electrical Inter	connect		2		
Advis	ories: See page	e 148 – 2010 Lo	w Battery	Ther	apy Function Co	mpromised		47		
	ge Displayed at I				Battery			5		
	rmance Note: Se				Electrical Com	ponent		36		
	nalies in MOSFET t Technology	Integrated			Electrical Inter	connect		4		
Circui	t recimology				Possible Early E	Battery Depleti	on	2		
§ 100										
90 90										
opapi 80 70							7-1			
Pro										
ival) 1	2	. 3		4 5	5	6	7 8	9	10
Device Survival Probability (%)	Years After	Implant	Exc	luding No	rmal Battery [Depletion	Inc	luding Normal	Battery Depletion	
vice		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	at 77 mo		
å %		100.0	100.0	99.9	99.5	97.0	91.1	90.3		
%		100.0	99.9	99.7	98.9	93.5	79.8	74.6		
#		97,500	80,900	64,600	49,600	33,700	8,740	790		
	Effective Sam	ple Size							·	·

Kappa 400 DR KDR401, KDR403



ppa	400 SK	KSR401, KS	K4U3							Produc	t Characte	eristics	
US Ma	rket Release		Feb	-98	Malfun	ctions (US)			5	NBG Cod	de		SSIR
Registered US Implants			15,	400	Thera	py Function	Not Compromi	sed	4	Serial Number Prefix		PEU, PGD	
Estima	ated Active US	Implants	1,	710	Ele	ectrical Comp	oonent		3	Estimate	ed Longevity		See page 7
Norma	al Battery Dep	etions (US)	1,	435	Po	ssible Early E	Battery Depletion	on	1				
Adviso	ories		N	one	Thera	py Function	Compromised		1				
					Ele	ectrical Interd	connect		1				
100													
90)								-	_			
80)												
70)												
60)												
50)												
40)												
30)										<u> </u>		
20)												
10)											1	
0)												
	0	1	2	3		4	5	6	7		8	9	10
	Years Afte	er Implant		xcludir	ng Norr	nal Battery	y Depletion	In	cludin	g Norma	al Battery D	epletion	
		1 yr	2 yr	3 yr		4 yr	5 yr	6 yr	7 y	/r	8 yr	9 yr	at 109 mo
%		100.0	100.0	100	.0	100.0	100.0	100.0	10	0.0	100.0	100.0	100.0
%		99.8	99.7	99.5	5	99.0	98.5	96.8	90	.5	63.9	17.0	10.3
#		13,000	11,300	9,830	0	8,550	7,290	5,990	4,4	90	2,070	200	100

25,000

1,930

3,789



US Market Release Registered US Implants

#

20,900

Effective Sample Size

19,000

17,000

15,200

Estimated Active US Implants

Normal Battery Depletions (US)

Performance Note: See page 159 -Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

Advisories: See page 157 – 2002 Potential Fractured Power Supply Wires; See also page 151 - 2009 Potential Separation of Interconnect Wires

Kappa 600 DR KDR601, KDR603, KDR606

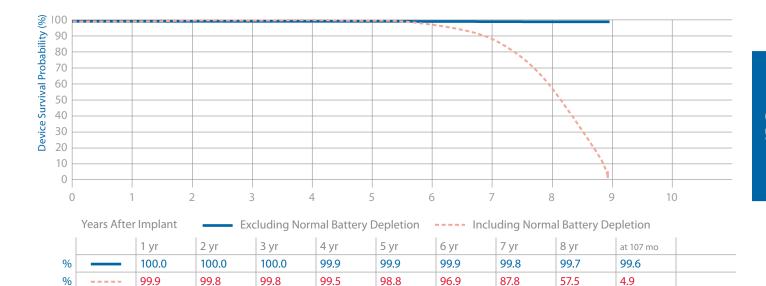
Malfunctions (US)	63
Therapy Function Not Compromised	5
Electrical Component	4
Other	1
Therapy Function Compromised	58
Electrical Component	3
Electrical Interconnect (34 malfunctions related to advisory)	55

Product Characteristics

NBG Code	DDD/RO
Serial Number Prefix	PHF, PHH, PHG
Estimated Longevity	See page 78

240

4,110



13,400

8,790

11,500



%

100.0

12,500

Effective Sample Size

99.9

11,400

99.8

10,300

99.4

9,160

Kappa 600 DR KDR651, KDR653

Product Characteristics

ρū	000 DK	KDNO51, KI	DIOJJ							riouuc	.t Characte	ristics	
S Ma	rket Release			Mar-01	Malfund	ctions (US)			56	NBG Cod	le		DDD/RO
legistered US Implants				16,400	Therapy Function Not Compromised			3	Serial Number Prefix			PLJ, PLK	
stima	ited Active US	Implants		1,340	Ele	ectrical Comp	onent		1	Estimate	d Longevity		See page
orma	al Battery Depl	etions (US)		2,717	Po	ssible Early B	attery Deplet	ion	2				
dviso	ories: See pag	e 157 – 2002	Potential		Thera	y Function (Compromised	d	53				
	red Power Sup				Ele	ctrical Comp	onent		1				
	151 – 2009 Pot onnect Wires	tential Separat	tion of			ctrical Interc			52				
	mance Note: S	ee page 159 <i>–</i>			(30 malfunctions related to advisory)								
erfori	mance note on	Dual Chambe	r										
acem	akers with Mea	asurement Loc	k-up ERI										
100													
90													
80													
70													
60													
50										,			
40													
30 20											1		
10											1		
0											1		
	0	1	2	3		 4	5	6	7		1 3	9	10
	U	I	_	3		→	J	Ü	/	(O .	J	10
	Years Afte	r Implant		Excludi	ing Norn	nal Battery	Depletion		Includi	ng Norma	l Battery D	epletion	
		1 yr	2 yr	3 y	r	4 yr	5 yr	6 yr	7	yr	8 yr	at 103 mo	
%		100.0	100.0	100	2.0	100.0	100.0	99.9		9.7	99.5	99.4	

98.2

8,080

94.9

6,960

81.2

4,960

43.7

1,850

6.3

170

Jan-99

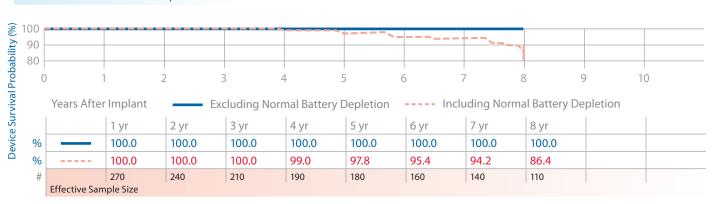


US Market Release

Kappa 700 D KD701, KD703, KD706

Malfunctions (US) 0 NBG Code DDD Serial Number Prefix PHK, PHM, PHL **Therapy Function Not Compromised** 0 **Therapy Function Compromised Estimated Longevity** 0 See page 79

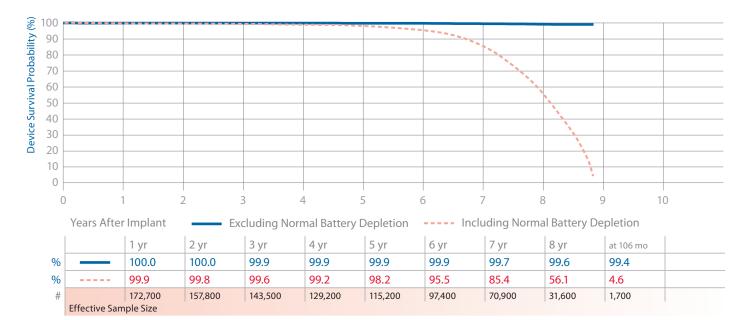
Registered US Implants	310					
Estimated Active US Implants	67					
Normal Battery Depletions (US)	17					
Advisories: See page 157 – 2002 Potential Fractured Power Supply Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires						
Performance Note: See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up FRI						



Kappa 700 DR KDR701, KDR703, KDR706

US Market Release	Jan-99	Malfunctions (US)	740
Registered US Implants	206,300	Therapy Function Not Compromised	38
Estimated Active US Implants	30,000	Battery	1
Normal Battery Depletions (US)	32,080	Electrical Component	27
Advisories: See page 157 – 2002 Potential Fractured Power Supply Wires; See also		Electrical Interconnect (1 malfunction related to advisory)	3
page 151 – 2009 Potential Separation of		Possible Early Battery Depletion	4
Interconnect Wires		Other	3
Performance Note: See page 159 –		Therapy Function Compromised	702
Performance note on Dual Chamber		Electrical Component	17
Pacemakers with Measurement Lock-up ERI		Electrical Interconnect (416 malfunctions related to advisory)	684
		Possible Early Battery Depletion	1



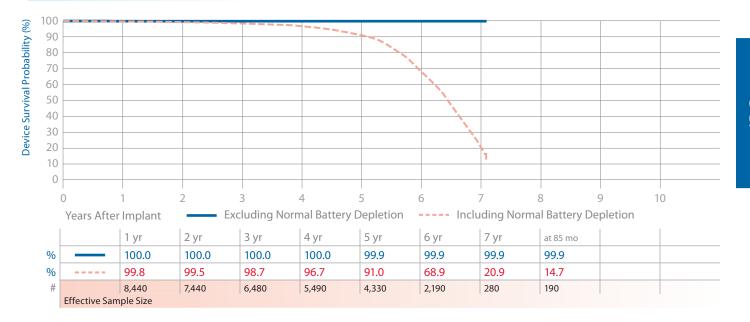




Kappa 700 DR KDR721

Performance Note: See page 159 -Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

appa 700 DR KDR721				Product Characteristics	
US Market Release	Feb-99	Malfunctions (US)	5	NBG Code	DDD/RO
Registered US Implants	9,830	Therapy Function Not Compromised	1	Serial Number Prefix	PGR
Estimated Active US Implants	780	Electrical Component	1	Estimated Longevity	See page 79
Normal Battery Depletions (US)	1,342	Therapy Function Compromised	4		
Advisories: See page 157–2002 Potential Fractured Power Supply Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires		Electrical Interconnect (4 malfunctions related to advisory)	4		



IPG

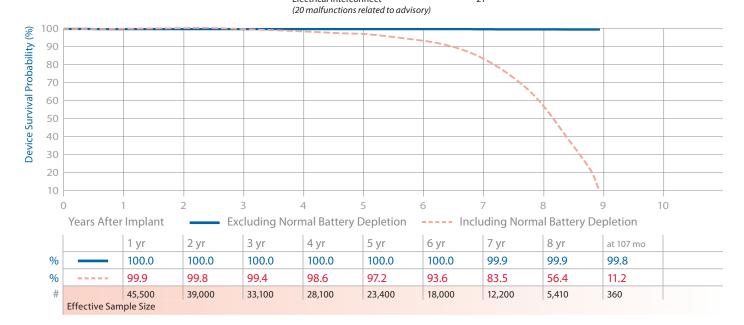
Kappa 700 SR KSR701, KSR703, KSR706

US Market Release	Jan-99	Malf
Registered US Implants	55,300	The
Estimated Active US Implants	6,960	
Normal Battery Depletions (US)	4,754	
Advisories: See page 151 – 2009 Potent Separation of Interconnect Wires	tial	The

Malfunctions (US)	28
Therapy Function Not Compromised	3
Electrical Component	2
Possible Early Battery Depletion	1
Therapy Function Compromised	25
Electrical Component	4
Electrical Interconnect	21

Product Characteristics

NBG Code	SSIR
Serial Number Prefix	PHT, PHW, PHU
Estimated Longevity	See page 79



Kappa 700 VDD KVDD701

US Market Release Jan-99 Registered US Implants 1,690 Estimated Active US Implants 210 Normal Battery Depletions (US) 172 Advisories: See page 157 – 2002 Potential

page 151 – 2009 Potential Separation of Interconnect Wires

Performance Note: See page 159 –
Performance note on Dual Chamber

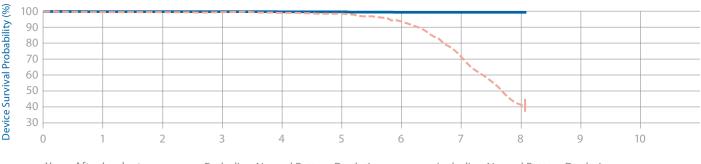
Pacemakers with Measurement Lock-up ERI

Fractured Power Supply Wires; See also

Product Characteristics

Malfunctions (US)	4	NBG Code	VDD/RO
Therapy Function Not Compromised	0	Serial Number Prefix	PHP
Therapy Function Compromised	4	Estimated Longevity	See page 79

Electrical Interconnect (4 malfunctions related to advisory)



	Years After Implant		Exc	luding Norn	nal Battery D	Depletion	Including Normal Battery Depletion				
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 97 mo	
%		99.9	99.9	99.9	99.8	99.8	99.6	99.6	99.6	99.6	
%		99.8	99.6	99.1	98.6	98.4	94.1	72.7	41.9	41.1	
#		1,480	1,320	1,180	1,050	960	790	430	110	100	
	Effective Sam	ple Size									



Kappa 800 DR KDR801, KDR803

Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

US Market Release	Jan-02
Registered US Implants	4,280
Estimated Active US Implants	840
Normal Battery Depletions (US)	592
Performance Note: <u>See page 159</u> –	

Therapy Function Compromised Electrical Interconnect

Malfunctions (US)

Therapy Function Not Compromised

Product Characteristics

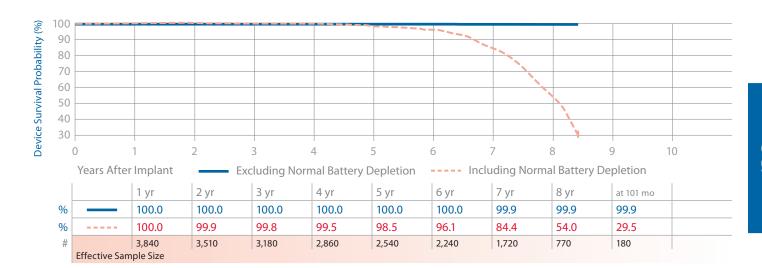
3

0

3

3

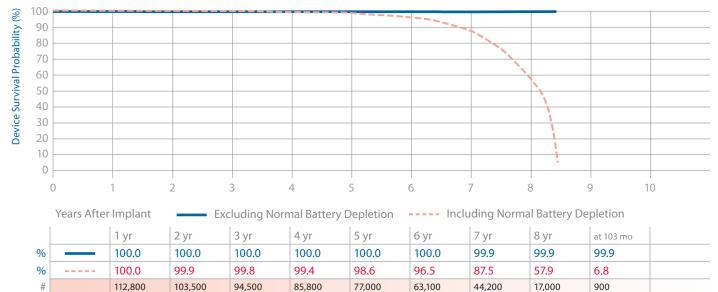
NBG Code	DDD/RO
Serial Number Prefix	PKW, PKY
Estimated Longevity	See page 79



Kappa 900 DR KDR901, KDR903, KDR906

Product Characteristics

US Market Release	Jan-02	Malfunctions (US)	74	NBG Code	DDR/RO
Registered US Implants	125,400	Therapy Function Not Compromised	18	Serial Number Prefix	PKM, PKN, PKP
Estimated Active US Implants	37,800	Electrical Component	16		
Normal Battery Depletions (US)	13,888	Electrical Interconnect	1	Estimated Longevity	See page 79
Performance Note: See page 159 –		Other	1		
Performance note on Dual Chamber Pacemakers with Measurement Lock-up E	RI	Therapy Function Compromised	56		
accinates with measurement book up E	T T	Electrical Component	11		
		Electrical Interconnect	45		

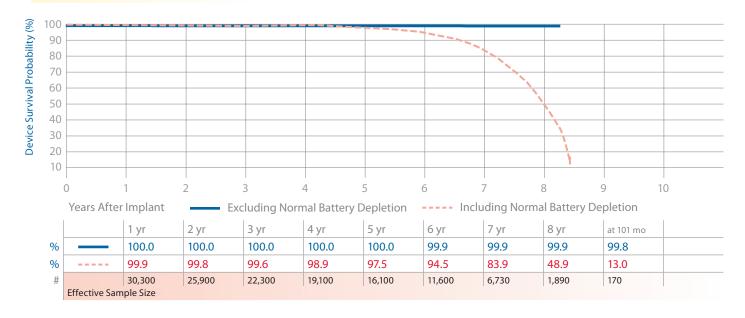


Effective Sample Size

Kappa 900 SR KSR901, KSR903, KSR906

Product Characteristics

US Market Release	Jan-02	Malfunctions (US)	17	NBG Code	SSIR
Registered US Implants	37,000	Therapy Function Not Compromised	9	Serial Number Prefix	PLF, PLG, PLH
Estimated Active US Implants	8,120	Electrical Component	7		
Normal Battery Depletions (US)	2,376	Electrical Interconnect (1 malfunction related to advisory)	1	Estimated Longevity	See page 79
Advisories: See page 151 – 2009		Possible Early Battery Depletion	1		
Potential Separation of Interconnect Wires	S	Therapy Function Compromised	8		
		Electrical Interconnect (7 malfunctions related to advisory)	8		



Kappa 900 VDD KVDD901

JS Market Release		Jan	-02 Malf	unctions (US)			2	NBG Code		VDD
Registered US Implants	S	(650 The	rapy Function	Not Compromi	sed	2	Serial Numbe	er Prefix	PLE
Estimated Active US Im	nplants		77	Software/Firm	ware Malfunctio	on	1	Estimated Lo	ngevity	See page 79
Normal Battery Deplet	ions (US)		80	Other			1			
Advisories: See page Potential Separation of	151 – 2009 f Interconnect	Wires	The	rapy Function	Compromised		0			
Performance Note: See Performance note on D Pacemakers with Meas	Oual Chamber	up ERI								
100										
80						-1				
70						<u> </u>				
						*	V V			
60										
60 50							_			
		2 E	3 xcluding No	4 ormal Batter	5 y Depletion	6 Inc	7 :ludin	8 g Normal Ba	9 attery Depletion	10 on
50		_					luding			. 0
0 Years After	Implant	E	xcluding No	ormal Batter	y Depletion	Inc	luding	g Normal Ba		. 0
0 Years After	Implant 1 yr	2 yr	xcluding No	armal Batter	y Depletion 5 yr	6 yr	luding	g Normal Ba		. 0



Kappa 920 DR KDR921

Registered US Implants

Estimated Active US Implants

Normal Battery Depletions (US)

US Market Release

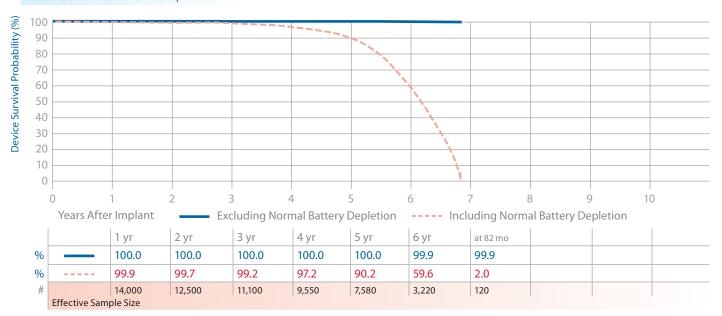
Jan-02 16,300 1,860 2,633

Advisories: See page 151 – 2009 Potential Separation of Interconnect Wires

Performance Note: See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI

Product Characteristics

Malfunctions (US)	4	NBG Code	DDD/RO
Therapy Function Not Compromised	1	Serial Number Prefix	PKR
Electrical Component	1		
Therapy Function Compromised	3	Estimated Longevity	See page 79
Electrical Interconnect (3 malfunctions	3		



related to advisory)

gond II 0424 0426 0427

	, •	426, 8	427											Produ	ct Cha	racter	istics		
S Market Rele	ease			Nov-9	1	Malfund	ctions (l	JS)				3	5 1	NBG Cod	de			SSIRO	
egistered US	Implan	ts		58,60	0	Therap	y Func	tion No	t Comp	romise	d	2	4 9	Serial Nu	umber F	refix		2P, 2T	2U
stimated Act	ve US Ir	nplants		5,83	0	Ba	ttery Ma	alfuncti	on				2 E	Estimate	ed Long	evity		Seep	age
ormal Batter	y Deple	tions (U	S)	2,61	1	Ele	ctrical	Compor	nent			1	8						
dvisories				Non	e	Po	ssible E	arly Bat	tery De	pletion			4						
						Therap	y Func	tion Co	mprom	ised		1	1						
						Ele	ctrical	Compor	nent				9						
						Ele	ctrical l	ntercor	nect				2						
100				 															
90																			
80																			
70																			
60																			
50																			
40																			



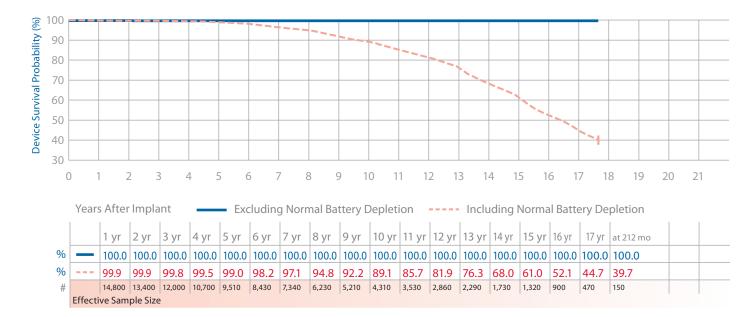
Minix/Minix ST 8340, 8341, 8341M, 8342, 8330, 8331, 8331M

Product Characteristics

#		49,900	43,400	37,400	31,800	27,000	22,600	18,600	15,100	12,600	10,700	9,230	8,060	7,120	6,360	5,720	4,930	3,840	2,750	1,690	770	170	
%		99.8	99.7	99.5	99.2	98.8	97.8	95.4	92.3	89.5	87.4	85.7	84.0	82.3	80.9	79.3	78.0	76.2	74.3	72.0	69.9	64.0	
%	_	100.0	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	17 yr	18 yr	19 yr	20 yr	at 247	mo
	Years	After	Impla	nt	_	E	kcludi	ng No	rmal	Batte	ery De	pletio	on		Incl	uding	y Norr	mal Ba	attery	Deple	etion	1	
0) 1	2	3	}	4	5	6	7	8	9	10	11	12	2 1	3 1	4	15	16	17	18	19	20	21
60																						-	
70																						1	
80																							
90																							
00																							
									Othe	er					1								
										,	lfunctio	on			1								
											ntercon				1								
											ompor				32								
estora	ation of	Permar	nent Set	tings				The	rapy F	unctio	on Com	promi	sed		35								
			e 158 –		otentia	l Delaye	ed		Possik	ole Earl	y Batte	ry Dep	letion		1								
orma	l Batter	y Deple	tions (U	IS)		1,7	768		Batter	y Malf	unction	ı			1								
tima	ted Act	ive US II	mplants			7,4	170		Electri	ical Co	mpone	nt			13	E	Estimat	ed Lon	gevity			See	oage
egiste	ered US	Implan	ts			58,6	500	The	rapy F	unctio	n Not	Compr	omise	d	15		Serial N	umber	Prefix				JS, 8W, IV, UX,
			_					Mair	unctio	ns (US))				50				D ('				
	rket Rel					Nov	00	MARIE	un eti -	ns (US)					50	, ,	NBG Co	do				CCICC), VVIC

Minuet 7107, 7108 **Product Characteristics**

US Market Release	Mar-92	Malfunctions (US)	3	NBG Code	DDDCO
Registered US Implants	16,800	Therapy Function Not Compromised	3	Serial Number Prefix	1Z1, 2G1
Estimated Active US Implants	1,930	Electrical Component	2	Estimated Longevity	See page 79
Normal Battery Depletions (US)	973	Possible Early Battery Depletion	1		
Advisories	None	Therapy Function Compromised	0		





Preva DR 7088, 7089

US Market Release	Jul-96	Malfunctions (US)	4	NBG Code	DDD/RO
Registered US Implants	25,500	Therapy Function Not Compromised	0	Serial Number Prefix	PGJ, PGK
Estimated Active US Implants	2,470	Therapy Function Compromised	4	Estimated Longevity	See page 79
Normal Battery Depletions (US)	2,886	Electrical Component	2		
Advisories	None	Electrical Interconnect	2		



Preva SR 8088, 8089

Product Characteristics

7 a 3	11 00	88, 80	J09													Produ	act Ci	iaraci	LETISE	IC3			
S Mar	ket Rel	ease				Jul-9	6	Malfun	ctions (l	JS)				1		NBG C	ode				S	SIR	
egiste	ered US	Implan	ts			17,80	0	Thera	py Func	tion No	t Comp	romise	d	0		Serial I	Numbe	r Prefix	(Р	GL, PC	ΞM
stimat	ted Act	ive US II	mplants			1,62	0	Thera	py Func	tion Co	mprom	ised		1		Estima	ted Lo	ngevity	/		S	ee pa	ige
lormal	l Batter	y Deple	tions (U	IS)		1,08	9	F	ossible	Early B	attery D	epletio	n	1									
dviso	ries					Non	e																
100																							
90																				-	-		_
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`	0		_	_				,		, ,	0 1		_ 1.			15	10	17	10	10	20		
	Year	After	Impla	nt		- Fxc	·ludina	n Norn	nal Ba	tterv [Depleti	ion		Includ	lino	Norn	nal Ba	tterv	Denl	etion			
	rear.														9						1		l
2,			2 yr	3 yr		5 yr	-						12 yr										-
%			100.0		100.0								100.0										_
%		99.8	99.7	99.4	99.0	98.3	97.2	95.0	92.1	87.3		59.1	43.3	26.3									
#		14,600	12,400	10,600	8,910	7,510	6,310	5,240	4,240	3,360	2,350	1,440	820	150									

Prevail S 8085, 8086

Effective Sample Size

US Mar	ket Rel	ease				Oct-9	95	Malfun	ctions (US)					1	NBG Cod	le				SS	SI	
Registe	ered US	Implan	ts			4,19	90	Thera	py Fund	ction No	ot Comp	romise	d		0	Serial Nu	ımber F	refix			PE	Y, PFA	
Estima	ted Act	ive US I	mplants	5		46	50	Thera	py Fund	ction Co	mprom	nised			1	Estimate	d Long	evity			Se	ee pag	ge 7
Norma	l Batter	y Deple	tions (L	JS)			8	E	Electrica	al Comp	onent				1								
Adviso	ries					Nor	ie																
100 -																							
100																							
90 -																							
80 -																							
70																							
0	1	2	3	4	. 5	5 6	7	8	9) 1(0 1	1 1	2 13	3 14	1 1	5 16	17	7 1	8 .	19	20	21	
	Years	After	r Impla	ant		- Ex	cludin	g Norr	nal Ba	ttery [Deplet	ion		Inclu	uding	Norma	l Batt	ery De	epleti	on			
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yı	at 175 mc							
%	_	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9	99.9							
%		99.7	99.6	99.6	99.6	99.1	98.9	97.9	96.8	95.2	92.8	90.0	89.3	86.5	84.8	83.9							
#				2,070	1,690	1,350	1,110	940	810	690	600	500	440	340	210	110							
	Effecti	ve Sam	ple Size	ē																,			



Prodigy DR 7860, 7861, 7862

US Market Release Registered US Implants **Estimated Active US Implants** Normal Battery Depletions (US)

Advisories

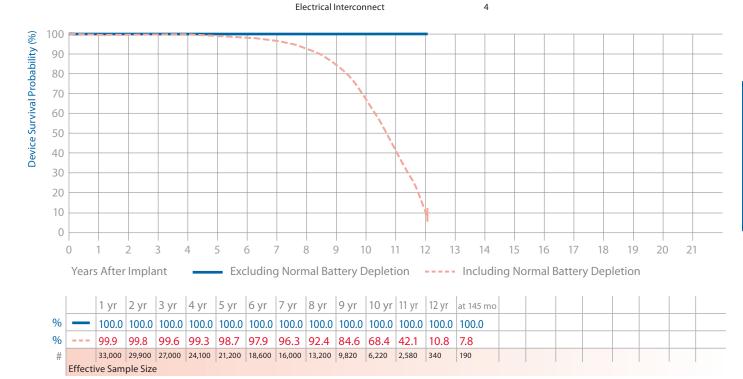
Oct-95	Malfunctions (US)	11
37,400	Therapy Function Not Compromised	5
3,140	Electrical Component	2
3,949	Possible Early Battery Depletion	2
None	Other	1

Therapy Function Compromised Electrical Component

Product Characteristics

2

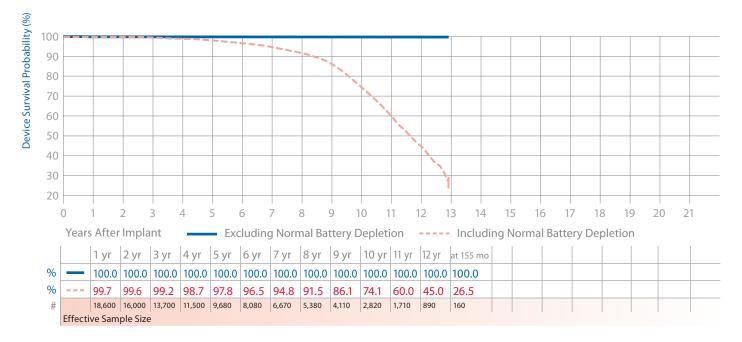
	NBG Code	DDD/RO
	Serial Number Prefix	PDH, PDJ, PDK
	Estimated Longevity	See page 80



Prodigy SR 8158, 8160, 8161, 8162

Product Characteristics

US Market Release	Oct-95	Malfunctions (US)	4	NBG Code	SSIR
Registered US Implants	22,300	Therapy Function Not Compromised	2	Serial Number Prefix	PEM, PED, PEE,
Estimated Active US Implants	2,350	Battery Malfunction	1		PEF
		Possible Early Battery Depletion	1		
Normal Battery Depletions (US)	1,348	Therapy Function Compromised	2	Estimated Longevity	See page 80
Advisories	None	Electrical Component	1		
		Electrical Interconnect	1		



Sensia DR SEDRO1, SED01

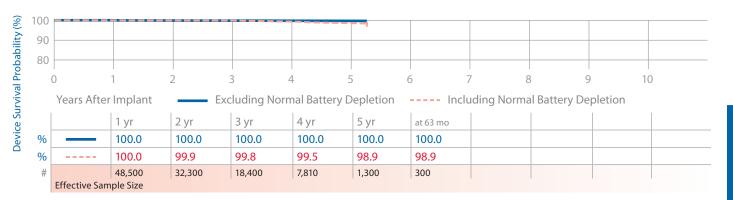
risia DK SEDROI, S	DEDUT						Product Character	istics	
US Market Release		Jul-06	Malfunctions (US)			12	NBG Code		DDD, DDDR
Registered US Implants		103,500	Therapy Function	Not Comprom	ised	8	Serial Number Prefix		PWL, PWK,
Estimated Active US Impla	ants	79,900	Electrical Com	oonent		8			NWL, NWK
Normal Battery Depletion	ns (US)	75	Therapy Function	Compromised		4	Estimated Longevity		See page 8
Performance Note: See pa	age 159 –		Electrical Com	oonent		3			
Performance note on Dual Pacemakers with Measure			Electrical Inter	connect		1			
100 90 80 0 1 Years After Im	2	3	4	5	6	7	8	9	10
Years After Im	plant	- Excludir	ng Normal Batter	/ Depletion	In	cludin	g Normal Battery De	epletion	
1 y	/r 2 yr	3 yr	4 yr	5 yr	at 64 mo				
% 10	0.0 100.	0 100.	0 100.0	100.0	100.0				
% 10	0.0 100.	0 99.8	99.6	99.1	98.9				
# 78,	800 56,00	0 34,30	15,700	2,770	240				
Effective Sample	Size								



Sensia SR SESR01, SES01

Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	4	NBG Code	SSIR, SSI
Registered US Implants	69,700	Therapy Function Not Compromised	3	Serial Number Prefix	PWR, PWS,
Estimated Active US Implants	49,200	Electrical Component	3		NWR, NWS
Normal Battery Depletions (US)	60	Therapy Function Compromised	1	Estimated Longevity	See page 80
Advisories	None	Electrical Interconnect	1		

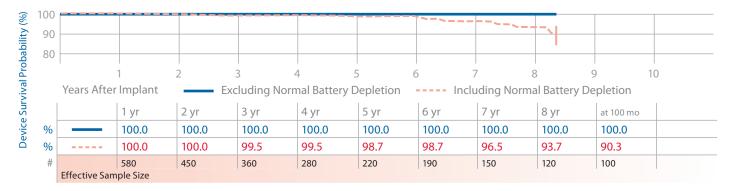


Sigma 100 S SS103, SS106

Product Characteristics

US Market Release	Aug-99	Malfunctions (US)	0	NBG Code	SSI
Registered US Implants	790	Therapy Function Not Compromised	0	Serial Number Prefix	PJG, PJH
Estimated Active US Implants	100	Therapy Function Compromised	0	Estimated Longevity	See page 80
Normal Battery Depletions (US)	18				

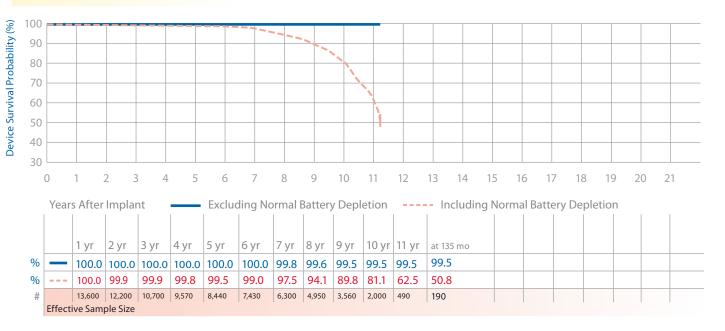
Advisories: See page 155 – 2005 Potential Separation of Interconnect Wires



Sigma 200 DR SDR203

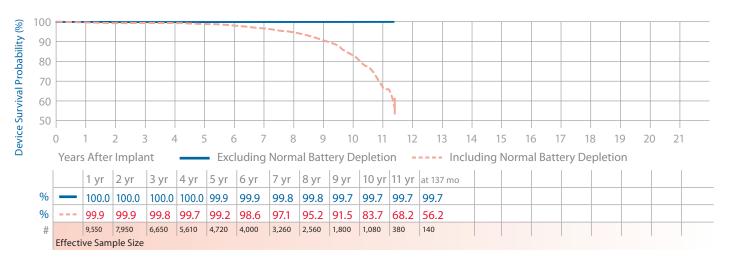
Product Characteristics

US Market Release	Aug-99	Malfunctions (US)	31	NBG Code	DDD/RO
Registered US Implants	15,800	Therapy Function Not Compromised	1	Serial Number Prefix	PJD
Estimated Active US Implants	3,940	Electrical Component	1	Estimated Longevity	See page 80
Normal Battery Depletions (US)	599	Therapy Function Compromised	30		
Advisories: See page 155 – 2005 Pote	ential	Electrical Component	1		
Separation of Interconnect Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires		Electrical Interconnect (19 malfunctions related to advisory)	29		



Sigma 200 SR SSR203, SS203

J						
US Market Release	Sep-99	Malfunctions (US)	11	NBG Code	SS	SIR
Registered US Implants	12,100	Therapy Function Not Compromised	0	Serial Number Prefix	PJ	IG
Estimated Active US Implants	2,110	Therapy Function Compromised	11	Estimated Longevity	Se	ee page 80
Normal Battery Depletions (US)	285	Electrical Interconnect (11 malfunctions related to advisory)	11			
Advisories: See page 155 – 2005 Po	tential					
Separation of Interconnect Wires; See	e also					
page 151 – 2009 Potential Separation Interconnect Wires	n of					



Sigma 300 DR SDR303, SDR306

Product Characteristics

gma	a 3	00 I	JK S	DR303	3, SDR	306										Produ	ct Cha	racte	ristics	5		
US N	Mark	et Rele	ease				Aug-99	9 1	Malfunc	tions (U	S)			208		NBG Cod	de				DDI	D/RO
Reg	ister	ed US	Implant	ts			106,700)	Therap	y Funct	ion Not	Compro	mised	10		Serial N	umber F	Prefix			PJD	, PJE
Estir	mate	d Acti	ve US In	nplants			34,300)	Ele	ctrical C	ompone	ent		5		Estimate	ed Long	evity			See	e page 80
Nori	mal E	Batter	y Deple	tions (U	S)		2,523	3	Ele	ctrical Ir	nterconn	ect		4								
				<u> 155</u> – 2					Pos	ssible Ea	rly Batte	ry Deple	etion	1								
				nect W					Therap	y Funct	ion Com	promise	ed	198								
		nect V		ential Se	paratio	n or			Ele	ctrical C	ompone	ent		8								
											nterconn			190								
10	00 =								(14.	5 malfur	ictions re	lated to	advisory)									
> '`																						
. 0	90 -																					
8	30 -																			_	_	
7	70 -																			_	_	
6	50																			\perp	\perp	
5 5	50												i									
2	10 -												i									
ž																		1	ı	- 1		
	0		1	2	3	4	5	6	7	8 9	9 10) 11	12	13 1	4	15	16	17	18	19	20	21
	,	Years	After	Impla	nt		Exc	luding	y Norm	nal Bat	tery De	epletio	n	Inclu	ding	Norma	al Batt	ery D	eplet	ion		
			1	2 . //	2	1	Eve	6	7	0	0.45	10 . //	11	126								
	%		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 136 mo						_	-	
	· -			100.0	100.0		99.9	99.9	99.8	99.6	99.5	99.5	99.5							-	-	
	% #			99.9	99.9	99.7	99.4	98.9	97.9	95.1	90.4	81.7 8,190	63.3 1,770	41.0 180								
	#		32,300	02,300	/3,300	04,000	22,400	40,000	34,900	23,100	13,900	0,190	1,//0	180								

Sigma 300 SR SSR303, SSR306

Effective Sample Size

#	Effecti	43,100 ve Samp	36,000	30,300	25,400	20,400	15,700	11,600	8,190	4,980	2,600	610	110							
%		100.0	99.9	99.8	99.6	99.2	98.6	97.2	94.9	90.5	81.8	65.8	46.9							
%		100.0	100.0	100.0	100.0	100.0	99.9	99.8	99.7	99.7	99.7	99.7	99.7							
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	at 136 mo							
	Years	After	Implar I	nt i		Exclud	ling N	ormal	Batter 	y Depl	etion 		Including	g Norm	al Batt	tery De	epletio	n 	ı	
40																				
50											1									
60											1									
70																				
80																				
90																				
100																				
											d to adviso	ory)	12							
nterco	nnect V	Vires								connect			42							
age 1	1 <mark>51</mark> – 20	09 Pote					In		anction cal Com	Compro	omised		45 3							
	_	e page						Other		_			1							
		y Deplet				872			cal Inter	connect			1							
stima	ted Acti	ve US Im	plants		1	2,300		Electric	cal Com	ponent			1	Estimat	ed Long	gevity			See p	age
egiste	red US	Implants	5		5	4,100	The	erapy Fu	unction	Not Cor	mpromise	ed	3	Serial N	umber	Prefix			PJG, PJ	Н
		ease			Α.	ıg-99	IVIdii	function	15 (U3)				48	NBG Co	ae				SSIR	

Sigma 300 VDD svDD303

Product Characteristics

IS M	1arket Rel	ease		Spr	o-99 I	Malfunction	ns (US)			1	NBG Cod	ρ		VDDD
	stered US		ts				, ,	lot Compromi	sed	0		mber Prefix		PJD
_	nated Act							Compromised	scu	1		d Longevity		See page 8
			tions (US)		49		cal Interc			1	Littinates	a Longevity		see page o
Advi	isories: Se	ee pag	e 155 – 2005 nnect Wires	Potential				elated to adviso	ry)					
10	00									\				
(90													
	80													
	70 —											`1		
	60													
	50													
	0		1	2	3	4		5	6	7		8	9	10
	Year	s After	Implant	E	Excluding	Normal	Battery	Depletion	Inc	cludin	g Norma	l Battery Dep	oletion	
			1 yr	2 yr	3 yr	4	yr	5 yr	6 yr	7	yr	8 yr	at 107 mo	
%	6 -		100.0	100.0	100.0	10	0.00	100.0	100.0	10	0.00	99.5	99.5	
%	6		100.0	100.0	100.0	10	0.00	99.4	98.1	94	4.2	89.6	74.6	
#	#		550	480	430	38	30	340	290	23	30	170	100	

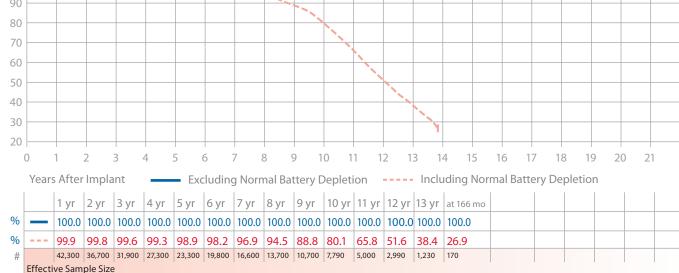
Thera-i DR 7960i, 7961i, 7962i

Effective Sample Size

US Ma	arket Re	lease				Oct-9	5	Malfun	ctions (l	US)				49		NBG C	ode					D	DD/R)
Regis	tered U	S Implar	nts			121,30	0	Thera	oy Fund	tion No	t Comp	romise	d	23		Serial I	Numb	er Pr	efix				OB, PC	C,
Estim	ated Ac	tive US I	Implants	5		10,40	0	Ba	attery N	1alfunct	ion			3								PI	DD	
Norm	al Batte	ry Deple	etions (L	JS)		14,02	9	Ele	ectrical	Intercor	nnect			1		Estima	ted Lo	onge	vity			S	ee pa	ge 80
Advis	ories					Non	e	Ele	ectrical	Compo	nent			7										
								Po	ssible E	arly Bat	tery De	pletion		9										
								Ot	her					3										
								Thera	oy Fund	tion Co	mprom	ised		26										
								Ele	ectrical	Intercor	nnect			20										
								Ele	ectrical	Compo	nent			6										
② 100													_											
6 A																								
illide 60										1	•													
roba											•													
<u>a</u> 20																								
N 0													1											
Se St	0	1)) :	3 4	1 -	5 6	5 7	7 8	2 (9 1	0 1	1 1	2 1	3 14		15	16	17	,	18	19	20	21	
Device Survival Probability (%) 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0 0		۸ 64	_ `		т										l:			17	D			20	_	
	rear	ı	r Impla				ludin	_	ı					Includ		g ivorn	iai b	atte	ry D	epie	uon		1	
		1 yr	2 yr	3 yr	4 yr	5 yr	буг	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 148 m	0									
%	_	100.0	100.0	100.0	100.0	100.0	100.0	99.9	99.9	99.9	99.9	99.9	99.9	99.9										
%		99.9	99.8	99.6	99.4		98.1	96.7	93.2	85.8	71.3	48.1	19.7	5.8										
#	T.C +:			91,600	82,900	74,500	66,100	57,200	47,700	36,600	23,700	11,500	2,580	510										
	Effecti	ive sam	ple Size																					

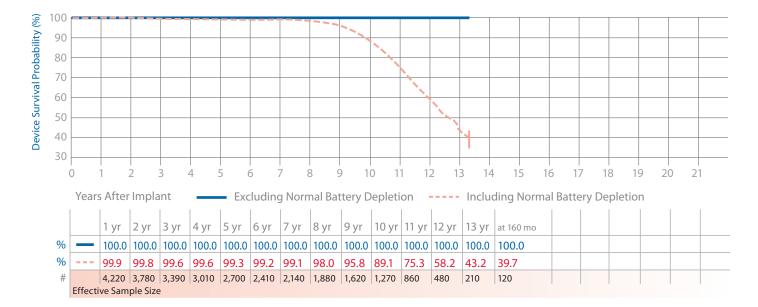


US Market Release Oct-95 Malfunctions (US) 8 NBG Code SSIR Registered US Implants 50,000 Therapy Function Not Compromised 2 Serial Number Prefix PDU, PDV, PDW Estimated Active US Implants 4,520 Electrical Component 1 Normal Battery Depletions (US) 2,884 Possible Early Battery Depletion 1 Estimated Longevity See page 80 Advisories None Therapy Function Compromised 6 Electrical Component 3 Electrical Interconnect 3	Th	era-i	SR 8	3960i,	8961i	, 8962	i										Produ	ct Cha	aracte	ristics		
Estimated Active US Implants 4,520 Electrical Component 1 Normal Battery Depletions (US) 2,884 Possible Early Battery Depletion 1 Estimated Longevity See page 80 Advisories None Therapy Function Compromised 6 Electrical Component 3 Electrical Interconnect 3		US Mar	ket Rele	ease				Oct-9	5	Malfund	ctions (l	JS)				8	NBG Co	de			SSIR	
Normal Battery Depletions (US) 2,884 Possible Early Battery Depletion 1 Estimated Longevity See page 80 Advisories None Therapy Function Compromised 6 Electrical Component 3 Electrical Interconnect 3		Registe	red US	Implant	s			50,00	0	Thera	py Func	tion No	t Comp	romise	d	2	Serial N	umber	Prefix			DV,
Advisories None Therapy Function Compromised Electrical Component 3 Electrical Interconnect 3		Estimat	ted Acti	ve US In	nplants			4,52	0	Ele	ectrical (Compor	nent			1					PDW	
Electrical Component 3 Electrical Interconnect 3		Norma	l Battery	/ Deplet	tions (U	S)		2,88	4	Po	ssible E	arly Batt	tery De	pletion		1	Estimat	ed Long	gevity		See pa	age 80
Electrical Interconnect 3		Adviso	ries					Non	e	Therap	oy Func	tion Co	mprom	ised		6						
										Ele	ectrical (Compor	nent			3						
90 Ookice Survival Probability (%) 100										Ele	ectrical I	ntercon	nect			3						
90 90 80 70 60 50 40 40 40 40 40 40 40 40 40 40 40 40 40																						
90 80 70 60 50 40 40 40 40 40 40 40 40 40 40 40 40 40	(%)	100																				
80 70 60 50 50 40 90 90 90 90 90 90 90 90 90 90 90 90 90	£	90																				
70 For Survival 40 For Surviva	hah	80										1										
Ookice Survival	Pro	70											1									
50 40 40 40	, i	60																				
40 40 Fig. 10 Fig. 10 40 Fig. 10 F	Z	- 00																				
40 40	وا	50													1							
	Dev	40																				



Thera-i VDD 8968i

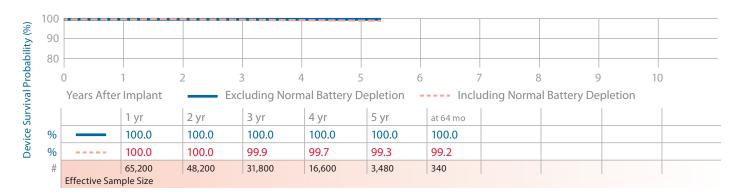
US Market Release Mar-95 Malfunctions (US) 0 NBG Co	ode VDD
	Number Prefix PEC
7-2	ited Longevity See page 80
	see page 80
Normal Battery Depletions (US) 331 Advisories None	



Versa DR VEDR01

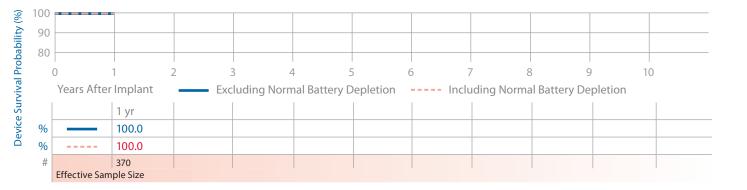
Product Characteristics

US Market Release	Jul-06	Malfunctions (US)	8	NBG Code	DDDR
Registered US Implants	83,000	Therapy Function Not Compromised	6	Serial Number Prefix	PWH, NWH
Estimated Active US Implants	64,600	Electrical Component	5	Estimated Longevity	See page 80
Normal Battery Depletions (US)	64	Electrical Interconnect	1		
Performance Note: <u>See page 159</u> –		Therapy Function Compromised	2		
Performance note on Dual Chamber Pacemakers with Measurement Lock-up E	RI	Electrical Component	2		



Revo MRI SureScan RVDR01

US Market Release	Feb-11	Malfunctions (US)	1	NBG Code	DDDRP
Registered US Implants	22,100	Therapy Function Not Compromised	0	Serial Number Prefix	PTN
Estimated Active US Implants	21,700	Therapy Function Compromised	1	Estimated Longevity	See page 80
Normal Battery Depletions (US)	0	Electrical Component	1		



IPG Implantable Pulse Generators, continued

Device Survival Summary (95% Confidence Interval)

The following table shows IPG device survival estimates with 95% confidence intervals. Estimates are shown both with and without normal battery depletions included

		14 yr 16 yr																
		12 yr																
		10 yr																
		8 yr													100.0	62.7		
		7 yr											99.9 +0.1/-0.1 at 81 mo	9.4 +1.2/-1.2 at 81 mo	100.0	87.5	100.0 +0.0/-0.0 at 80 mo	26.0 +3.8/-3.7 at 80 mo
	-	6 yr	100.0 +0.0/-0.0 at 65 mo	99.2 +0.1/-0.2 at 65 mo	100.0 +0.0/-0.0 at 62 mo	99.7 +0.1/-0.2 at 62 mo	100.0 +0.0/-0.0 at 63 mo	94.4 +1.2/-1.5 at 63 mo	100.0 +0.0/-0.0 at 64 mo	98.3 +0.3/-0.4 at 64 mo			99.9 +0.1/-0.1	50.7	100.0	96.9	100.0	63.6
(9)		5 yr	100.0	99.4 +0.1/-0.1	100.0	99.7	100.0 +0.0/-0.0	95.0 +0.9/-1.0	100.0	98.3 +0.3/-0.4	100.0 +0.0/-0.0 at 53 mo	100.0 +0.0/-0.0 at 53 mo	99.9 +0.1/-0.1	84.3 +0.8/-0.9	100.0	98.4 +0.3/-0.4	100.0	92.6
bility (%		4 yr	100.0	99.7	100.0	99.7	100.0	98.87	100.0	99.3 +0.1/-0.2	100.0	100.0	99.9 +0.1/-0.1	97.6 +0.3/-0.4	100.0	99.2 +0.2/-0.3	100.0	96.8
Device Survival Probability (%)	plant	3 yr	100.0	99.9	100.0	99.9 +0.0/-0.1	100.0	99.6 +0.1/-0.1	100.0	99.7 +0.1/-0.1	100.0	100.0	100.0	99.5 +0.1/-0.2	100.0	99.9	100.0	99.0
Surviva	Years After Implant	2 yr	100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.9	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	100.0	99.8	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.7
Device	Years	1 yr	100.0	100.0	100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0	100.0	100.0	99.9 +0.0/-0.1	100.0	100.0 +0.0/-0.0	100.0	100.0
			o and	ng on y	ng ra	ng S L	gr z e	ng on y	o y	פֿר 7 כ	gr r o	o Z u	ng on	gn 5.	gr y u	ng ri o	gr S	gr S C
			Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	le:	τοΤ	51 Excludi Normal Batte Depleti	Includi Normal Batte Depleti	5 Norm	Includi Normal Batte Depleti	5 Excludi Normal Batte Depleti	Includi Normal Batte Depleti	5	Includii Normal Batte Depletii	0	Includi Normal Batte Depleti	6	Includi Normal Batte Depleti	-	Includi Normal Batte Depleti	0	Includi Normal Batte Depleti
ons (US)	erapy nction Not mpromised al	IU1 IOD	Norm	Includi Normal Batte Depleti	Norn	Includi Normal Batte Depleti	3 = 5	Includi Normal Batte Depleti	1 = 5	Includi Normal Batte Depleti		Includi Normal Batte Depleti		Includi Normal Batte Depleti		Includi Normal Batte Depleti	0 = 0	Includi Normal Batte Depleti
Malfunctions (US)	nction Not mpromised	Fur The Ind Turi	= 51 Norm	Includi Normal Batte Depleti	= 5 Norm	Includi Normal Batte Depleti	II 72	Includi Normal Batte Depleti	= 5	Includi Normal Batte Depleti	0 =	includi Normal Batte Depleti	6	Includi Normal Batte Depleti	 II	includi Normal Batte Depleti	0	Includi Normal Batte Depleti
Malfunctions (US)	notion mpromised erapy notion Not mpromised	The Fur Col	+ 32 = 51 Norm		+ 4 = 5 Norm		+ 3 = 5		+ + = 5	Includi Normal Batte Depleti	0 = 0 +	Norm	+ 4 = 9	Norm	+		0 = 0 +	Norm
Malfunctions (US)	erapy notion mpromised erapy rotion Not mpromised	Actinity Month of the Month of	242,600 155 19 + 32 = 51 Norm		1 + 4 = 5 Norm		2 + 3 = 5		4 + 1 = 5	Includi Normal Batte Depleti	0 = 0 + 0	Norm	5 + 4 = 9	Norm	+ 1 = 1		0 = 0 + 0	Norm
Malfunctions (US)	ine US solutes battery pletrions (US) pletrions (US) screen constructions (US) solutions bearing the construction with the construction with the construction of the c	Est Act Imp Ind Ind Ind Ind Ind Ind Ind Ind Ind Ind	155 19 + 32 = 51 Norm		9 1 + 4 = 5 Norm		84 2 + 3 = 5		72 4 + 1 = 5	Includi Normal Batte Depleti	0 = 0 + 0	Norm	2,658 5 + 4 = 9	Norm	550 0 + 1 = 1		1,850 190 349 0 + 0 = 0	Norm
Malfunctions (US)	imated ive US Joants rmal Battery pletions (US) arapy arction mpromised prespy myromised myromised	Regular Regula	242,600 155 19 + 32 = 51 Norm		48,900 9 1 + 4 = 5 Norm		21,400 84 2 + 3 = 5		38,100 72 4 + 1 = 5	Includi Normal Batte Depleti	0 = 0 + 0 0 069 068 90-Inf	Norm	1,140 2,658 5 + 4 = 9	Norm	2,630 550 0 + 1 = 1		190 349 0 + 0 = 0	Norm
included. Malfunctions (US)	gistered Implants inated sive US solutions (US) pletions (US) pletions (US) are proportion (US) are propor	Nuise See See See See See See See See See S	291,500 242,600 155 19 + 32 = 51 Norm	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI Depleti	53,900 48,900 9 1 + 4 = 5 Norm	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI Depleti	28,000 21,400 84 2 + 3 = 5	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI Depleti	54,000 38,100 72 4 + 1 = 5	Includi Normal Batte Depleti	0 = 0 + 0 0 069 068	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI Depleti	10,800 1,140 2,658 5 + 4 = 9	See page 164 – Performance note on AT500 Pacing System Follow-Up Protocol Depleti	6,820 $2,630$ 550 0 $+ 1$ $= 1$	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI Depleti	1,850 190 349 0 + 0 = 0	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI Depleti

14 yr | 16 yr

P
l

12 yr 99.9 +0.0/-0.0 at 105 mo 10.8 +0.8/-0.8 at 105 mo 100.0 +0.0/-0.0 at 109 mo 10.3 +2.1/-1.9 at 109 mo 10 yr 100.0 99.9 100.0 +0.0/-0.0 at 92 mo 63.9 +1.5/-1.5 8 yr 90.5 +0.7/-0.8 100.0 90.8 +0.3/-0.4 100.0 +0.0/-0.0 at 79 mo 29.5 +2.8/-2.8 at 79 mo 100.0 +0.0/-0.0 at 81 mo 99.5 +0.4/-1.7 at 81 mo 100.0 +0.0/-0.0 81.4 +1.3/-1.3 100.0 +0.0/-0.0 at 75 mo 76.6 +5.6/-6.9 at 75 mo 90.3 +0.4/-0.4 at 77 mo 99.9 87.9 +0.4/-0.4 100.0 +0.0/-0.0 74.6 +1.0/-1.1 at 77 mo 7 yr 94.3 +0.4/-0.5 96.8 +0.4/-0.4 100.0 79.8 +0.5/-0.5 97.2 +0.2/-0.2 100.0 +0.0/-0.0 97.4 +0.1/-0.1 100.0 +0.0/-0.0 68.5 +1.3/-1.4 100.0 99.5 +0.4/-1.7 100.0 +0.0/-0.0 86.8 91.1 +0.3/-0.3 99.9 +0.0/-0.0 100.0 +0.0/-0.0 6 yr 98.5 100.0 100.0 100.0 100.0 100.0 97.7 +0.2/-0.3 100.0 97.0 +0.2/-0.2 93.5 99.9 100.0 91.7 +0.6/-0.7 99.1 **98.9** +0.1/-0.1 **98.9** +0.1/-0.1 5 yr Device Survival Probability (%) 99.0 98.9 100.0 100.0+0.0/-0.0 100.0 100.0 100.0 100.0 100.0 +0.0/-0.0 99.5 100.0 +0.0/-0.0 98.9 99.4 +0.1/-0.1 99.5 +0.1/-0.1 4 yr 100.0 99.8 99.2 100.0+0.0/-0.0 100.0 100.0 +0.0/-0.0 100.0 99.5 100.0 100.0 99.9 99.7 100.0 +0.0/-0.0 99.6 +0.1/-0.1 100.0 +0.0/-0.0 99.5 +0.1/-0.1 3 yr **Years After Implant** 100.0 99.9 100.0 100.0 100.0 100.0+0.0/-0.0 99.9 100.0 100.0 100.0 99.9 100.0 100.0 99.7 +0.1/-0.1 99.7 +0.1/-0.1 2 yr 100.0 99.8 100.0 +0.0/-0.0 100.0+0.0/-0.0 100.0 100.0+0.0/-0.0 100.0 +0.0/-0.0 100.0 +0.0/-0.0 100.0 100.0 100.0+0.0/-0.0 **99.8** +0.1/-0.1 100.0 +0.0/-0.0 +0.0/-0.0 +0.0/-0.1 +0.0/-0.0 1 yr 0.001 100.0 Excluding Normal Battery Depletion Including Normal Battery Depletion Including Normal Battery Depletion Excluding Normal Battery Depletion Including Normal Battery Depletion Excluding Normal Battery Depletion Including Normal Battery Excluding Normal Battery Depletion Including Normal Battery Depletion Normal Battery Depletion Total 23 0 4 0 (advisory-related subset) 24 2 Malfunctions (US) II II П П п П П П Compromised (185)2,851 7 Function Not 7 0 0 m 0 4 Тһегару + + + + + + + + Compromised 0 0 47 0 9 9 Therapy Function **Device Survival Summary** continued 1,268 7,619 1,435 Depletions (US) Advisories: See page 148 – 2010 Low Battery Voltage Displayed at Device Interrogation 638 296 See page 159 – Performance note on Dual Chamber See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI See page 159 – Performance note on Dual Chamber 4 See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI See page 161 – Performance note on anomalies in MOSFET Integrated Circuit Technology Normal Battery Implants Pacemakers with Measurement Lock-up ERI Pacemakers with Measurement Lock-up ERI 54,700 76,300 4,820 1,710 9,160 **Active US** 420 260 Estimated 109,700 25,500 46,800 15,400 12,200 US Implants 640 580 Registered May-05 Dec-03 Feb-98 Feb-04 Feb-04 Feb-04 Jan-98 Dec-03 Release US Market E2VDD01 P1501DR KDR401, KDR403 KSR401, KSR403 E2DR21 E2SR01, E2SR03, E2SR06 Иитрег IəboM EnRhythm continued EnPulse 2 DR Kappa 400 Kappa 400 **EnPulse 2 EnPulse 2 EnPulse 2 EnPulse 2**

DR

Family

DR

DR

SR

VDD

SR

DR

Device Survival Summary continued

					E	Malfunct	Malfunctions (US)	Ī	Device	Device Survival Probability (%)	l Probak	oility (%)								
γli	lel nber	Narket ase	bered staniqm	nəted SU sv Sants	val Battery (SU) snoitel	rapy ction npromised	rapy ction Not opsimorqr Il		Years A	Years After Implant	ylant									·
швЯ	ooM	NS N	N2 I Ked	itoA	Nori Dep	un	enT nu∃ no⊃		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr
Kappa 600 DR	KDR601, KDR603, KDR606	Jan-99	25,000	1,930	3,789	+ 85	5 = 63	Excluding Normal Battery Depletion	100.0	100.0	100.0	99.9	99.9	99.9	99.8	99.7	99.6 +0.1/-0.2 at 107 mo			
	Advisories: Power Supp Potential Se	See page oly Wires; Separation o	Advisories: See page 157–2002 Potential F Power Supply Wires; See also page 151 – 2C Potential Separation of Interconnect Wires	Advisories: See page 157–2002 Potential Fractured Power Supply Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires	tured	(34) + (advisory-r	$\frac{(34)}{(advisory-related subset)} + (0) = (34)$	Including Normal Battery Depletion	99.9	99.8	99.8 +0.1/-0.1	99.5 +0.1/-0.1	98.8	96.9 +0.3/-0.3	87.8 +0.6/-0.6	57.5	4.9 +0.9/-0.8 at 107 mo			
	See page 15 Pacemakers	59 – Perfo	See page 159 – Performance note on Dual (Pacemakers with Measurement Lock-up ERI	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber															
Kappa 600 DR	KDR651, KDR653	Mar-01	16,400	1,340	2,717	53 +	3 = 56	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	99.9	99.7	99.5	99.4 +0.2/-0.3 at 103 mo			
	Advisories: Power Supp Potential Se	See page oly Wires; Separation o	157 – 2002 l ee also pag if Interconn	Advisories: See page 157 – 2002 Potential Fractured Power Supply Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires	ctured	(30) + (0) (advisory-relat	(0) = (30) -related subset)	Including Normal Battery Depletion	100.0	99.9	99.8	99.4	98.2 +0.3/-0.3	94.9 +0.5/-0.5	81.2 +0.9/-1.0	43.7	6.3 +1.2/-1.1 at 103 mo			
	See page 1! Pacemakers	59 – Perfor s with Meas	See page 159 – Performance note on Dual (Pacemakers with Measurement Lock-up ERI	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber			_												
Kappa 700 D	KD701, KD703, KD706	Jan-99	310	29	17	+	0 = 0	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	100.0	100.0	100.0	100.0				
	Advisories: Power Supp Potential Se	See page oly Wires; Separation o	Advisories: See page 157–2002 Potential F Power Supply Wires; <u>See also page 151</u> – 2C Potential Separation of Interconnect Wires	Advisories: See page 157–2002 Potential Fractured Power Supply Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires	tured	(0) + (0) (advisory-relat	(0) = (0) -related subset)	Including Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	99.0	97.8	95.4	94.2 +2.7/-4.8	86.4				
	See page 1! Pacemakers	59 – Perfo	See page 159 – Performance note on Dual (Pacemakers with Measurement Lock-up ERI	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber			_												
Kappa 700 DR	KDR701, KDR703, KDR706	Jan-99	206,300	30,000	32,080	702 +	38 = 740	Excluding Normal Battery Depletion	100.0	100.0	99.9	99.9	99.9	99.9	99.7	99.6	99.4 +0.1/-0.1 at 106 mo			
	Advisories: Power Supp Potential Se	See page oly Wires; Separation o	Advisories: See <u>page 157 – 2002 Potential F</u> Power Supply <u>Wires; See also page 151 – 2C</u> Potential Separation of Interconnect Wires	Advisories: See page 157 – 2002 Potential Fractured Power Supply Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires		(416) + (advisory-r	$\frac{(416)}{(400)} + \frac{(41)}{(400)} = \frac{(417)}{(400)}$	Including Normal Battery Depletion	99.9	99.8	99.6	99.2	98.2	95.5	85.4	56.1	4.6 +0.4/-0.3 at 106 mo			
	See page 1! Pacemakers	59 – Perfor s with Meas	See page 159 – Performance note on Dual ' Pacemakers with Measurement Lock-up ERI	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber			_												
Kappa 700 DR	KDR721	Feb-99	6,800	780	1,342	4	1 = 5	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0	+0.1/-0.1	99.9	99.9	99.9 +0.1/-0.1 at 85 mo				
	Advisories: Power Supp Potential Se	See page oly Wires; Separation o	Advisories: See <u>page 157– 2002</u> Potential F Power Supply <u>Wires; See also page 151 – 2C</u> Potential Separation of Interconnect Wires	Advisories: See page 157–2002 Potential Fractured Power Supply Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires		(4) + (advisory-r	(4) + (0) = (4) (advisory-related subset)	Including Normal Battery Depletion	99.8 +0.1/-0.1	99.5	98.7	96.7	91.0 +0.7/-0.8	68.9	20.9	14.7 +2.0/-1.9 at 85 mo				
	See page 1: Pacemakers	59 – Perfol s with Meas	See page 159 – Performance note on Dual Pacemakers with Measurement Lock-up ERI	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	amber															

					E	Malfunctions	ctions		Device	Surviva	Device Survival Probability (%)	ility (%)								
γlin	del mber	Market ease	yistered Implants	bətsmi SU əvi stnslc	rmal Battery oletions	erapy oction mpromised	erapy Iction Not mpromised Al		Years A	Years After Implant	lant									
Fan	oM iuM	Rel NS		tэА		ın-ı	un⊣		1 yr	2 yr	3 yr	4 yr	5 yr 6	6 yr 7	7 yr 8	8 yr	10 yr	12 yr	14 yr	16 yr
Kappa 700 SR	KSR701, KSR703, KSR706	Jan-99 6	55,300	096'9	4,754	25	+ 3 = 28	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0 +	100.0	100.0 + 0.0/-0.0	99.9	99.9 +0.0/-0.1 a	99.8 +0.1/-0.1 at 107 mo			<i>x</i> 150 00
	Advisories: See also page 151 – 2009 Potential Separation of Interconnect Wires	also page 15 ires	1 – 2009 Po	itential Sepai	ation of	(20) + (advisory-re	+ (0) = (20) y-related subset)	Including Normal Battery Depletion	99.9	99.8	99.4	98.6 + 0.1/-0.1 +	97.2 +0.2/-0.2 +	93.6 +0.3/-0.3 +	83.5 5 +0.5/-0.6	56.4 +0.9/-0.9 a	11.2 +1.2/-1.1 at 107 mo			.iiciac
Kappa 700 VDD	KVDD701	Jan-99	1,690	210	172	4	+ 0 +	Excluding Normal Battery Depletion	99.9	99.9	99.9	99.8	99.8 +0.1/-0.4	99.6	99.6	99.6 +0.2/-0.6	99.6 +0.2/-0.6 at 97 mo			713, 601
	Advisories: See page 157 – 2002 Potential Fractured Power Supply Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires	page 157 – 2 ee also page Wires	2002 Potent	tial Fracturec Potential Se _l	l Power oaration	(4) + (advisory-rel	+ (0) = (4) -related subset)	Including Normal Battery Depletion	99.8	99.6	99.1	98.6 +0.5/-0.8	98.4 +0.6/-0.9	94.1	72.7 +	41.9 +4.7/-4.7	41.1 +4.7/-4.8 at 97 mo			ntinued
	<u>See page 159</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Performanc h Measurem€	e note on D ent Lock-up	oual Chamber ERI																
Kappa 800 DR	KDR801, KDR803	Jan-02	4,280	840	592	e E	» » » » » » » » » » » » » » » » » » »	Excluding Normal Battery Depletion	100.0	100.0	100.0+0.0/-0.0	100.0 +0.0/-0.0	100.0+0.0/-0.0	100.0 + 0.0/-0.0	99.9 + +0.1/-0.4	99.9 + 0.1/-0.4	99.9 +0.1/-0.4 at 101 mo			
	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Performanc h Measurem€	e note on D ent Lock-up	oual Chamber ERI				Including Normal Battery Depletion	100.0	99.9	99.8	99.5	98.5 +0.4/-0.5	96.1 8. +0.7/-0.8	84.4 5.1.5/-1.6 +;	54.0 +2.3/-2.4 a	29.5 +3.1/-3.0 at 101 mo			
Kappa 900 DR	KDR901, KDR903, KDR906	Jan-02	125,400	37,800	13,888	. 26	+ 18 = 74	Excluding Normal Battery Depletion	100.0	100.0	100.0+0.0/-0.0	100.0	100.0	100.0 9	99.9	99.9 + 0.0-/0.0+ a	99.9 +0.0/-0.1 at 103 mo			
								Including Normal Battery Depletion	100.0	99.9	99.8	99.4 +0.0/-0.1	98.6 +0.1/-0.1	96.5 8 +0.1/-0.1	87.5 +0.3/-0.3 +1	57.9 +0.5/-0.5 a	6.8 +0.8/-0.7 at 103 mo			
Kappa 900 SR	KSR901, KSR903, KSR906	3 , Jan-02	37,000	8,120	2,376	80	+ 9 = 17	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0 +0.0/-0.0	100.0 9	99.9	99.9 ++0.0/-0.1	99.9 +0.0/-0.1 a	99.8 +0.1/-0.1 at 101 mo			
	Advisories: See page 151 – 2009 Potential Separation of Interconnect Wires	page 151 – ires	- 2009 Poter	ntial Separati	on of	(7) + (advisory-re	+ (1) = (8) y-related subset)	Including Normal Battery Depletion	99.9	99.8	99.6	98.9 +0.1/-0.1	97.5 +0.2/-0.2 +	94.5 +0.3/-0.4 ++	83.9 +0.7/-0.7	48.9 +1.4/-1.4	13.0 +2.3/-2.1 at 101 mo			
	<u>See page 159</u> – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	Performanc h Measurem€	e note on D ent Lock-up	oual Chamber ERI																
Kappa 900 VDD	KVDD901	Jan-02	650	77	80	0	+ 2 = 2	Excluding Normal Battery Depletion	100.0	100.0	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	99.6 +0.3/-1.9 #	99.6 +0.3/-1.9 at 83 mo					
	Advisories: See page 151 – 2009 Potential Separation of Interconnect Wires	page 151 - ires	- 2009 Poter	ntial Separati	on of			Including Normal Battery Depletion	100.0	100.0	100.0 +0.0/-0.0	99.0 + 0.6/-1.6	97.9 97.1+1.1/-2.1	90.7 +2.7/-3.7 ++	55.2 +6.4/-7.0 at 83 mo					

Device Survival Summary continued

J	Implantabl	C 1	uise G	enerat	.013, CC			ı								ı	1
		16 yr				99.9 +0.0/-0.0 at 218 mo	41.9 +2.5/-2.6 at 218 mo	99.9 +0.0/-0.1 at 247 mo	64.0 +2.5/-2.6 at 247 mo	100.0 +0.0/-0.0 at 212 mo	39.7 +2.6/-2.6 at 212 mo					99.9 +0.1/-0.3 at 175 mo	83.9 +2.9/-3.5 at 175 mo
		14 yr				99.9	70.9	99.9	80.9	100.0 +0.0/-0.0	68.0 +1.5/-1.5	100.0 +0.0/-0.0 at 147 mo	5.5 +1.1/-1.0 at 147 mo	100.0 +0.0/-0.0 at 13 yr	26.3 +2.4/-2.4 at 13 yr	99.9 +0.1/-0.3	84.8 +2.7/-3.3
		12 yr				99.9	82.2 +0.6/-0.6	99.9	84.0 +0.6/-0.6	100.0	81.9 +1.0/-1.1	100.0	14.0 +1.2/-1.1	100.0	43.3 +1.9/-1.9	99.9 +0.1/-0.3	89.3
		10 yr				99.9	88.6 +0.4/-0.4	99.9	87.4 +0.5/-0.5	100.0	89.1 +0.7/-0.8	100.0	66.4 +1.0/-1.1	100.0	75.2 +1.3/-1.4	99.9	92.8
		8 yr				99.9	94.8 +0.3/-0.3	99.9	92.3	100.0	94.8 +0.5/-0.5	100.0	92.4 +0.5/-0.5	100.0	92.1	99.9	96.8 +0.9/-1.3
		7 yr	99.9 +0.0/-0.1 at 82 mo	2.0 +0.0/-0.1 at 82 mo		99.9	97.3 +0.2/-0.2	99.9	95.4 +0.3/-0.3	100.0 +0.0/-0.0	97.1 +0.3/-0.4	100.0	96.2 +0.3/-0.3	100.0	95.0 +0.5/-0.5	99.9	97.9
		6 yr	99.9 +0.0/-0.1	59.6 +1.2/-1.2		99.9	98.2 +0.1/-0.1	99.9	97.8 +0.2/-0.2	100.0	98.2 +0.2/-0.3	100.0	97.7 +0.2/-0.3	100.0	97.2 +0.3/-0.4	99.9	98.9
(9)		5 yr	100.0 +0.0/-0.0	90.2		99.9	98.9	99.9	98.8 +0.1/-0.1	100.0	99.0	100.0	98.7	100.0	98.3 +0.2/-0.3	99.9	99.1
Device Survival Probability (%)		4 yr	100.0 +0.0/-0.0	97.2 +0.3/-0.3		99.9	99.2	99.9	99.2 +0.1/-0.1	100.0	99.5	100.0	99.3	100.0	99.0	100.0	99.6 +0.2/-0.3
al Proba	plant	3 yr	100.0	99.2 +0.1/-0.2		100.0	99.5	99.9	99.5	100.0	99.8	100.0	99.5	100.0	99.4 +0.1/-0.2	100.0	99.6
Surviv.	Years After Implant	2 yr	100.0 +0.0/-0.0	99.7		100.0 +0.0/-0.0	99.7	99.9 +0.0/-0.0	99.7 +0.0/-0.1	100.0	99.9	100.0	99.8 +0.1/-0.1	100.0	99.7	100.0	99.6
Device	Years	1 yr	100.0 +0.0/-0.0	99.9		100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	99.8	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	99.8 +0.0/-0.1	100.0 +0.0/-0.0	99.8 +0.1/-0.1	100.0 +0.0/-0.0	99.7
			פֿ≻ַכ	9 > 5		۵ > ٦	のシェ	の>c	ם > ב	שאר	ם > כ	~ ~ c	- × -	שאכ	B > C	ם > כ	o > ⊏
			Excluding Normal Battery Depletion	Including Normal Battery Depletion		Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
		ToT	4			35	Includin Normal Batter Depletio	20	— Includin Normal Batter Depletio	т	Includin Normal Batter Depletio	4	Including Normal Battery Depletior	-	Includin Normal Batter Depletio	-	Includin Normal Batter Depletio
tions	yrapy oction Mot npromised la	Fun ToD	1 = 4	= 3 subset)		24 = 35	Includin Normal Batter Depletio	15 = 50	— Includin Normal Batter Depletio	3 E	Includin Normal Batter Depletio	0 = 4	Including Normal Battery Depletior	0 = 1	Includin Normal Batter Depletio	0 = 1	Includin Normal Batter Depletio
Malfunctions	toN not pesimorqn	The The The Tun Too	4	= 3 d subset)		= 35	Includin Normal Batter Depletio	= 50	— Includin Normal Batter Depletio	т П	includin Normal Batter Depletio	4	Including Normal Battery Depletior		Includin Normal Batter Depletio		Includin Normal Batter Depletio
Malfunctions	nction npromised erapy totion Not npromised	Ther Fun Con Ther Ther Ther	+ + + + + + + + + + + + + + + + + + + +	(3) + (0) = 3 (advisory-related subset)	прег	+ 24 = 35	Includin Normal Batter Depletio	+ 15 = 50	1	8 8 +	Includin Normal Batter Depletio	+ 0 +	Including Normal Battery Depletion	+ 0 = 1	Includin Normal Batter Depletio	+ 0 +	Includin Normal Batter Depletio
Malfunctions	sletions srapy rction npromised srapy rction Not nction Not	Action Month of the Month of th	3 + 1 = 4	(3) + (0) = 3 (advisory-related subset)	on Dual Chamber k-up ERI	11 + 24 = 35	Includin Normal Batter Depletio	35 + 15 = 50	1	0 + 3	Includin Normal Batter Depletio	4 + 0 = 4	Including Normal Batter Depletion	1 + 0 = 1	Includin Normal Batter Depletio	1 + 0 = 1	Includin Normal Batter Depletio
Malfunctions	ive US hlants mal Battery hlations stories reply retion notion stories stories retion Not	Esti Mon Imp Mon Dep Fun Con The Fun Con	2,633 3 + 1 = 4	(3) + (0) = 3 (advisory-related subset)	nance note on Dual Chamber ement Lock-up ERI	2,611 11 + 24 = 35	Includin Normal Batter Depletio	1,768 35 + 15 = 50	1	973 0 + 3 = 3	Includin Normal Batter Depletio	2,886 4 + 0 = 4	Including Normal Batter Depletion	1,089 1 + 0 = 1	Includin Normal Batter Depletio	58 1 + 0 = 1	Includin Normal Batter Depletio
Malfunctions	mated ive US slants slants mal Battery sletions srepy crtion crtion srepy srepy srepy crtion Not crtion Not crtion Not crtion Not	Region Selection of the	1,860 $2,633$ $3 + 1 = 4$	(3) + (0) = 3 (advisory-related subset)	– Performance note on Dual Chamber ith Measurement Lock-up ERI	5,830 2,611 11 + 24 = 35	Includin Normal Batter Depletio	7,470 1,768 35 + 15 = 50	1	1,930 973 0 + 3 = 3	Includin Normal Batter Depletio	2,470 2,886 4 + 0 = 4	Including Normal Battery Depletion	1,620 $1,089$ $1 + 0 = 1$	Includin Normal Batter Depletio	460 58 1 + 0 = 1	Includin Normal Batter Depletio
Malfunctions	Market Basse listered Implants ive US ive US liants mal Battery sletions srepy scrion mpromised repy repy repy repy repy repy	USI Rela Mor Imp Mor Imp The Fun Thu Con	16,300 1,860 2,633 3 + 1 = 4	= 3 subset)	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	58,600 5,830 2,611 11 + 24 = 35	Includin Normal Batter Depletio	58,600 7,470 1,768 35 + 15 = 50	Advisories: <u>See page 158</u> – 1991 Potential Delayed – – Normal Batter Restoration of Permanent Settings Depletio	16,800 1,930 973 0 + 3 = 3	Includin Normal Batter Depletio	25,500 2,470 2,886 4 + 0 = 4	Including Normal Battery Depletion	$17,800 1,620 1,089 \qquad 1 + 0 = 1$	Includin Normal Batter Depletio	4,190 460 58 1 + 0 = 1	Includin Normal Batter Depletio

					Į	Malfunctions	tions		ŀ	Device	Device Survival Probability (%)	Probab	llity (%)								J
			s				tol bes														шрк
γlin	del mber	Market ease	jistered Implants	bətsmi SU əvi stnslo	ta8 lam anoitelo	erapy netion mpromi	erapy N notion Mpromis	ls		Years A	Years After Implant	lant									aritabi
Fan	oM inM	leЯ NS	SN Beg	tэА	Del	ru7 100	The ruil	toT		1 yr	2 yr	3 yr	4 yr	5 yr (6 yr 7	7 yr 8	8 yr 1	10 yr	12 yr	14 yr	16 yr
Prodigy DR	7860, 7861, 7862	Oct-95	37,400	3,140	3,949	+ 9	r2 II	=	Excluding Normal Battery Depletion	100.0	100.0	100.0 + +0.0/-0.0	100.0+0.0/-0.0+	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 +1	100.0 +0.0/-0.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0 a	100.0 +0.0/-0.0 at 145 mo	uise de
									Including Normal Battery Depletion	99.9	99.8	99.6	99.3	98.7 +0.1/-0.1	97.9 +0.2/-0.2 +	96.3 9;	92.4 +0.4/-0.4 +0	68.4 +0.9/-0.9	10.8 +1.1/-1.0 a	7.8 +1.1/-1.0 at 145 mo	nerate
Prodigy SR	8158, 8160, 8161, 8162	Oct-95	22,300	2,350	1,348	+	2 =	4		0.0										100.0 +0.0/-0.0 at 155 mo	ors, contin
									Including Normal Battery Depletion	99.7	99.6	99.2 +0.1/-0.1 +	98.7 +0.2/-0.2 +	97.8 +0.2/-0.3 +	96.5 9	94.8 +0.4/-0.5 +1	91.5 74+0.6/-0.6 +1	74.1 4	45.0 2 +1.8/-1.8 +	26.5 +2.5/-2.5 at 155 mo	ded
Sensia DR	SEDR01, SED01	90-Inr	103,500	006'62	75	4	II ∞	12	Excluding Normal Battery Depletion	100.0	100.0	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 a	100.0 +0.0/-0.0 at 64 mo						
	See page 159 – Performance note on Dual or Pacemakers with Measurement Lock-up ERI	9 – Perfor with Meas	mance note urement Lo	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI	mber				Including Normal Battery Depletion	100.0	100.0 +	99.8	99.6	99.1 +0.2/-0.2 a	98.9 +0.3/-0.4 at 64 mo						
Sensia SR	SESR01, SES01	90-Inr	69,700	49,200	09	+	н К	4	Excluding Normal Battery Depletion	100.0	100.0	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 a	100.0 +0.0/-0.0 at 63 mo						
									Including Normal Battery Depletion	100.0	99.9	99.8	99.5	98.9 +0.2/-0.3 a	98.9 +0.2/-0.3 at 63 mo						
Sigma 100 S	SS103, SS106	Aug-99	790	100	81	+	0	0	Excluding Normal Battery Depletion	100.0	100.0	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0 +1	100.0 +0.0/-0.0 at	100.0 +0.0/-0.0 at 100 mo			
	Advisories: of Interconn	See page 1. lect Wires	55 – 2005 Pc	Advisories: See page 155 – 2005 Potential Separation of Interconnect Wires		(0) + (advisory-r	$\frac{(0)}{(0)} + (0) = (0)$ (advisory-related subset)	(0) oset)	Including Normal Battery Depletion	100.0	100.0 + 0.0/-0.0	99.5	99.5	98.7 +0.8/-2.3	98.7 +0.8/-2.3 +	96.5 99.1-1.8/-3.6 +2.4	93.7 +2.8/-4.8 +3 at	90.3 +3.8/-6.1 at 100 mo			
Sigma 200 DR	SDR203	Aug-99	15,800	3,940	599	30 +	-	31	Excluding Normal Battery Depletion	100.0	100.0	100.0 + +0.0/-0.0	100.0 + +0.0/-0.0	100.0 +0.0/-0.0	100.0 + 0.0/-0.0 +	99.8 +0.1/-0.1	99.6 +0.1/-0.2 +0	99.5 +0.1/-0.2 a	99.5 +0.1/-0.2 at 135 mo		
	Advisories: of Interconn Potential Se	See page 1 lect Wires; paration of	55 – 2005 Pose also para l'Interconne	Advisories: See page 155 – 2005 Potential Separation of Interconnect Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires	_	(19) + (0) advisory-related		= (19) subset)	Including Normal Battery Depletion	100.0	99.9	99.9 + 0.0/-0.1	99.8	99.5 +0.1/-0.2	99.0 +0.2/-0.2 +	97.5 9.4+0.3/-0.4	94.1 81+0.6/-0.6	81.1 +1.2/-1.3 a	50.8 +3.4/-3.5 at 135 mo		
Sigma 200 SR	SSR203, SS203	Sep-99	12,100	2,110	285	+	0	Ε	Excluding Normal Battery Depletion	100.0	100.0	100.0 + +0.0/-0.0	100.0 + 0.0/-0.0	99.9	99.9 +0.1/-0.2 +	99.8 +0.1/-0.2	99.8 +0.1/-0.2 +(99.7 +0.1/-0.2	99.7 +0.1/-0.2 at 137 mo		
	Advisories: See page 155 – 2005 Potential S of Interconnect Wires; See also page 151 – Potential Separation of Interconnect Wires	See page 1 lect Wires; paration of	55 – 2005 Pose also para l'Interconne	Advisories: See page 155 – 2005 Potential Separation of Interconnect Wires; <u>See also page 151</u> – 2009 Potential Separation of Interconnect Wires		(11) + (advisory-r	$\frac{(11)}{(11)} + (0) = (11)$ $\frac{(11)}{(11)} + (0)$	(11) (3set)	Including Normal Battery Depletion	99.9	99.9	99.8	99.7	99.2 +0.2/-0.3	98.6 +0.3/-0.4 +	97.1 9.1+0.5/-0.6	95.2 83.4+0.7/-0.8 +1	83.7 5 +1.6/-1.7 a	56.2 +4.3/-4.6 at 137 mo		
Sigma 300 DR	SDR303, SDR306	Aug-99	106,700	34,300	2,523	198 +	10 =	208	Excluding Normal Battery Depletion	100.0	100.0	100.0 + 0.0/-0.0	99.9	99.9	99.9 + 0.0/-0.0+	99.8	99.6 +0.1/-0.1	99.5 +0.1/-0.1	99.5 +0.1/-0.1 at 136 mo		
1	Advisories: See page 155 – 2005 Potential S of Interconnect Wires; See also page 151 – 2 Potential Separation of Interconnect Wires	See page 1. lect Wires; paration of	55 – 2005 Po See also par Interconne	Advisories: See page 155 – 2005 Potential Separation of Interconnect Wires; See also page 151 – 2009 Potential Separation of Interconnect Wires		(145) + (advisory-r	$\frac{(145)}{(advisory-related subset)}$	(145) oset)	Including Normal Battery Depletion	100.0	99.9	99.9	99.7	99.4 + 0.1/-0.1	98.9 +0.1/-0.1	97.9 +0.1/-0.1 ++	95.1 81	81.7 +0.6/-0.6 a	41.0 +3.5/-3.5 at 136 mo		
confinition	מם																				

Device Survival Summary continued

		16 yr														
		14 yr					99.9 +0.0/-0.0 at 148 mo	5.8 +0.6/-0.5 at 148 mo	100.0 +0.0/-0.0 at 166 mo	26.9 +1.9/-1.8 at 166 mo	100.0 +0.0/-0.0 at 160 mo	39.7 +3.7/-3.8 at 160 mo				
		12 yr	99.7 +0.1/-0.1 at 136 mo	46.9 +4.8/-4.9 at 136 mo			99.9	19.7	100.0	51.6	100.0 +0.0/-0.0	58.2 +2.9/-3.0				
		10 yr	99.7 +0.1/-0.1	81.8	99.5 +0.4/-2.5 at 107 mo	74.6 +5.7/-7.0 at 107 mo	99.9	71.3 +0.4/-0.4	100.0	80.1	100.0	89.1				
		8 yr	99.7	94.9	99.5	89.6 +3.2/-4.6	99.9	93.2 +0.2/-0.2	100.0	94.5 +0.3/-0.3	100.0 +0.0/-0.0	98.0				
		7 yr	99.8 +0.1/-0.1	97.2 +0.2/-0.3	100.0 +0.0/-0.0	94.2 +2.2/-3.6	99.9	96.7 +0.1/-0.1	100.0	96.9 +0.2/-0.2	100.0 +0.0/-0.0	99.1 +0.3/-0.4				
		6 yr	99.9	98.6 +0.1/-0.2	100.0 +0.0/-0.0	98.1 +1.0/-2.2	100.0	98.1 +0.1/-0.1	100.0	98.2 +0.2/-0.2	100.0 +0.0/-0.0	99.2 +0.3/-0.4	100.0 +0.0/-0.0 at 64 mo	99.2 +0.2/-0.2 at 64 mo		
(6		5 yr	100.0 +0.0/-0.0	99.2	100.0 +0.0/-0.0	99.4 +0.4/-1.6	100.0	98.9 +0.1/-0.1	100.0	98.9 +0.1/-0.1	100.0 +0.0/-0.0	99.3 +0.2/-0.3	100.0 +0.0/-0.0	99.3 +0.1/-0.2		
bility (%		4 yr	100.0 +0.0/-0.0	99.6 +0.1/-0.1	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.4 +0.0/-0.1	100.0	99.3 +0.1/-0.1	100.0 +0.0/-0.0	99.6 +0.2/-0.3	100.0 +0.0/-0.0	99.7 +0.1/-0.1		
al Proba	plant	3 yr	100.0 +0.0/-0.0	99.8	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.9	100.0	99.6 +0.1/-0.1	100.0 +0.0/-0.0	99.6 +0.2/-0.3	100.0 +0.0/-0.0	99.9 +0.0/-0.0		
Device Survival Probability (%)	Years After Implant	2 yr	100.0 +0.0/-0.0	99.9	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.9	100.0	99.8	100.0 +0.0/-0.0	99.8 +0.1/-0.2	100.0 +0.0/-0.0	100.0 +0.0/-0.0		
Device	Years	1 yr	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0	100.0	99.9	100.0	99.9	100.0 +0.0/-0.0	99.9 +0.1/-0.1	100.0 +0.0/-0.0	100.0	100.0 +0.0/-0.0	100.0 +0.0/-0.0
			ing ery itio	ng on	D 주 G	פֿר אַ נ	ع ح م	ם אים	호 > 트	פ א ב	ق > 5	ם א ב	שֿ≻ב	ם א ב	ם אַ בּ	ם > ב
			Excluding Normal Battery Depletio	Including Normal Battery Depletion	Excluding Normal Battery Depletio	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion	Excluding Normal Battery Depletion	Including Normal Battery Depletion
	ls	JoT	48 Excludi Normal Batt	Norm	1 Excludi Normal Batte Deplet	Norm	49 Excludin Normal Batter Depletio	Includir Normal Batter Depletic	8 Excludin Normal Batter Depletio	Includir Normal Batte Depletic	O Excludin Normal Batter Depletio	Includin Normal Batter Depletio	8 Norn	Includin Normal Batter Depletio	1 Excludin Normal Batter Depletio	Includin Normal Batter Depletio
ions	oction Not npromised	Fun Con	= 48 Norm	Norm	= 1	= (1) Norm	= 49 Norm	Includir Normal Batter Depletic	Norm	Includir Normal Batte Depletic	0 = Norm	Includin Normal Batter Depletio	Norn	Includin Normal Batter Depletio	= 1	Includin Normal Battei Depletio
alfunctions	nction npromised repy retion Not notion	Fun The Tun Tun	48 Norm	+ (0) = (37) Norm visory-related subset)	Norn	= (1) Norm	+ 23 = 49 Norm	Includir Normal Batte Depletic	8 Norm	Includir Normal Batte Depletic	0 Norm	includin Normal Batter Depletio	8 Norn	Includin Normal Batter Depletio	1 Norm	Includin Normal Batter Depletio
Malfunctions	very orition npromised erection orition npromised	ed fund no no fund no no	45 + 3 = 48 Norm	(37) + (0) = (37) Norm (advisory-related subset)	0 = 1		26 + 23 = 49 Norm	Includir Normal Batte Depletic	6 + 2 = 8 Norm	Includir Normal Batte Depletic	0 = 0 + 0	Includin Normal Batter Depletio	2 + 6 = 8 Norm	Norm	1 + 0 = 1 Norm	Includir Normal Batter Depletic
Malfunctions	nction npromised repy retion Not notion	Dep The no The nu The no O	+ 3 = 48	(37) + (0) = (37) Norm (advisory-related subset)	+ 0 = 1		+ 23 = 49 Norm	Includir Normal Batte Depletic	+ 2 = 8 Norm	Includir Normal Batte Depletic	+ 0 = 0 +	Includin Normal Batter Depletio	+ 6 = 8 Norn	Norm	+ 0 = 1	Includir Normal Batter Depletio
Malfunctions	shetions repy oction npromised srepy oction Mot npromised	Acti Mor Dep The Tun Con The Tun The	45 + 3 = 48 Norm	(37) + (0) = (37) Norm (advisory-related subset)	1 + 0 = 1 Norn		10,400 14,029 26 + 23 = 49 Norm	Includir Normal Batte Depletic	6 + 2 = 8 Norm	Includir Normal Batte Depletic	0 = 0 + 0	Includin Normal Batter Depletio	2 + 6 = 8 Norm	Norm	1 + 0 = 1 Norm	Includir Normal Batter Depletic
Malfunctions	hlants mal Battery nal Battery snoisel scrions crion iction crion iction of crion of	Esti Acti Imp Morn Morn Morn The Fun Con The Fun Con	872 45 + 3 = 48 Norm	(37) + (0) = (37) Norm (advisory-related subset)	49 1 + 0 = 1 Norm		14,029 26 + 23 = 49 Norm	Includir Normal Batte Depletic	2,884 6 + 2 = 8 Norm	Includir Normal Batte Depletic	331 0 + 0 = 0 Norm	Includin Normal Batter Depletio	64 2 + 6 = 8 Norm	Norm	0 1 + 0 = 1 Norm	Includir Normal Batter Depletio
Malfunctions	mated ive US idents mal Battery strions srapy promised region Not regoy promised	Reger USI Estimate More More The Pun More The The The The The The The The The Th	12,300 872 45 + 3 = 48 Norm	(37) + (0) = (37) Norm (advisory-related subset)	110 49 1 + 0 = 1 Norm	e 155 – 2005 Potential Separation of (1) + 0 = (1) Norm (advisory-related subset)	10,400 14,029 26 + 23 = 49 Norm	Includir Normal Batte Depletic	4,520 2,884 6 + 2 = 8 Norm	Includir Normal Batte Depletic	570 331 0 + 0 = 0 Norm	Includin Normal Batter Depletio	64,600 64 2 + 6 = 8 Norm	Norm	21,700 0 1 + 0 = 1 Norm	Includir Normal Batte
Malfunctions	Market seese iistered implants mated ive US ine US	NS I Rela Regolusion No. 1 No.	54,100 12,300 872 45 + 3 = 48 Norm	+ (0) = (37) Norm visory-related subset)	640 110 49 1 + 0 = 1 Norm	= (1) Norm	121,300 10,400 14,029 26 + 23 = 49 Norm	Includir Normal Batte Depletic	50,000 4,520 2,884 6 + 2 = 8 Norm	Includir Normal Batte Depletic	4,860 570 331 0 + 0 = 0 Norm	Includin Normal Batter Depletio	83,000 64,600 64 2 + 6 = 8 Norm	See page 159 – Performance note on Dual Chamber Pacemakers with Measurement Lock-up ERI Depletio	22,100 21,700 0 1 + 0 = 1 Norm	Includir Normal Batter Depletic



Reference Chart

The longevity estimates provided are mean values calculated for the parameters given. The longevity estimates shown here assume a lower rate of 60 ppm, 100% pacing, and pulse width of 0.4 ms unless noted otherwise. The actual longevity achieved for any device while implanted will depend on the actual programmed parameters and patient factors, and may differ significantly from these estimates. The elective replacement time is indicated via telemetry indication, and rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet), unless noted otherwise.

		Estimated L	ongevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Adapta DR	ADDR01, ADDR03, ADDR06, ADD01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.4 6.0	**
Adapta DR	ADDRS1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.3 3.2	6.1 5.4 4.4	**
Adapta DR	ADDRL1	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.3 5.4	10.0 8.9 7.2	**
Adapta SR	ADSR01, ADSR03, ADSR06	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 5.1	7.9 7.5 6.3	**
Adapta VDD	ADVDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.5 4.4	6.5 6.2 5.4	**
AT500	AT501, 7253	Low 2.0 V (A, RV) Nominal 3.0 V (A, RV) High 5.0 V (A, RV)	7.7 5.8 3.7	8.3 7.0 5.2	Telemetry indication. Pacing mode and rate (magnet and non-magnet) as programmed.
EnPulse DR	E1DR01, E1DR03, E1DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse DR	E1DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR01, E2DR03, E2DR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.5 6.2 4.4	8.5 7.6 5.9	**
EnPulse 2 DR	E2DR21	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.4 4.3 3.0	6.0 5.4 4.2	**
EnPulse 2 DR	E2DR31, E2DR33	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.0 7.4 5.2	10.1 9.1 7.1	**
EnPulse 2 SR	E2SR01, E2SR03, E2SR06	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.2 6.3 4.8	7.7 7.3 6.1	**
EnPulse 2 VDD	E2VDD01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.1 5.5 4.3	6.5 6.2 5.4	**
EnRhythm DR	P1501DR	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.7 7.3 4.9	11.2 9.4 7.1	**
Kappa 400 DR	KDR401, KDR403	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.8 6.4 5.1	8.5 7.5 6.5	**
Kappa 400 SR	KSR401, KSR403	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.9 6.9 5.8	8.4 7.7 7.0	**
Kappa 600 DR	KDR601, KDR603, KDR606	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 600 DR	KDR651, KDR653	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**

^{**}Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

		Estimated Long	jevity		
Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Kappa 700 D	KD701, KD703, KD706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR701, KDR703, KDR706	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 700 DR	KDR721	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.2	**
Kappa 700 SR	KSR701, KSR703, KSR706	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 4.9	7.9 7.5 6.2	**
Kappa 700 VDD	KVDD701	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.3	**
Kappa 800 DR	KDR801, KDR803	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR901, KDR903, KDR906	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.7 6.3 4.4	8.6 7.7 6.0	**
Kappa 900 DR	KDR921	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	5.5 4.4 3.0	6.1 5.5 4.3	**
Kappa 900 SR	KSR901, KSR903, KSR906	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.3 6.4 4.9	7.9 7.4 6.1	**
Kappa 900 VDD	KVDD901	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	6.2 5.6 4.4	6.6 6.3 5.4	**
Legend II	8424, 8426, 8427	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.9 9.4 7.8	14.5 11.8 10.5	If programmed to non-rate responsive mode (e.g., VVI), rate decrease of 10% from programmed rate. Telemetry indication. If programmed to rate responsive mode (e.g., VVIR), rate change to 65 ppm and mode change to VVI. Telemetry indication.
Minix	8340, 8341, 8341M, 8342	Low 2.5 V (RV) Nominal 3.3 V (RV) High 5.0 V (RV)	14.9 10.2 7.9	17.3 13.6 11.3	Telemetry indication. Rate decrease of 10% from programmed rate.
Minix ST	8330, 8331, 8331M	Low 2.5 V (RV) Nominal 5.0 V (RV) High 8.0 V (RV)	14.9 7.9 4.0	17.3 11.4 7.0	Telemetry indication. Rate decrease of 10% from programmed rate.
Minuet	7107, 7108	Low 2.5 V, 0.36 ms (RV) Nominal 3.3 V, 0.36 ms (RV) High 5.0 V, 0.36 ms (RV)	12.5 7.7 4.7	15.6 10.9 7.6	**
Preva DR	7088, 7089	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Preva SR	8088, 8089	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Prevail S	8085, 8086	Low 2.5 V, 0.42 ms (RV) Nominal 3.3 V, 0.42 ms (RV) High 5.0 V, 0.42 ms (RV)	16.4 10.8 8.6	19.4 14.4 12.4	Telemetry indication. Rate decrease of 10% from programmed rate.

 $[\]ensuremath{^{**}}\text{Telemetry}$ indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).



Reference Chart continued

Family	Model Number	Amplitude Setting	500 Lead Ω	1000 Lead Ω	Elective Replacement Indicators
Prodigy DR	7860, 7861, 7862	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	9.9 7.4 5.4	11.3 9.4 7.5	**
Prodigy SR	8158, 8160, 8161, 8162	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	9.8 8.0 6.4	10.7 9.5 8.1	**
Sensia DR	SEDR01, SED01	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	7.4 6.0 4.5	8.2 7.4 6.0	**
Sensia SR	SESR01, SES01	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	7.4 6.5 5.1	7.9 7.5 6.3	**
Sigma 100 S	SS103, SS106	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 200 DR	SDR203	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 200 SR	SSR203	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 DR	SDR303, SDR306	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)	10.1 7.5 5.5	11.7 9.6 7.8	**
Sigma 300 SR	SSR303, SSR306	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	10.1 8.2 6.4	11.1 9.8 8.4	**
Sigma 300 VDD	SVDD303	Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)	8.9 7.3 5.8	9.7 8.6 7.4	**
Thera-i DR	7960i, 7961i,	Low 2.5 V (A, RV) Nominal 3.5 V (A, RV)	9.9 7.4	11.3 9.4	**

9.4 7.5

10.7

9.5

8.1

12.4

11.1 9.7

8.2

7.4

6.0

11.2

7.1

**

9.8

8.0

11.5

9.6 7.7

7.4

6.0

4.5

9.7

4.9

Estimated Longevity

7962i

8960i,

8961i,

8962i

8968i

VEDR01

RVDR01

Thera-i SR

Thera-i VDD

Versa DR

Revo MRI

SureScan

High 5.0 V (A, RV)

Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)

Low 2.5 V (RV) Nominal 3.5 V (RV) High 5.0 V (RV)

Low 2.5 V (A, RV) Nominal 3.5 V (A, RV)

Low 2.5 V (A, RV) Nominal 3.5 V (A, RV) High 5.0 V (A, RV)

High 5.0 V (A, RV)

^{**}Telemetry indication. Rate and mode change to 65 ppm and VVI respectively (VOO/65 with magnet).

Method for Estimating Lead Performance

Medtronic CRDM has tracked lead survival for over 28 years with its multicenter, global chronic lead studies.

Leads Performance Analysis

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. While IPGs and ICDs have a battery that will deplete after a predictable length of time, a lead's longevity cannot be predicted, nor are there simple indicators that a lead is approaching the end of its service life. Therefore, regular monitoring while implanted, and evaluation of lead integrity upon IPG or ICD replacement, is necessary to determine if a lead may be approaching the end of its service life.

Returned Product Analysis Shortfalls

All leads and lead segments returned to Medtronic are analyzed to determine whether or not they meet performance limits established by Medtronic. Although returned product analyses are valuable for gaining insight into lead failure mechanisms, this data cannot be used by itself for determining the survival probability of leads because only a small fraction of leads are explanted and returned for analysis. Additionally, those leads that are returned cannot be assumed to be statistically representative of the performance of the total population for a given lead model. Partial or total lead extraction can result in significant damage to a lead, making a definitive analysis of a suspected failure and its cause impossible. Thus, lead survival probabilities are more appropriately determined through a clinical surveillance study. Although returned product analysis results are presented in this report, Medtronic tracks lead survival through its System Longevity Study.

System Longevity Study (SLS)

The SLS is a prospective, non-randomized multicenter, global study designed to monitor the performance of market-released cardiac therapy products. Medtronic has been monitoring the performance of its cardiac therapy products with a multicenter study for 28 years and has evaluated the performance of more than 75,000 leads, with data reported from 14 countries on four continents.

The primary purpose of the SLS is to evaluate and publish the long-term reliability and performance of Medtronic market-released cardiac therapy products by analyzing product survival probabilities. Productrelated adverse events, indicating the status of the product, are collected to measure survival probabilities. The data gathered in this study may also be used to support the design and development of investigational plans for new cardiac therapy products. The SLS is designed to continue indefinitely, encompassing new products as they become commercially available.

Eligible products for study enrollment include all Medtronic market-released cardiac therapy products. Medtronic may limit overall enrollment of any product when the number of enrollments provides an adequate number to effectively assess product survivability. Medtronic reserves the right to close enrollment of a product at a site level in order to ensure all participating sites have an equal opportunity to enroll.

To ensure a sufficiently large and representative source of data, participating clinical centers must meet specific selection criteria. In addition, centers are selected to be representative of the range of clinical environments in which Medtronic conducts business.

Investigators enroll qualified subjects with specific Medtronic market-released cardiac therapy products and follow these subjects from their implant date until they can no longer be followed (e.g., death and lost to follow-up). Using a Clinical Investigation Plan, each center monitors and reports on the performance of specific Medtronic market-released cardiac therapy products (e.g., product-related adverse events, replacements and abandonments) and subject status (e.g., subject death and subject withdrawal from the study). Subjects will be followed by their respective center in accordance with the center's established practices for routine follow-up.

Patients are eligible for enrollment in the study if:

- 1. They are within 6 months post-implant of a Medtronic market-released lead connected to a market-released CRT, ICD, or IPG device, and the lead is used for a pacing, sensing, or defibrillation application, or
- 2. They participated in a qualifying study of a marketreleased Medtronic cardiac therapy product; complete implant and follow-up data are available; and the data is appropriately and legally released for use in the study.

The Standard Actuarial Method is used to determine estimates of lead survival.

The SLS protocol requires regular follow-up reporting on all leads actively followed in the study. The follow-up schedule for this study is based on utilizing routine, scheduled office/clinic visits and unscheduled office/ clinic visits prompted by symptoms or complaints. Data collected at each follow-up includes routine clinical electrical data, any system modifications, and any lead or generator adverse events.

Each study center must inform Medtronic whenever a lead complication has occurred or when a patient is no longer participating in the study. Under the study protocol, each lead is assumed to be normally active unless a lead-related complication is confirmed, the lead is abandoned or explanted, the patient is no longer available for follow-up, or more than 24 months have passed since last follow-up. The data analyses assume that the patient is still part of the study and no lead complications had occurred as of the report cutoff date unless specifically reported by the center.

Medtronic evaluates center compliance with study protocol through clinical monitoring at each study site. Additionally, study center personnel must be trained in the study procedures prior to participating, and they must adhere to the policies and procedures of their local ethics boards.

Lead Complications

All adverse events are critically evaluated by a Medtronic technical review committee and the investigator is asked to assess the relationship of the adverse event to the presence or performance of the implanted system, generator and/or lead(s).

The SLS complication criteria are defined below. These criteria do not, however, enable a lead integrity or "hardware" failure to be conclusively differentiated from other clinical events such as an undetected lead dislodgement, exit block, or concurrent pulse generator failure manifested as a sensing or capture problem.

A lead-related complication is considered to have occurred if at least one of the following clinical observations is reported and at least one of the following clinical actions is made 30 days or more after the implant.

Clinical Observations

- Failure to capture
- Failure to sense/undersensing
- Oversensing
- Abnormal pacing impedance (based on lead model, but normal range is typically 200-3,000 ohms)
- Abnormal defibrillation impedance (based on lead model, but normal range is typically 20-200 ohms)
- Insulation breach, observed visually, that has degraded system performance
- Conductor fracture, observed visually or radiographically
- Extracardiac stimulation
- Cardiac perforation
- Lead dislodgement

Clinical Actions

- Lead surgically abandoned/capped
- Lead electrically abandoned/capped
- Lead explanted
- Lead replaced
- Polarity reprogrammed (i.e., bipolar to unipolar; unipolar to bipolar)
- Lead use continued based on medical judgment despite a known clinical performance issue
- Other lead-related surgery performed (e.g., lead mechanical alteration or unsuccessful repositioning)

Note: Successful lead repositioning is not a qualifying action.

Data Analysis Methods

The performance of leads is expressed in terms of lead survival estimates, where "survival" refers to the function of the lead, not the survival of the patient. These survival estimates are intended to illustrate the probability that a lead will survive for a given number of years without a lead-related complication.

The survival estimates are determined from the analysis of the data collected through the SLS. These data are presented graphically and numerically.

Survival times are calculated from the implant date to the earlier of the complication date, out-of-service date (for example, subject leaves the study, the lead is no longer being used, or no data has been reported within a specified time interval), or the cutoff date of the report. If a lead experiences more than one complication, the first is used to calculate survival time; although all complications associated with a lead are in the tables in this report.

Of the several different statistical methods available for survival analysis, the Standard Actuarial Method, with suspensions assumed distributed across the intervals (Cutler-Ederer Method), is used to determine estimates of lead survival. This method is commonly used by medical researchers and clinicians.

On the following pages, each graph includes a survival curve where events include qualifying lead-related complications. This survival estimate is a good representation of the probability a lead will survive a period of time without a lead-related complication. For example, if a survival probability is 95% after 5 years of service, then the lead has a 5% chance of experiencing a lead-related complication in the first 5 years following implant.

Since the survival estimate can become very imprecise with small effective sample sizes, Medtronic truncates the survival curve when the number of leads entering an interval is less than 50 leads. When the number of leads entering an interval reaches 50, the next data point is added to the survival curve.

Although the report provides tabular data in 1-year intervals, the curves are actually computed and plotted using 3-month intervals.

The data in the tables is rounded to the nearest tenth of one percent. Occasionally, a graph may show 100% survival, but have one or more complications. This occurs because even with the complications, the data rounds to 100%.

The survival curves are statistical estimates. As performance experience accumulates, the estimation improves. Confidence intervals are provided as a way to indicate the degree of certainty of the estimates. Greenwood's formula is used to calculate corresponding 95% confidence intervals for the standard errors, and the complementary log-log method is used to produce the confidence bounds.

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use.

Sample Size and How the Population and Population Samples Are Defined

The population sample from which the survival estimates are derived is comprised of the patients successfully enrolled in the SLS as of the report cutoff date. The number of enrolled implants is listed for each model.

This sample based on SLS enrollments is considered to be representative of the worldwide population, including data from 14 countries on four continents, and therefore the survival estimates shown in this report should be representative of the performance worldwide of these models.

In general, a model or model family will be included in this report when more than 100 leads have been enrolled and no fewer than 50 leads followed for at least 6 months. Models will remain in the report for at least 20 years as long as Medtronic estimates at least 500 leads remain active in the United States, based on estimated US implants.

Medtronic, at its discretion, may stop providing updated performance information on lead models that received original US market-release approval 20 or more years ago. These models may be removed from this report at that time.

Returned Product Analysis Results

Every lead or lead portion returned to Medtronic receives an analysis. Although the returned product analysis data is not used to generate the survival estimates, the data provides valuable insight into the causes of lead malfunction.

For reporting returned product analysis results, Medtronic CRDM considers a lead as having malfunctioned whenever the analysis shows that any parameter was outside the performance limits established by Medtronic while implanted and in service. To be considered a malfunction for returned product analysis reporting, the lead must have been returned to Medtronic and analyzed.

The results of the analysis is presented in four categories. The lead reporting categories are:

• Conductor Fracture: Conductor malfunction with complete or intermittent loss of continuity that could interrupt current flow (e.g., fractured conductors), including those associated with clavicle flex fatigue or crush damage.

- Insulation Breach: A malfunction of the insulation allowing inappropriate entry of body fluids or inappropriate current flow between the conductors, or between the conductor and the body. Examples include cuts, tears, depressions, abrasions, and material degradation.
- Crimps/Welds/Bonds: Any malfunction in a conductor or lead body associated with a point of connection.
- Other: Malfunctions of specific lead mechanical attributes, such as sensors, connectors, seal rings, or malfunction modes not included in the three categories

A lead subject to a safety advisory is not considered to have malfunctioned unless it has been returned to Medtronic CRDM and found, through analysis, to actually have performed outside the performance limits established by Medtronic.

For leads designed for either ventricular or atrial use, the numbers listed in the Returned Product Analysis tables include both.

The numbers of malfunctions listed in the Returned Product Analysis tables are the actual numbers confirmed in the returned product analysis from the United States. The numbers of complications listed in the complications tables are the actual numbers observed in the SLS centers around the world.

US Reports of Acute Lead Observations (Occurring within First Month of Service)

In the first weeks following lead implantation, physiologic responses and lead performance can vary until longterm lead stability is attained. Acute (defined as the first month after implant) lead performance may be subject to a number of factors, including patient-specific anatomy,

clinical conditions and/or varying implant conditions/ techniques. After a period of time, the implant and the lead performance stabilizes. It is for this reason that the System Longevity Study results, which are intended to measure long-term performance, do not include complications that occur within the first 30 days after implant.

Information about the clinical experience in the first month of service is included in this report. The source for this information is Medtronic's complaint handling system database. The information is summarized in tables titled "US Reports of Acute Lead Observations." To be included in this summary of observations, a lead must first be successfully implanted and registered in Medtronic's Device and Registrant Tracking system.

Each Event Report received by Medtronic's complaint handling system is assigned one or more Reason for Report codes based on the information received. The Reason for Report codes have been grouped into Acute Lead Observation categories. The categories used for this product performance report are drawn from the "FDA Guidance for Submission of Research and Marketing Applications for Permanent Pacemaker Leads and for Pacemaker Lead Adapter 510(k) Submissions." The categories are:

- 1. Cardiac Perforation
- 2. Conductor Fracture
- 3. Lead Dislodgement
- 4. Failure to Capture
- 5. Oversensing
- 6. Failure to Sense
- 7. Insulation Breach
- 8. Impedance Abnormal
- 9. Extracardiac Stimulation
- 10. Unspecified

Although multiple observations are possible for any given lead, only one observation is reported per lead. The observation reported is the observation highest on the list. For example, if an Event Report includes observations for both Lead Dislodgement and Failure to Sense, Lead Dislodgement is reported.

The lead event reported to Medtronic may or may not have involved clinical action or product returned to Medtronic. The lead may have remained implanted and in service.

Estimated Number of Implanted and Active Leads in the United States

In addition to providing the number of leads enrolled in the SLS, this report also provides the number of leads registered as implanted and the number remaining active in the United States based on the status recorded in the Medtronic Device and Registrant Tracking system.

Some lead models do not have a survival curve presented in this report. These lead models do not have a survival curve because they have insufficient sample size in the System Longevity Study. Returned Product Analysis results for these models are included here for reference and comparison.

2 yr

99.1

92

1 yr

99.1

109

Effective Sample Size

3 yr

99.1

71

2187 Attain LV

Product Characteristics

US Market Release	Aug-01	Serial Number Prefix	LEY	US Returned Product Anal	ysis
Registered US Implants	11,900	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Continuous Curve	Conductor Fracture Crimp/Weld/Bond	0
Estimated Active US Implants	2,900	Polarity	Unipolar	Insulation Breach	0
Advisories	None	Steroid	No	Other	1

System Longevity Study Results **Qualifying Complications** 1 Total 134 Failure to Capture Number of Leads Enrolled in Study 6,481 Cumulative Months of Follow-Up Number of Leads Active in Study 21 100 Lead Survival Probability (%) 90 80 2 3 4 5 8 9 10 0 Years After Implant

at 54 mo

99.1

51

2188 Attain CS

%

Product Characteristics

4 yr

99.1

57

	US Market Release	Aug-01	Serial Number Prefix	LEB		U:	S Returned Product A	nalysis
	Registered US Implants	1,800	Type and/or Fixation	Transvenous, Coronar Cardiac Vein, Canted	y Sinus/		Conductor Fracture Crimp/Weld/Bond	
	Estimated Active US Implants	300	Polarity	Bipolar			Insulation Breach	
	Advisories	None	Steroid	No			Other	
em	Longevity Study Results		Qı	ualifying Complications	1 Total			
	Number of Leads Enrolled in Study	15	i	Extra Cardiac Stimulation	1			
	Cumulative Months of Follow-Up	487						
	Number of Leads Active in Study	0)					
	-							
)							
100	Survival estimate not available due	to insufficient	sample size					
100 90	Survival estimate not available due	to insufficient	sample size					
100	Survival estimate not available due	to insufficient	sample size					
100 90	Survival estimate not available due	to insufficient	sample size	5 6	7	8	9 10	
100 90	Survival estimate not available due			5 6	7	8	9 10	
100 90	Survival estimate not available due 0 1 2			5 6	7	8	9 10	
100 90	Survival estimate not available due 0 1 2 Years After Implant			5 6	7	8	9 10	

545

Effective Sample Size

437

357

4193 Attain OTW

Product Characteristics

US N	Market Release	May-02	Serial	Number Prefix	BAA			U	JS Returned	Product Ana	alysis
Reg	istered US Implants	100,600	Type a	ınd/or Fixation		enous, Left Ver Double Curve	ntricular Cardia	c Vein,		or Fracture Veld/Bond	4
Esti	mated Active US Implants	37,900	Polarit	ty	Unipo	lar			Insulat	on Breach	5
Adv	risories	None	Steroi	d	Yes					Other	8
ystem Loi	ngevity Study Results			Qua	alifying Con	nplications	37 Total				
Nun	mber of Leads Enrolled in Stu	dy	675		Lead [Dislodgement	14		Unspecified C	linical Failure	3
Cum	nulative Months of Follow-Up	29,	104		Failu	ire to Capture	12		Extra Cardia	c Stimulation	7
Nun	mber of Leads Active in Study		156		Condu	uctor Fracture	1				
100											
90 -											
80 –											
0	1 2	3		4	5	6	7	8	9	10	
90 90 90 90 90 90 90 90 90 90 90 90 90 9	ears After Implant										
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	at 90 r	mo		
%	95.9	95.0	94.3	94.3	94.3	93.2	93.2	91.5			

194

LFG

124

66

47

US Returned Product Analysis

4194 Attain OTW

US Market Release

Product Characteristics

Serial Number Prefix

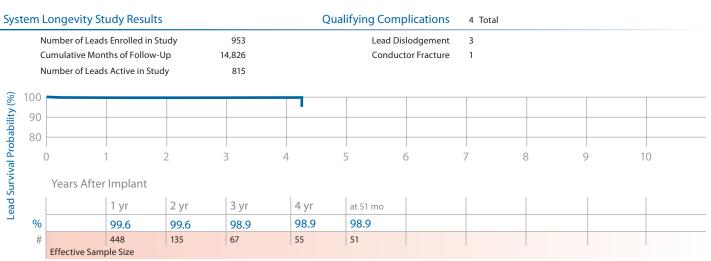
274

	Re	egistered US Im	plants	102,700	Type and	or Fixation		ous, Left Ver ein, Distal D	ntricular ouble Curve			ductor Fracti mp/Weld/Bo		10 0
	Es	stimated Active	US Implants	63,800	Polarity		Bipolar					sulation Brea		38
	A	dvisories		None	Steroid		Yes					Otl	her	6
Syster	n L	ongevity Stu	ıdy Results			Qual	ifying Comp	lications	23 Total					
	N	umber of Leads	Enrolled in Stu	dy 1,2	14		Lead Dislo	odgement	12		Extra (Cardiac Stimula	ation	3
	Cı	umulative Mont	hs of Follow-Uլ	p 28,0	24		Failure 1	to Capture	5					
	N	umber of Leads	Active in Study	/ 8-	48		Insula	ation (ESC)	1					
						Insul	ation (not furthe	er defined)	2					
@ 10	00						4							
i i 9	0													
abil	80													
rob														
A P	0)	2	2 3	4		5 6)	7	8	Š)	10	
Lead Survival Probability (%)		Years After	Implant											
s pa			1 yr	2 yr 3	3 yr	4 yr	5 yr							
۳	%		99.0	97.9	97.9	97.5	96.2							
	#		774	450 2	262	150	54							
		Effective Samp	le Size											

4195 Attain StarFix

Product Characteristics

US Market Release	Aug-08	Serial Number Prefix	AAD	US Returned Product Analysis
Registered US Implants	12,600	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Deployable Lobe Fixation	Conductor Fracture 1 Crimp/Weld/Bond 0
Estimated Active US Implants	10,300	Polarity	Unipolar	Insulation Breach 1
Advisories	None	Steroid	Yes	Other 7



4196 Attain Ability

	US Market Rele	ase	May-09	Serial Number P	refix P\	' I			US Returned Pr	oduct Ana	alvsis
	Registered US I	mplants	38,800	Type and/or Fixa		ansvenous, Left V eformed Body, Do		ac Vein,	Conductor Fracture Crimp/Weld/Bond		2
	Estimated Activ	e US Implants	33,100	Polarity	Bi	oolar			Insulation		0
	Advisories		None	Steroid	Ye	S				Other	1
Syste	m Longevity S	tudy Results			Qualifying (Complications	5 17 Total				
	Number of Lea	ds Enrolled in St	udy 1,859)	Le	ad Dislodgement	t 7				
	Cumulative Mo	nths of Follow-U	Jp 20,670)		Failure to Capture	4				
	Number of Leads Active in Study		ly 1,525	i	Extra Ca	ardiac Stimulation	n 6				
(% 1/	00										
ity (
abil	90										
rob	30										
valF	0	1	2 3	4	5	6	7	8	9	10	
Lead Survival Probability (%)	Years Afte	er Implant									
ead.		1 yr	2 yr								
	%	98.9	98.5								
	#	665	64								
	Effective San	nple Size									

0

Left-Heart Leads continued

4296 Attain Ability Plus

Product Characteristics

US Market Release	Apr-11	Serial Number Prefix	RRA	US Returned Product Analysis
Registered US Implants	3,700	Type and/or Fixation	Transvenous, Left Ventricular Cardiac Vein, Distal Double Curve	Conductor Fracture 0 Crimp/Weld/Bond 0
Estimated Active US Implants	3,500	Polarity	Bipolar	Insulation Breach 0
Advisories	None	Steroid	Yes	Other 0

System Longevity Study Results Qualifying Complications 0 Total Number of Leads Enrolled in Study 151 Lead Dislodgement Cumulative Months of Follow-Up 140 Conductor Fracture 0 Number of Leads Active in Study 148 Extra Cardiac Stimulation 0 Lead Survival Probability (%) 100 Survival estimate not available due to insufficient sample size 90 80 0 2 3 4 5 6 8 9 10 Years After Implant

4396 Attain Ability Straight

US Market Release

Registered US Implants

Product Characteristics

Serial Number Prefix

Type and/or Fixation

Mar-11

1,000

E	Estimated Active US	Implants	1,000	Polarity	В	polar			Insulati	on Breach
Α	Advisories		None	Steroid	Ye	25				Other
em l	Longevity Study	Results			Qualifying	Complication	S 0 Total			
N	Number of Leads Eni	olled in Study	5	4	L	ead Dislodgemer	nt 0			
C	Cumulative Months	of Follow-Up	32	1		Failure to Captui	re 0			
N	Number of Leads Act	ive in Study	5	3	Extra C	ardiac Stimulatio	on 0			
100 90	Survival estimate	e not available due	to insufficie	nt sample size						
80									_	10
	0 1	2	3	4	5	6	7	8	9	10
	0 1 Years After Im	plant	3	4	5	6	7	8	9	10

Transvenous, Left Ventricular Cardiac Vein,

US Returned Product Analysis

Conductor Fracture

Lead Survival Summary (95% Confidence Interval)

		se		Study		ths of udy	Device	Device Survival Probability (%)								
		t Relea	olled	ive in	g tions	/e Mor o in Stu	Years After Implant									
Model Number	Family	US Market Release	Leads Enrolled	Leads Active in Study	Qualifying Complications	Cumulative Months of Follow-Up in Study	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
2187	Attain LV	Aug-01	134	21	1	6,481	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1	99.1 +0.8/-5.1 at 54 mo					
2188	Attain CS	Aug-01	15	0	1	487	100.0 at 0 mo									
4193	Attain OTW	May-02	675	156	37	29,104	95.9 +1.3/-1.8	95.0 +1.4/-2.1	94.3 +1.6/-2.3	94.3 +1.6/-2.3	94.3 +1.6/-2.3	93.2 +2.0/-2.8	93.2 +2.0/-2.8	91.5 +3.2/-5.0 at 90 mo		
4194	Attain OTW	Aug-04	1,214	848	23	28,024	99.0 +0.4/-0.9	97.9 +0.8/-1.3	97.9 +0.8/-1.3	97.5 +1.0/-1.5	96.2 +2.0/-4.1					
4195	Attain StarFix	Aug-08	953	815	4	14,826	99.6 +0.3/-0.8	99.6 +0.3/-0.8	98.9 +0.8/-3.2	98.9 +0.8/-3.2	98.9 +0.8/-3.2 at 51 mo					
4196	Attain Ability	May-09	1,859	1,525	17	20,670	98.9 +0.4/-0.7	98.5 +0.7/-1.3								
4296	Attain Ability Plus	Apr-11	151	148	0	140	100.0 at 0 mo									
4396	Attain Ability Straight	Mar-11	54	53	0	321	100.0 at 0 mo									

Source: System Longevity Study Data as of January 31, 2012

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
2187	Attain LV	Aug-01	11,900	2,900	0	0	0	1
2188	Attain CS	Aug-01	1,800	300	1	0	0	0
4193	Attain OTW	May-02	100,600	37,900	47	0	5	8
4194	Attain OTW	Aug-04	102,700	63,800	10	0	38	6
4195	Attain StarFix	Aug-08	12,600	10,300	1	0	1	7
4196	Attain Ability	May-09	38,800	33,100	2	0	0	1
4296	Attain Ability Plus	Apr-11	3,700	3,500	0	0	0	0
4396	Attain Ability Straight	Mar-11	1,000	1,000	0	0	0	0

Source: Returned Product Analysis Data as of January 31, 2012

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture		Failure to Capture	Oversensing	Failure to Sense		Impedance Abnormal	Extracardiac Stimulation	Unspecified
2187	Attain LV	11,900	0	0	9	4	0	1	0	0	1	0
2188	Attain CS	1,800	0	0	2	0	0	0	0	0	0	0
4193	Attain OTW	100,600	0	0	45	11	1	0	0	0	15	2
4194	Attain OTW	102,700	1	2	92	21	1	0	1	6	25	3
4195	Attain StarFix	12,600	1	0	22	8	0	0	0	0	20	1
4196	Attain Ability	38,800	1	2	90	28	0	0	1	4	37	3
4296	Attain Ability Plus	3,700	0	0	9	2	0	0	0	0	2	0
4396	Attain Ability Straight	1,000	0	1	6	2	0	0	0	0	3	0

Report Cutoff Date: January 31, 2012

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
2187	Attain LV	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
2188	Attain CS	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 BI
4193	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)	MP35N	Platinized Platinum	IS-1 UNI
4194	Attain OTW	Transvenous Cardiac Vein Preformed Body	Polyurethane (55D)/ Silicone (4719)	MP35N	Platinum Alloy	IS-1 BI
4195	Attain StarFix	Transvenous Cardiac Vein Deployable Lobes	Polyurethane (55D)	MP35N	Platinum Alloy	IS-1 UNI
4196	Attain Ability	Transvenous Cardiac Vein Preformed Body	Polyurethane (outer) SI-polyimide (inner)	Ag-core- MP35N	Platinum iridium alloy with titanium nitride coating	IS-1 BI
4296	Attain Ability Plus	Transvenous Cardiac Vein Distal Double Curve	Polyurethane (outer) Silicone (inner)	Ag-core- MP35N	Platinum iridium alloy with titanium nitride coating	IS-1 BI
4396	Attain Ability Straight	Transvenous Cardiac Vein Tines	Polyurethane (outer) Silicone (inner)	Ag-core- MP35N	Platinum iridium alloy with titanium nitride coating	IS-1 BI

Defibrillation Leads

6721, 6921 Epricardial Patch

Product Characteristics

US Market Release	Feb-93	Serial Number Prefix	TBH, TBG, TBB, TAD, TAC, or TAB	US Returned Product Analy	ysis
Registered US Implants	8,700	Type and/or Fixation	Epicardial Defib Patch, Suture	Conductor Fracture	66
Estimated Active US Implants	1,400	Polarity	Defib Electrode only	Crimp/Weld/Bond	1
Advisories	None	Steroid	No	Insulation Breach	9
				Other	0

System Longevity Study Results

Qualifying Complications 47 Total

132

95

66

56

50

	Number of Leads Enrolled in Study Cumulative Months of Follow-Up Number of Leads Active in Study		407 23,303			ailure to Capture	8 21		Impedance Out of Range Oversensing		
Number			4		Insulation (not further defined)						
100											
90											
80											
70											
0	1	2	3	4	5	6	7	8	9	10	
Years	After Implant										
	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	at 111 mo	
%	96.5	95.0	92.7	91.9	90.0	85.1	83.7	83.7	83.7	83.7	

176

6930 Sprint Fidelis

330

Effective Sample Size

301

256

Lead Survival Probability (%)

Product Characteristics

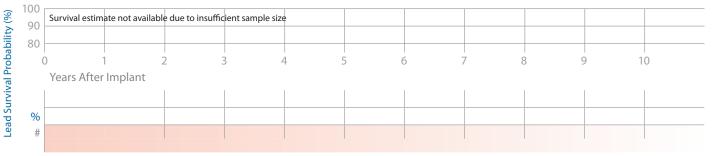
209

US Market Release	Sep-04	Serial Number Prefix	LFK	US Returned Product Analy	ysis
Registered US Implants	400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	3
Estimated Active US Implants	200	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond	0
Advisories:		Steroid	Yes	Insulation Breach	0
See page 153 – 2007 Potential Co	onductor			Other	0

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	4
Cumulative Months of Follow-Up	151
Number of Leads Active in Study	2



6931 Sprint Fidelis

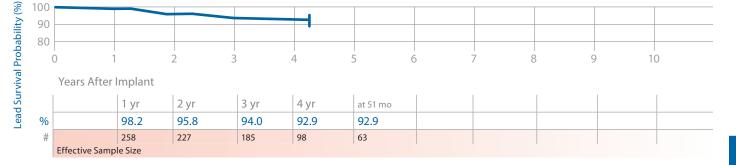
Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFL	US Returned Product Analysis
Registered US Implants	8,100	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture 450
Estimated Active US Implants	4,100	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond 0
Advisories		Steroid	Yes	Insulation Breach 0
See page 153 – 2007 Potential Co Wire Fracture	onductor			Other 5

System Longevity Study Results

Qualifying Complications 18 Total

Number of Leads Enrolled in Study	294	Lead Dislodgement	2	Impedance Out of Range	4
Cumulative Months of Follow-Up	11,469	Failure to Capture	3	Oversensing	3
Number of Leads Active in Study	159	Conductor Fracture	4	Other	1
		Failure to Sense	1		



6932 Sprint

Product Characteristics

US Market Release	Aug-96	Serial Number Prefix	TCA	US Returned Product Analysis
Registered US Implants	14,900	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture 20
Estimated Active US Implants	4,500	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 23
				Other 3

System Longevity Study Results

Qualifying Complications

Number of Leads Enrolled in Study	411	Failure to Capture	2	Extra Cardiac Stimulation	1
Cumulative Months of Follow-Up	24,784	Failure to Sense	2	Oversensing	4
Number of Leads Active in Study	51	Impedance Out of Range	1		



6933, 6937, 6937A, 6963 SVC/CS **Product Characteristics**

US Market Release	Dec-93	Serial Number Prefix	x TAT, TBU, TDB, TAF		US Returned Product Ana	alysis
Registered US Implants	16,200	Type and/or Fixation	n Transvenous CS or SVC	Defib	Conductor Fracture	167
Estimated Active US Implants	2,600	Polarity	One Coil		Crimp/Weld/Bond	0
Advisories	None	Steroid	No		Insulation Breach	32
					Other	3
tem Longevity Study Results		(Qualifying Complications	47 Total		
Number of Leads Enrolled in Study	9	66	Lead Dislodgement	1	Impedance Out of Range	3
Cumulative Months of Follow-Up	54,3	59	Failure to Capture	6	Unspecified Clinical Failure	4
Number of Leads Active in Study		19	Conductor Fracture	16	Extra Cardiac Stimulation	4
			Failure to Sense	1	Oversensing	10
			Insulation (not further defined)	2		



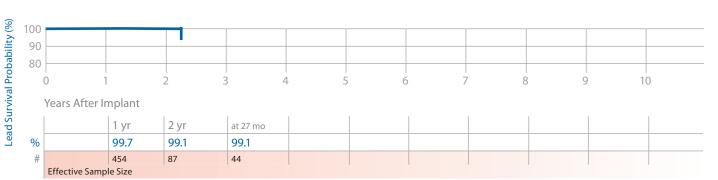


6935 Sprint Quattro Secure **Product Characteristics**

US Market Release	Nov-08	Serial Number Prefix	TAU	US Returned Product Analysis
Registered US Implants	28,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture 22
Estimated Active US Implants	26,400	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 0
Performance Note: See page 160 Helix Retraction of the Sprint Qua and Sprint Quattro Secure 6947		35		Other 6

System Longevity Study Results

Qualifying Complications 4 Total Number of Leads Enrolled in Study 1,329 Conductor Fracture Cumulative Months of Follow-Up 13,473 Failure to Sense 1 Number of Leads Active in Study 1,191 Oversensing 2



6936, 6966 Transvene

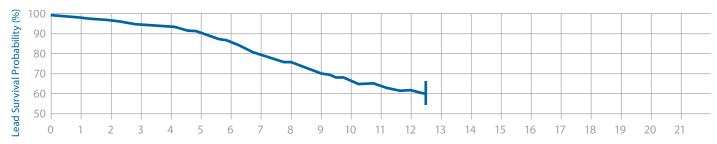
Product Characteristics

US Market Release	Dec-93	Serial Number Prefix	TAV, TAL	US Returned Product An	alysis
Registered US Implants	23,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	176
Estimated Active US Implants	2,400	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	342
				Other	7

System Longevity Study Results

Qualifying Complications 187 Total

Number of Leads Enrolled in Study	1,349	Failure to Capture	15	Impedance Out of Range	7
Cumulative Months of Follow-Up	75,072	Conductor Fracture	21	Unspecified Clinical Failure	5
Number of Leads Active in Study	19	Failure to Sense	7	Extra Cardiac Stimulation	6
		Insulation (not further defined)	14	Oversensing	112



Years After Implant

		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	at 150 mo				
%		98.2	97.0	95.2	94.3	91.1	86.8	79.8	75.9	70.2	65.8	63.6	61.8	59.5				
#		1,140	956	807	659	530	414	284	210	142	104	75	56	49				
	Effectiv	ve Sami	محنک ماد															

6939, 6999 Sub-Q Patch

Product Characteristics

US Market Release	Dec-93	Serial Number Prefix	TBA, TAP	US Returned Product Ana	ılysis
Registered US Implants	3,700	Type and/or Fixation	Subcutaneous Defib Patch, Suture	Conductor Fracture	28
Estimated Active US Implants	300	Polarity	Defib Electrode Only	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	4
				Other	1

System Longevity Study Results

Lead Survival Probability (%)

Qualifying Complications 41 Total

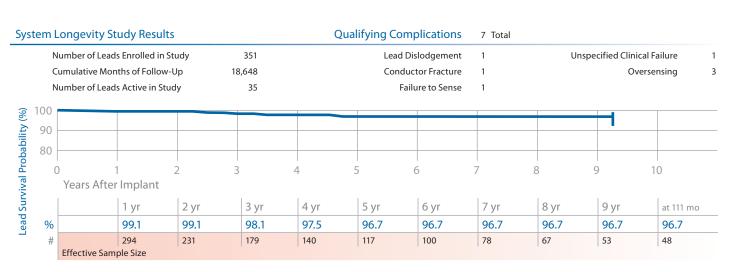
1	Number of Lead	ls Enrolled in	Study	384			Failure to Captui	re 8	Impedance Out of Ra		Out of Range	1
(Cumulative Mor	nths of Follov	w-Up	20,555		C	onductor Fractui	re 10		Unspecified C	linical Failure	2
ı	Number of Lead	ls Active in S	tudy	1			Failure to Sens	se 1		Extra Cardia	c Stimulation	4
						Insulation (no	ot further defined	d) 6			Oversensing	9
100		1										
90												
80												
	0	1	2	3	4	5	6	7	8	9	10	
	Years After	Implant										
	I.	ı	1	1	1	1	1	1	1	ı	ı	

,			_			_	,			10
	Years After I	mplant								
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 99 mo
%		96.0	94.1	93.7	93.7	91.5	89.2	86.7	85.2	85.2
#		312	273	232	188	154	115	78	54	51
	Effective Samp	ole Size								

6942 Sprint

Product Characteristics

US Market Release	Jul-97	Serial Number Prefix	ТСВ	US Returned Product An	alysis
Registered US Implants	17,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	14
Estimated Active US Implants	5,700	Polarity	Integrated Bipolar/Two Coils	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	21
				Other	2



6943 Sprint

Product Characteristics

1,311

US Market Release	Oct-97	Serial Number Prefix	TCE	US Returned Product Analy	ysis
Registered US Implants	20,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	64
Estimated Active US Implants	6,700	Polarity	True Bipolar/One Coil	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	27
				Other	3

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 82 Total Lead Dislodgement

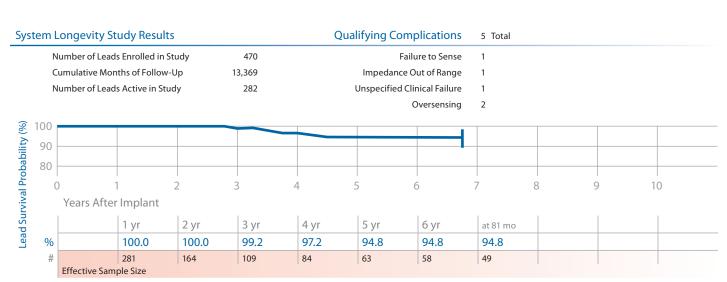
	C	umulati	ve Mon	ths of F	ollow-U	р	78	8,866					Failure to C	aptu	re 8	3			Impe	dance O	ut of Ra	nge	8
	N	umber (of Leads	s Active	in Stud	y		252					Conductor F	ractu	re 17	7		ı	Jnspec	ified Clir	nical Fail	ure	3
													Failure to	Sens	se 6	5				C	versens	ing	37
																					Ot	her	1
(%)	100																						
Probability	90						~							_									
oabi	80																						
rok	00) 1	-) 3	3 /	L G	5 6	5 -	7 8	3) 1(n 1	1 12	13	14	15	16	17	18	3 19	20	21	
		, 1			, –	Γ ~		, ,		, ,	, 1,	0 1	1 12	13	17	13	10	17	10) 12	20	۷.	
Ξ		Years	After	Impla	nt																		
d St																							
Lead Survival			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 126 mo										
	%		98.6	97.7	96.5	95.6	93.7	92.4	91.5	91.0			88.0										
	#		1,146		874	745	620	491	359	259	160	76	56										
	π	Effectiv			0, 1	, 13	020	121	333	233	100	, 0	30										I

Insulation (not further defined)

6944 Sprint Quattro

Product Characteristics

US Market Release	Dec-00	Serial Number Prefix	TDC	US Returned Product An	alysis
Registered US Implants	39,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	80
Estimated Active US Implants	21,300	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	2
				Other	1



6945 Sprint

Product Characteristics

US Market Release	Sep-97	Serial Number Prefix	TDA	US Returned Product Ana	alysis
Registered US Implants	42,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	114
Estimated Active US Implants	13,600	Polarity	Integrated Bipolar/Two Coils	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	32
				Other	6

System Longevity Study Results

Qualifying Complications 37 Total

Number of Leads Enrolled in Study	1,154	Failure to Capture	2	Unspecified Clinical Failure	1
Cumulative Months of Follow-Up	65,925	Conductor Fracture	7	Extra Cardiac Stimulation	1
Number of Leads Active in Study	139	Failure to Sense	4	Oversensing	17
		Impedance Out of Range	5		



6947 Sprint Quattro Secure

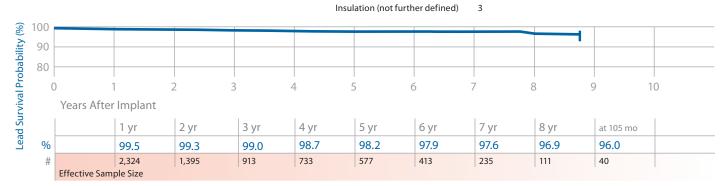
Product Characteristics

US Market Release	Nov-01	Serial Number Prefix	TDG	US Returned Product Analysis
Registered US Implants	340,700	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture 328
Estimated Active US Implants	236,900	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond 4
Advisories	None	Steroid	Yes	Insulation Breach 21
Performance Note: See page 160 Helix Retraction of the Sprint Qua and Sprint Quattro Secure 6947		935		Other 58

System Longevity Study Results

Qualifying Complications 31 Total

6	Impedance Out of Range	3	Lead Dislodgement	2,708	Number of Leads Enrolled in Study
2	Unspecified Clinical Failure	1	Failure to Capture	100,486	Cumulative Months of Follow-Up
10	Oversensing	4	Conductor Fracture	1,406	Number of Leads Active in Study
		2	Failure to Sense		



6948 Sprint Fidelis

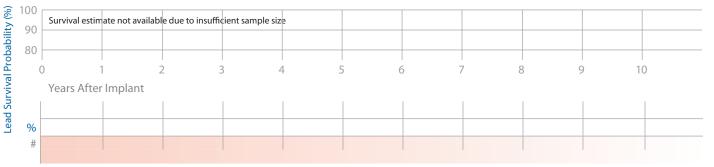
Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFH	US Returned Product Ana	alysis
Registered US Implants	10,400	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Tines	Conductor Fracture	120
Estimated Active US Implants	5,500	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond	0
Advisories		Steroid	Yes	Insulation Breach	1
See page 153 – 2007 Potential Cor Wire Fracture	nductor			Other	0

System Longevity Study Results

Qualifying Complications 0 Total

Number of Leads Enrolled in Study	30
Cumulative Months of Follow-Up	1,253
Number of Leads Active in Study	19



6949 Sprint Fidelis

Product Characteristics

US Market Release	Sep-04	Serial Number Prefix	LFJ	US Returned Product Ar	nalysis
Registered US Implants	186,600	Type and/or Fixation	Transvenous, Vent, Defib and Pace/Sense, Screw-in	Conductor Fracture	5,244
Estimated Active US Implants	90,600	Polarity	True Bipolar/Two Coils	Crimp/Weld/Bond	2
Advisories		Steroid	Yes	Insulation Breach	12
See page 153 – 2007 Potential Co Wire Fracture	onductor			Other	60

System Longevity Study Results

Qualifying Complications 54 Total

1	Insulation (not further defined)	1	Lead Dislodgement	794	Number of Leads Enrolled in Study
10	Impedance Out of Range	2	Failure to Capture	33,520	Cumulative Months of Follow-Up
1	Unspecified Clinical Failure	22	Conductor Fracture	364	Number of Leads Active in Study
14	Oversensing	2	Failure to Sense		
1	Other				



6996 Sub-Q Lead

Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	TCR	US Returned Product Ana	lysis
Registered US Implants	3,400	Type and/or Fixation	Subcutaneous Defib Coil, Suture	Conductor Fracture	15
Estimated Active US Implants	2,000	Polarity	One Defib Coil	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	0
				Other	0

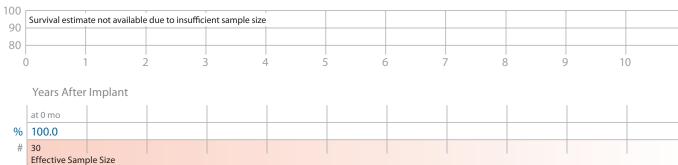
System Longevity Study Results

Lead Survival Probability (%)

Qualifying Complications 1 Total

Number of Leads Enrolled in Study	32	Conductor Fracture	
Cumulative Months of Follow-Up	864		





		seəle	рə	nt2 ni		ıt2 ni o	Device 5	urvival	Device Survival Probability (%)	ty (%)									
		ket Ro	nroll		icatioi	dN-wo	Years Af	Years After Implant	ant										
	Family	ns Mar	l eads I	Leads /	ıldwoɔ	Slumul Ollo Tollo	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	10 yr	12 yr	14 yr	16 yr	18 yr
6721, Ep 6921	Epicardial Patch	Feb-93	407	4	47 2	23,303	96.5	95.0	92.7 +2.3/-3.4	91.9	90.0	85.1 +3.9/-5.2	83.7 +4.2/-5.6	83.7 +4.2/-5.6	83.7 +4.2/-5.6 at 111 mo				
6930 Sp	Sprint Fidelis	Sep-04	4	2	0	151	100.0 at 0 mo												
Ad	Advisories: <u>See page 153</u> – 2007 Potential Conductor Wire Fracture	2007 Potential	l Conducto	r Wire Fract	ure														
6931 Sp	Sprint Fidelis	Sep-04	294	159	18 1	11,469	98.2	95.8 +1.9/-3.2	94.0 +2.3/-3.9	92.9 +2.6/-4.2	92.9 +2.6/-4.2								
Ad	Advisories: <u>See page 153</u> – 2007 Potential Conductor Wire Fracture	2007 Potential	l Conducto	r Wire Fract	ure						at 51 mo								
6932 Sp	Sprint	Aug-96	411	51	10 2	24,784	99.2	98.3 +0.9/-2.0	98.3 +0.9/-2.0	98.3 +0.9/-2.0	97.8 +1.2/-2.6	97.8 +1.2/-2.6	97.8 +1.2/-2.6	96.8 +1.8/-3.8	96.8	95.1 +2.8/-6.4 at 129 mo			
6933, SV 6937, 6937A, 6963	SVC/CS	Dec-93	996	19	47 5	54,359	98.4 +0.7/-1.0	97.5 +0.9/-1.3	97.2 +0.9/-1.4	96.7	95.4	94.9	93.9	93.4 +1.9/-2.7	91.2	91.2 +2.8/-4.2 at 138 mo			
6935 Sp	Sprint Quattro Secure Nov-08 1,329 1,191 4 See page 160 – Performance note on Helix Retraction 6935 and 6947	Nov-08 se note on Heli	1,329 ix Retractio	1,191 on 6935 and		13,473	99.7	99.1 +0.6/-1.9	99.1 +0.6/-1.9 at 27 mo										
6936, Tra	Transvene	Dec-93	1,349	19	187 7	75,072	98.2 +0.6/-1.0	97.0 +0.8/-1.2	95.2	94.3 +1.3/-1.6	91.1	86.8 +2.3/-2.8	79.8 +3.1/-3.6	75.9 +3.5/-4.0	65.8 +4.9/-5.5	61.8 +5.6/-6.2	59.5 +6.2/-6.8 at 150 mo		
6939, Su 6999	Sub-Q Patch	Dec-93	384	-	41 2	20,555	96.0	94.1 +2.0/-3.1	93.7 +2.2/-3.2	93.7 +2.2/-3.2	91.5	89.2 +3.3/-4.8	86.7 +4.0/-5.6	85.2 +4.6/-6.4	85.2 +4.6/-6.4 at 99 mo				
6942 Sp	Sprint	Jul-97	351	35	7 1	18,648	99.1	99.1	98.1 +1.1/-2.7	97.5	96.7	96.7	96.7 +1.8/-3.7	96.7	96.7 +1.8/-3.7 at 111 mo				
6943 Sp	Sprint	Oct-97	1,311	252	82 7	78,866	98.6	97.7 +0.7/-1.1	96.5 +1.0/-1.2	95.6	93.7	92.4	91.5	91.2	88.0	88.0 +3.0/-3.8 at 126 mo			
6944 Sp	Sprint Quattro	Dec-00	470	282	5	13,369	100.0	100.0	99.2 +0.7/-5.1	97.2 +1.9/-5.7	94.8 +3.0/-7.0	94.8 +3.0/-7.0	94.8 +3.0/-7.0 at 81 mo						
6945 Sp	Sprint	Sep-97	1,154	139	37 6	65,925	99.4	98.7 +0.5/-1	98.2 +0.7/-1.1	97.6 +0.8/-1.3	96.8 +1.1/-1.6	96.1	95.6 +1.4/-2.0	94.5	93.1 +2.1/-3.1	93.1 +2.1/-3.1 at 129 mo			
6947 Sp	Sprint Quattro Secure Nov-01 2,708 1,406 31 See page 160 - Performance note on Helix Retraction 6935 and 6947	Nov-01	2,708 ix Retractic	1,406 on 6935 and	_	00,486	99.5	99.3	99.0	98.7	98.2 +0.7/-1.0	97.9	97.6 +0.9/-1.4	96.9	96.0 +1.8/-3.3 at 105 mo				
6948 Sp	Sprint Fidelis	Sep-04	30	19	0	1,253	100.0 at 0 mo												
Ad	Advisories: See page 153 – 2007 Potential Conductor Wire Fracture	2007 Potential	l Conducto	r Wire Fract	ure														
6949 Sp	Sprint Fidelis Sep-04 794 364 54 Advisories: See page 153 – 2007 Potential Conductor Wire Fracture	Sep-04 2007 Potential	794	364 or Wire Fract		33,520	98.7 +0.6/-1.2	96.9 +1.1/-1.5	94.6	92.7	90.7	88.6 +3.3/-4.5 at 69 mo							
ns 9669	Sub-Q Lead	Jun-01	32	17	-	864	100.0 at 0 mo												

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
6721, 6921	Epicardial Patch	Feb-93	8,700	1,400	66	1	9	0
6930	Sprint Fidelis	Sep-04	400	200	3	0	0	0
6931	Sprint Fidelis	Sep-04	8,100	4,100	450	0	0	5
6932	Sprint	Aug-96	14,900	4,500	20	0	23	3
6933, 6937, 6937A, 6963	SVC/CS	Dec-93	16,200	2,600	167	0	32	3
6935	Sprint Quattro Secure	Nov-08	28,700	26,400	22	0	0	6
6936, 6966	Transvene	Dec-93	23,600	2,400	176	0	342	7
6939, 6999	Sub-Q Patch	Dec-93	3,700	300	28	0	4	1
6942	Sprint	Jul-97	17,700	5,700	14	1	21	2
6943	Sprint	Oct-97	20,700	6,700	64	1	27	3
6944	Sprint Quattro	Dec-00	39,700	21,300	80	1	2	1
6945	Sprint	Sep-97	42,600	13,600	114	1	32	6
6947	Sprint Quattro Secure	Nov-01	340,700	236,900	328	4	21	58
6948	Sprint Fidelis	Sep-04	10,400	5,500	120	0	1	0
6949	Sprint Fidelis	Sep-04	186,600	90,600	5,244	2	12	60
6996	Sub-Q Lead	Jun-01	3,400	2,000	15	0	0	0

Source: Returned Product Analysis Data as of January 31, 2012

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense	Insulation Breach		Extracardiac Stimulation	Unspecified
6721, 6921	Epicardial Patch	8,700	1	1	0	0	1	0	2	5	0	6
6930	Sprint Fidelis	400	0	0	0	0	0	0	0	0	0	1
6931	Sprint Fidelis	8,100	1	2	1	1	3	1	0	0	0	0
6932	Sprint	14,900	0	0	4	2	0	2	0	1	0	2
6933, 6937, 6937A, 6963	SVC/CS	16,200	0	0	1	2	1	0	1	0	0	5
6935	Sprint Quattro Secure	28,700	6	3	19	14	19	5	1	13	1	1
6936, 6966	Transvene	23,600	5	2	1	5	3	4	1	1	0	4
6939, 6999	Sub-Q Patch	3,700	0	0	0	0	0	0	0	0	0	1
6942	Sprint	17,700	0	1	1	4	1	0	0	3	0	2
6943	Sprint	20,700	1	0	0	1	1	1	1	2	0	0
6944	Sprint Quattro	39,700	0	3	12	11	12	3	0	6	0	6
6945	Sprint	42,600	0	1	4	7	9	1	2	1	1	1
6947	Sprint Quattro Secure	340,700	22	19	92	64	101	22	4	56	2	17
6948	Sprint Fidelis	10,400	0	1	7	7	2	0	0	0	0	2
6949	Sprint Fidelis	186,600	9	39	22	30	30	22	6	17	0	19
6996	SubQ	3,400	0	0	1	0	1	0	0	2	0	0

Report Cutoff Date: January 31, 2012

Reference Chart

			Pin Configuration		_			
Model Number	Family	Туре	Pace/Sense	High Voltage	Lead Body Diameter	Insulation, Lead Body	Fixation, Steroid	
6721	Epicardial Patch	Epi Patch	_	DF-1	S, M, L	Silicone, Single Lumen	Suture	
6921	Epicardial Patch	Epi Patch	_	6.5 mm	S, M, L	Silicone, Single Lumen	Suture	
6930	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid	
6931	Sprint Fidelis	Endo RV True Bipolar Sensing	IS-1	DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid	
6932	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid	
6933	SVC/CS	Endo SVC/CS Coil	_	DF-1	7 Fr	Silicone, Single Lumen	Passive	
6934S	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	12 Fr	Silicone, Coaxial	Passive, Steroid	
6935	Sprint Quattro Secure	Endo RV True Bipolar Sensing	IS-1	DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid	
6936	Transvene	Endo RV True Bipolar Sensing	IS-1	DF-1	10 Fr	Polyurethane, Coaxial	Active	
6937	SVC/CS	Endo SVC Coil	_	DF-1	5.5 Fr	Silicone, Single Lumen	Passive	
6937A	SVC/CS	Endo SVC Coil	_	DF-1	7.5 Fr	Silicone with Polyurethane Overlay, Single Lumen	Passive	
6939	Sub-Q Patch	SQ Patch	_	DF-1	One Size	Silicone, Single Lumen	Suture	
6942	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Passive, Steroid	
6943	Sprint	Endo RV True Bipolar Sensing	IS-1	DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid	
6944	Sprint Quattro	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid	
6945	Sprint	Endo RV/SVC Integrated Bipolar Sensing	IS-1	2 DF-1	7.8 Fr	Silicone, Multilumen	Active, Steroid	
6947	Sprint Quattro Secure	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	8.2 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid	
6948	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Passive, Steroid	
6949	Sprint Fidelis	Endo RV/SVC True Bipolar Sensing	IS-1	2 DF-1	6.6 Fr	Silicone with Polyurethane Overlay, Multilumen	Active, Steroid	
6963	SVC/CS	Endo SVC/CS Coil	_	6.5 mm	7 Fr	Silicone, Single Lumen	Passive	
6966	Transvene	Endo RV True Bipolar Sensing	3.2 mm L.P.	6.5 mm	10 Fr	Polyurethane, Coaxial	Active	
6996	Sub-Q Lead	SQ Coil	_	DF-1	7.5 Fr	Silicone, Single Lumen	Passive	
6999	Sub-Q Patch	SQ Patch	_	6.5 mm	One Size	Silicone, Single Lumen	Suture	

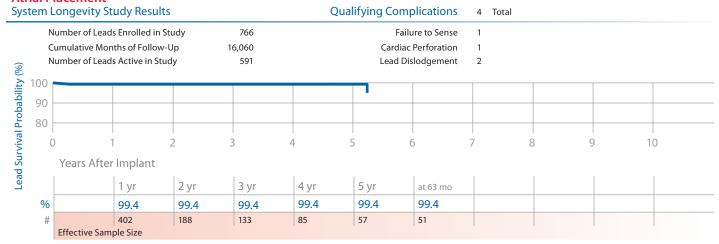
Pacing Leads

3830 SelectSecure

Product Characteristics

US Market Release	Aug-05	Serial Number Prefix	LFF	US Returned Product Ana	lysis
Registered US Implants	20,800	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	3
Estimated Active US Implants	16,500	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	10
				Other	3

Atrial Placement

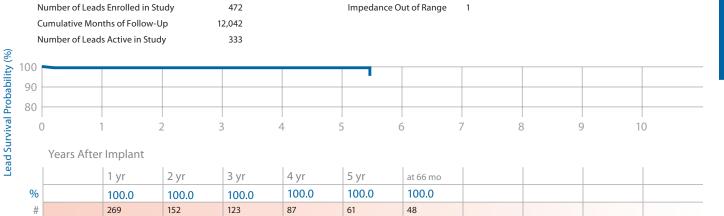


Ventricular Placement

System Longevity Study Results

Effective Sample Size





4023 CapSure SP

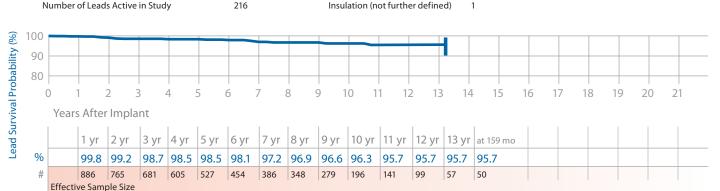
Product Characteristics

US Market Release	Aug-91	Serial Number Prefix	LAK	US Returned Product Analy	/sis
Registered US Implants	41,100	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	14
Estimated Active US Implants	7,700	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	4
				Other	2

System Longevity Study Results

Qualifying Complications 22 Total

Number of Leads Enrolled in Study	1,158	Lead Dislodgment	2	Impedance Out of Range	2
Cumulative Months of Follow-Up	73,316	Failure to Capture	16	Extra Cardiac Stimulation	1
Number of Leads Active in Study	216	Insulation (not further defined)	1		



4024 CapSure SP

Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAJ	US Returned Product Ana	lysis
Registered US Implants	221,300	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	29
Estimated Active US Implants	43,800	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	159
				Other	8

System Longevity Study Results

Qualifying Complications 4 Total

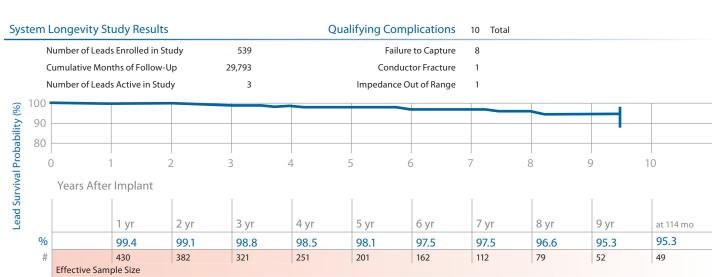
Number of Leads Enrolled in Study	1,215	Failure to Capture	3
Cumulative Months of Follow-Up	50,855	Insulation (not further defined)	1
Number of Leads Active in Study	17		



4033 CapSure Z

Product Characteristics

US Market Release	Not US released	Serial Number Prefix	LCA	US Returned Product Analys	sis
Registered US Implants	NA	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	0
Estimated Active US Implants	NA	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	0
				Other	0



4067 CapSureFix

100

90

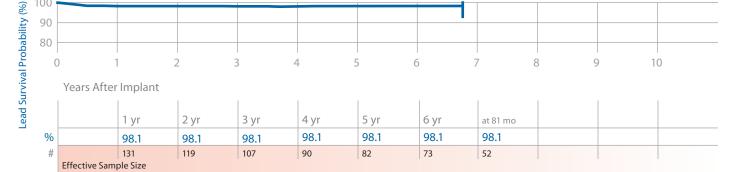
Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LCV	US Returned Product Analys	sis
Registered US Implants	1,000	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	1
Estimated Active US Implants	200	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	0
				Other	0



Qualifying Complications 8 Total

Number of Leads Enrolled in Study	171	Failure to Capture	6
Cumulative Months of Follow-Up	11,097	Impedance Out of Range	1
Number of Leads Active in Study	44	Oversensing	1



4068 CapSureFix

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCE	US Returned Product An	alysis
Registered US Implants	124,300	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	44
Estimated Active US Implants	32,200	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	147
				Other	5

Atrial Placement

System Longevity Study Results

Qualifying Complications 69 Total

2	Insulation (ESC)	8	Lead Dislodgement	2,413	Number of Leads Enrolled in Study
2	Insulation (MIO)	22	Failure to Capture	131,591	Cumulative Months of Follow-Up
7	Impedance Out of Range	2	Conductor Fracture	301	Number of Leads Active in Study
3	Unspecified Clinical Failure	11	Failure to Sense		
2	Extra Cardiac Stimulation	2	Insulation (not further defined)		
0	0				





Years After Implant

		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	at 159 mo				
%		98.9	98.7	98.2	98.0	97.4	97.2	96.9	95.6	95.1	94.1	93.2	92.0	91.1	91.1				
#		1,907	1,637	1,370	1,116	897	734	567	450	324	235	174	120	68	52				
	Effecti	ve Samı	ole Size																

Ventricular Placement

System Longevity Study Results

Effective Sample Size

Qualifying Complications 44 Total

C	Number of Leads Enrolled in Study Cumulative Months of Follow-Up Number of Leads Active in Study				1,799 94,169 208			lacul.		Conduct Failu	to Capture for Fracture re to Sense er defined)	21 3 3			Ur	nspecifi	nce Out ed Clinio rdiac St	cal Failu imulati	ire on			
100 90 80)	1	2	3	4	5	6	7	8		0 1	1 1	2 13	14	15	16	17	18	19	ersensi	21	
%		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr		at 138 mo	··-								
90 #		99.3	98.7	98.7	98.2	97.8	97.3	394	95.5	94.2	114	94.2	52									

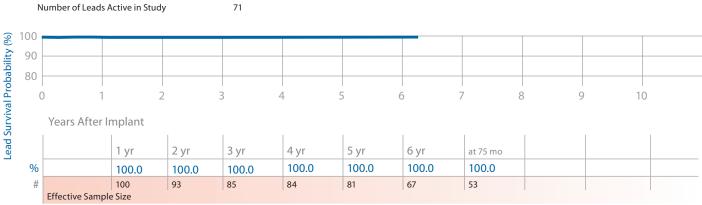
4073 CapSure Sense

Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBF	US Returned Product Analysis
Registered US Implants	700	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 0
Estimated Active US Implants	300	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 0
				Other 0

0 Total

Qualifying Complications System Longevity Study Results 102 Number of Leads Enrolled in Study Cumulative Months of Follow-Up 7,095



4074 CapSure Sense

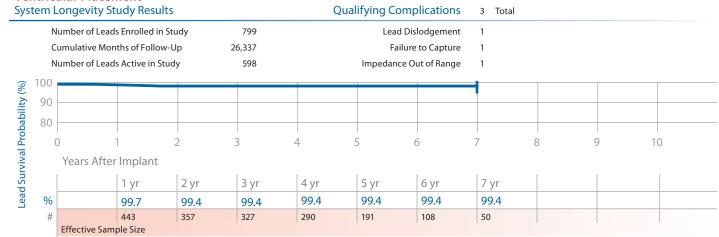
Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBD	US Returned Product Analysis
Registered US Implants	85,400	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 1
Estimated Active US Implants	53,700	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 16
				Other 1

Atrial Placement

	Longevity S	,			Qualifying Complications								
N	Number of Lead	ls Enrolled in	Study	215		Lead	l Dislodgement	1					
C	Cumulative Mo	nths of Follow	/-Up	13,875			Failure to Sense	1	1				
N	Number of Lead	ls Active in St	udy	151									
100								-					
90								•					
80													
(0	1	2	3	4	5	6	7	8	9	10		
	Years Afte	r Implant	_	3		3		,			10		
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr					
%		99.1	99.1	99.1	99.1	99.1	99.1	99.1					
#		199	189	183	169	126	86	54					

Ventricular Placement



4076 CapSureFix Novus

Product Characteristics

US Market Release Feb-04		Serial Number Prefix	BBL	US Returned Product Ana	lysis
Registered US Implants	376,400	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	22
Estimated Active US Implan	ts 289,700	Polarity	Bipolar	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	21
				Other	16

Atrial Placement

System	Longevity St	udy Results			Qı	ualifying Co	mplications	6 Total				
	Number of Lead	s Enrolled in St	udy	1,657		Lead	Dislodgement	3				
	Cumulative Mon	ths of Follow-U	Jр	48,631	Failure to Capture			1				
	Number of Lead	s Active in Stuc	ły	1,190 Failure to Sense				1				
					In	sulation (not fu	irther defined)	1				
<u>ş</u> 100)											
90)											
80)											
	0	1	2	3	4	5	6	7	8	9	10	
\ \ \	Years After	· Implant	_									
N N		1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo					
Lead Survival Probability (%) 80 80 80		99.8	99.6	99.6	99.6	99.6	99.6					
<u>"</u>		1,415	775	448	249	110	49					
	Effective Sam	ple Size						,	,		,	

Ventricular Placement

/sten	n Long	jevity Stu	udy Results			Q	ualifying Co	mplications	3 1	otal				
	Numb	er of Leads	Enrolled in Stu	ıdy	1,227		Fail	ure to Capture	2					
	Cumul	ative Mont	hs of Follow-U	lp	40,162		Extra Cardiac Stimulation			1				
	Number of Leads Active in Study			848	848									
10	00							1						
	90 -													
8	30													
	0		1	7	3	4	5	6	7	8	 }	9	10	
		ars After	Implant	_	3		3		,		,			
			1 yr	2 yr	3 yr	4 yr	5 yr	at 69 mo						
(%		99.8	99.8	99.8	99.8	99.5	99.5						
	#		1,055	637	429	286	139	58						
	Effe	ctive Samp	ole Size											

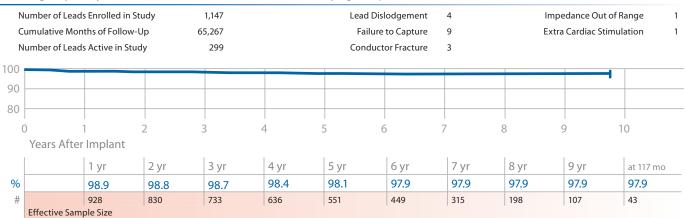
4092 CapSure SP Novus

Product Characteristics

US Market Release Sep-98		Serial Number Prefix	LEP	US Returned Product Ana	llysis
Registered US Implants	172,100	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	7
Estimated Active US Implants	80,000	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	35
				Other	2

System Longevity Study Results

Qualifying Complications 18 Total



4523 CapSure SP

Lead Survival Probability (%)

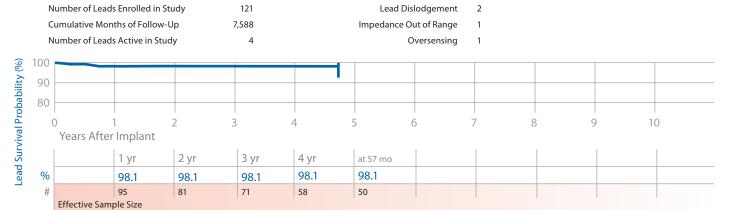
Product Characteristics

US Market Release	Aug-91	Serial Number Prefix	ZE	US Returned Product Analys	is
Registered US Implants	11,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	1
Estimated Active US Implants	2,500	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	2
				Other	1

System Longevity Study Results

Qualifying Complications 4

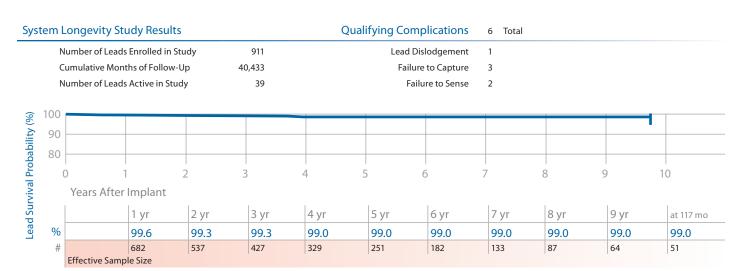
Total



4524 CapSure SP

Product Characteristics

US Market Release	Oct-91	Serial Number Prefix	LAR	US Returned Product An	alysis
Registered US Implants	101,300	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	1
Estimated Active US Implants	25,100	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	53
				Other	3



4533 CapSure Z

Product Characteristics

206

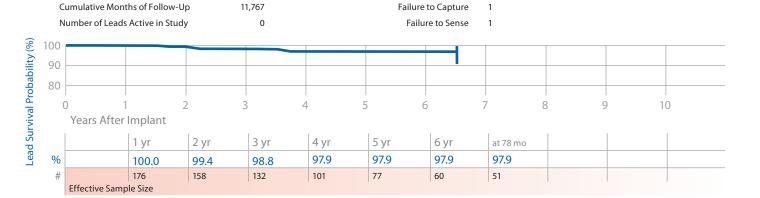
US Market Release	Not US released	Serial Number Prefix	LCB	US Returned Product Analys	is
Registered US Implants	NA	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	0
Estimated Active US Implants	NA	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	0
				Other	0

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 4 Total Lead Dislodgement

1



Oversensing

4558M Screw-In

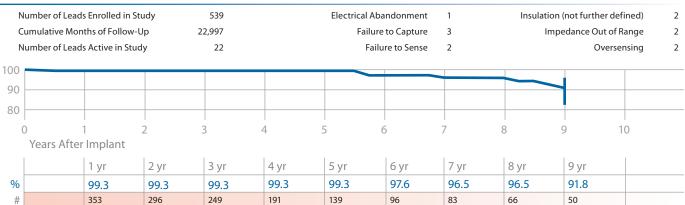
Product Characteristics

US Market Release	elease Nov-94		LDC	US Returned Product Analysis	
Registered US Implants 19,900		Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Conductor Fracture	1
Estimated Active US Implants	4,100	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories No		Steroid	No	Insulation Breach 18	8
				Other (0



Effective Sample Size

Qualifying Complications 12 Total



4568 CapSureFix

Lead Survival Probability (%)

Product Characteristics

656

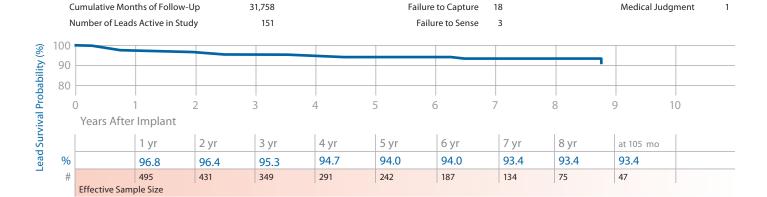
US Market Release	Jan-97	Serial Number Prefix	LDD	US Returned Product Analy	/sis
Registered US Implants	69,500	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Conductor Fracture	3
Estimated Active US Implants	23,200	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	57
				Other	1

System Longevity Study Results

Number of Leads Enrolled in Study

Qualifying Complications 33 Total Lead Dislodgement

9



Impedance Out of Range

2

4574 CapSure Sense

Product Characteristics

US Market Release	Jun-02	Serial Number Prefix	BBE	US Returned Product Analysis
Registered US Implants	56,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 5
Estimated Active US Implants	38,200	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 3
				Other 0

System Longevity Study Results

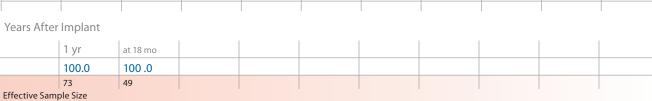
Qualifying Complications 0 Total

319 Number of Leads Enrolled in Study Cumulative Months of Follow-Up 3,076 271 Number of Leads Active in Study



100

Lead Survival Probability (%)



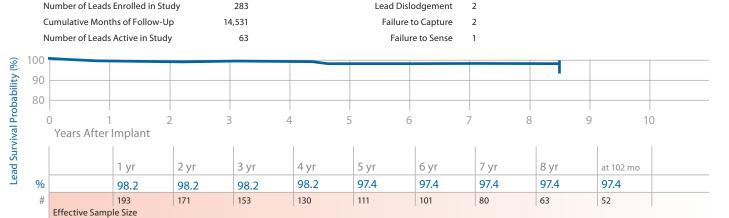
4592 CapSure SP Novus

Product Characteristics

US Market Release	Oct-98	Serial Number Prefix	LER	US Returned Product Ana	lysis
Registered US Implants	83,500	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	6
Estimated Active US Implants	41,100	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	12
				Other	1

System Longevity Study Results

Qualifying Complications 5 Total



5023, 5023M CapSure SP

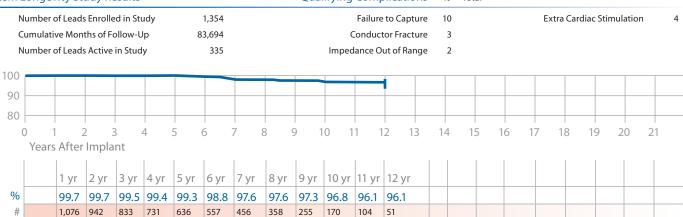
Product Characteristics

US Market Release		Nov-88	Serial Number Prefix	SX or LAS	US Returned Product Analy	/sis
Registered US Impl	lants	9,800	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	5
Estimated Active U	IS Implants	2,200	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories		None	Steroid	Yes	Insulation Breach	0
					Other	0



Lead Survival Probability (%)

Qualifying Complications Total 19



5024, 5024M CapSure SP

Effective Sample Size

Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	SY or LAT	US Returned Product Analysis
Registered US Implants	200,700	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 51
Estimated Active US Implants	44,700	00 Polarity Bipolar		Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 50
				Other 9

System Longevity Study Results

Qualifying Complications 56 Total

Number of Leads Enrolled in Study	8,153	Lead Dislodgement	6	Impedance Out of Range	3
Cumulative Months of Follow-Up	441,672	Failure to Capture	27	Unspecified Clinical Failure	1
Number of Leads Active in Study	321	Conductor Fracture	3	Extra Cardiac Stimulation	2
		Failure to Sense	2	Oversensing	4
		Insulation (not further defined)	5	Other	2
		Insulation (ESC)	1		

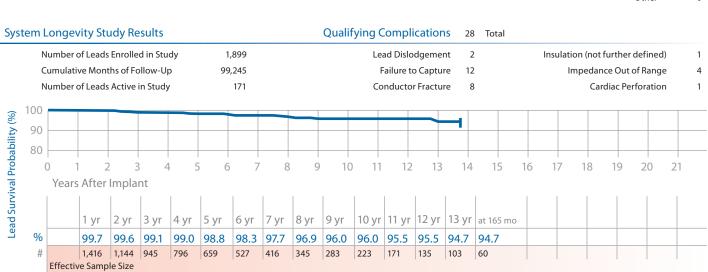


		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	11 yr	12 yr	13 yr	14 yr	15 yr	16 yr	at 201 mo		
%		99.6	99.6	99.5	99.4	99.3	99.3	99.1	99.0	98.9	98.8	98.5	98.5	98.3	98.3	97.3	97.3	97.3		
#		6,128	5,277	4,477	3,747	3,113	2,460	1,926	1,453	1,096	823	612	440	321	224	140	82	55		
	Effectiv	e Samp	le Size																	

5033 CapSure Z

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDK	US Returned Product Analysis	
Registered US Implants	2,300	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture 1	
Estimated Active US Implants	500	Polarity	Unipolar	Crimp/Weld/Bond 0	
Advisories	None	Steroid	Yes	Insulation Breach 0	,
				Other 0	



5034 CapSure Z

Product Characteristics

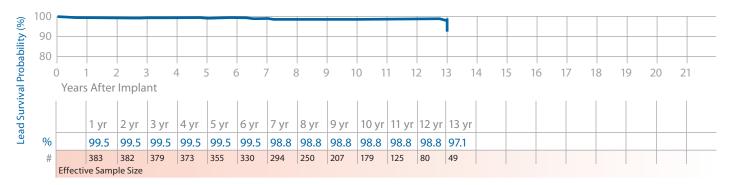
US Market Release	Feb-96	Serial Number Prefix	LDF	US Returned Product Ana	lysis
Registered US Implants	56,000	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	12
Estimated Active US Implants	13,100	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	12
				Other	3

Atrial Placement

System Longevity Study Results

Qualifying Complications 5 Total

Number of Leads Enrolled in Study	386	Failure to Capture	2	Impedance Out of Range 1
Cumulative Months of Follow-Up	43,665	Conductor Fracture	1	
Number of Leads Active in Study	135	Failure to Sense	1	



Ventricular Placement

Number of Le	ads Enroll	ed in Stu	ıdy		1,209					Lead	Dislodg	ement	1				F	ailure to	Sense	
Cumulative M	onths of F	ollow-U	р	44	4,323					Fail	ure to C	apture	7							
Number of Le	ads Active	in Stud	y		15					Cond	uctor Fr	acture	1							
100																				
90							•													
80	-						-													
0 1	2	3	4	5	6	7	8	9	10	11	12	13	14	15	16	17	18	19	20	21
Voars Aft	er Impla	nt																		
							1													
lears Art																				
	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr													
1 y 99.		3 yr	4 yr	5 yr	6 yr 98.8	7 yr 98.1	8 yr 96.6													

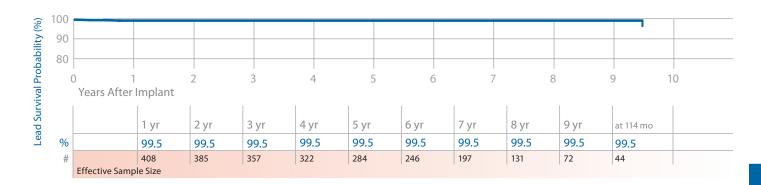
5054 CapSure Z Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEH	US Returned Product Analysis
Registered US Implants	94,000	Type and/or Fixation Transvenous, Vent, Tines		Conductor Fracture 10
Estimated Active US Implants	41,500	Polarity	Bipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 21
				Other 3

Atrial Placement

Longevity Study Results		Qualifying Complications	2 Total	
Number of Leads Enrolled in Study	424	Lead Dislodgement	1	
Cumulative Months of Follow-Up	32,186	Failure to Capture	1	
Number of Leads Active in Study	169			



Ventricular Placement

System Longevity Study Results

Number of Leads Enrolled in Study	967	Lead Dislodgement	1	Impedance Out of Range	1
Cumulative Months of Follow-Up	38,256	Failure to Capture	6		
Number of Leads Active in Study	113	Failure to Sense	1		

Qualifying Complications

Total



5068 CapSureFix

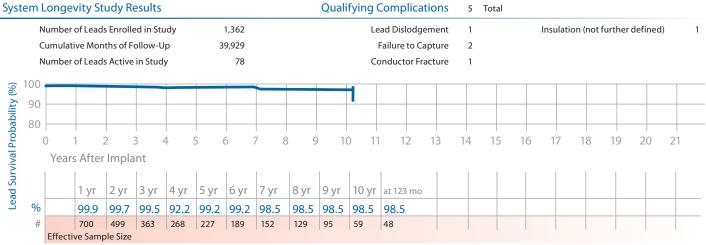
Product Characteristics

US Market Release	Jan-97	Serial Number Prefix	LDJ	US Returned Product Ana	alysis
Registered US Implants	102,800	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	36
Estimated Active US Implants	30,900	Polarity	Bipolar	Crimp/Weld/Bond	2
Advisories	None	Steroid	Yes	Insulation Breach	53
				Other	4

Atı

		lacem onge		udy Re	esults						Quali	fying (Complicat	ions	6	Total						
	Number of Leads Enrolled in Study				968				Le	ad Dislodge	ment	1			lı	mpedar	ice Out	of Rang	e 1			
	Cumulative Months of Follow-Up		3	3,708					Failure to Ca	pture	2					Ove	rsensin	g 1				
	N	umber	of Leads	s Active	in Study	y		37			Insula	ition (no	t further def	ined)	1							
Lead Survival Probability (%)	100 90 80		1 2	2 3		1	5 6	5 7	7 8	3 9) 10) 11	12	13	14	15	16	17	18	19	20	21
r×i		Years	After	Impla	nt																	
ad Su			1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr	at 123 mo									
Å	%		99.6	99.6	99.3	99.3	99.3	99.3	99.3	97.6	97.6	97.6	97.6									
	#		553	425	322	254	211	160	131	104	77	60	53									
		Effectiv	ve Samp	ole Size																		

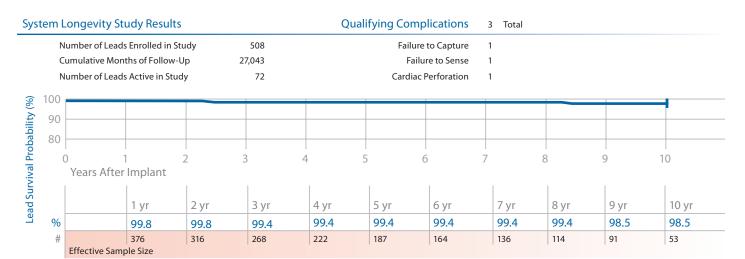
Ventricular Placement



5072 SureFix

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEM	US Returned Product Analy	/sis
Registered US Implants	9,800	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	2
Estimated Active US Implants	4,300	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	6
				Other	0



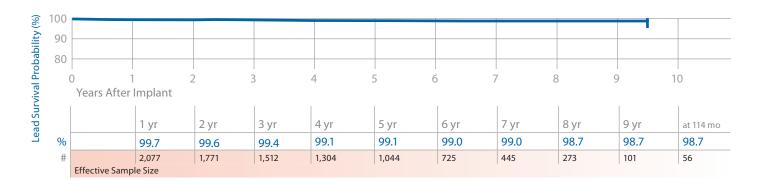
5076 CapSureFix Novus

Product Characteristics

US Market Release	Aug-00	Serial Number Prefix	PJN	US Returned Product Ana	alysis
Registered US Implants	1,402,900	Type and/or Fixation	Transvenous, V or A, Screw-in	Conductor Fracture	322
Estimated Active US Implants	894,200	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	333
				Other	97

Atrial Placement

System Longevity Study Results		Qualifying Complications	19 Total		
Number of Leads Enrolled in Study	2,740	Lead Dislodgement	4	Impedance Out of Range	3
Cumulative Months of Follow-Up	129,717	Failure to Capture	5	Extra Cardiac Stimulation	2
Number of Leads Active in Study	755	Conductor Fracture	1	Oversensing	2
		Insulation (not further defined)	1	Cardiac Perforation	1



Ventricular Placement

System Longevity Study Results

Qualifying Complications 10 Total

N	umber of Leads	Enrolled in St	udy	1,538		Lead	l Dislodgement	2		Failure to	Sense	
C	umulative Mon	ths of Follow-l	Jp	64,681		Fai	lure to Capture	3	In	npedance Out of	Range	
N	umber of Leads	Active in Stud	dy	308		Cond	ductor Fracture	1		Cardiac Perfo	ration	
100								_		1		_
90										•		_
80												_
() 1	1	2	3	4	5	6	7	8	9	10	
	Years After	Implant										
		1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	at 105 mo		
%		99.6	99.4	99.3	99.0	99.0	99.0	99.0	99.0	99.0		
#		1,081	898	742	607	475	362	227	134	47		
	Effective Samp	ole Size										

5086MRI CapSureFix Novus

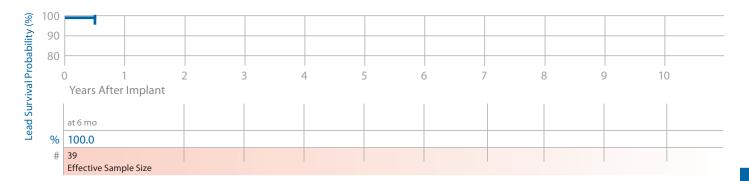
Product Characteristics

US Market Release	Feb-11	Serial Number Prefix	LFP	US Returned Product Analy	sis
Registered US Implants	44,300	Type and/or Fixation	Transvenous, A or V, Screw-in	Conductor Fracture	0
Estimated Active US Implants	43,300	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	1
				Other	2

System Longevity Study Results

Qualifying Complications 0 Total

1,592 Number of Leads Enrolled in Study Cumulative Months of Follow-Up 1,413 Number of Leads Active in Study 1,552



5092 CapSure SP Novus

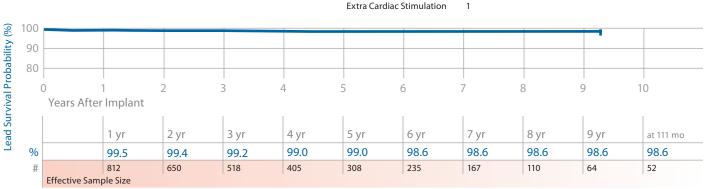
Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LET	US Returned Product Ana	alysis
Registered US Implants	128,400	Type and/or Fixation	Transvenous, Vent, Tines	Conductor Fracture	7
Estimated Active US Implants	59,800	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	33
				Other	1

System Longevity Study Results

Qualifying Complications 9 Total

Number of Leads Enrolled in Study	1,172	Lead Dislodgement	5
Cumulative Months of Follow-Up	46,803	Failure to Capture	2
Number of Leads Active in Study	150	Impedance Out of Range	1
		Futura Canadia a Caina ulatiana	1



5524, 5524M CapSure SP

Product Characteristics

US Market Release	Mar-90	Serial Number Prefix	XV or LAV	US Returned Product Analysis
Registered US Implants	60,300	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 11
Estimated Active US Implants	16,600	Polarity	Bipolar	Crimp/Weld/Bond 1
Advisories	None	Steroid	Yes	Insulation Breach 11
				Other 2

System Longevity Study Results

Qualifying Complications 39 Total

1	Insulation (not further defined)	4	Lead Dislodgement	4,496	Number of Leads Enrolled in Study
1	Impedance Out of Range	23	Failure to Capture	252,709	Cumulative Months of Follow-Up
4	Oversensing	1	Conductor Fracture	307	Number of Leads Active in Study
1	Other	4	Failure to Sense		



5534 CapSure Z

Lead Survival Probability (%)

Product Characteristics

US Market Release	Feb-96	Serial Number Prefix	LDG	US Returned Product Analys	is
Registered US Implants	26,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	3
Estimated Active US Implants	7,200	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	5
				Other	2

System Longevity Study Results

Qualifying Complications 6 Total

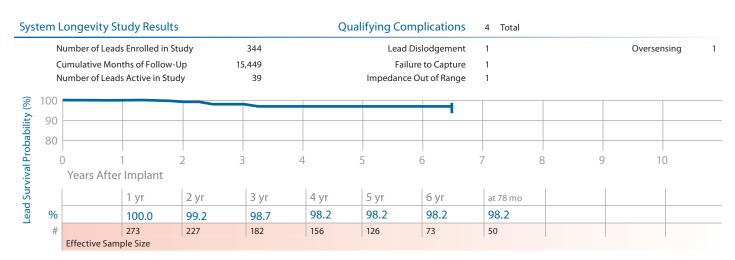
Number of Leads Enrolled in Study	264	Failure to Capture	5
Cumulative Months of Follow-Up	12,959	Impedance Out of Range	1
Number of Leads Active in Study	6		



5554 CapSure Z Novus

Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEJ	US Returned Product Analysis
Registered US Implants	60,700	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture 9
Estimated Active US Implants	29,500	Polarity	Bipolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 17
				Other 1



5568 CapSureFix

Product Characteristics

1,053

39,855

US Market Release	Jan-97	Serial Number Prefix	LDN	US Returned Product Ana	alysis
Registered US Implants	87,200	Type and/or Fixation	Transvenous, Atrial-J, Screw-in	Conductor Fracture	8
Estimated Active US Implants	49,500	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	27
				Other	7

System Longevity Study Results

Number of Leads Enrolled in Study

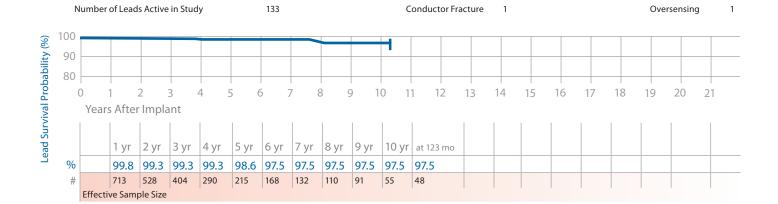
Cumulative Months of Follow-Up

Qualifying Complications 11 Total Lead Dislodgement

Failure to Capture

1

5



Failure to Sense

Extra Cardiac Stimulation

2

5592 CapSure SP Novus

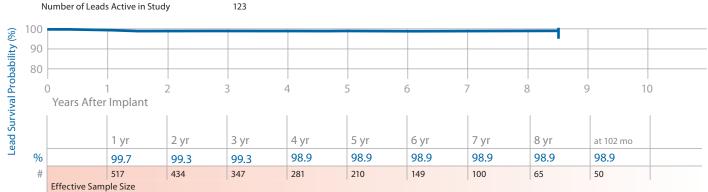
Product Characteristics

US Market Release	Jun-98	Serial Number Prefix	LEU	US Returned Product Analys	sis
Registered US Implants	33,200	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	3
Estimated Active US Implants	18,600	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	3
				Other	0



Qualifying Complications 5 Total





5594 CapSure SP Novus

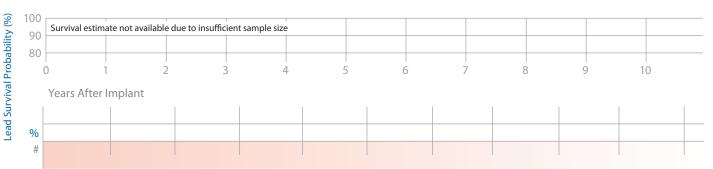
Product Characteristics

US Market Release	Jun-01	Serial Number Prefix	LFD	US Returned Product Ana	lysis
Registered US Implants	14,800	Type and/or Fixation	Transvenous, Atrial-J, Tines	Conductor Fracture	4
Estimated Active US Implants	9,900	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	6
				Other	1

System Longevity Study Results

Qualifying Complications 0 Total

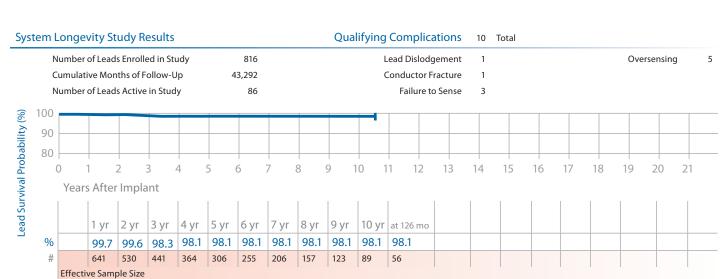
Number of Leads Enrolled in Study	21
Cumulative Months of Follow-Up	1,452
Number of Leads Active in Study	11



6940 CapSureFix

Product Characteristics

US Market Release	Oct-98	Serial Number Prefix	TCP	US Returned Product Analy	'sis
Registered US Implants	25,300	Type and/or Fixation	Transvenous, Atrial-J , Screw-in	Conductor Fracture	12
Estimated Active US Implants	7,600	Polarity	Bipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	Yes	Insulation Breach	17
				Other	1



	_	20 y														
	_	18 yr														
		16 yr														
		14 yr			95.7 +1.6/-2.6 at 159 mo				91.1 +2.7/-3.9 at 159 mo							
		12 yr			95.7 +1.6/-2.6				92.0 +2.3/-3.3	92.7 +2.9/-4.8 at 138 mo						
		10 yr			96.3 +1.3/-2.1	98.8 +1.0/-5.0 at 117 mo	95.3 +2.5/-5.1 at 114 mo		94.1 +1.6/-2.2	94.2 +1.8/-2.6						97.9 +0.8/-1.3 at 117 mo
		8 yr			96.9	99.8	96.6		95.6 +1.1/-1.6	95.5						97.9 +0.8/-1.3
	_	7 yr			97.2 +1.1/-1.8	99.8 +0.1/-0.7	97.5 +1.3/-2.7	98.1 +1.3/-3.9 at 81 mo	96.9 +0.8/-1.1	96.2 +1.1/-1.7	100 .0 at 75 mo	99.1 +0.7/-2.8	99.4 +0.4/-1.3			97.9 +0.8/-1.3
	_	6 yr	99.4 +0.4/-1.1 at 63 mo	100.0 at 66 mo	98.1 +0.8/-1.3	99.8 +0.1/-0.7	97.5 +1.3/-2.7	98.1 +1.3/-3.9	97.2 +0.7/-1.0	97.3 +0.9/-1.2	100.0	99.1 +0.7/-2.8	99.4 +0.4/-1.3	99.6 +0.2/-0.5 at 69 mo	99.5 +0.4/-1.6 at 69 mo	97.9 +0.8/-1.3
	_	5 yr	99.4 +0.4/-1.1	100.0	98.5 +0.7/-1.1	99.8 +0.1/-0.7	98.1 +1.0/-2.2	98.1 +1.3/-3.9	97.4 +0.7/-0.9	97.8 +0.7/-1.1	100.0	99.1 +0.7/-2.8	99.4 +0.4/-1.3	99.6 +0.2/-0.5	99.5 +0.4/-1.6	98.1 +0.7/-1.2
ity (%)	_	4 yr	99.4 +0.4/-1.1	100.0	98.5 +0.7/-1.1	99.8 +0.1/-0.7	98.5 +0.8/-1.9	98.1	98.0 +0.5/-0.8	98.2 +0.6/-1.0	100.0	99.1 +0.7/-2.8	99.4	99.6	99.8	98.4 +0.6/-1.1
Probabil	ant	3 yr	99.4 +0.4/-1.1	100.0	98.7 +0.6/-1.1	99.8 +0.1/-0.7	98.8 +0.7/-1.6	98.1	98.2 +0.5/-0.7	98.7	100.0	99.1 +0.7/-2.8	99.4 +0.4/-1.3	99.6	99.8	98.7 +0.5/-1.0
Device Survival Probability (%)	Years After Implant	2 yr	99.4 +0.4/-1.1	100.0	99.2	99.8 +0.1/-0.7	99.1 +0.6/-1.5	98.1 +1.3/-3.9	98.7 +0.4/-0.6	98.7	100.0	99.1 +0.7/-2.8	99.4 +0.4/-1.3	99.6 +0.2/-0.5	99.8	98.8
Device	Years A	1 yr	99.4 +0.4/-1.1	100.0	99.8 +0.2/-0.6	99.9 +0.1/-0.5	99.4 +0.4/-1.4	98.1 +1.3/-3.9	98.9 +0.4/-0.5	99.3 +0.3/-0.6	100.0	99.1 +0.7/-2.8	99.7 +0.2/-1.1	99.8 +0.1/-0.5	99.8	98.9 +0.5/-0.9
Months o in Study			16,060	12,042	73,316	50,855	29,793	11,097	131,591	94,169	2,095	13,875	26,337	48,631	40,162	65,267
su	ifying plicatio	Coml	4	←	22	4	10	∞	69	44	0	2	m	9	m	18
in Study			591	333	216	17	ю	44	301	208	71	151	298	1,190	848	299
рә	s Enroll	реәղ	992	472	1,158	1,215	539	171	2,413	1,799	102	215	799	1,657	1,227	1,147
əseələ	arket R	w sn	Aug-05	Aug-05	Aug-91	Oct-91	Not US released	Jan-97	Mar-96	Mar-96	Jun-02	Jun-02	Jun-02	Feb-04	Feb-04	Sep-98
	uper	Сһап	Atrial	Vent	Vent	Vent	Vent	A or V	Atrial	Vent	Vent	Atrial	Vent	Atrial	Vent	Vent
	Įλ	ims4	SelectSecure	SelectSecure	CapSure SP	CapSure SP	CapSure Z	CapSureFix	CapSureFix	CapSureFix	CapSure Sense	CapSure Sense	CapSure Sense	CapSureFix Novus	CapSureFix Novus	CapSure SP Novus
		mnN muN	3830	3830	4023	4024	4033	4067	4068	4068	4073	4074	4074	4076	4076	4092

		20 yr														
	_	18 yr									97.3 +1.2/-2.0 at 201 mo					
	_	16 yr									97.3 +1.2/-2.0					
	_	14 yr									98.3 +0.6/-0.9	94.7 +2.0/-3.3 at 165 mo	97.1 +2.1/-6.7 at 156 mo			
	_	12 yr								96.1	98.5 +0.5/-0.7	95.5 +1.6/-2.5	98.8 +0.8/-1.9			
		10 yr		99.0 +0.6/-1.2 at 117 mo		91.8 +4.3/-8.8 at 108 mo	93.4 +2.1/-2.9 at 105 mo		97.4 +1.5/-3.8 at 102 mo	96.8 +1.3/-2.2	98.8 +0.3/-0.6	96.0	98.8 +0.8/-1.9		99.5 +0.4/-1.4 at 114 mo	97.9 +1.1/-2.4 at 111 mo
		8 yr		99.0		96.5	93.4 +2.1/-2.9		97.4 +1.5/-3.8	97.6	99.0 +0.3/-0.4	96.9	98.8	96.6	99.5	97.9
		7 yr		99.0 +0.6/-1.2	97.9 +1.4/-4.2 at 78 mo	96.5	93.4 +2.1/-2.9		97.4	97.6	99.1	97.7 +0.9/-1.3	98.8 +0.8/-1.9	98.1	99.5	97.9
		6 yr		99.0	97.9 +1.4/-4.2	97.6 +1.6/-4.2	94.0 +1.8/-2.6		97.4 +1.5/-3.8	98.8 +0.5/-1.2	99.3 +0.2/-0.3	98.3 +0.7/-1.2	99.5 +0.4/-1.6	98.8 +0.6/-1.1	99.5 +0.4/-1.4	97.9
		5 yr	98.1 +1.4/-5.3 at 57 mo	99.0 +0.6/-1.2	97.9 +1.4/-4.2	99.3 +0.5/-1.4	94.0 +1.8/-2.6		97.4 +1.5/-3.8	99.3 +0.4/-0.9	99.3 +0.2/-0.2	98.8 +0.5/-0.9	99.5 +0.4/-1.6	98.8 +0.6/-1.1	99.5 +0.4/-1.4	99.1
ity (%)		4 yr	98.1	99.0	97.9	99.3 +0.5/-1.4	94.7		98.2 +1.1/-3.0	99.4 +0.3/-0.7	99.4 +0.2/-0.2	99.0	99.5	98.8 +0.6/-1.1	99.5	99.1
Probabili	ant	3 yr	98.1	99.3 +0.4/-1.0	98.8 +0.9/-3.6	99.3 +0.5/-1.4	95.3		98.2 +1.1/-3.0	99.5 +0.3/-0.6	99.5	99.1 +0.4/-0.7	99.5 +0.4/-1.6	99.1	99.5	99.4
Device Survival Probability (%)	Years After Implant	2 yr	98.1	99.3 +0.4/-1.0	99.4	99.3 +0.5/-1.4	96.4	100.0 at 18 mo	98.2 +1.1/-3.0	99.7 +0.2/-0.6	99.6	99.6	99.5	99.4	99.5	99.4
Device 5	Years Af	1 yr	98.1 +1.4/-5.3	99.6 +0.3/-0.7	100.0	99.3	96.8	100.0	98.2 +1.1/-3.0	99.7 +0.2/-0.5	99.6	99.7	99.5	99.7	99.5	99.5
Months in Study			7,588	40,433	11,767	22,997	31,758	3,076	14,531	83,694	441,672	99,245	43,665	44,323	32,186	38,256
su	fying oiteatio	ilauQ ImoD	4	9	4	12	33	0	rv	19	56	28	5	=	2	6
ybut2 ni s	evitoA a	Геэд	4	39	0	22	151	271	63	335	321	171	135	15	169	113
рә	lloan3 s	Гезд	121	911	206	539	929	319	283	1,354	8,153	1,899	386	1,209	424	296
əseələ	arket R	w sn	Aug-91	Oct-91	Not US released	Nov-94	Jan-97	Jun-02	Oct-98	Nov-88	Mar-90	Feb-96	Feb-96	Feb-96	Jun-98	Jun-98
	ıpeı	Cham	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Vent	Vent	Vent	Atrial	Vent	Atrial	Vent
	٨	lims4	CapSure SP	CapSure SP	CapSure Z	Screw-In	CapSureFix	CapSure Sense	CapSure SP Novus	CapSure SP	CapSure SP	CapSure Z	CapSure Z	CapSure Z	CapSure Z Novus	CapSure Z Novus
		ppoM JmuM	4523	4524	4533	4558M	4568	4574	4592	5023, 5023M	5024, 5024M	5033	5034	5034	5054	5054

Lead Survival Summary continued

		20 yr														
		18 yr														
		16 yr								97.5 +0.8/-1.1 at 186 mo						
		14 yr								97.5 +0.8/-1.1						
		12 yr	97.6 +1.6/-4.2 at 123 mo	98.5 +1.0/-2.5 at 123 mo						97.5 + 0.8/-1.1 +			97.5 +1.3/-2.8 at 123 mo			98.1 +0.9/-1.6 at 126 mo
		10 yr	97.6	98.5 +1.0/-2.5	98.5	98.7 +0.6/-0.9 at 114 mo	99.0 +0.5/-0.9 at 105 mo		98.6 +0.7/-1.6 at 111 mo	97.7 +0.8/-1.0			97.5	98.9 +0.7/-1.6 at 102 mo		98.1 +0.9/-1.6
		8 yr	97.6	98.5 +1.0/-2.5	99.4	98.7	99.0		98.6	98.4			97.5	98.9		98.1 +0.9/-1.6
		7 yr	99.3	98.5 +1.0/-2.5	99.4	99.0	99.0		98.6	98.9	97.1 +1.6/-3.5 at 78 mo	98.2 +1.1/-3.0 at 78 mo	97.5 +1.3/-2.8	98.9 +0.7/-1.6		98.1
		6 yr	99.3 +0.5/-1.2	99.2 +0.5/-1.6	99.4 +0.5/-1.7	99.0	99.0		98.6 +0.7/-1.6	99.2 +0.2/-0.5	97.1 +1.6/-3.5	98.2 +1.1/-3.0	97.5 +1.3/-2.8	98.9 +0.7/-1.6		98.1 +0.9/-1.6
		5 yr	99.3	99.2	99.4	99.1 +0.3/-0.6	99.0		99.0	99.2 +0.3/-0.4	97.1	98.2 +1.1/-3.0	98.6 +0.8/-2.0	98.9		98.1
ity (%)		4 yr	99.3 +0.5/-1.2	99.2 +0.5/-1.6	99.4 +0.5/-1.7	99.1 +0.3/-0.6	99.0+0.5/-0.9		99.0	99.3 +0.3/-0.4	97.1 +1.6/-3.5	98.2 +1.1/-3.0	99.3	98.9 +0.7/-1.6		98.1
Device Survival Probability (%)	ant	3 yr	99.3 +0.5/-1.2	99.5 +0.3/-1.2	99.4 +0.5/-1.7	99.4 +0.2/-0.5	99.3		99.2	99.5 +0.2/-0.3	97.8 +1.3/-3.0	98.7 +0.9/-2.6	99.3	99.3 +0.4/-1.3		98.3
Survival	Years After Implant	2 yr	99.6	99.7 +0.2/-0.9	99.8 +0.2/-1.4	99.6 +0.2/-0.3	99.4 +0.3/-0.6		99.4 +0.3/-0.8	99.7 +0.1/-0.2	97.8 +1.3/-3.0	99.2 +0.6/-2.4	99.3	99.3 +0.4/-1.3		99.6
Device	Years A	1 yr	99.6 +0.3/-0.9	99.9 +0.1/-0.8	99.8 +0.2/-1.4	99.7 +0.1/-0.4	99.6 +0.2/-0.5	100.0 at 6 mo	99.5	99.7 +0.2/-0.2	98.3 +1.1/-2.7	100.0	99.8 +0.1/-0.7	99.7 +0.2/-1.1	100.0 at 0 mo	99.7
Months o in Study			33,708	39,929	27,043	129,717	64,681	1,413	46,803	252,709	12,959	15,449	39,855	30,202	1,452	43,292
su		JilsuQ qmoD	9	2	ю	19	10	0	6	39	9	4	1	5	0	10
γpn1S ni s	Active	Feads	37	78	72	755	308	1,552	150	307	9	39	133	123	=	86
pə	Enroll	reads	896	1,362	208	2,740	1,538	1,592	1,172	4,496	264	344	1,053	672	21	816
elease	rket R	_B M 2U	Jan-97	Jan-97	Jun-98	Aug-00	Aug-00	Feb-11	Jun-98	Mar-90	Feb-96	Jun-98	Jan-97	Jun-98	Jun-01	Oct-98
	per	Chaml	Atrial	Vent	A or V	Atrial	Vent	A or V	Vent	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial	Atrial
	,	(lime7	CapSureFix	CapSureFix	SureFix	CapSureFix Novus	CapSureFix Novus	CapsureFix Novus	CapSure SP Novus	CapSure SP	CapSure Z	CapSure Z Novus	CapSureFix	CapSure SP Novus	CapSure SP Novus	CapSureFix
		dmuM dmuM	2068	5068	5072	5076	5076	5086MRI	5092	5524, 5524M	5534	5554	5568	5592	5594	6940

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
3830	SelectSecure	Aug-05	20,800	16,500	3	0	10	3
4023	CapSure SP	Aug-91	41,100	7,700	14	0	4	2
4024	CapSure SP	Oct-91	221,300	43,800	29	0	159	8
4033	CapSure Z	Not US released	NA	NA	0	0	0	0
4067	CapSureFix	Jan-97	1,000	200	1	0	0	0
4068	CapSureFix	Mar-96	124,300	32,200	44	0	147	5
4073	CapSure Sense	Jun-02	700	300	0	0	0	0
4074	CapSure Sense	Jun-02	85,400	53,700	1	0	16	1
4076	CapSureFix Novus	Feb-04	376,400	289,700	22	1	21	16
4092	CapSure SP Novus	Sep-98	172,100	80,000	7	0	35	2
4523	CapSure SP	Aug-91	11,200	2,500	1	0	2	1
4524	CapSure SP	Oct-91	101,300	25,100	1	0	53	3
4533	CapSure Z	Not US released	NA	NA	0	0	0	0
4558M	Screw-in	Nov-94	19,900	4,100	1	0	18	0
4568	CapSureFix	Jan-97	69,500	23,200	3	0	57	1
4574	CapSure Sense	Jun-02	56,200	38,200	5	0	3	0
4592	CapSure SP Novus	Oct-98	83,500	41,100	6	0	12	1
5023, 5023M	CapSure SP	Nov-88	9,800	2,200	5	0	0	0
5024, 5024M	CapSure SP	Mar-90	200,700	44,700	51	1	50	9
5033	CapSure Z	Feb-96	2,300	500	1	0	0	0
5034	CapSure Z	Feb-96	56,000	13,100	12	0	12	3
5054	CapSure Z Novus	Jun-98	94,000	41,500	10	1	21	3
5068	CapSureFix	Jan-97	102,800	30,900	36	2	53	4
5072	SureFix	Jun-98	9,800	4,300	2	0	6	0
5076	CapSureFix Novus	Aug-00	1,402,900	894,200	322	0	333	97
5086MRI	CapSureFix Novus	Feb-11	44,300	43,300	0	0	1	2
5092	CapSure SP Novus	Jun-98	128,400	59,800	7	0	33	1
5524, 5524M	CapSure SP	Mar-90	60,300	16,600	11	1	11	2
5534	CapSure Z	Feb-96	26,200	7,200	3	0	5	2
5554	CapSure Z Novus	Jun-98	60,700	29,500	9	0	17	1
5568	CapSureFix	Jan-97	87,200	49,500	8	0	27	7
5592	CapSure SP Novus	Jun-98	33,200	18,600	3	0	3	0
5594	CapSure SP Novus	Jun-01	14,800	9,900	4	0	6	1
6940	CapSureFix	Oct-98	25,300	7,600	12	0	17	1

Source: Returned Product Analysis Data as of January 31, 2012

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure to Sense	Insulation Breach	Extracardiac Stimulation	Impedance Abnormal	Unspecified
3830	SelectSecure	20,800	6	1	26	14	1	1	1	1	0	2
4023	CapSure SP	41,100	0	1	3	4	1	1	3	1	0	2
4024	CapSure SP	221,300	12	11	50	109	0	15	1	2	7	21
4033	CapSure Z	Not US Released	0	0	0	0	0	0	0	0	0	0
4067	CapSure Fix	1,000	1	0	0	0	0	0	0	0	0	0
4068	CapSure Fix	124,300	4	3	31	25	0	5	1	1	4	4
4073	CapSure Sense	700	0	0	0	0	0	0	0	0	0	0
4074	CapSure Sense	85,400	8	1	25	25	0	1	0	0	3	1
4076	CapSure Fix Novus	376,400	37	4	121	66	6	17	1	5	8	8
4092	CapSure SP Novus	172,100	2	4	19	25	0	0	1	0	3	2
4523	CapSure SP	11,200	0	0	2	2	0	1	0	0	0	0
4524	CapSure SP	101,300	0	2	24	17	0	4	2	0	1	14
4533	CapSure Z	NA	0	0	0	0	0	0	0	0	0	0
4558M	Screw-in	19,900	2	0	2	2	0	1	0	1	2	1
4568	CapSure Fix	69,500	3	1	4	7	0	1	0	0	3	1
4574	CapSure Sense	56,200	0	2	25	11	1	4	0	0	0	3
4592	CapSure SP Novus	83,500	0	0	22	7	2	1	0	0	0	2
5023, 5023M	CapSure SP	9,800	0	1	2	0	0	0	0	0	0	0
5024, 5024M	CapSure SP	200,700	10	9	33	50	1	9	6	3	3	14
5033	CapSure Z	2,300	0	0	1	0	0	0	0	0	0	0
5034	CapSure Z	56,000	3	3	16	32	0	3	2	0	0	12
5054	CapSure Z Novus	94,000	2	2	17	20	0	0	1	0	0	8
5068	CapSure Fix	102,800	13	4	22	34	1	5	1	0	1	6
5072	SureFix	9,800	0	0	2	1	0	0	0	0	0	1
5076	CapSure Fix Novus	1,402,900	137	9	447	214	24	38	7	13	15	31
5086MRI	CapsureFix Novus	44,300	67	0	92	46	7	16	1	10	3	5
5092	CapSure SP Novus	128,400	5	1	36	27	1	6	4	3	0	9
5524, 5524M	CapSure SP	60,300	1	3	20	13	0	9	2	0	0	10
5534	CapSure Z	26,200	0	0	6	3	0	2	0	2	0	4
5554	CapSure Z Novus	60,700	0	1	31	23	0	2	0	0	0	3
5568	CapSure Fix	87,200	6	0	26	18	2	4	1	1	1	5
5592	CapSure SP Novus	33,200	0	0	21	4	0	2	0	0	0	2
5594	CapSure SP Novus	14,800	0	1	7	0	0	0	0	0	0	2
6940	CapSure Fix	25,300	0	1	6	1	0	0	0	0	1	0

Report Cutoff Date: January 31, 2012

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
3830	SelectSecure	Transvenous V or A Screw-In	Polyurethane/Silicone (55D,4719)	MP35N 5 Filars/ Cable	1.8 mm Helix/Steroid	IS-1 BI
4023	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4 Filars	Porous Platinized/ Steroid	IS-1 UNI
4024	CapSure SP	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4033	CapSure Z	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4067	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A)	MP35N 3 Filars	1.8 mm Helix/Steroid	IS-1 UNI
4068	CapSureFix	Transvenous V or A Screw-In	Polyurethane (80A/55D)	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4073	CapSure Sense	Transvenous Ventricular Tines	Polyurethane (55D)	MP35N 5 Filars	TiN Coated Platinum Iridium/Steroid	IS-1 UNI
4074	CapSure Sense	Transvenous Ventricular Tines	Polyurethane/Silicone (55D, 4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium/ Steroid	IS-1 BI
4076	CapSureFix Novus	Transvenous V or A Screw-In	Polyurethane/Silicone (55D, 4719)	MP35N 4/6 Filars	TiN Coated Platinum Alloy/Steroid	IS-1 BI
4092	CapSure SP Novus	Transvenous Ventricular Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/4 Filars	Porous Platinized/ Steroid	IS-1 BI
4523	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	Porous Platinized/ Steroid	IS-1 UNI
4524	CapSure SP	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 4/5 Filars	Porous Platinized/ Steroid	IS-1 BI
4533	CapSure Z	Transvenous Atrial-J Tines	Polyurethane (55D)	MP35N 2 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
4558M	Screw-In	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4568	CapSureFix	Transvenous Atrial-J Screw-In	Polyurethane (80A/55D)	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
4574	CapSure Sense	Transvenous Atrial -J Tines	Polyurethane/Silicone (55D,4719)	MP35N 5/5 Filars	TiN Coated Platinum Iridium	IS-1 BI
4592	CapSure SP Novus	Transvenous Atrial-J Tines	Polyurethane/Silicone (55D/4719)	MP35N 6/3 Filars	Porous Platinized/ Steroid	IS-1 BI
5023, 5023M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	Porous Platinized/ Steroid	5 mm (5023) IS-1 UNI (5023M)
5024, 5024M	CapSure SP	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5024) IS-1 BI (5024M)
5033	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4 Filars	CapSure Z Platinized/Steroid	IS-1 UNI
5034	CapSure Z	Transvenous Ventricular Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5054	CapSure Z Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	CapSure Z Porous/Platinized/ Steroid	IS-1 BI
5068	CapSureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5072	SureFix	Transvenous V or A Screw-In	Silicone	MP35N 4/5 Filars	1.8 mm Helix/Steroid	IS-1 BI
5076	CapSureFix Novus	Transvenous V or A Screw-In	Silicone (4719)	MP35N 4/6 Filars	Porous Platinized/ Steroid	IS-1 BI
5086MRI	CapsureFix Novus	Transvenous A or V Screw-in	Silicone	MP35N	Titanium nitride coated platinum alloy	IS-1 BI
5092	CapSure SP Novus	Transvenous Ventricular Tines	Silicone (4719)	MP35N 5/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5524, 5524M	CapSure SP	Transvenous Atrial-J Tines	Silicone	MP35N 6/5 Filars	Porous Platinized/ Steroid	3.2 mm Low Profile (5524) IS-1 BI (5524M)

continued

Reference Chart continued

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5534	CapSure Z	Transvenous Atrial-J Tines	Silicone	MP35N 4/5 Filars	CapSure Z Platinized/Steroid	IS-1 BI
5554	CapSure Z Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	CapSure Z Porous Platinized/ Steroid	IS-1 BI
5568	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 6/3 Filars	1.8 mm Helix/Steroid	IS-1 BI
5592	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Porous Platinized/ Steroid	IS-1 BI
5594	CapSure SP Novus	Transvenous Atrial-J Tines	Silicone (4719)	MP35N 6/5 Filars	Platinized Platinum/ Steroid	IS-1 BI
6940	CapSureFix	Transvenous Atrial-J Screw-In	Silicone	MP35N 3/6 Filars	Platinum Alloy	IS-1 BI

Epi/Myocardial Pacing Leads

4951, 4951M Spectraflex

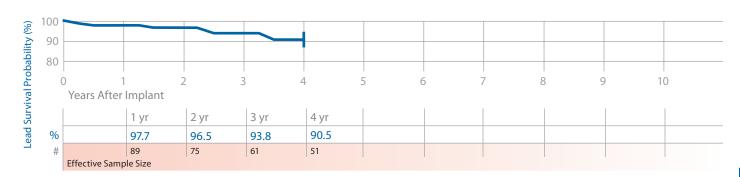
Product Characteristics

US Market Release	Oct-81	Serial Number Prefix	TF or LBJ	US Returned Product Ana	alysis
Registered US Implants	11,700	Type and/or Fixation	Myocardial Stab-in, V or A, Peds	Conductor Fracture	36
Estimated Active US Implants	2,600	Polarity	Unipolar	Crimp/Weld/Bond	0
Advisories	None	Steroid	No	Insulation Breach	8
				Other	6

System Longevity Study Results

Qualifying Complications 14 Total

Number of Leads Enrolled in Study	179	Failure to Capture	7	Insulation (not further defined)	1
Cumulative Months of Follow-Up	5,929	Conductor Fracture	1	Insulation (ESC)	1
Number of Leads Active in Study	4	Failure to Sense	3	Impedance Out of Range	1



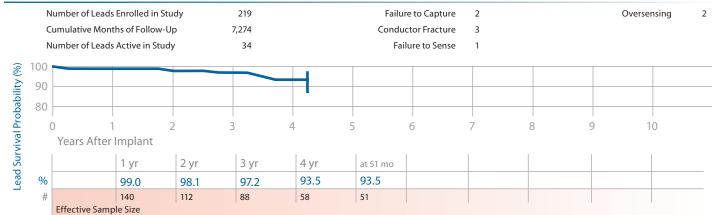
4965 CapSure Epi

Product Characteristics

US Market Release	Sep-96	Serial Number Prefix	LBT	US Returned Product Analy	/sis
Registered US Implants	20,100	Type and/or Fixation	Epicardial Suture-On V or A	Conductor Fracture	136
Estimated Active US Implants	9,300	Polarity	Unipolar	Crimp/Weld/Bond	1
Advisories	None	Steroid	Yes	Insulation Breach	32
				Other	0

System Longevity Study Results

Qualifying Complications 8 Total



Epi/Myocardial Pacing Leads continued

4968 CapSure Epi

Product Characteristics

US Market Release	Sep-99	Serial Number Prefix	LEN	US Returned Product Anal	US Returned Product Analysis		
Registered US Implants	24,400	Type and/or Fixation	Epicardial Suture-On V or A	Conductor Fracture	23		
Estimated Active US Implants	15,200	Polarity	Bipolar	Crimp/Weld/Bond	0		
Advisories	None	Steroid	Yes	Insulation Breach	8		
				Other	1		

System Longevity Study Results

Qualifying Complications 41 Total

2	Insulation (not further defined)	17	Failure to Capture	736	Number of Leads Enrolled in Study
3	Impedance Out of Range	8	Conductor Fracture	34,073	Cumulative Months of Follow-Up
7	Oversensing	3	Failure to Sense	385	Number of Leads Active in Study
1	Other				



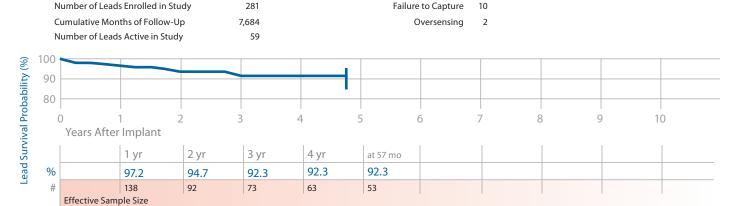
5071 Screw-in

Product Characteristics

US Market Release	Dec-92	Serial Number Prefix	LAQ	US Returned Product Analysis
Registered US Implants	41,800	Type and/or Fixation	Myocardial Screw-in Vent.	Conductor Fracture 12
Estimated Active US Implants	14,500	Polarity	Unipolar	Crimp/Weld/Bond 0
Advisories Nor		Steroid	No	Insulation Breach 2
				Other 0



Qualifying Complications 12 Total



Lead Survival Summary (95% Confidence Interval)

	ı	1									
		16 yr									
		14 yr									
		12 yr									
		10 yr			88.9 +4.0/-6.0 at 108 mo						
	Years After Implant	8 yr			92.5 +2.4/-3.6						
;y (%)							7 yr			92.5 +2.4/-3.6	
			6 yr			93.2 +2.1/-3.1					
					5 yr		93.5 +3.5/-7.1 at 51 mo	93.7 +2.0/-2.9	92.3 +3.6/-6.4 at 57 mo		
			4 yr	90.5	93.5 +3.5/-7.1	94.8 +1.7/-2.5	92.3 +3.6/-6.4				
Probabili		3 yr	93.8	97.2 +1.8/-4.9	96.7 +1.2/-2.0	92.3					
Device Survival Probability (%)		After Impla	After Impla	After Impl	2 yr	96.5 +2.2/-5.8	98.1 +1.3/-4.0	97.6	94.7 +2.6/-4.9		
Device.		1 yr	97.7 +1.6/-4.8	99.0 +0.7/-3.0	99.6 +0.3/-1.0	97.2 +1.5/-3.5					
Months oute ni d			5,929	7,274	34,073	7,684					
	oitsoil	Pilau Qmo D	4	∞	41 3	12					
but2 ni s	vitoA	греэд	4	34	385	59					
pə	llorn3	speə7	179	219	736	281					
US Market Release			Oct-81	Sep-96	Sep-99	Dec-92					
	,	(lime7	Spectraflex	CapSure Epi Sep-96	CapSure Epi	Screw -in					
Model Number			4951, 4951M	4965	4968	5071					

Epi/Myocardial Pacing Leads continued

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
4951, 4951M	Spectraflex	Oct-81	11,700	2,600	36	0	8	6
4965	CapSure Epi	Sep-96	20,100	9,300	126	1	32	0
4968	CapSure Epi	Sep-99	24,400	15,200	23	0	8	1
5071	Screw-in	Dec-92	41,800	14,500	12	0	2	0

Source: Returned Product Analysis Data as of January 31, 2012

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Cardiac Perforation	Conductor Fracture	Lead Dislodgement	Failure to Capture	Oversensing	Failure To Sense	Impedance Abnormal	Extracardiac Stimulation
4951, 4951M	Spectraflex	11,700	0	1	0	8	0	0	0	0
4965	CapSure Epi	20,100	0	1	0	4	0	2	3	0
4968	CapSure Epi	24,400	1	0	3	9	2	0	1	0
5071	Screw-in	41,800	1	0	1	26	0	0	2	3

Model Number	Family	Estimated US Implants	Insulation Breach	Unspecified
4951, 4951M	Spectraflex	11,700	0	1
4965	CapSure Epi	19,700	0	3
4968	CapSure Epi	22,800	1	0
5071	Screw-in	40,700	0	1

Report Cutoff Date: Data as of January 31, 2012

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
4951, 4951M	Spectraflex	Myocardial Stab-In V or A/Peds	Polyurethane (80A)	MP35N 4 Filars	Barb	5 mm (4951) IS-1 UNI (4951M)
4965	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 UNI
4968	CapSure Epi	Epicardial Suture V or A	Silicone	MP35N 5 Filars	Porous Platinized/ Steroid	IS-1 B1
5071	Screw-in	Myocardial Screw-In Ventricular	Silicone	MP35N Multifilars	2-Turn Helix	IS-1 UNI

VDD Single Pass Pacing Leads

5032 CapSure VDD

Product Characteristics

US Market Release	Mar-96	Serial Number Prefix	LCL, LCN, LCM	US Returned Product Analysis
Registered US Implants	5,400	Type and/or Fixation	Transvenous, Atr-Vent, Tines	Conductor Fracture 7
Estimated Active US Implants	1,300	Polarity	Quadripolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 7
				Other 0

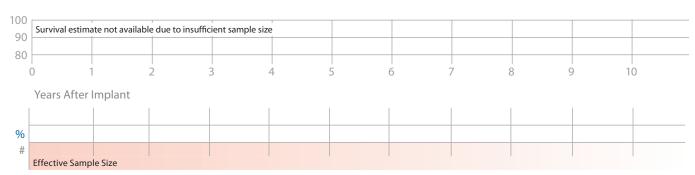
System Longevity Study Results

Lead Survival Probability (%)

Qualifying Complications 1 Total

Failure to Sense

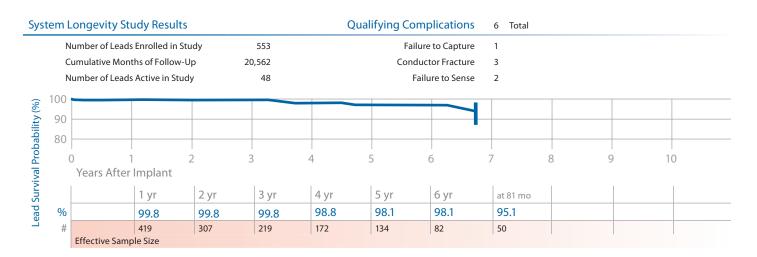
38 Number of Leads Enrolled in Study 1,683 Cumulative Months of Follow-Up Number of Leads Active in Study 0



5038 CapSure VDD-2

Product Characteristics

US Market Release	Sep-98	Serial Number Prefix	LEE, LEG, or LEF	US Returned Product Analysis
Registered US Implants	8,900	Type and/or Fixation	Transvenous, Atr-Vent., Tines	Conductor Fracture 4
Estimated Active US Implants	3,500	Polarity	Quadripolar	Crimp/Weld/Bond 0
Advisories	None	Steroid	Yes	Insulation Breach 1
				Other 0



VDD Single Pass Pacing Leads continued

Lead Survival Summary (95% Confidence Interval)

ā		US Market Release	Leads Enrolled	Active in Study	Qualifying Complications	Cumulative Months of Follow-Up in Study		Survival fter Impl		ity (%)						
Model Number	Family	US Mai	Leads	Leads	Qualif Compl	Cumul of Foll	1 yr	2 yr	3 yr	4 yr	5 yr	6 yr	7 yr	8 yr	9 yr	10 yr
5032	CapSure VDD	Mar-96	38	0	1	1,683	100.0 at 0 mo									
5038	CapSure VDD-2	Sep-98	553	48	6	20,562	99.8 +0.2/-1.4	99.8 +0.2/-1.4	99.8 +0.2/-1.4	98.8 +0.8/-2.8	98.1 +1.2/-3.3	98.1 +1.2/-3.3	95.1 +3.0/-7.4 at 81 mo			

Source: System Longevity Study Data as of January 31, 2012

US Returned Product Analysis Summary

Model Number	Family	US Market Release	Estimated US Implants	Estimated US Active	Conductor Fracture	Crimp/Weld/ Bond	Insulation Breach	Other
5032	CapSure VDD	Mar-96	5,400	1,300	7	0	7	0
5038	CapSure VDD-2	Sep-98	8,900	3,500	4	0	1	0

Source: Returned Product Analysis Data as of January 31, 2012

US Reports of Acute Lead Observations

Model Number	Family	Estimated US Implants	Lead Dislodgement	Failure to Capture	Failure to Sense	Extracardiac Stimulation
5032	CapSure VDD	5,400	1	3	1	0
5038	CapSure VDD-2	8,900	1	1	0	1

Report Cutoff Date: January 31, 2012

Reference Chart

Model Number	Family	Туре	Insulation	Conductor Material	Tip Electrode	Connector Type
5032	CapSure VDD	Transvenous V and A Tines	Silicone	MP35N 5/6/1 Filars	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI
5038	CapSure VDD-2	Transvenous V and A Tines	Silicone	MP35N	Porous Platinized/ Steroid	Atr. IS-1 BI, Vent. IS-1 BI

ICD and CRT-D Charge Time Performance

Medtronic continues its commitment to providing updated information on charge time performance.

Introduction

Information on charge time performance of Medtronic products is presented in this section of the CRDM Product Performance Report. Medtronic implemented the collection of charge time data on July 1, 1999. The data are collected via our ongoing active clinical study of long-term system performance called the System Longevity Study. The study protocol requests device data be routinely taken and sent to Medtronic at no more than 6-month intervals.

In our analysis performed for this report, only charge times resulting from full energy charges are considered. To ensure consistent reporting across devices, the charge time reported at implant represents the last charge time available from date of implant. When more than one charge time is available in a 6-month interval, a conservative approach has been adopted whereby only the maximum charge time in each 6-month interval is reported. As charge time is directly proportional to the time elapsed since the last capacitor reformation, charges occurring within 15 days of a previous charge are excluded. This precludes the reporting of overly optimistic results.

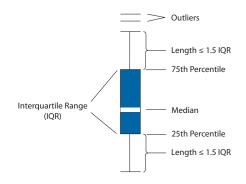
Data from over 20,000 devices contribute to the charge time data in this report. By tracking and reporting this charge time data, Medtronic is able to ascertain the actual performance of its charging circuitry. The insight gained through this information is applied to Medtronic's ongoing efforts to provide charge times that are short and consistent over the life of the product.

Data Presentation

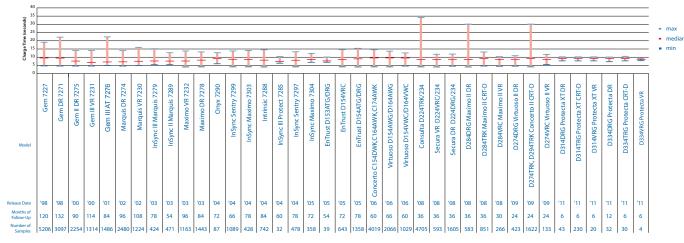
Charge time data for ICD and CRT-D models are presented using boxplots at 6-month intervals. The shaded box on the plots represents the middle half of the data – the Interquartile Range (IQR). The white line in the middle of each box is the median charge time. The top of the box representing the IQR is the third quartile or the 75th percentile (i.e., 75% of all charge times fall below this line), whereas the bottom of the box represents the first quartile or the 25th percentile. Vertical lines are drawn from the quartiles to the farthest value not more than 1.5 times the interquartile range. Any values more extreme than the vertical lines are considered outliers.

Results

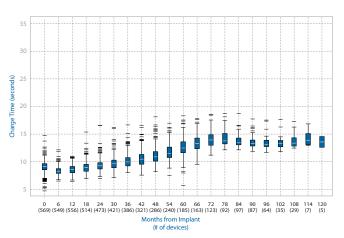
The graph below shows the overall maximums, minimums, and medians for Medtronic ICD and CRT-D products, beginning with the 7221 Micro Jewel.



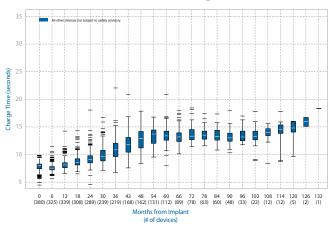




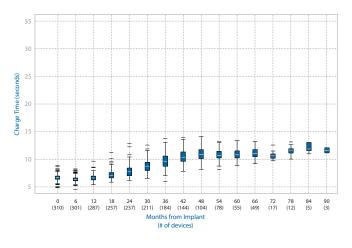
7227 **GEM** Charge Time



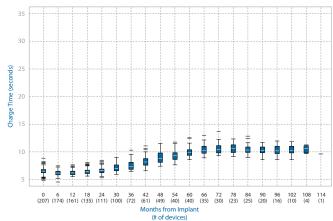
7271 GEM DR Charge Time



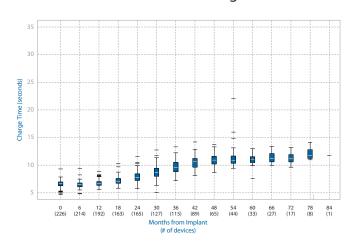
7275 GEM III DR Charge Time



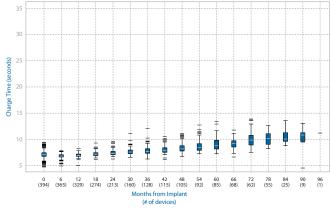
7231 GEM III VR Charge Time



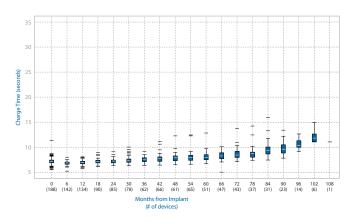
7276 GEM III AT Charge Time



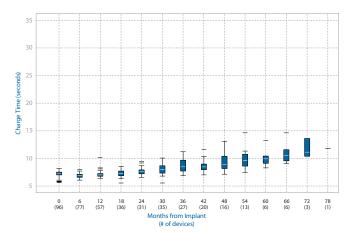
7274 Marquis DR Charge Time



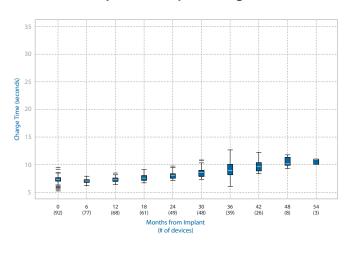
7230 Marquis VR Charge Time



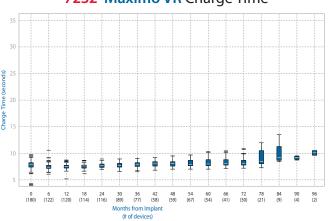
7279 InSync III Marquis Charge Time



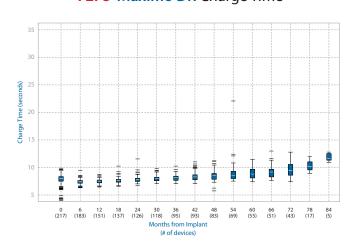
7289 InSync II Marquis Charge Time



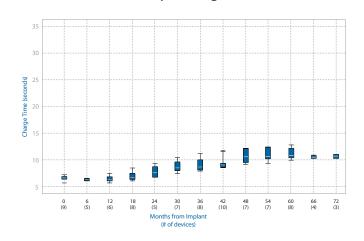
7232 Maximo VR Charge Time



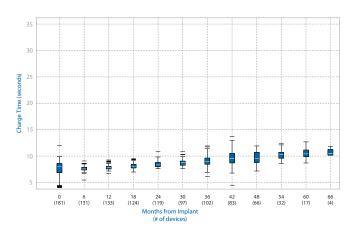
7278 Maximo DR Charge Time



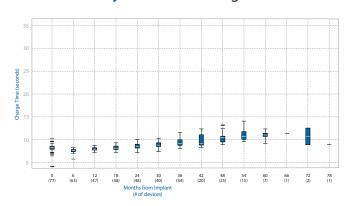
7290 Onyx Charge Time



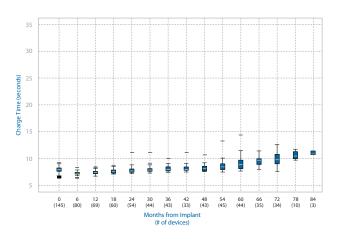
7299 InSync Sentry Charge Time



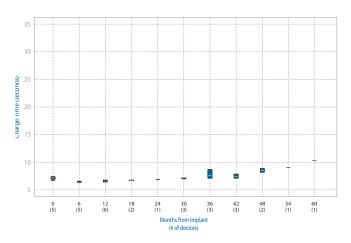
7303 InSync Maximo Charge Time



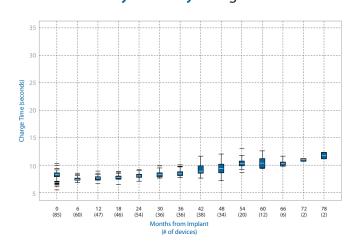
7288 Intrinsic Charge Time



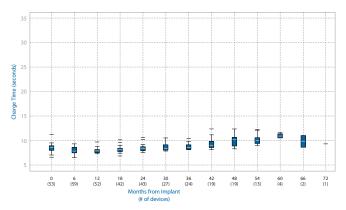
7285 InSync III Protect Charge Time



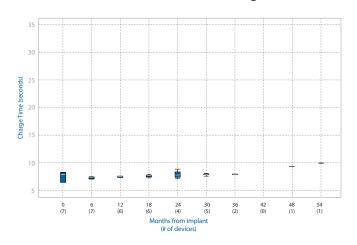
7297 InSync Sentry Charge Time



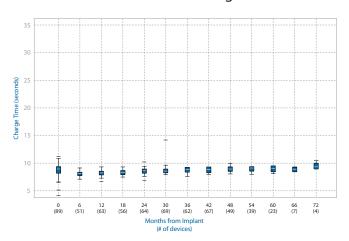
7304 InSync Maximo Charge Time



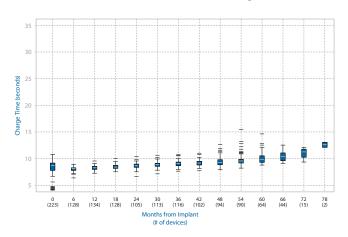
D153ATG, DRG EnTrust Charge Time



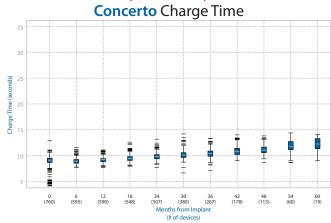
D154VRC EnTrust Charge Time



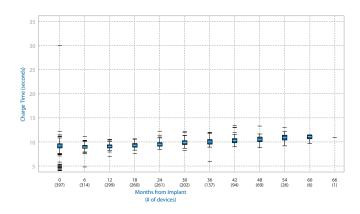
D154ATG, DRG EnTrust Charge Time



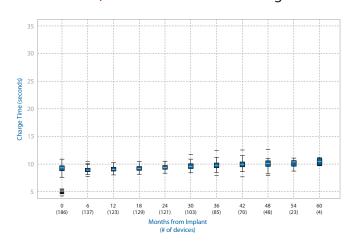
C154DWK, C164AWK, C174AWK



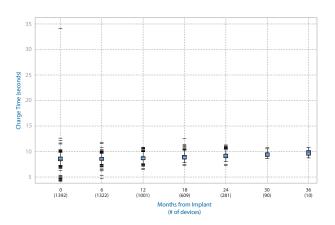
D154AWG, D164AWG Virtuoso Charge Time



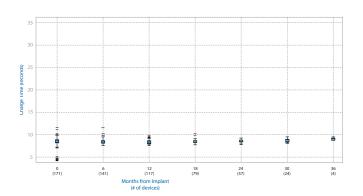
D154VWC, D164VWC Virtuoso Charge Time



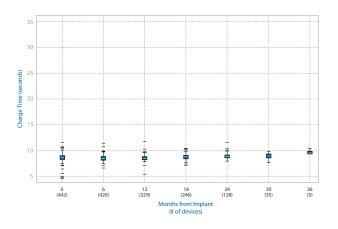
D224TRK/234 Consulta Charge Time



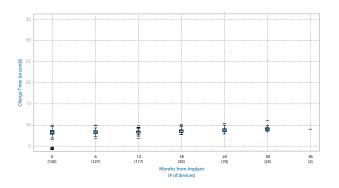
D224VRC/234 Secura VR Charge Time



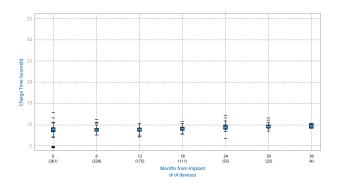
D224DRG/234 Secura DR Charge Time



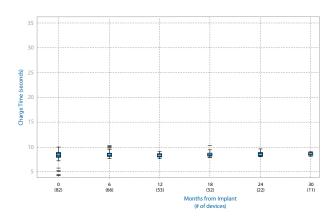
D284DRG Maximo II DR Charge Time



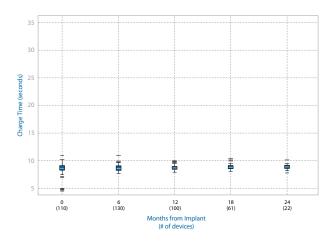
D284TRK Maximo II CRT-D Charge Time



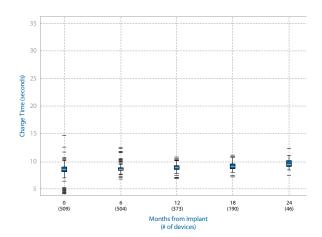
D284VRC Maximo II VR Charge Time



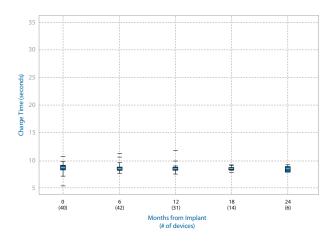
D274DRG Virtuoso II DR Charge Time



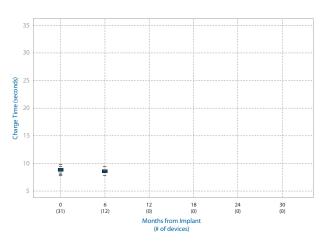
D274TRK, D294TRK Concerto II CRT-D Charge Time



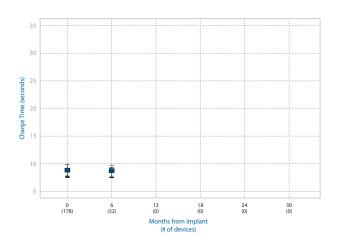
D274VRC Virtuoso II VR Charge Time



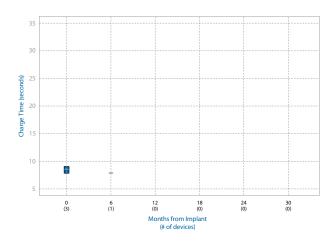
XT DR D314DRG Protecta Charge Time



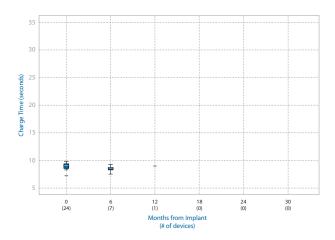
XT CRT-D D314TRG Protecta Charge Time



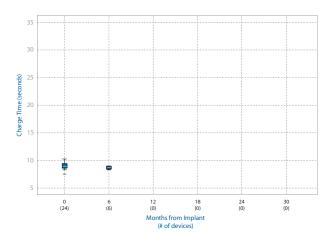
D334VRG Protecta VR Charge Time



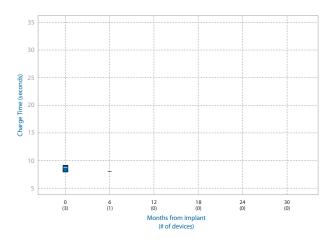
DR D334DRG Protecta Charge Time



CRT-D D334TRG Protecta Charge Time



VR D334VRG Protecta Charge Time



Advisories

EnTrust ICDs

Original Date of Advisory: March 2012

Potential Rapid Battery Depletion

Product

All EnTrust ICDs.

Advisory

A small percentage of EnTrust ICDs may not meet expected longevity or provide at least three months of device operation between the Elective Replacement Indicator (ERI) and End of Life (EOL) due to a morerapid-than-expected drop in battery voltage. An estimated 39,000 EnTrust ICDs are currently implanted worldwide. No patient deaths or serious injuries have been reported as a result of this issue.

The reported events have involved a drop in battery voltage from ~3.0 V to ERI (2.61 V) over a time period ranging from approximately one week to six months. All reported events have occurred at least 30 months after implant.

Medtronic has identified the cause of these occurrences to be an internal battery short that develops as the battery capacity is consumed. The exact sequence of events and use conditions that lead to the battery short is still being investigated.

Patient Management Recommendations (As of March 2012)

After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following patient management recommendations:

- Physicians should continue routine follow-up sessions at least every three months in accordance with product labeling.
- Physicians should program the audible patient alerts for "Low Battery Voltage ERI" and "Excessive Charge Time EOL" to ON.
- Physicians should replace devices promptly after they reach ERI if the decline in voltage is more rapid than expected.
- Prophylactic replacement of EnTrust ICDs is not recommended.

Status Update

As of February 20, 2012, there have been 60 confirmed events. No patient deaths or serious injuries have been reported. No reports have been made of a failure to deliver high voltage therapy.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)
69,000 Worldwide (42,600 United States)	60 Worldwide (44 United States)	39,000 Worldwide (23,100 United States)	0.09% Worldwide (0.10% United States)

EnRhythm Pacemakers

Original Date of Advisory: February 2010

Low Battery Voltage Displayed at Device Interrogation

Product

All EnRhythm pacemakers.

Advisory

Two specific battery issues with EnRhythm pacemakers have been identified and both are addressed by a Medtronic software update.

First Issue

As of February 2010, Medtronic had received 62 reports (out of approximately 110,000 devices worldwide) indicating that the battery voltage at device interrogation was lower than the battery voltage that is tracked by the device to provide data for the elective replacement indicator (ERI) notification. The lower voltage measurement caused confusion and occasionally resulted in unnecessary explants.

Medtronic's investigation has shown that none of these reports resulted in loss of therapy. Importantly, the ERI notification, which uses the nightly battery measurement, is unaffected and accurate. Medtronic has identified the root cause as higher than expected battery resistance.

Medtronic's internal testing has shown that there is no current risk for compromised therapy delivery. If the software update referenced above is not implemented, there will be a potential risk of loss of device functionality in a small percent (less than 0.08% 6 years post-implant) of devices. The software update eliminates this risk.

Second Issue

Through internal accelerated testing, Medtronic has identified a second issue that projects battery voltage could decrease sooner than expected due to a slightly increased rate of lithium depletion. This issue has not been clinically observed and is not expected to occur until approximately 9 years post-implant. If the software update referenced above is not implemented, there may be a potential risk for loss of therapy at or near ERI in a small number of devices. The software will eliminate this issue by changing ERI criteria.

Software Update (As of October 2010)

The battery issues described above and subsequent software update are summarized in the table below. When a device receives the software update, if battery impedance is greater than the new ERI threshold ERI will be triggered shortly thereafter. Therefore, clinicians may observe an ERI/EOL indicator at the next patient follow-up. When ERI is triggered by battery impedance, additional battery capacity remains and can support device function at ERI parameters for at least one

year. Medtronic is not aware of any reports of loss of therapy due to this issue.

As a reminder, when ERI is triggered, EnRhythm devices revert to VVI pacing at 65 ppm at the programmed output settings. EOL is declared 90 days after ERI or at a battery voltage of 2.69 V, whichever comes sooner.

Battery Issue	Software Update	
Battery voltage could decrease sooner than expected due to a slightly increased rate of lithium depletion	Changed ERI battery voltage threshold from 2.59 V to 2.81 V to ensure 90 days of therapy from ERI to EOL	
Higher than expected battery impedance	Added a secondary ERI trigger based on battery impedance. This new criteria will identify devices with increased battery impedance before device performance is impacted.	
	If triggered, displayed battery voltage is reset to 2.81 V to ensure alignment with ERI battery voltage threshold	

Updated Performance Information (as of August 2011)

We now have access to battery impedance and ERI performance on more than 5,000 EnRhythm devices that have received the EnRhythm software update. Our modeling based on these data shows that approximately 6-10% of devices will reach ERI within 5 years post-implant. Consistent with our previous communications, we continue to expect average device longevity to be reduced by approximately 10-15%, with the expected average longevity remaining at 8.5 to 10.5 years, depending on device settings.1

Updated Patient Management Recommendations (as of August 2011)

After consultation with Medtronic's Independent Physician Quality Panel, we recommend:

Performing a device follow-up within 90 days after the software download to identify devices that triggered ERI shortly after the software update. Subsequent follow-up can be performed per standard practice. During programmer interrogation of a device at ERI, there is a slight possibility a transient drop in pacing amplitude could occur. If this is noted, either remove the programmer head or temporarily program to a higher output voltage.

continued



EnRhythm Pacemakers

Original Date of Advisory: February 2010

Low Battery Voltage Displayed at Device Interrogation, continued

If an unanticipated ERI/EOL is declared, it is likely due to battery impedance. In such cases, additional battery capacity remains and can support device function at ERI parameters for at least one year. However, when ERI or EOL (typically 90 days after ERI) declaration is seen, schedule device replacement.

Status Update

As of February 24, 2012, 342 devices out of approximately 146,500 devices worldwide have been confirmed as having exhibited an advisory event related to the original advisory, in which higher than expected battery impedance caused a drop in battery voltage at interrogation. Approximately 103,000 remain implanted.

Included in the August 2011 Performance Update was information about the projected percentage of devices that would encounter an early ERI due to unexpected high battery impedance. As of January 2012, analysis of over 16,000 US CareLink patients whose devices reached ERI continues to occur with the rate of 6-10% within 5 years post-implant as communicated with our August 2011 Performance Update.

 $^{\rm 1}$ The 8.5 year estimate represents a high use scenario (DDD, 100% pacing in atrium and ventricle with 3.0 V output in both chambers). The 10.5 year estimate represents a typical use scenario for a sinus node dysfunction patient with the MVP function ON (AAI(R) <=> DDD(R), 50% pacing in atrium and 5% pacing in ventricle with 3.0 V output in both chambers). Projections are based on modeling and not actual field returns, due to limited availability of implant experience beyond 6 years. Field performance will continue to be monitored and modeling updated to reflect actual data.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	· ·	The software update eliminates any potential future risk of the two battery issues described above by changing the ERI criteria.
All EnRhythm pacemakers (146,500 Worldwide)	342 Worldwide	103,000 Worldwide	0.23%	



Concerto CRT-D and Virtuoso ICD

Original Date of Advisory: September 2009

Potential Reduced Device Longevity

Product

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity. Go to www.medtronic. com/CRDMProductPerformance to determine if a specific device is affected.

Advisory

A subset of Concerto CRT-D and Virtuoso ICD devices may not meet expected device longevity due to gradually increasing current drain caused by low voltage capacitor degradation. This issue may present in the affected devices as reaching the Recommended Replacement Time (RRT) earlier than projected. This issue does not compromise device functionality or affect therapy delivery.

Based on information from returned devices, Medtronic expects that affected devices will continue to provide at least 3 months of normal device function between RRT and End of Service (EOS) as described in device labeling.

A total of 8,900 devices worldwide are affected by this advisory. An estimated 6,300 of these devices were active at the time of the original advisory communication.

Concerto and Virtuoso devices in the affected subset were manufactured primarily in 2006 and can be traced to a specific subset of low voltage capacitors.

Patient Management Recommendations

After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients with devices in the affected subset:

Physicians should continue routine follow-up sessions at least every 3 months in accordance with product labeling.

Physicians should verify that the Low Battery Voltage RRT alert is programmed to "On-High." This provides an audible, alternating tone when the device reaches RRT. These devices are shipped with this alert programmed nominally to "On-High."

Physicians may consider monitoring patients through CareLink. The CareLink home monitor can be used to automatically notify the clinician when the device reaches RRT.

Status Update

As of February 27, 2012, 3,668 devices out of approximately 8,900 devices in this subset worldwide have been confirmed as having exhibited this capacitor degradation. Out of the initial advisory population of 8,900 worldwide, approximately 800 remain implanted. Approximately 600 of these are in the United States.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)
8,900 Implanted Worldwide (7,000 United States)	3,668 Worldwide (3,154 United States)	800 Worldwide (600 United States)	41% Worldwide (45% United States)

Advisories continued

Kappa 600/700/900 Pacemakers Sigma 100/200/300 Pacemakers

Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires (2009)

Product

A specific subset of Kappa and Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Go to www.medtronic.com/CRDMProductPerformance to determine if a specific device is affected.

Advisory Population

Specific subsets of Kappa and Sigma series pacemakers may fail at a higher than expected rate due to separation of wires that connect the electronic circuit to other pacemaker components (e.g., battery, connector). This may present clinically as loss of rate response, premature battery depletion, loss of telemetry, or no output.

Some patients, whose devices experience a wire separation resulting in a loss of pacing output, will experience a return of bradycardia symptoms (e.g., fainting or lightheadedness). In rare cases involving pacemaker dependent patients, loss of pacing output may result in death or serious injury.

Since 1997, there have been over 1.7 million Kappa and Sigma devices implanted worldwide. At the time of the original advisory communication, an estimated 15,200 Kappa and 6,100 Sigma devices affected by the advisory remained implanted and active. These devices were manufactured primarily between November 2000 and November 2002. Most of these devices have been implanted in patients for five years or longer and may be nearing normal elective replacement time.

There is no provocative testing that can predict which specific devices may fail, and no device programming can mitigate this issue if it occurs.

Patient Management Recommendations

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients:

- Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).
- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Advisory Population

Patient management recommendations remain unchanged. As of February 27, 2012, Medtronic has observed 458 Kappa devices and 281 Sigma devices with this failure mechanism from the Kappa and new Sigma device subsets. This represents 0.79% (Kappa) and 1.89% (Sigma) of the original affected implant population.

Four hundred twenty-one (421) of the Kappa devices (0.72%) and 218 of the Sigma devices (1.46%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 37 Kappa devices (0.06%) and 63 Sigma devices (0.42%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

As of May 2009, our modeling predicts failure rates due to this issue of 1.1% (Kappa) and 4.8% (Sigma) over the remaining lifetime of those pacemakers still in service at that time.

Out of the initial advisory population of 58,300 Kappa devices and 14,900 Sigma devices worldwide, approximately 3,600 Kappa devices and 2,800 Sigma devices remain implanted. Of these, approximately 1,100 Kappa and 700 Sigma devices are in the United States.

Continued Vigilance

Included in the advisory communication was information about an additional subset of Kappa devices where we have observed a much lower rate of occurrence of this issue. Approximately 16,000 devices of this subset remain active. We have observed a failure rate of approximately 0.094% in this subset and our May 2009 modeling predicts a failure rate of 0.12% over the remaining device life of those pacemakers still in service at that time. After review with our Independent Physician Quality Panel, we do not recommend any specific actions for this group of devices. We will continue to monitor performance and inform you if any specific patient management recommendations are warranted.

continued



Kappa 600/700/900 Pacemakers

Sigma 100/200/300 Pacemakers Original Date of Advisory: May 2009

Potential Separation of Interconnect Wires, continued

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
Kappa Pacemakers				
58,300 Implanted Worldwide (est.) (17,600 United States)	421 Worldwide (221 United States) with information indicating a clinical presentation. An additional 37 worldwide (25 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	3,600 Worldwide (1,100 United States)	0.79% Worldwide 1.40% (United States)	1.1%
Sigma Pacemakers				
14,900 Implanted Worldwide (est.) (3,700 United States)	218 Worldwide (43 United States) with information indicating a clinical presentation. An additional 63 worldwide (15 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	2,800 Worldwide (700 United States)	1.89% Worldwide 1.57% (United States)	4.8%

Advisories continued

6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture

Product

All Model 6930, 6931, 6948, and 6949 implantable defibrillation leads

Advisory

There are two primary locations where chronic conductor fractures have occurred on Sprint Fidelis leads: 1) the distal portion of the lead, affecting the anode (ring electrode) and 2) near the anchoring sleeve tie-down, predominantly affecting the cathode (helix tip electrode), and occasionally the high voltage conductor. These two locations account for approximately 90% of the chronic fractures identified in Returned Product Analysis (RPA). The remaining 10% of chronic fractures occurred in the DF-1 connector leg and the proximal portion of the RV coil. High voltage conductor fractures could result in the inability to deliver defibrillation therapy. Anode or cathode conductor fractures (at either location) may present clinically as increased impedance, oversensing, increased interval counts, multiple inappropriate shocks, and/or loss of pacing output.

Patient Management Recommendations (Updated April 2011)

The Lead Integrity Alert (LIA) provides three days advance notice prior to inappropriate therapy to 76% of patients with lead fractures.1 As a result, we strongly recommend that all Sprint Fidelis patients who have the ability to upgrade to Lead Integrity Alert do so promptly. Also ensure that high voltage lead impedance alerts (maximum of 100 ohms) are programmed. When a lead fracture is suspected or confirmed, immediate patient attention is strongly recommended. Physicians should inform their patients to seek medical attention without delay if they experience unexpected shocks

- · If a Fidelis lead fracture of any type has occurred, we recommend implanting a new high voltage lead with or without extraction of the Fidelis lead.
- In patients with normal device function and no manifestation of lead fracture, no action is recommended. The risk of prophylactic intervention appears to be greater than serious injury resulting from lead fracture even for pacemaker dependent patients, except in select individual patient circumstances as determined by the physician.
- In the event of a device change-out or upgrade procedure, with no manifestation of lead fracture, consider the patient age and lead model data above, as well as patient life expectancy, co-morbidities, ease of extraction related to implant time, patient preference, etc., for the following options:
 - Leave a properly performing lead intact.
 - Implant a new ICD lead without extraction of the existing lead.

- Carefully consider all factors before prophylactic placement of a pace-sense lead. Data shows an increased risk of high voltage conductor fracture if a pace-sense conductor fracture has previously occurred. This data is available at www.medtronic.com/fidelis
- Individual patient circumstances may warrant extracting and implanting a new ICD lead. If warranted, Medtronic's Independent Physician Quality Panel recommends the lead extraction procedure be performed by a physician with extensive lead extraction experience.2

Status Update

As of February 1, 2012, of the initial implant population of 205,600 in the United States, approximately 100,400 remain implanted. According to System Longevity Study results, lead survival is estimated to be 88.6% (+3.3/-4.5) at 69 months. As the implanted population ages and the sample size increases for each time interval, the accuracy of the estimated survival probability will increase as shown by tighter confidence intervals.

- ¹ Swerdlow C, Gunderson B, Ousdigian K, et al. Downloadable Algorithm to Reduce Inappropriate Shocks Caused by Fractures of Implantable Cardioverter-Defibrillator Leads, Circulation. November 2008; 118:2122-2129.
- ² Wilkoff B, Love C, Byrd C, et al. Transvenous Lead Extraction: Heart Rhythm Society Expert Consensus on Facilities, Training, Indications, and Patient Management. Heart Rhythm. July 2009;6:1085-1104.

continued



6930, 6931, 6948, 6949 Sprint Fidelis Defibrillation Leads

Original Date of Advisory: October 2007

Potential Conductor Wire Fracture, continued

Keeping Physicians Informed

The most recent Sprint Fidelis lead performance information, including survival curves, physician letters, and subpopulation data, $% \left(1\right) =\left(1\right) \left(1$ can be found at www.medtronic.com/fidelis and will be updated $\,$ semi-annually. Medtronic's website also has a selected list of peerreviewed publications related to Fidelis lead performance and extraction. Medtronic is committed to answering your questions and keeping you informed. If you have any questions or concerns, please contact your Medtronic Representative or Medtronic Technical Services at 1 (800) 723-4636 (US).

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Additional information about the Sprint Fidelis lead is available at: www.medtronic.com/fidelis.
205,600 (United States)	5,355 (United States)	100,400 (United States)	



Sigma Implantable Pulse Generators

Original Date of Advisory: November 2005

Potential Separation of Interconnect Wires (2005)

Product

A specific subset of Sigma series pacemakers may fail due to separation of interconnect wires from the hybrid circuit. Go to www.medtronic.com/CRDMProductPerformance to determine if a specific device is affected.

Advisory

This subset of Sigma series pacemakers that may fail due to separation of interconnect wires from the hybrid circuit may present clinically as loss of rate response, premature battery depletion, intermittent or total loss of telemetry, or no output.

Separation of redundant interconnect wires has been observed on hybrid terminal blocks. Device failure occurs only where both interconnect wires separate from a hybrid terminal block. In October 2005, testing and analysis identified the root cause of these failures and the affected population. Hybrid circuits used in this subset of devices were cleaned during manufacturing with a particular cleaning solvent that could potentially reduce the strength of the interconnect wire bond over time.

No provocative testing can predict which devices may fail.

Patient Management Recommendations

Recommendation for the management of patients who have pacemakers affected by this advisory were changed in May 2009. Current recommendations are:

We realize that each patient requires unique clinical consideration and we support your judgment in caring for your patients. After consultation with Medtronic's Independent Physician Quality Panel, Medtronic offers the following recommendations for patients in the 2005 Sigma advisory:

- Physicians should advise their patients to seek medical attention immediately if they experience symptoms (e.g., fainting or lightheadedness).
- Physicians should consider device replacement for patients who are both pacemaker dependent and who have been implanted with a device in the affected subsets. Medtronic will offer a supplemental device warranty if the device is not already at elective replacement time.
- Physicians should continue routine follow-up in accordance with standard practice for those patients who are not pacemaker dependent.

Status Update

Patient management recommendations remain unchanged. As of February 27, 2012, 731 devices out of approximately 40,000 devices worldwide have been confirmed as having experienced interconnect wire separation.

Three hundred seventy-four (374) of the Sigma devices (0.94%) were returned with information indicating a problem with the patient's pacing system prior to explant. The remaining 357 Sigma devices (0.89%) were returned with no information indicating a potential malfunction while implanted or with insufficient information to determine the state of the device at explant. Lacking definite information indicating proper operation until explant, these remaining devices are conservatively categorized as having experienced interconnect wire separation while implanted.

Our original modeling predicted a failure rate from 0.17% to 0.30% over the remaining lifetime of these pacemakers. However, as of May 2009 updated updated modeling now predicts a failure rate of 3.9% over the remaining device life of those devices still in service at that time.

Out of the initial advisory population of 40,000 worldwide, approximately 7,700 remain implanted. Approximately 1,900 of these are in the United States.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still in Service as of May 2009
40,000 Implanted Worldwide (est.) (9,900 United States)	374 Worldwide (74 United States) with information indicating a clinical presentation.An additional 357 Worldwide (63 US) without information indicating a clinical presentation or with insufficient information to determine the state of the device at explant.	7,700 Worldwide (1,900 United States)	1.83% Worldwide 1.38% (United States)	3.9%

7274 Marquis DR 7230 Marquis VR 7278 Maximo DR 7232 Maximo VR

7277 InSync Marquis **7289** InSync II Marquis 7279 InSync III Marquis 7285 InSync III Protect

Original Date of Advisory: February 2005

Potential Premature Battery Depletion Due to Battery Short

Product

The specific subset of Marquis family ICD and CRT-D devices having batteries manufactured prior to December 2003 is affected. Devices manufactured with batteries produced after December 2003 are not affected. Go to www.medtronic.com/CRDMProductPerformance to determine if a specific device is affected.

Advisory

Medtronic Marquis family of ICD and CRT-D devices having batteries manufactured prior to December 2003 may experience rapid battery depletion due to a specific internal battery short mechanism. Battery design changes were implemented in December 2003 that eliminate the possibility of this internal shorting mechanism.

Highly accelerated bench testing indicated the rate of this shorting mechanism may increase as the battery is depleted. As of February 2005, the rate of shorting was approximately 1 in 10,000 (0.01%); bench test data indicated the rate may increase to between 0.2% and 1.5% over the second half of device life.

No provocative testing can predict which of these devices will experience this issue. Once a short occurs, battery depletion can take place within a few hours to a few days. After depletion the device ceases to function. It is also possible that as the battery depletes quickly, patients may experience temporary warmth in the area surrounding the ICD.

Patient Management Recommendations

We recommend you consider the following patient management options:

 Conduct quarterly (i.e., every 3 months) follow-up procedures

- Inform patients that should they experience warmth in the area surrounding the ICD to seek follow-up care promptly
- Program Low Battery Voltage ERI Patient Alert to "On-High." This will result in an audible, alternating tone in the limited circumstances where a battery depletes slowly over a number of days. Data indicates most shorts will occur rapidly and will not be detected by this feature.
- Provide a hand-held magnet to patients to check device status and program the Low Battery Voltage ERI Patient Alert to "On-High." Device operation may be monitored periodically (e.g., daily) by patients placing the magnet over the device for 1-2 seconds. If the device is functional, a steady tone will sound for approximately 20 seconds. If no tone is heard, follow-up care should be sought promptly.

Status Update

The Marquis Family device performance related to the battery shorting mechanism continues to be within Medtronic's engineering projections. As of February 27, 2012, 192 Marquis Family devices have been confirmed as having this internal battery shorting mechanism. One hundred fifteen (115) of these devices were returned from the United States.

Out of the initial advisory population of 87,000 worldwide, approximately 8,000 remain implanted. Approximately 7,000 of these are in the United States.

The Patient Management Recommendations set forth in the advisory remain unchanged.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
87,000 Implanted Worldwide (76,000 United States)	192 Worldwide (115 United States)	8,000 Worldwide (7,000 United States)	0.22% Worldwide (0.15% United States)	Consistent with Medtronic projections, the observed rate of shorting may increase to between 0.2% and 1.5% over the second half of device life.



Kappa 600, 700 Dual Chamber (D, DR, and VDD) IPGs

Original Date of Advisory: March 15, 2002

Potential Fractured Power Supply Wires

Product

A specific subset of Kappa 700/600 dual chamber (D, DR, and VDD) implantable pulse generators has been identified by serial numbers. Hospitals and Physicians were notified. Go to www.medtronic.com/ <u>CRDMProductPerformance</u> to determine if a specific device is affected.

Advisory

As of March 15, 2002, Medtronic observed 53 related failures (0.02%) in over 255,000 Kappa 700/600 dual chamber (D, DR, and VDD) series devices sold worldwide. Medtronic voluntarily communicated this information to physicians because these failures had been observed in patients having submuscular implants.

These devices have presented with an electrical reset, intermittent output, or no output. Our investigation identified the root cause as fractured wires supplying power to the pacemaker. This has been directly correlated to submuscular placement of these devices. Submuscular implant locations (e.g., subpectoral, abdominal, etc.) can result in additional stress and repetitive flexing on the implanted device causing excessive fatigue on these wires. Of the estimated 4,000 devices implanted submuscular, approximately 200 (5%) may experience this failure. These stresses on the implanted device are unique to submuscular implant sites and do not exist with subcutaneous implants.

Patient Management Recommendations

While there is no provocative testing or time dependency that will predict which submuscular placed device will fail, certain electrical resets may be an indicator that a wire fracture has occurred. Normal electrical resets can occur as a result of electrosurgical procedures such as cautery and ablation or from defibrillation therapy. If none of the normal causes of electrical reset can be confirmed, or if a device serial number presents as "000000" following an electrical reset, this may be an indicator of a wire fracture.

For patients who have submuscular implants of devices within the designated serial number range and who are pacemaker dependent with no underlying rhythm, replacement of the device should be considered. Medtronic will provide the replacement device free of charge under the terms of its warranty program if a device is replaced in these patients.

For patients having subcutaneous implants, no change to your current patient care and follow-up is advised.

Status Update

Patient management recommendations remain unchanged. As of February 27, 2012, 337 out of approximately 180,000 distributed (0.18% incidence) Kappa family devices worldwide have been confirmed as having fractured power supply wires. One hundred seventy (170) of these devices were returned from the United States. Out of the initial implant population of 121,000 in the United States, less than 500 remain implanted.

Initial Affected Population	Number of Confirmed Advisory Related Events	Estimated Remaining Active Population	Current Malfunction Rate (Confirmed Malfunctions over total population)	Predicted Malfunction Rate Over the Remaining Life of the Devices Still Implanted Population
180,000 Active Worldwide at time of advisory (121,000 United States)	337 Worldwide (170 United States)	< 500 Worldwide (< 500 United States)	0.19% Worldwide (0.14% United States)	0.03%



Minix and Minix ST IPGs

Original Date of Advisory: May 6, 1991

Potential Delayed Restoration of Permanent Settings

Product

All Models of the Minix and Minix ST families of implantable pulse generators

Advisory

Possibility of delayed restoration of permanent pacing mode and parameters, after the magnet or programming head is removed under certain conditions.

Patient Management Recommendations

To eliminate any potential risk associated with temporary programming, depress the INTERROGATE key and verify successful interrogation before moving the programming head away from the pulse generator. The delay condition can also be terminated by repositioning the programming head and depressing the EMERGENCY VVI key.

Status Update

Device performance related to this advisory continues to be within Medtronic's engineering projections. Patient management recommendations remain unchanged. Out of the initial implant population of 65,000 in the United States, approximately 2,000 remain implanted. The devices affected by this advisory are nearing the end of their expected longevity.

Initial Affected Population	Active Population programming, depress the INTERROGA successful interrogation before moving	To eliminate any potential risk associated with temporary programming, depress the INTERROGATE key and verify successful interrogation before moving the programming head
All Minix and Minix ST implantable pulse generators	2,000	away from the pulse generator.

Performance Notes

Dual Chamber Pacemakers with Measurement Lock-up ERI Kappa 600, 700, 800, 900, EnPulse, Adapta, Versa, Sensia, Relia, and Vitatron Models E50A1, E60A1, and G70A1

Purpose of this Information

This Performance Note describes a rare measurement lock-up issue that impacts the Medtronic dual chamber pacemakers listed above. If this measurement lock-up occurs, the device will trigger a false Elective Replacement Indicator (ERI). A reset is available to clear this condition and there is no need to explant the device. This issue does not impact battery longevity.

Background

If this rare measurement lock-up occurs in the pacemaker, it causes the device to read a value of zero for battery voltage. After four measurements of zero, the device will trigger ERI and revert to a VVI pacing mode at 65 bpm. There is no loss of ventricular pacing and the output voltage will remain the same.

Programmer Software Reset Method (Adapta, Versa, Sensia, Relia, Vitatron Series E and G)

Programmer software is available which can differentiate a regular ERI and an ERI caused by the measurement lock-up issue. Upon interrogation of a device with the measurement

Example 1 – Programmer Software Detects Measurement Lock-up ERI



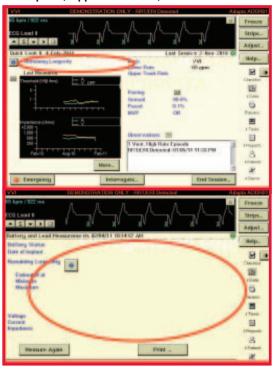
lock-up ERI, the programmer software recognizes the issue and guides the clinician to clear the ERI (Example 1). Following an ERI reset, the device parameters should be reviewed and reprogrammed to clinician specifications.

Reset Method for Kappa and EnPulse

A service tool continues to be available through Medtronic Technical Services to clear the measurement lock-up issue for Kappa and EnPulse devices.

The issue can be identified using the programmer or via CareLink transmission; the battery voltage measurements and remaining longevity will appear as blank values (Example 2). If this measurement lock-up occurs, contact Medtronic Brady Technical Services at 1-800-505-4636 for assistance.

Example 2 – Programmer Screens for Measurement Lock-up ERI (Kappa and EnPulse)



Helix Retraction of the Sprint Quattro Secure S 6935 and **Sprint Quattro Secure 6947**

Purpose of this Information

This performance note is intended to provide guidance regarding retraction of the helix of Sprint Quattro Model 6935 or 6947 leads.

Background

In certain cases, over-retraction of the helix, during initial implant or subsequent repositioning, may result in the inability to extend the helix. This does not impact acute or chronic performance of successfully implanted leads.

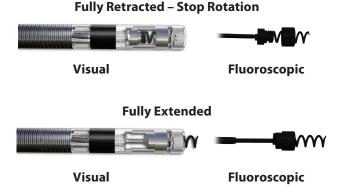
The root cause is over-retraction of the helix mechanism beyond the retraction stop, resulting in the inability to extend the helix in a subsequent attempt.

Recommendations

Consistent with the Technical Manual, the following steps can be used to mitigate this issue.

- Fluoroscopy should be used to confirm when the helix is fully retracted.
- Rotation of fixation tool should be stopped once full helix retraction is visually verified.
- If helix is unable to extend, replace with a new lead and report the issue to Medtronic.

Retraction Stop



Potential Malfunction of CRT, ICD, and IPG Products due to Anomalies in MOSFET Integrated Circuit Technology

Medtronic has detected a specific pattern of MOSFET IC malfunctions in its Concerto, Virtuoso and EnRhythm family of devices. As of July 2009, Medtronic has confirmed twenty-eight (28) malfunctions related to this pattern out of 115,000 EnRhythm and 233,000 Concerto/Virtuoso products distributed worldwide. Reliability analysis of this pattern shows the probability of occurrence decreases with time and over 90% of the malfunctions related to the pattern had occurred within the first twelve months after implant. With process improvements in place, Medtronic expects few additional malfunctions related to this pattern.

The pattern involves metal-oxide-semiconductor field-effect transistors (MOSFET). A MOSFET is an electronic circuit used to amplify or switch electronic signals. MOSFETs have been used in the electronics industries for decades and MOSFET technology is the most widely used type of integrated circuit. Medtronic uses this technology in the circuitry of its CRT, ICD, and IPG products. Each product contains thousands of MOSFETs in its electronic circuitry.

Each MOSFET depends on a layer of insulating material to electrically isolate its components. The integrity of this insulating layer is important to the operation of the MOSFET. Variation in the thickness of the insulating layer can cause the MOSFET to operate in an undesirable manner. Process variations for electronic circuits can affect the integrity of the insulating material, and can lead to MOSFET malfunction. Medtronic's quality system strives to control process variation and detect undesired anomalies that are characteristic of all MOSFET manufacturing. In addition, Medtronic's post-market vigilance activities monitor malfunctions and may implement screening and testing improvements when a pattern of related malfunctions is identified.

The pattern with the Concerto, Virtuoso and EnRhythm models has presented clinically as high lead impedance, sensing difficulty, loss of pacing therapy and/or early battery depletion due to higher than normal battery drain. The degree of battery drain varies case by case, such that the time from the onset to battery depletion has ranged from several days to several months. If not detected by normal patient follow-up procedures, the use of patient alerts or CareLink remote monitoring, the battery will fully deplete, leaving the patient without therapy.

As of March 2009, Medtronic has implemented additional electrical screening and stress tests to address this specific pattern for products being sold.

Since these rates of malfunction are low and the probability of occurrence decreases with time, Medtronic recommends physicians continue following patients in accordance with standard practice.

Clinical Management of VCM near Elective Replacement

Background

Medtronic Technical Services has received reports of devices going to ERI or end of life (EOL) sooner than expected after a normal follow-up in which the device longevity was projected to be approximately 18 months. It has been noted that these cases typically involve Kappa 700 devices where Ventricular Capture Management set the ventricular lead to high output (5 V, 1 ms), which occurs by device design when a high threshold is measured. It is important for physicians and allied professionals to understand VCM behavior as it relates to longevity so that they can, in turn, understand how this affects management of the device and follow-up visits as VCM equipped IPGs near the end of their expected longevity.

Device Longevity and VCM Behavior

Ventricular Capture Management is a feature that uses evoked response sensing to determine the stimulation threshold needed to capture the ventricular chamber. Proper detection of the evoked response is crucial to the VCM algorithm determining an accurate capture threshold. There are rare conditions, however, during which the VCM algorithm will not be able to measure the evoked response accurately. When this occurs, for safety reasons the VCM algorithm will reprogram the output to 5 V, 1 ms until the subsequent VCM measurement.

If the device has considerable remaining longevity, these occasional excursions to high output do not substantially affect remaining longevity. However, if the device has less than approximately 18 months remaining longevity, there is the possibility that the high output condition caused by the 5 V, 1 ms output will drain the battery and trigger ERI.

When ERI is declared by the device, VCM is disabled and the outputs are left at 5 V, 1 ms until the device is reprogrammed at an in-office follow-up. This increased current drain of a high output condition will speed depletion of the device, possibly resulting in the device getting to the EOL (battery voltage ≤ 2.15 V).

Please note that the following parameter changes occur when the device goes to ERI:

Table: IPG Therapy Parameter Changes at ERI

Parameter	Value
Pacing Mode	VVI
Lower Rate	65 bpm
Single Chamber Hysteresis	OFF
Sleep Function	OFF
Ventricular Capture Management	OFF
Atrial Sensing Assurance	OFF
Ventricular Sensing Assurance	OFF

Kappa 700 is Medtronic's first-generation VCM algorithm, which has a relatively higher incidence of evoked response undersensing compared to subsequent algorithms, resulting in more frequent high output conditions. Therefore, Kappa 700 products are the primary focus of this note. It should be noted that IPGs equipped with the second-generation VCM algorithm (Kappa 900, EnPulse, Adapta/Versa/Sensia, and Relia) have not been observed with evoked response undersensing in the general population, though the items listed in "Follow-Up Considerations" may also be used on these devices.

Follow-Up Considerations

- Estimated longevity in the event the device goes to high output can be determined by the following steps. This allows the clinician to determine follow-up frequency if he or she is concerned the device may go to ERI due to high output.
 - Program the ventricular channel to 5 V, 1 ms
 - Navigate to Data/Battery and Lead Measurements
 - When the message stating "Warning Old Data" is displayed, select "Yes" to measure battery voltage and lead impedance at the new ventricular outputs
 - An updated remaining longevity estimate will be calculated on the elevated outputs. Note the "Minimum Remaining Longevity." Clinical decisions can be based on this value.
 - Program the Amplitude and Pulse Widths back to their original values before leaving the session
- If the capture trends and lead impedance trends are stable, VCM can be programmed to "Monitor Only" for the remaining device life. This should be considered only if remaining longevity is 18 months or less.
- Follow-up frequency can be increased for those patients who do not have stable capture or lead impedance trends. This can be done via a CareLink Home Monitor, or in-office.

¹ Medtronic, Inc. (2001). Medtronic Kappa 700/600 Series Pacemaker Reference Guide (Chapter 4, p. 27). Can be retrieved from http://manuals.medtronic.com

Ensuring the Accuracy of Battery Longevity Estimates

Purpose of This Information

This article is intended to help the clinician understand how Medtronic estimates CRT-D, ICD, and IPG device longevity and Medtronic's performance against these estimates.

Device Longevity and Battery Depletion

The device service life ends when the usable battery capacity is depleted. The time to battery depletion depends on three factors:

- The amount of electrical energy expended in providing therapy to the patient
- The amount of energy consumed by the electronic circuitry to perform the functions of the device (e.g., operating the microprocessor, telemetry, memory, and charging component)
- The energy capacity of the battery

Medtronic has developed a statistical model for device longevity that accounts for each of these factors, and has validated the model with real time clinical performance. During the development of its products, Medtronic engineers characterize device longevity using this model. Testing begins during development and continues after market release to ensure the accuracy of device longevity estimates.

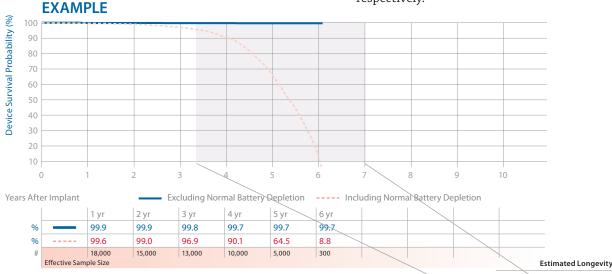
Using Survival Curves to Assess Longevity

The survival curves in the Product Performance Report represent the composite experience of thousands of devices over a wide range of programming options and patient use conditions. While the curves are useful for understanding the overall performance of a population of devices, they cannot be used to accurately predict the longevity of a specific device in a specific patient. To get a longevity prediction for a specific device, the longevity model must be used. The model is available by contacting Medtronic's Technical Services Department.

Because the survival curves are an aggregate result, the Reference pages in the Product Performance Report include several longevity estimates for a range of use conditions. These longevity estimates are mean values calculated for the parameters given. This range of longevity estimates can be compared to the survival curve including normal battery depletion to assess the overall clinical performance of a device model against the original longevity estimates.

If most of a device model's population is being used at nominal parameters and conditions, the time at which the survival curve including normal battery depletion equals 50% should approximate the midpoint in the range of longevity estimates.

If devices tend to be used at conditions that consume more or less energy than nominal, then the time at which the survival curve equals 50% should tend toward the lower or higher end of the range of longevity estimates, respectively.



This figure shows the range of the estimated longevity values given in the reference chart in relation to the survival curve. The range of longevity is representative of a typical range of use values, not the absolute minimum or maximum longevities possible. In this example, the survival curve including normal battery depletion is approaching 50% at approximately the mid-point of the range of longevity values.

AT500 Pacing System Follow-Up Protocol

Purpose of This Information

This article is intended to provide clinical guidance regarding follow-up practice and patient management when the AT500 battery voltage approaches the Elective Replacement Indicator (ERI) level of 2.6 volts.

Background

Many AT500 pacing systems are now reaching their ERI voltage level (2.6 volts). This is expected since the battery used has an approximate longevity of 5-6 years under normal conditions (100% DDD pacing, 3 volts, 0.4 ms).

Technical Services has received reports of battery voltage levels below end of life (EOL of 2.2 volts) where EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary. It is important for physicians and allied professionals to understand battery depletion characteristics between ERI and EOL so that they, in turn, can understand how this affects management of follow-up visits for the AT500 as this device nears the end of its expected longevity.

AT500 Battery and Longevity Information

In contrast to other IPGs, the AT500 does not change its mode, stimulation rate, or any other parameter when the battery voltage drops below the ERI level of 2.6 volts (with or without magnet applied). The Threshold Margin Test (TMT) is also not available.

Therefore, it is not possible to perform transtelephonic assessment of AT500 battery status. This must be done during an in-clinic follow-up session. A warning will be displayed on the Quick Look screen at the beginning of a programmer (follow-up) session when the ERI battery level occurs. The measured battery voltage will also appear on the programmer display and on printouts.

Battery depletion curves are shown in Figure 1, with special focus on device longevity when programming EGM prestorage ON or OFF.

Medtronic's review of ongoing AT500 battery life test data matches our original longevity modeling and so meets our expectations. However, when using longer durations between follow-up periods (> 3 months), clinicians should consider the following in setting their remaining longevity expectations.

- Enabling the "EGM Pre-storage On" capability will increase current and reduce device longevity by approximately 9 days for each month pre-storage is ON
- Longevity decreases with an increase in pacing rate, an increase in pacing amplitude or pulse width, a decrease in pacing impedance, a higher ratio of paced to sensed events, or extended use of the Atrial Preference Pacing, EGM prestorage, or Holter Telemetry features

Recommendations

Follow-up frequency should always be accelerated as devices reach ERI voltage levels to ensure device explant/replacement occurs prior to end of life voltage levels. With the wide variety of follow-up schedules being used, Medtronic recommends a 3-month follow-up frequency for the AT500 pacing systems. This is particularly important for patients in whom EGM prestorage is programmed ON, or higher outputs and/or pacing rates are necessary.

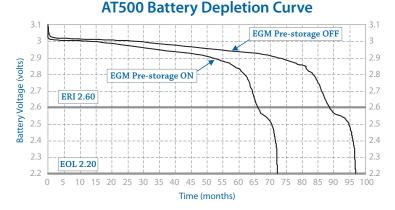


Figure 1

AT500 battery depletion curve for common parameter settings of DDDR, LR 70 ppm, UR 120 ppm, 100% pacing, Atrial - 2 V, 0.4 ms, 600 ohms, Ventricle - 2 V, 0.6 ms, 900 ohms, and EGM Pre-storage ON versus OFF.

Insertion of the Lead into the Device

The implantable system consists of a pulse generator and at least one lead. The system operation depends on proper electrical and mechanical operation. With the advent of internationally recognized connector standards, the challenge of ensuring proper mechanical fit between the lead and device connectors has been simplified, although the international connector standard does not address all aspects of the procedure for connecting a lead to the device.

If the lead connector is not fully installed, oversensing may result as described in the connector problems section of the performance note, "Clinical Management of High Voltage Lead System Oversensing."

Performing the following steps can be used for each lead connection during the implant procedure:

1 Insert the torque wrench into the appropriate setscrew. For easier lead insertion, insert the lead closest to the device first.

- 2 Look down the connector port to verify that the port is not obstructed. If the port is obstructed, retract the setscrew to clear the bore. Take care not to disengage the setscrew from the connector block.
- 3 Push the lead into the connector port until the lead pin is clearly visible beyond the setscrew block.
- 4 Hold the lead in position while tightening the setscrew until the torque wrench clicks.
- **5** Tug gently on the lead to confirm a secure fit.

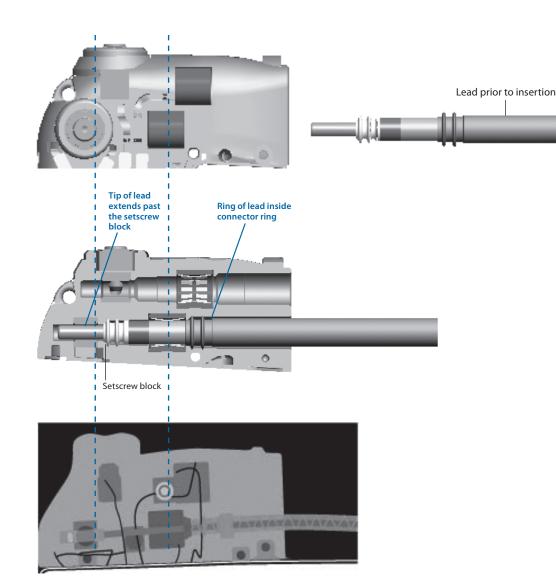
Current publications may provide additional information on implant procedures used by others, e.g., radiographic evaluation of the terminal pin beyond the terminal post.1

¹ Pickett RA III, Saavedra P, Ali MF, Darbar D, Rottman JN. Implantable cardioverter-defibrillator malfunction due to mechanical failure of the header connection. J Cardiovasc Electrophysiol. September 2004;15(9):1095-1099.

Connector module before lead insertion

Cross-section of connector module after lead fully installed

X-ray image of connector module after lead fully installed



GEM II DR/VR and GEM III DR/VR/AT ICD Battery Discharge Behavior

Medtronic manufactured and utilized a unique lithium/ silver vanadium oxide battery in the GEM II/III family of ICDs. This battery has a distinctive voltage discharge with two regions of constant voltage at 3.2 volts and 2.6 volts.

The battery discharge curve (see curve below) is characterized by a significant decrease in the battery voltage approaching middle of life (MOL), followed by a plateau (MOL to ERI) where the battery voltage remains around 2.6 volts. The transition to the plateau could be easily misinterpreted as the battery rapidly approaches ERI, which occurs at 2.55 volts, when the battery may in fact have several years remaining until ERI.

It is important to understand that this battery voltage decrease in the GEM II/III family of ICDs is a normal

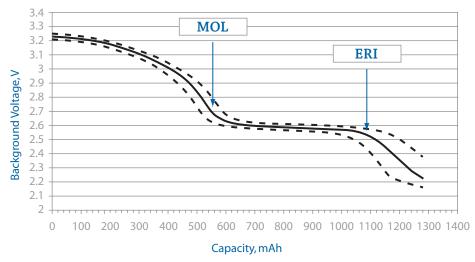
characteristic of the battery function in these devices and should not create a need for additional follow-up or monitoring.

As a general rule of thumb, the longevity from implant to MOL = MOL to ERI.

The design of the battery in subsequently released models has been modified to present a more linear battery discharge curve.

If you are concerned about early ERI in your patient's device, you can utilize the battery trend measurements stored in the save-to-disk file, which can be accessed and interpreted through the Medtronic Technical Services at 1 (800) 723-4636.

GEM II/III Battery Discharge Curve



General Follow-Up and Replacement of ICD Leads

Implanted leads operate in the challenging biochemical environment of the human body and the body's response to foreign objects. Implanted leads are also subject to mechanical stresses associated with heart motion, body motion, and patient anatomy.

In this environment, pacemaker and defibrillation leads cannot be expected to last forever. Unlike implantable cardioverter defibrillators (ICDs), a lead's longevity cannot be predicted nor are there simple indicators that a lead is approaching the end of its service life. The determination that a lead may be approaching end of service life requires follow-up of the chronically implanted lead and thorough evaluation of lead integrity at ICD replacement.

Follow-Up of Chronically Implanted Leads

The frequency of follow-up for ICD patients will depend on a number of factors including the patient's medical condition, ICD system implant time, hospital/clinic follow-up practice, and Medicare guidelines. In all cases, it is important to assess the functionality of the ICD system and the integrity. For newly implanted leads, it is beneficial to establish a baseline of chronic performance parameters once the lead has stabilized, generally within 6 to 12 months after implant. These performance parameters should include pacing and sensing thresholds and impedance. During routine patient follow-up, these procedures can be used to evaluate lead integrity.

- Measure pacing and sensing threshold and compare to the chronic baseline. Significant increases or decreases may be indicative of lead failure, dislodgement, perforation, exit block, etc.
- Measure pacing impedance where possible and compare to the chronic baseline. Decreases of 30% or more or pacing impedances below 200-250 ohms may be indicative of insulation failure. Sudden and significant increases in pacing impedance may be indicative of conductor fracture.
- High voltage lead circuit impedance should be between 10-75 ohms at system implant. Chronic measurements below 10 and above 200 ohms may be indicative of high voltage lead circuit failure.
- Carefully review ECGs or the nonsustained detection log on Medtronic ICDs for indications of pacing and/or sensing abnormalities such as oversensing, undersensing, and loss of capture
- Elicit and investigate any patient complaints/symptoms that may be suggestive of potential lead failure

Where routine follow-up indicates, additional tools should be used to further evaluate performance. Tools include radiographic data, ICD electrograms, ICD Patient Alert and performance information from the System Longevity Study (SLS).

The final decision on the functional integrity and continued use of an implanted lead must be a matter of medical judgment based on these factors as well as specific patient conditions.

General Criteria for Lead Replacement

The evaluation of a chronically implanted lead is an important part of the decision to continue to use the lead with a new ICD. However, these results alone do not necessarily predict the future integrity of that lead. With the expected longevity of today's ICDs varying between approximately 5 and 10 years, a physician replacing a device should consider a number of factors, including those listed below.

Factors that should be considered in a decision to replace or continue to use include:

- Pacing and sensing thresholds should be evaluated for the potential to maintain acceptable levels
- Pacing impedance should be measured. Bear in mind that pacing impedance below 250 ohms results in excessive battery current drain, which may seriously compromise ICD longevity, regardless of lead integrity.
- The physical appearance of the lead should be examined for insulation cracks, breaches, or other indications of lead wear or degradation
- Medtronic System Longevity Study data should be referenced. Actuarial survival of the lead and the observed lead failure mechanisms are specific factors to consider. Use of a new lead should be considered if failure mechanisms suggest an increased time dependency as suggested in the shape of performance curve for the specific lead model.
- Current publications may provide additional information on the clinical management of leads.¹⁻³ Ultimately, the decision to replace an implanted lead involves medical judgment.
- ¹ Hauser RG, Cannom D, Hayes DL, et al. Long-term structural failure of coaxial polyurethane implantable cardioverter defibrillator leads. *PACE*. June 2002;25(6):879-882.
- ² Ellenbogen KA, Wood MA, Shepard RK, et al. Detection and management of an implantable cardioverter defibrillator lead failure: incidence and clinical implications. *J Am Coll Cardiol*. January 1, 2003;41(1):73-80.
- ³ Hauser RG, Kallinen LM, Almquist AK, Gornick CC, Katsiyiannis WT. Early failure of a small-diameter high-voltage implantable cardioverter-defibrillator lead. *Heart Rhythm*. July 2007;4(7):892-896.

Clinical Management of High-Voltage Lead System Oversensing

Appropriate sensing by an ICD system refers to the sensing of cardiac events that may or may not require therapy delivery. ICD systems must sense relatively large QRS complexes while avoiding sensing of smaller T waves, yet continue to sense often small variable amplitude ventricular fibrillation. Thus, ICD systems attempt to dynamically adjust sensing of electrical events and discriminate between them based on detection algorithms and programmed settings.

Inappropriate sensing can occur when an ICD system classifies events of non-cardiac origin as QRS/VF events, or senses and counts T and far-field P waves as ventricular depolarizations. This is often referred to as "oversensing," and may result in delivery of inappropriate high-voltage therapies. This is due, in part, to the desire to err on the side of delivering lifesaving high voltage therapy rather than withholding it. Thus, an ICD system that is experiencing oversensing issues will continue to deliver therapeutic shocks as required, but may also subject the patient to unnecessary shocks.

Oversensing can be difficult to manage, in that the precipitating cause of the oversensing can be problematic to isolate. Oversensing can be caused by many factors, including myopotentials/farfield sensing, electromagnetic interference, T wave sensing, connector issues, incomplete or complete conductor fractures, and insulation breaches. While the individual physician must exercise medical judgment in determination of appropriate clinical management of ICD systems, the chart below may assist in the process of causal factor differentiation and possible intervention.

Phenomenon	Causal Factors	Characteristics	Management/Comments
Myopotentials/ Far-field sensing	Diaphragmatic muscle potentials in breathing, wide tip-to-ring (coil on integrated bipolar leads) spacing	Nonphysiological sensed event on EGM, which may confuse detection potentially resulting in false positive shocks	Check R waves for deterioration. Reprogram sensitivity. Try repositioning lead. Consider change-out to true bipolar lead, or if true bipolar lead in use, one with closer tip-to-ring spacing than current lead.
EMI (Electro-Magnetic Interference)	Arc welders, electrical generators, store walk-through security scanners, poorly insulated electrical equipment	Multiple and consecutive short intervals (< 140 ms) independent of underlying sinus beats. Associated with proximity to the EMI source.	Avoid EMI areas. True bipolar leads less susceptible.
T-wave sensing	Drugs, ischemic tissue, exercise, Long QT syndrome, electrolyte imbalance	Sense markers seen on EGM related to T wave. False positive detection.	Check for R wave deterioration and characteristics. If R wave > 3.0 mV, reprogram sensitivity. If R wave < 3.0 mV, reposition/replace lead. Address causal factor (e.g., drugs [if appropriate/medically viable]).
Connector problems	Loose setscrew, cross-threaded setscrew, incomplete lead insertion into header	This is an acute phenomenon seen within 6 months of implant (usually sooner)	Requires invasive check of connections. May be reproducible with pocket manipulation.
Incomplete conductor fracture	One or more filars of a multifilar conductor fracturing while leaving enough filars intact to provide a conduction circuit	Characterized by chaotic oversensing related to motion of the fracture site	Check EGMs and x-rays. Manipulate lead at suspected fracture site if possible as a provocative test. If confirmed, replace lead.
Lead insulation breach	Cuts, tears, metal ion oxidization, abrasion, cold flow, environmental stress cracking	Characterized by cyclical and/or erratic, intermittent, spontaneous oversensing; often post-pace or post-shock can cause false positives	Replace lead. If acute, usually secondary to implant damage/replacement damage. If late, material characteristic.
Oversensing during interrogation with programming head (not wireless telemetry) with complete lead fracture	Interrogation with a programming head in combination with complete lead fracture that creates an open circuit can induce noise on the sensing circuitry inside the ICD can	Nonphysiologic sensed event on EGM. If detection is enabled during interrogation, oversensing may result in inappropriate therapy.	Quickly remove the programming head. CANCEL the interrupted interrogation and manually load the software for the specific device model. Reposition the programmer head over the device and immediately select SUSPEND. Device will resume detection when programming head is removed, or when RESUME is selected. Replace lead.

Technical Services is available at all times to advise clinicians in the troubleshooting and management of Medtronic products. For assistance in the United States, please call 1 (800) 723-4636. In other countries, please contact your local Medtronic representative.

Tests and Observations for Clinical Assessment of Chronic Pacing Leads

Test/Observation	Possible Insulation Failure	Possible Conductor Failure	Possible Other System Failure	Effect on Test/ Observation
Pacing Impedance (Telemetered or Measured Invasively)	Sudden and Significant Decrease	Sudden and Significant Increase	Dislodgement	
Pacing Thresholds (Telemetered/Programmed or Measured Invasively)	Sudden and Significant Increase, Especially in Bipolar System	Sudden and Significant Increase	Dislodgement	Increase Increase Increase
Electrograms (Telemetered or Measured Invasively)	Sudden and Significant Decrease in Amplitudes and/or Slew Rates for P and/or R Waves	Sudden and Significant Decrease or Disappearance of Amplitudes and/or Slew Rates for P and/or R Waves	Dislodgement	Decrease Decrease .Decrease
Waveform Analysis (Oscillographs of Pacer Artifact from ECG Electrodes)	Sudden Increase in Ratios of Leading-Edge Voltages to Trailing-Edge Voltages (i.e., over 25% increase)	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)	Improper IPG/Lead Connection	Intermittent or No Pacer Artifacts (Even in Asynchronous Mode)
Radiographs (Post-Implant, Recent, Current)	Not Discernible	Visual Observation of Conductor/Connector/ Electrode Fracture (Sometimes Discernible)	Dislodgement or Perforation. Improper IPG/Lead Connection.	Sometimes Discernible
Visual Inspection (Invasive)	Insulation Breach and/or Degradation, or Ligature Cut-Through	Not Easily Discernible	Connector Defect or Connector Pulled Apart. Improper IPG/ Lead Connection.	Sometimes Discernible
Pectoral Muscle Stimulation	Sudden Onset, Especially in Bipolar System		Connector Defect in Bipolar or Unipolar. Hypersensitivity to Unipolar Pulse Generator Can. Anti-Stim Coating or Protection Deficient.	
Phrenic Nerve/ Diaphragmatic Stimulation	Sudden Onset in Bipolar or Unipolar Systems		Perforation or Displacement of Atrial Lead (Phrenic Nerve)	
Pacemaker ECG Stimulus Artifact Size and Morphology Change (May Not Be Possible with Digital ECG)	Sudden Onset and Significant Change, Especially in Bipolar System (Increase in Size)	Sudden Changes, Usually a Decrease in Size	Perforation or Dislodgement. Connector Defect. Improper IPG/ Lead Connection.	Sometimes Discernible
Oversensing (Intermittent or Continuous)	Sudden Onset, Especially in Bipolar Systems		Physical Contact between the Electrode(s) on the Lead and that of Another Lead. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Undersensing (Intermittent or Continuous)	Sudden Onset in Either Unipolar or Bipolar Systems	Sudden Onset in Either Unipolar or Bipolar Systems	Dislodgement or Perforation. Infarct at Electrode Site. Electrolyte Imbalance. Inappropriate IPG Parameter Setting. Improper IPG/Lead Connection.	Sometimes Discernible
Loss of Capture	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	See "Pacing Thresholds" Above	

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Mailer Kits Available for Returning Product

Medtronic urges all physicians to return explanted products and to notify Medtronic when a product is no longer in use, regardless of reason for explant or removal from use. The procedures for returning products vary by geographic location.

Mailer kits with prepaid US postage are available for use within the United States to send CRT, ICD, IPG, and leads to Medtronic's CRDM Returned Product Analysis Lab. These mailers are sized to accommodate the devices and leads from a single patient or clinical event and are designed to meet US postal regulations for mailing biohazard materials.

If the product being returned is located outside the United States, please contact your local Medtronic representative for instructions.

Medtronic also requests the return of devices from non-clinical sources, such as funeral homes, and will assume responsibility for storage and disposal of the product once received.

Mailer kits can be obtained by contacting the Returned Product Lab.

CRDM Returned Product Analysis Laboratory

Phone: 1 (800) 328-2518, ext. 44800 Email: crdm.returnedproduct@medtronic.com



www.medtronic.com

World Headquarters

Medtronic, Inc. 710 Medtronic Parkway Minneapolis, MN 55432-5604 USA

Tel: (763) 514-4000 Fax: (763) 514-4879

Medtronic USA, Inc.
Toll-free: 1 (800) 328-2518
(24-hour technical support for physicians and medical professionals)

Europe

Medtronic International Trading Sàrl Route du Molliau 31 CH-1131 Tolochenaz Switzerland

Tel: (41 21) 802 7000 Fax: (41 21) 802 7900

Canada

Medtronic of Canada Ltd. 6733 Kitimat Road Mississauga, Ontario L5N 1W3

Tel: (905) 826-6020 Fax: (905) 826-6620 Toll-free: 1 (800) 268-5346

Asia Pacific

Medtronic International, Ltd.
16/F Manulife Plaza
The Lee Gardens, 33 Hysan Avenue
Causeway Bay
Hong Kong
Tel: (852) 2891 4456

Fax: (852) 2891 4456 enquiryap@medtronic.com

Latin America

Medtronic USA, Inc. Doral Corporate Center II 3750 NW 87th Avenue Suite 700 Miami, FL 33178

USA

Tel: (305) 500-9328 Fax: (786) 709-4244

